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FROM QUANTUM TO CLASSICAL INTERACTIONS BETWEEN A
FREE ELECTRON AND A SURFACE

by Peter James Beierle

A DISSERTATION

Presented to the Faculty of
The Graduate College at the University of Nebraska
In Partial Fulfillment of Requirements
For the Degree of Doctor of Philosophy

Major: Physics and Astronomy

Under the Supervision of Professor Herman Batelaan

Lincoln, Nebraska

November, 2017

FROM QUANTUM TO CLASSICAL INTERACTIONS BETWEEN A
FREE ELECTRON AND A SURFACE

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University of Nebraska, 2017

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Quantum theory is often cited as being one of the most empirically validated theories in terms of its predictive power and precision. These attributes have led to numerous scientific discoveries and technological advancements. However, the precise relationship between quantum and classical physics remains obscure. The prevailing description is known as decoherence theory, where classical physics emerges from a more general quantum theory through environmental interaction. Sometimes referred to as the decoherence program, it does not solve the quantum measurement problem. We believe experiments performed between the microscopic and macroscopic world may help finish the program. The following considers a free electron that interacts with a surface (the environment), providing a controlled decoherence mechanism.

There are non-decohering interactions to be examined and quantified before the weaker decohering effects are filtered out. In the first experiment, an electron beam passes over a surface that's illuminated by low-power laser light. This induces a surface charge redistribution causing the electron deflection. This phenomenon's parameters are investigated. This system can be well understood in terms of classical electrodynamics,

and the technological applications of this electron beam switch are considered. Such phenomena may mask decoherence effects.

A second experiment tests decoherence theory by introducing a nanofabricated diffraction grating before the surface. The electron undergoes diffraction through the grating, but as the electron passes over the surface it's predicted by various physical models that the electron will lose its wave interference property. Image charge based models, which predict a larger loss of contrast than what is observed, are falsified (despite experiencing an image charge force).

A theoretical study demonstrates how a loss of contrast may not be due to the irreversible process decoherence, but dephasing (a reversible process due to randomization of the wavefunction's phase). To resolve this ambiguity, a correlation function on an ensemble of diffraction patterns is analyzed after an electron undergoes either process in a path integral calculation. The diffraction pattern is successfully recovered for dephasing, but not for decoherence, thus verifying it as a potential tool in experimental studies to determine the nature of the observed process.

Preface

The experimental work “A Low-Power Optical Electron Switch” described in Chapter 3 has been published in *Journal of Physics D: Applied Physics*

The experimental work “Experimental Test of Decoherence Theory using Electron Matter Waves” described in Chapter 4 has been submitted for publication in *Physical Review Letters*.

The theoretical work “Spatial Correlation in Matter Wave Interference as a measure of Decoherence, Dephasing and Entropy” described in Chapter 5 has been submitted for publication in *Physical Review A*.



We appreciate funding support from the National Science Foundation and the
Department of Education.

Acknowledgments

I would like to thank my research advisor Herman Batelaan for his graciousness in giving me the precious opportunity to work and learn under his mentorship whilst exploring and contributing to a subject that I find meaningful. I appreciate the patience, passion, and wisdom that you have delivered in this process.

I would like to thank the members of my Ph.D committee, Herman Batelaan, Kees Uiterwaal, Mathias Fuchs, Christian Binek, and Reina Hayaki. Your contribution in providing feedback was quite useful in improving the quality of this product.

Thank you to my group members Herman Batelaan, Roger Bach, Wayne Huang, Maria Becker, Eric Jones, Derek Ruffner, Maaneli Derakhshani, Liyun Zhang, Phillip Wiebe, Sam Kemerati, and Zilin Chen. The many instances of inciteful collaboration has been very valuable. A special thanks to Roger Bach and Wayne Huang for their contribution for their work in Chapter 3, as well as Liyun Zhang and Zilin Chen for their contribution to the work in Chapters 4 and 5.

Surface preparation and characterization was very important in this work. Thank you to those who provided me helpful advice and assistance; including Keith Foreman, George Peterson, Vijay Singh, Uday Singh, Stephen Ducharme, Kishan Sinha and Sy-Hwang Liou.

Thank you to my classmates and friends who fought alongside me to conquer the graduate school program. The endlessly long hours of studying and problem solving together was much appreciate

I would like to thank my previous teachers and mentors in science, particularly Linda Walters-Wallace, Gregory Wallace, Kimberly Skinner, and Xu Du. I would not be at this position without your early fostering of my curiosity and interest in physics, and opportunities that you granted me through your guidance.

Last, but not least, thank you to my wife Yao, my parents Peter and Debe, and my siblings Stephanie, Rebecca and Michael for your love and support and has been crucial to my success. I greatly appreciate your sacrifices, care and understanding.

TABLE OF CONTENTS

Preface	iv
Acknowledgments	v
Chapter 1: Introduction	1
1.1 Motivation	1
1.2 Summary of Chapters	7
1.2.1 Electron-Optical Switch	8
1.2.2 Decoherence Experiment	8
1.2.3 Dephasing vs Decoherence	9
1.3 Chapter 1 Bibliography	9
Chapter 2: Theory	10
2.1 Introduction	10
2.2 Classical Electron Propagation over a Conducting Surface	11
2.2.1. Classical Image Charge	11
2.2.2. Deflection from Induced Light Potential	13
2.3 Quantum Electron Propagation in Free Space	14
2.4 Coherence of Matter Waves	17
2.4.1 Partial Coherence and Density Matrix Formalism	17
2.4.2 Relationship between Coherence and Observed Interference	19
2.4.3 Coherence Length for a Collimated Matter Wave	21
2.4.4 Comparison of Coherence Measures (Transverse Coherence Length and Visibility)	24
2.5 Decoherence Theory	27
2.5.1 Zurek's Formalism	27
2.5.2 Density Matrix and Coherence	29
2.6 Mechanisms of Decoherence Due to Conducting Surfaces	31
2.6.1 Free Electron-Surface Decoherence Models	32
2.7 Decoherence vs Dephasing	37
2.7.1 Correlation Function	38
2.8 Chapter 2 Bibliography	40
Chapter 3: Optical Electron Switch	42
3.1 Introduction.....	42
3.2 Setup and Procedure.....	43
3.3 Measurements and Results.....	46
3.5 Conclusion and Outlook	50
3.6 Chapter 3 Bibliography	51

Chapter 4: Decoherence Experiment	52
4.1 Introduction.....	52
4.2 Experimental Setup	53
4.3 Analysis	55
4.4 Comparison between Experimental Results and Physical Models	58
4.5 Outlook and Conclusion.....	61
4.6 Chapter 4 Bibliography.....	63
Chapter 5: Dephasing vs Decoherence	65
5.1 Introduction.....	65
5.2 Path Integral Simulation with Dephasing and Decoherence	67
5.3 Spatial Correlation Method	73
5.4 Conclusion and Outlook	80
5.5 Chapter 5 Bibliography.....	81
Chapter 6: Conclusions and Outlook.....	82
6.1 Optical-Electron Switch	82
6.2 Decoherence Experiment.....	82
6.3 Dephasing vs. Decoherence.....	85
6.4 Chapter 6 Bibliography.....	86
Appendix A: Matlab Code for Image Analysis	88
A.1 Matlab Code for Decoherence Experiment Analysis	88
A.2 Visualization of Loss of Coherence.....	99
Appendix B: Matlab Code for Coherence Length Calculation I	100
Appendix C: Theoretical Method for Classical Beam Propagation and Calculation of Transverse Coherence Length	118
C.1 Classical Simulation Perpendicular to the Surface	118
C.2 Quantum Decoherence Simulation Parallel to the Surface	121
C.3 Fortran Code for Classical Beam Propagation and Coherence Propagation	125
Appendix D: Surfaces & Grating; Mount Design and Prep	140
D.1 Summary	140
D.2 Surface and Grating Mounts	140
D.3 Surface Preparation	144
D.4 Pitch Alignment	147
D.5 Effects of Lensing	148
D.6 Appendix D Bibliography.....	154

Appendix E: Programs for Dephasing vs Decoherence	155
E.1 Decoherence and Dephasing Path Integral Program Version 1.....	155
E.2 Dephasing Path Integral Program Version 2	169
E.3 Decoherence Path Integral Program Version 2	181
E.4 Matlab Code for Entropy Calculation	193
E.5 Matlab Code for Correlation Calculation	195
List of Figures and Tables.....	196

CHAPTER 1

INTRODUCTION

1.1 Motivation

Particle-wave duality is the bedrock of quantum theory, and can be most famously realized in the controlled electron double slit experiment, where an individual electron “interacts” with two neighboring slits (figure 1.1a, also known as a double slit), then travels to a phosphorous screen “detector” which lights up in an individual location indicating the position in which the electron has landed (the backstop detector in figure 1.1) [1]. If multiple electrons followed classical Newtonian motion, they would statistically form a pattern at the detector resembling that of the sum two smooth Gaussian-like distributions corresponding to the electron travelling through either the first or the second slit (figure 1.1b). However, successive iterations of such electron events result in a buildup of a histogram (figure 1.1 i-v) on the detection screen resembling an interference pattern (figure 1.1c). This is interpreted to mean that each electron originally behaved as a wave and the interaction is that of wave diffraction through both slits, thus constructive and destructive interference from both sources occurs. It is this behavior which prompts us to implement the Schrödinger equation to explain the dynamics, where the electron propagates from a superposition of two separate position states.

Yet when we detect or measure the electron at the phosphorous screen, we only ever observe the electron at one position, never in multiple locations or a continuum of locations (hence its particle behavior). It is not obvious why this would be the case given the prior description of the evolution of the quantum state. Given that one can compute a

nonzero probability of the electron being at two spatially separate positions at a detector from the electron's wave function, it would seem reasonable to expect to observe this; but this does not occur. Bohr indeed admits that, within the Copenhagen interpretation of quantum theory, a measurement of the state changes the state of the system which cannot be described by quantum mechanics [2]. Thus, there is an additional measurement axiom in which the wave function collapses to one or more states according to the Born Rule. But it is not clear under what conditions a "measurement" is said to occur. For example, a particle in a bubble chamber has presumably undergone measurement, as only single particle tracks are observed. On the other hand, should the same particle travel through free space, a dilute gas, or in an electromagnetic field, we may or may not defer to regarding to a quantum measurement collapse, or consider the system undergoing unitary evolution in quantum mechanics. The physical environment which the particle interacts with is not sufficient to a priori determine what type of evolution to invoke. These are the central issues behind what is known as "the quantum measurement problem" [3].

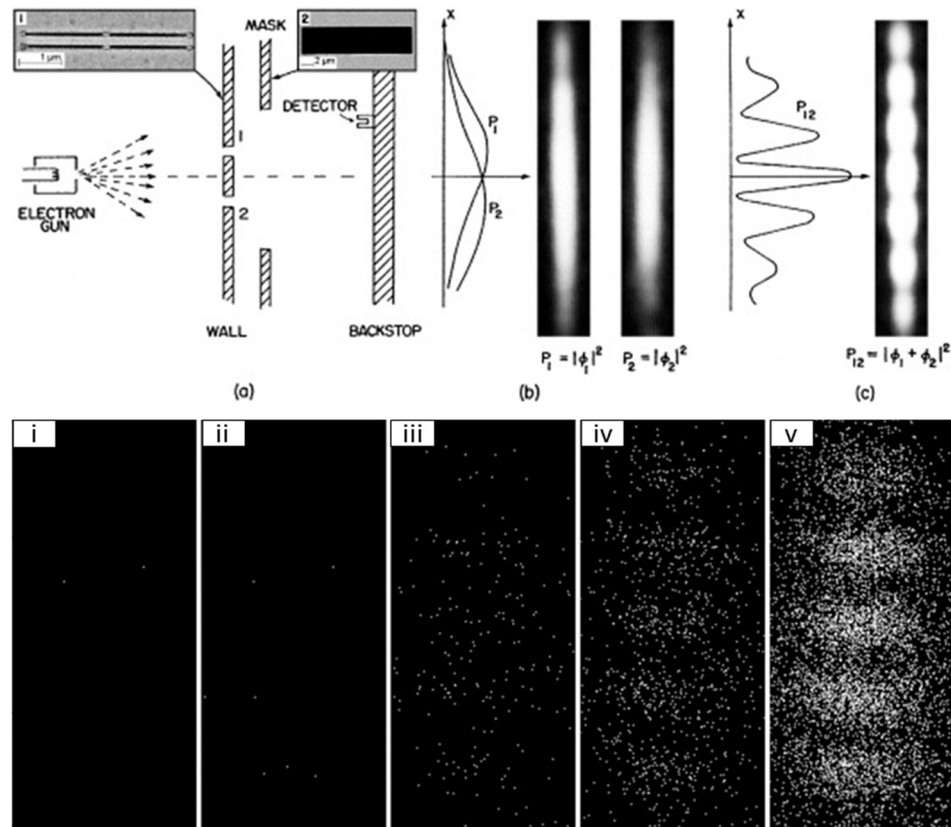


Figure 1.1: Double Slit Diffraction: Wave Interference vs Classical Distribution (images and experiment from Roger Bach et al. in [1]). An electron gun fires individual electrons through two slits (double slit (a)) and land on the backstop detector. After successive buildup of each electron at the detector (i-v) an interference pattern is formed (v and (c)) rather than the classical sum of travelling through the two individual slits (b). decoherence aims to predict how through quantum interaction (via entanglement) with an external environment an electron's motion can transition the observed probability distribution from quantum interference $|\phi_1 + \phi_2|^2$ (c) to more classical statistical behavior $|\phi_1|^2 + |\phi_2|^2$ (b).

To take the double-slit experiment further, Richard Feynman expanded the thought experiment to include a detector which monitors which slit the electron passes through [4]. With this addition, the distribution of electrons that is recorded at the detector is no longer an interference pattern, but the sum of two smooth Gaussian-like distributions. It seems that this detector disrupted the electron's behavior such that it has

transitioned from quantum to classical mechanics. The theory of decoherence sets out to describe why and how this transition occurs.

Taking an emergent point of view, it seems reasonable to claim that all of classical theory must be a subset of quantum theory, and is just a special case (as Galilean classical relativity can be thought of as the special case of Einsteinian special relativity in the limit of $v/c \ll 1$). Similarly, for matter if you take the de Broglie Wavelength of an object $\lambda_{dB} = h/(mv)$ in the limit of large mass, then the wavelength would resultantly be exceedingly small. Richard Feynman eloquently illustrates this concept in a lecture contained in the book Six Easy Pieces [5], where one imagines exchanging the electrons in the double-slit experiment with bullets (see Figure 1.2). He argued that if were one to fire these coherent bullets through the double slit, then the far field histogram pattern one might hope to observe would be in principle that of an interference pattern, but because of the very small wavelength of these bullets, the distance between of such interference fringes would be so small that in practice no detector could hope to resolve them. Thus, the resulting pattern would be a smeared distribution. It is in this way it is argued that the Copenhagen interpretation remains consistent.

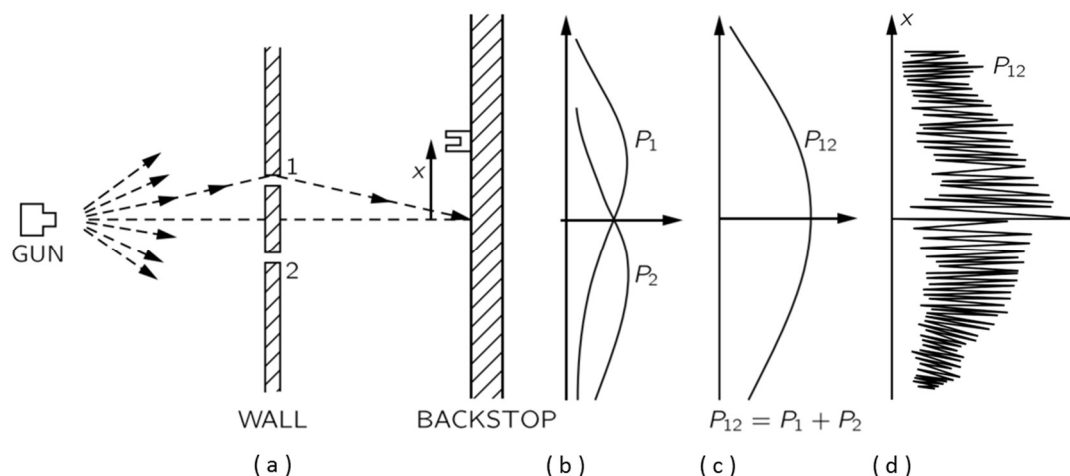


Figure 1.2: Double Slit Experiment With Classical Bullets (from Feynman's Six Easy Pieces [5]). According to the Copenhagen interpretation of quantum mechanics, because the deBroglie wavelength of a high momentum object (like a classical bullet) is so small, any interference pattern produced in a macroscopic double-slit like experiment would result in a fringe periodicity too small to be resolved (d) and as a result the final observed distribution will be smeared out (c).

Is this a sufficient story however? Does this imply that if the momentum of the object is sufficiently small, as in a slow electron, then it will always exhibit quantum behavior such as the superposition principle? Are there no other factors to consider except for momentum?

The Decoherence Program starts with ordinary quantum theory and has found that a quantum system coupled (i.e. entangled) by even a small amount with an environment can result in a large transfer of the wave's phase information from the system to the environment. This loss results in the loss of coherence between different orthogonal states of the wave function, which is precisely what allows them to interfere in the first place. Thus if such an interaction is permitted to occur comparable to the timescale called the decoherence time (also known as the decorrelation time) [6], then interference is not observed; and the system reduces to classical behavior. For the case of the electron and

the double slit, this theory specifies how the statistical distribution of the electron can be changed from the interference pattern (figure 1.1 c) to the addition of two smooth distributions (figure 1.1 b). Symbolically, this means;

$$|\phi_1 + \phi_2|^2 \xrightarrow{\text{decoherence}} |\phi_1|^2 + |\phi_2|^2. \quad (1.1)$$

One ought to ask how long it takes for a wave packet to reduce to a single position state. This is particularly of interest in the classical world of macroscopic parameters, such as the prior double slit bullet example. To take a similar scenario, Wojciech H. Zurek [7] considered a free particle of mass 1 g at room temperature that is coherently split into a superposition of two distinct positions that is separated by a distance $\Delta x = 1 \text{ cm}$. The state is considered weakly coupled to an environment (or bath) of quantum harmonic oscillators. For such a case, the decorrelation timescale θ of this spatial superposition can be compared to the timescale τ of energy dissipation from the particle to the environment by $\theta = \tau \left[\left(\hbar / \sqrt{4mkT} \right) / \Delta x \right]^2$.

Substituting in the aforementioned macroscopic parameters yields a ratio of these two timescales of $\theta/\tau \sim 10^{-40}$. For reference, this means that even if one could ideally build an experimentally isolated system such that the timescale in which energy dissipates from the particle to the outside environment is that of the age of the universe ($\tau \sim 5 \times 10^{17} \text{ s}$), then the spatial superposition of our 1 g particle would still very quickly decay on the timescale of $\theta \sim 5 \times 10^{-23} \text{ s}$. This is, for comparison, of the order of the typical strong nuclear interaction [8]. This provides some explanation for why we don't see the such bizarre quantum phenomena in the ordinary world, and why we need not

worry if Schrödinger's torturous experiments can put our feline friends in a superposition limbo.

The goal of the decoherence program is to not only explain why macroscopic objects do not exist in quantum superposition within the framework of quantum theory, but also how microscopic objects such as electrons can lose their quantum behavior. Can environmental interactions described by decoherence make predictions about the loss of "quantumness" of the electron (by, for example, controlling the strength of this environmental interaction)?

1.2 Summary of Chapters

The following chapters feature three projects related to the coherent electron beam interaction with conducting and semiconducting surfaces. Chapter 2 provides an extensive introduction to the theoretical background and tools this work is grounded upon. This includes well established concepts such as image charge potentials which we use to understand our data, as well as competing decoherence models we sought out to directly test. Chapter 3 details the development and characterization of an electron beam switch which is controlled by the field produced by a surface charge distribution produced by a low-power optical laser. Chapter 4 involves the experimental test of decoherence theories by bringing gold and n -doped silicon surfaces near an electron beam undergoing diffraction through a nanofabricated grating. Chapter 5 presents a theoretical investigation of the differences between decoherence and dephasing in matter wave propagation (such as electron waves). It is also shown how it is possible to distinguish between dephasing and decoherence processes that may distort the

interference pattern in the far field. Finally, Chapter 6 gives concluding remarks regarding this work and an outlook on what opportunities this work leads to.

1.2.1 Electron-Optical Switch

A beam of 4 keV electrons passes by a metallic surface, which is illuminated by a low-power continuous laser beam (typically 10 mW and 658 nm) [9,10]. These electrons experience a force that deflects the beam's direction by $550\text{ }\mu\text{rad}$ when the electrons are approx. $10\text{ }\mu\text{m}$ from the surface. This “electron switch” has a response time of approximately $6\text{ }\mu\text{s}$. The deflection of the electron beam is shown to decrease as the beam's distance from the wall increases, giving an observed electron deflection as far as $200\text{ }\mu\text{m}$ from the surface. This switching mechanism is shown to be robust, as it is demonstrated for various optical wavelengths and surfaces. This type of electronic-free electron manipulation has potential use in electron beam microscopy (EBM) and electron beam lithography (EBL).

1.2.2 Decoherence Experiment

A controlled decoherence environment is studied experimentally by free electrons interacting with semi-conducting and metallic plates. The results are compared with physical models applied to decoherence theory to describe the quantum-classical transition. The experiment is consistent with decoherence theory and rules out established Coulomb interaction models in favor of a plasmonic excitation model. In contrast to previous decoherence experiments the present experiment is sensitive to the onset of decoherence.

1.2.3 Dephasing vs Decoherence

In this theoretical work, we study the loss of contrast in double-slit electron-diffraction. We show how the spatial autocorrelation spectrum of the far field intensity distribution can be used to distinguish between a loss of contrast caused by dephasing or decoherence processes. This establishes a measure of time-reversibility that does not require the determination of coherence terms of the density matrix (correlations between spatial states). This contrasts with entropy, another measure of time-reversibility, that does require the coherence terms. This spatial autocorrelation technique is promising, taking into consideration the need to diminish the detrimental experimental effect of loss of contrast, identifying what kind of processes or environments cause irreversible damage to interference and which can be reconstructed, and for fundamental studies regarding the transition from the classical to the quantum regime.

1.3 Chapter 1 Bibliography

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CHAPTER 2

THEORY

2.1 Introduction

Outlined in this chapter are the models used to test the experimental and theoretical work completed in Chapters 3-5. The Chapter also provides some details about the underlying theories and concepts these models make use of. This begins in Section 2 with classical electron propagation both in free space and over a conducting surface, including effects born from classical image charge and classical surface charge induced by light (the latter pertaining to Chapter 3). Section 3 introduces quantum propagation of electrons, in particular the electron's wave propagation and the interference which results. In Section 4 the concepts of wave coherence of light and electrons are summarized. Section 5 is an introduction to the theory of decoherence, which aims to bridge the gap between classical and quantum mechanics by attempting to arrive at classical results entirely within a quantum framework. Section 6 provides various physical models which have been developed by others to predict decoherence effects due to a free electron propagating over a conducting surface (which we test in the experiment in Chapter 4). Finally, Section 7 gives an introductory comparison between decoherence and dephasing, and examines the concepts and measures (i.e. spatial autocorrelation and entropy) associated with these two phenomena. This is the subject of the theoretical work of Chapter 5.

2.2 Classical Electron Propagation over a Conducting Surface

Classical motion of non-relativistic electrons which propagate in free space as well as interacting in an electric field can be well approximated using Newtonian mechanics and classical electrodynamics [1]. Importantly, in classical mechanics the motion of an electron is well defined in terms of definite position $\vec{x}(t)$ and definite velocity $\vec{v}(t)$ at any given time. When it comes to electrons interacting with a surface, the term “free” is used to indicate that the electron approaches a surface (perhaps from a different source) and then moves away from the surface until it experiences a negligible or no force due to its field. This contrasts with electrons that may collide with the surface and remain bound to it, or electrons that are emitted from the surface (which are the subject of phenomena such as thermionic electron emission and inverse photoemission). Also not considered are electrons which make contact and rebound from the surface (contact collisions).

The source of the electromagnetic interactions that are taken into consideration from the surface include those surface charge distributions which most simply model the change in momentum the electron experiences perpendicular to the plane of the surface in the later experiments. These surface charge distributions we consider, attributed to maintaining zero electric field inside the conductor, include 1) image charge and 2) the charges which produce the ponderomotive potential induced by laser light effects.

2.2.1 Classical Image Charge

In the classical case, the electric force a point charge experiences in vacuum at a distance d away from a boundary separating vacuum from a conducting surface is a

convenient electrostatics problem to solve, and the symmetry of the problem simplifies it further. Consider that in static case, one would have to solve for an electron with charge $-e$ located at \vec{r} experiencing a potential $\Phi(\vec{r})$ due to a charge distribution with charge density $\rho(\vec{r}')$ [2],

$$\vec{F}(\vec{r}) = -e\vec{\nabla}\Phi(\vec{r}) = -\frac{|e|}{4\pi\epsilon_0}\vec{\nabla}\int\frac{\rho(\vec{r}')}{|\vec{r}-\vec{r}'|}d^3r'. \quad (2.1)$$

Because of assumed rotational symmetry about the perpendicular line crossing through the electron, as well as translational symmetries in the x & z directions and the reflection symmetries in the x - y and z - y planes (see figure 1), and ignoring fringe fields of the finite surface (assume y is much smaller than the size of the surface) as well as skin-depth effects, this simplifies to

$$\vec{F}(y) = -\frac{e^2}{4\pi\epsilon_0}\frac{\hat{y}}{(2y)^2}. \quad (2.2)$$

Note that this form is that of an electron experiencing a coulomb force due to a positive charge $+|e|$ at a distance $2y$ away from the electron, thus this surface charge has is called an “image” or “mirror” charge.

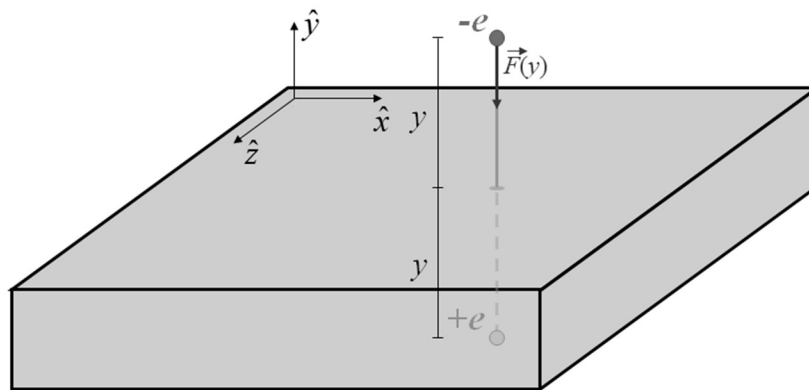


Figure 2.1 Image Charge Configuration

However, there is a slight reduction of this force for the case of the non-perfect conductor with a static dielectric constant $\varepsilon = \varepsilon_0 \varepsilon_r$. In this case, the image charge's strength reduces to

$$q' = +|e| \frac{(\varepsilon - \varepsilon_0)}{(\varepsilon + \varepsilon_0)}. \quad (2.3)$$

If one takes as an example silicon whose relative dielectric constant $\varepsilon_r \approx 11.7$, then

$q' = .843|e|$. Thus, the force is modified to become

$$\vec{F}(y) = -\frac{eq'}{4\pi\varepsilon_0} \frac{\hat{y}}{(2y)^2} = -\frac{e^2}{4\pi\varepsilon_0} \frac{(\varepsilon - \varepsilon_0)}{(\varepsilon + \varepsilon_0)} \frac{\hat{y}}{(2y)^2}. \quad (2.4)$$

See Chapter 4.5 for details on how this is implemented in modelling the deflection the electron experiences.

2.2.2 Deflection from Induced Light Potential

A surface charge distribution model was also produced by Wayne Huang to predict the force in the developed electron switch described in Chapter 3 [3]. When a laser light is incident perpendicular to a surface, a thin surface layer ($\delta \approx 1 \text{ nm}$) of electrons can be redistributed (again as a result of maintaining zero electric field inside the material). This lateral force on these surface electrons is

$$\vec{F}_p(x, z) = -\frac{e^2 \lambda^2}{8\pi^2 m_e c^3 \varepsilon_0} \vec{\nabla} I(x, z), \quad (2.5)$$

where λ is the wavelength of the laser, and $I(x, z)$ is the intensity distribution of the focused laser on the surface. Assuming a that this force induces a dipole moment distribution, and thus produces a surface charge distribution,

$$\sigma(x, z) = (-\vec{\nabla} \cdot \vec{P}) \delta = -\frac{1}{\alpha} \frac{n_0 e^3 \lambda^2 \delta}{8\pi^2 m_e c^3 \epsilon_0} \nabla^2 I(x, z), \quad (2.6)$$

where α is a fitting parameter in the linear dipole approximation and n_0 is the free electron density of the material. The electron travelling over the surface then experiences a force depending upon its x - z position on the surface as

$$\vec{F}(x, z) \approx \frac{e\sigma(x, z)}{2} \hat{y}. \quad (2.7)$$

Note that the approximation is used that one is near the surface such that the propagating electron experiences the local surface charge (thus the distance dependence was not worked out). Also, note that the force changes as a function of the path the electron travels along the surface (so much so that the deflection direction can change due to the Laplacian of the laser's intensity spatial distribution on the surface $\nabla^2 I(x, z)$ changing sign). This is in direct contrast with the modelling of image charge, where it is assumed that the force of the electron over the surface is the same everywhere over the surface and that the magnitude of the force depends on the distance to the surface in the y direction.

2.3 Quantum Electron Propagation in Free Space

While there are many situations where it is appropriate to approximate the motion of an electron using classical physics, electrons in the right contexts also demonstrate

properties that are not associated with classical particle motion. This includes phenomena such as wave interference (via the superposition principle), quantized states such as quantized angular momentum states when bound in a hydrogen atom, and electron degeneracy arising from fermionic statistics [4].

As an initial framework to describe quantum electron propagation in free space as it is ordinarily introduced, we begin with the emphasis of some of the postulates of quantum mechanics. For a more comprehensive formulation of all of these postulates, see Cohen-Tannoudjii et al [5]. The first postulate is stated as,

First Postulate: At a fixed time t_0 , the state of a physical system is defined by specifying

a ket $|\psi(t_0)\rangle$ belonging to the state space \mathcal{E} .

The physical system in this case (and throughout this thesis) is the free electron. The state space \mathcal{E} is a complex Hilbert space where the included states are unit vectors (i.e. it is a type of complex vector space). Importantly, because the state is described in terms of a complex vector, it follows that a linear combination of states within \mathcal{E} is itself a state within \mathcal{E} ,

$$|\Psi\rangle = \sum_i \alpha_i |\psi_i\rangle. \quad (2.8)$$

It is this feature of quantum states which is known as the superposition principle.

The sixth postulate according to Cohen-Tannoudjii et al. is the foundation of the propagation, or time evolution of the quantum state,

Sixth Postulate: The time evolution of the state vector $|\psi(t)\rangle$ is governed by the

Schrodinger equation:

$$i\hbar \frac{\partial}{\partial t} |\psi(t)\rangle = H(t) |\psi(t)\rangle \quad (2.9)$$

where $H(t)$ [the Hamiltonian] is the observable associated with the total energy of the system.

The combination of the unitary evolution of the quantum state described by the Schrodinger equation and the superposition principle is what leads to the wave properties of the quantum state of the electron.

Consider now an electron wave that is split into two states $|\psi_1(x,t)\rangle$ and $|\psi_2(x,t)\rangle$ (see Figure 2) where x corresponds to the coordinate position in the transverse direction of propagation. After wave propagation of these separate states, assume that the evolution was prepared such that it leads to recombination at a detection screen (at the detection screen, there is at least some spatial overlap of these two states). One will observe the electron landing at a specific position x on the detector determined by the probability distribution in terms of the wavefunction in position representation,

$$P(x) = I(x) \propto |\psi_1(x) + \psi_2(x)|^2 = |\psi_1(x)|^2 + |\psi_2(x)|^2 + 2\text{Re}(\psi_1(x)\psi_2^*(x)) \quad (2.10)$$

where the first two terms correspond to the probabilities of the two separate wave functions alone, and the third mixed term provides the interference. At the position x when $2\text{Re}(\psi_1(x)\psi_2^*(x)) = -(|\psi_1(x)|^2 + |\psi_2(x)|^2)$, total destructive interference takes place and the probability of the electron landing at that position is zero. At the position x when $2\text{Re}(\psi_1(x)\psi_2^*(x)) = +(|\psi_1(x)|^2 + |\psi_2(x)|^2)$, total constructive interference takes

place and the probability of the electron landing at that position is maximized for that position.

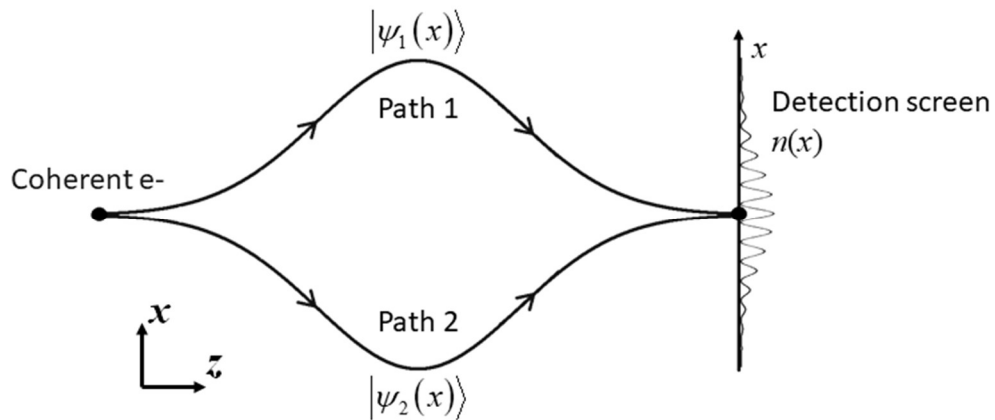


Figure 2.2 Coherent Interference between Two States.

2.4 Coherence of Matter Waves

In the previous section, it was shown how matter wave propagation leads to quantum interference. If the state of the electron can be described in this way, then it is said that the electron state (or the wave function) is coherent. Here, by coherent we informally define coherence as the electron state to undergo “full” interference (total constructive interference, or total destructive interference is possible). This does not necessarily need to be the case, and the following sections described the consequences of the case when the wave function is partially coherent.

2.4.1 Partial Coherence and Density Matrix Formalism

To describe a partially coherent (or mixed) quantum state, the density matrix (also known as a density operator [6]) formalism is a convenient mathematical tool to do so, as the previously described convention is insufficient to do so. Starting with the simple example of a fully coherent state as in equation 2.8, the density matrix of this state can be written as

$$\rho = |\Psi\rangle\langle\Psi|. \quad (2.11)$$

If the state is constructed from a wave function (e.g. equation 2.8), the state is said to be pure and $\rho^2 = \rho$. If a quantum state is pure, then it is also fully coherent.

A mixed state can be constructed by statistically adding pure states together as a convex sum,

$$\rho^{mixed} = \sum_k p_k \rho_k^{pure} = \sum_k p_k |\Psi\rangle_k \langle\Psi|_k, \quad (2.12)$$

with the convex condition $\sum_k p_k = 1$. Such a statistical mixture may evolve in a unitary manner according to the von Neumann equation (which can be deduced from the Schrodinger equation and vice versa [6]):

$$[\hat{H}, \rho] = i\hbar \frac{\partial}{\partial t} \rho. \quad (2.13)$$

If the density matrix is written in the position representation (in the x -direction) then the final spatial probability distribution can be found by taking the (main) diagonal of the density matrix;

$$P(x) = \langle x | \rho | x \rangle = \text{diag}[\rho(x)]. \quad (2.14)$$

2.4.2 Relationship between Coherence and Observed Interference

The nature of coherence can be best understood by its relation to observed interference. Starting again as in section 2.3 with an initial electron wave split into two states, $|\psi_1\rangle$ and $|\psi_2\rangle$, and evolves along separate paths as shown in Figure 2. This time however, the evolution somehow corrupts the two states (examples, such as density matrix state reduction, will be described in sections 2.5-2.7). For the two state case, analogous to equation 2.10, the observed intensity distribution observed in the far field is proportional to [7],

$$I = |\psi_1|^2 + |\psi_2|^2 + 2V \operatorname{Re}(\psi_1\psi_2^* + \text{H.O.T.}), \quad (2.15)$$

where H.O.T. corresponds to higher order terms, and V corresponds to the visibility of the interference pattern:

$$V = \frac{I_{\max} - I_{\min}}{I_{\max} + I_{\min}}. \quad (2.16)$$

I_{\max} is the maximum envelope of the intensity distribution and I_{\min} corresponds to the minimum envelope that develops as a result of loss of contrast in interference (see Figure 3). Thus, if $I_{\min} = 0$, then $V = 1$, and the final state is fully coherent. If $I_{\min} = I_{\max}$, then $V = 0$ and the state may be fully incoherent. If $0 < I_{\min} < I_{\max}$, then $0 < V < 1$ and the final state may be partially coherent. Thus, visibility is often used as a measure of coherence.

An example diffraction pattern that models such a case is double slit diffraction, with a far field intensity distribution,

$$I = I_0 \left(\frac{\sin(\gamma)}{\gamma} \right)^2 \frac{(1 + V \cos(2\alpha))}{2}, \quad (2.17)$$

where I_0 is the central intensity value for $V=1$ and $x=0$, $\gamma = \frac{\pi c}{\lambda} \sin(\theta)$ and

$\alpha = \frac{\pi a}{\lambda} \sin(\theta)$. c is the width of the slit, a is the distance between slits, λ is the de-

Broglie wavelength, and θ is the angle with respect to the normal of the double slit plane. In the small angle approximation at a distance z away from the surface (see Figure 3);

$$I(x) = \frac{I_0}{2} \left(\sin\left(\frac{\pi cx}{\lambda z}\right) / \frac{\pi cx}{\lambda z} \right)^2 \left(1 + V \cos\left(\frac{2\pi ax}{\lambda z}\right) \right), \quad (2.18)$$

In the limit $V \rightarrow 1$, I approaches the ordinary double-slit Fraunhofer equation:

$$I = I_0 \left(\frac{\sin(\gamma)}{\gamma} \right)^2 \cos^2(\alpha) \quad (2.19)$$

and in the limit $V \rightarrow 0$, it approaches the single slit Fraunhofer equation:

$$I = \frac{I_0}{2} \left(\frac{\sin(\gamma)}{\gamma} \right)^2. \quad (2.20)$$

Thus, a 2-path experiment (such as a double-slit experiment or a 2-path interferometer), visibility is a useful measure of the loss of coherence in a system as measured at the detector.

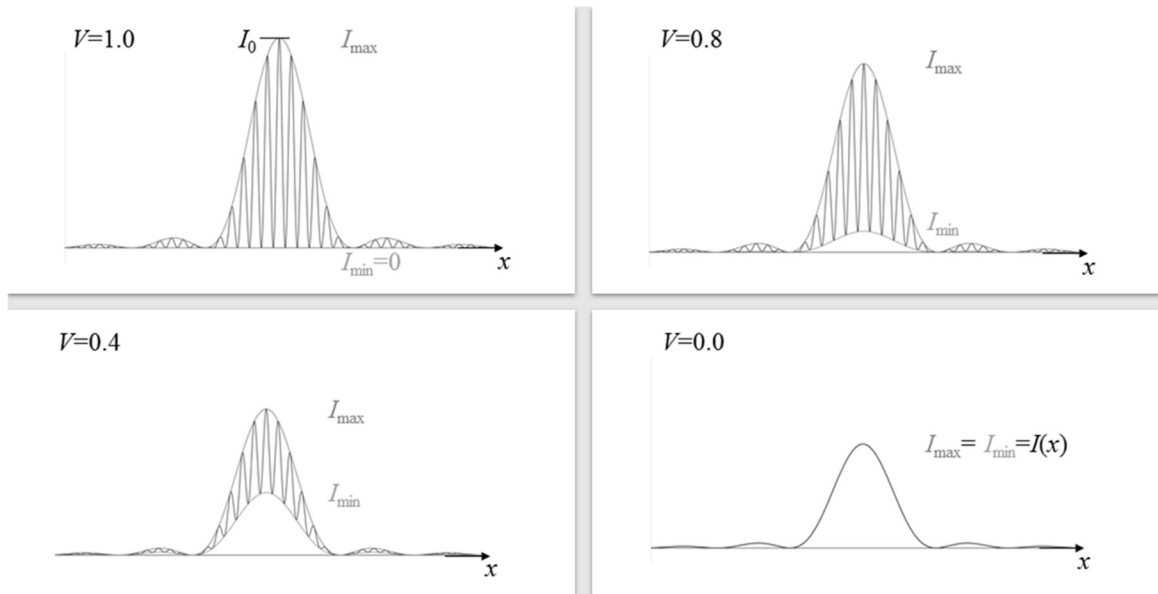


Figure 2.3 Far Field Double-slit Interference Pattern for Various Visibility Values. If $V=1$, then the interfering waves are fully coherent. See equation (2.17). If $0 < V < 1$, then interfering waves are partially coherent with respect to each other. If $V=0$, then there is no interference between interfering waves (bottom left).

2.4.3 Coherence Length for a Collimated Matter Wave

For the case of a matter wave (such as atoms, electrons, etc) that is collimated (using for example collimation slits, see Figure 4), the coherence length can be computed starting with the Heisenberg uncertainty relation:

$$\Delta x \Delta p_x \sim h, \quad (2.21)$$

where we take the uncertainty in position Δx to be the transverse coherence length, and Δp_x corresponds to uncertainty in the beam's transverse momentum. Taking into consideration the geometry of beam collimation in the small angle limit:

$$\frac{\Delta p_x}{p_z} = \tan(\theta_{coll}) \approx \theta_{coll}, \quad (2.22)$$

where θ_{coll} correspond to the beam's divergence angle. This can be substituted into the uncertainty relation:

$$\Delta x \cdot p_z \cdot \theta_{coll} = h. \quad (2.23)$$

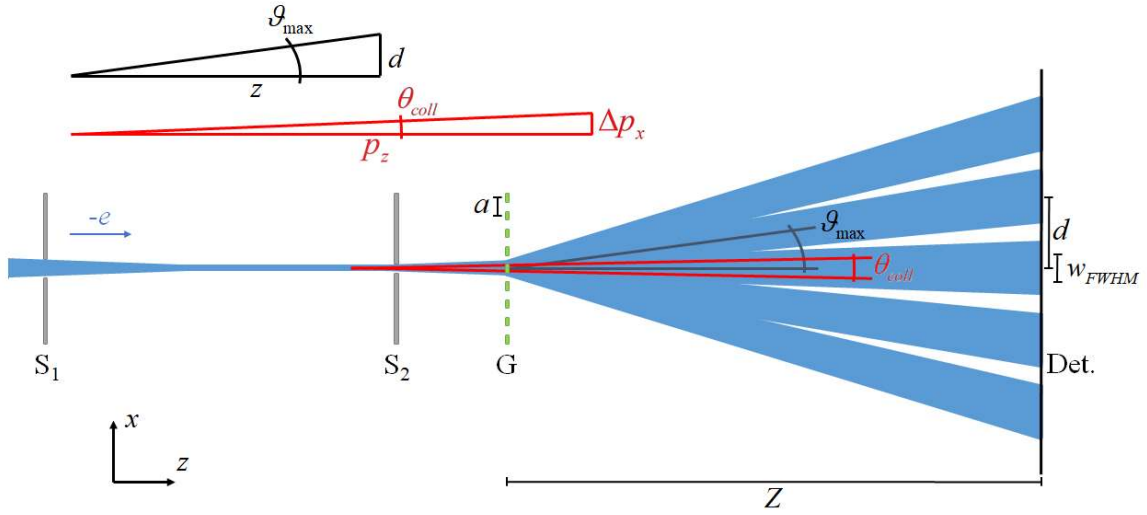


Figure 2.4: Schematic of Collimated Diffraction. The divergence of the electron beam θ_{coll} depends on the geometry of two collimation slits (S_1 and S_2). This ultimately determines the initial width w_{FWHM} of the diffraction peaks. The diffraction angle ϑ_{max} depends on nanofabricated diffraction Grating's (G) periodicity a along with the electron's wavelength. This determines the periodicity d of the observed diffraction at the detector through the diffraction equation (equation 2.27). These parameters are what influence the measure of the initial transverse coherence length (equation 2.30).

Using the definition of the De Broglie wavelength:

$$\lambda_{dB} = \frac{h}{p}, \quad (2.24)$$

the transverse coherence length becomes, in agreement with [8],

$$\Delta x \equiv L_{coh} \approx \frac{\lambda_{dB}}{\theta_{coll}}. \quad (2.25)$$

To calculate this transverse coherence length in terms of measurable quantities, a diffraction grating can be introduced after the beam has been collimated. For grating diffraction, the well-known diffraction equation is invoked,

$$a \cdot \sin(\mathcal{G}_{\max}) = n\lambda, \quad (2.26)$$

where a is the periodicity of the grating, n corresponds to the n^{th} order diffraction peak, and \mathcal{G}_{\max} corresponds to the angle between the incident beam and the direction which the far field diffraction peaks propagate. This can be used to determine the distance d between the diffraction peak maxima in the far field in the small diffraction angle approximation;

$$\sin(\mathcal{G}_{\max}) \approx \mathcal{G}_{\max} \approx \tan(\mathcal{G}_{\max}) = \frac{d}{z}, \quad (2.27)$$

where z is the distance between the grating and the plane in which diffraction peaks that are detected.

Equations (2.26) and (2.27) can be combined for a new expression of the De Broglie wavelength:

$$\lambda_{dB} = \frac{ad}{z}. \quad (2.28)$$

Similarly, the collimation angle can be determined in the small angle approximation by the width of the diffraction peaks w_{FWHM} at a distance z away from the grating;

$$\theta_{coll} \approx \tan(\theta_{coll}) \approx \frac{w_{FWHM}}{z}. \quad (2.29)$$

Finally, the calculation of transverse coherence length of the electron at the grating can be determined entirely in terms of measurable quantities observed at the detector by substituting in equations (2.28) and (2.29) into (2.25):

$$L_{coh} = \frac{ad}{w_{FWHM}}. \quad (2.30)$$

Thus, a loss of coherence is associated with a widening of the width of the diffraction peaks w_{FWHM} rather than a loss of contrast. Notice that this measure is independent of the distance z between the grating and the detector (provided that the detector is in the Fraunhofer diffraction region), and that only the ratio of the peak-to-peak distance to the width of the peaks matters. We can therefore measure coherence in terms of the transverse coherence length of the diffracted beam as observed at the detector.

2.4.4 Comparison of Coherence Measures (Transverse Coherence Length and Visibility)

To illustrate the effects of irreducible background on the measurement of visibility, let's first take the simple case of a detected interference pattern that is in a spatial range $0 < x < L$ perfectly sinusoidal with no irreducible background. Such an intensity distribution can be modeled as:

$$I_{clean}(x) = \frac{I_{total}}{L} (1 + V \cos(n\pi x)), \quad (2.31)$$

where I_{total} is the total integrated intensity in $0 < x < L$ of the particles of interest, $0 < V < 1$ describes the visibility associated with dephasing or decoherence one is trying to measure, and n controls the observed periodicity of the intensity pattern. In such a case with a maximum intensity of $\max[I_{clean}(x)] = \frac{I_{total}}{L}(1+V)$, and a minimum intensity of $\min[I_{clean}(x)] = \frac{I_{total}}{L}(1-V)$, then using equation (2.16) the computed visibility becomes by design

$$V_{clean} = \frac{\frac{I_{total}}{L}(1+V) - \frac{I_{total}}{L}(1-V)}{\frac{I_{total}}{L}(1+V) + \frac{I_{total}}{L}(1-V)} = V. \quad (2.32)$$

Now we introduce to this intensity a constant *irreducible background* with total intensity Ld , then the interference intensity distribution is modified to become

$$I_{clean+bckd}(x) = \frac{I_{total}}{L}(1+V \cos(n\pi x)) + d. \quad (2.33)$$

With a new maximum intensity of $\max[I_{clean+bckd}(x)] = \frac{I_{total}}{L}(1+V) + d$ and a minimum intensity of $\min[I_{clean+bckd}(x)] = \frac{I_{total}}{L}(1-V) + d$, once more using equation (2.16) the visibility in this case is

$$V_{clean+bckd} = \frac{I_{total}V}{I_{total} + Ld}. \quad (2.34)$$

Note that in the limit $d \rightarrow 0$; $V_{clean+bckd} \rightarrow V_{clean}$. With a combined total intensity of $I_{total} + Ld$, the fraction of the intensity that is background is

$$f = \frac{Ld}{I_{total} + Ld}; f \in [0,1); \quad (2.35)$$

thus the total background in terms of its fraction to the combined total intensity is

$$Ld = \frac{I_{total}f}{1-f}. \quad (2.36)$$

Finally, substituting this result into equation (2.34) the total visibility as a function of percent irreducible background is

$$V_{clean+bckd}(f) = V_{clean} \left(\frac{1}{1+\frac{f}{1-f}} \right) = V_{clean}(1-f), \quad (2.37)$$

which is plotted in Figure 5. Note how this differs from when calculating the transverse coherence length, in this case subtracting the irreducible background does not change the calculation of the coherence length, because $L_{coh}(f) = const.$

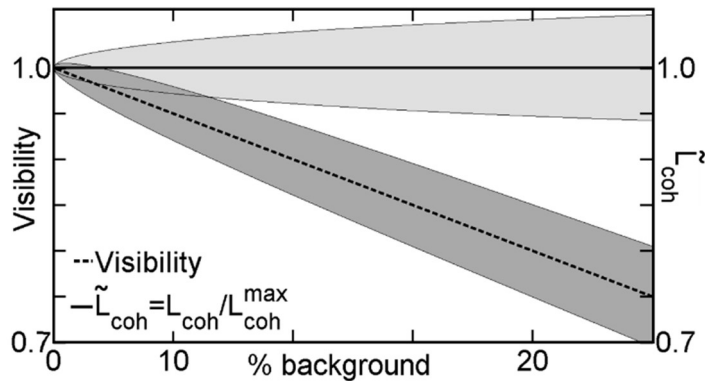


Figure 2.5. Comparison between visibility (V) and normalized transverse coherence length ($\tilde{L}_{coh} = L_{coh}/L_{coh}^{max}$). For interferometry, the visibility is used to place a bound on decoherence. For diffraction, the decoherence measure is coherence length. The advantage of using diffraction rather than interferometry is that the decoherence measure is not background dependent. In other words, the linear drop of visibility in an interferometer (dashed line) due to a weak background signal masks the decoherence. This makes diffraction well-suited to search for weak decoherence.

The shaded areas correspond to uncertainty due to the statistical error introduced by the background.

This illuminates the advantage of using diffractometry (as described in Chapter 4) over interferometry, which lies in their respective decoherence measures, L_{coh} and V

(Figure. 5). The background signal can be subtracted for diffraction without distorting the measured value of L_{coh} . This is not the case when measuring visibility in an interferometer. The visibility V drops off linearly due to a weak background signal, which can mask decoherence. For a weak decoherer that scatters the incident beam and introduces background, diffractometry is thus well suited.

2.5 Decoherence Theory

As introduced in Chapter 1, Decoherence Theory [9,10] sets out to describe and predict how classical behavior emerges out of quantum mechanics when a quantum object or system becomes unable to sufficiently isolate itself from interacting through entanglement with its external environment. Despite Decoherence Theory being an extension of the rules of ordinary quantum mechanics, this explanation is a break from the orthodoxy of the Copenhagen interpretation of quantum mechanics, where the observation of quantum effects of any object is only limited by the devising of a suitable classical measuring device that can carry out the task with the suitable precision [11].

2.5.1 Zurek's Formalism

The process of decoherence according to Zurek can be summarized in the following way [12]: starting with an initial state $|\psi_s\rangle$ of the "system" (in this case the electron) which is in a superposition of states $|\sigma_i\rangle$ which can be written in the form

$|\psi_s\rangle = \sum_i \alpha_i |\sigma_i\rangle$. Separate from this is an external environment in an initial state $|\varepsilon_0\rangle$.

The system then interacts with the environment via entanglement, resulting in a new entangled state $|\Psi_{SE}(t)\rangle$. This process can be illustrated by:

$$|\Psi_{SE}(0)\rangle = |\psi_S\rangle \otimes |\varepsilon_0\rangle = \left(\sum_i \alpha_i |\sigma_i\rangle \right) \otimes |\varepsilon_0\rangle \xrightarrow[\text{entanglement}]{\text{interaction}} |\Psi_{SE}(t)\rangle = \sum_i \alpha_i |\sigma_i\rangle \otimes |\varepsilon_i\rangle. \quad (2.38)$$

The Hamiltonian of this interaction, H_{SE} , has the important feature that in relationship to the states of the system, the commutation relationship $[H_{SE}, |\sigma_i\rangle\langle\sigma_i|] = 0$ is obeyed.

What this means is that there exists a set of states $|\sigma_i\rangle$, known as pointer states, which remain unchanged under entanglement.

The combined state is itself a pure state. Because we are interested only in the system and not the combined state, a partial trace is performed over the environment, resulting in a diagonalized density matrix,

$$\rho_s(t) = Tr_E |\Psi_{SE}(t)\rangle\langle\Psi_{SE}(t)| = \sum_i |\alpha_i|^2 |\sigma_i\rangle\langle\sigma_i|. \quad (2.39)$$

which is a diagonalized matrix with no remaining coherences (the off-diagonal elements are zero). Importantly, the set of states that end up on the diagonal of the density matrix is always the same [12], (hence the pointer states being “preferred” states). The process in which these pointer states are selected by the environment is known as “environment-induced superselection” or “einselection” [9]. If the system was to start in one of these preferred states, the interaction of the environment would do nothing to it, and the system would remain unperturbed. These stable pointer states that appear on the diagonal of $\rho_s(t)$ after a decoherence time with probabilities $|\alpha_i|^2$ (see equation 2.14), are

effectively classical states, as the coherences between these $|\sigma_i\rangle$ states become insignificant (or in the extreme case completely uncorrelated) [12].

2.5.2 Density Matrix and Coherence

An important example of a decoherence process (applied to models such as the one described in section 2.6.1) is a particle interacting with an environment of harmonic oscillators [11,13], i.e. a quantum scalar field φ [14]. Excitations of this scalar field scatter off the particle, carrying with it information about the particle's position x . This therefore leads to the localization of the particle in position space [15].

The system-environment interaction takes the form via the Hamiltonian [13],

$$H_{se} = x \sum_i c_i q_i, \quad (2.40)$$

where q_i corresponds to the position of the i^{th} quantum oscillator with coupling strength c_i . After tracing over the environment this results in a new evolution equation of the particles density matrix (also known as a master equation) which has an exact solution [16]. In the high temperature limit of the harmonic bath (thermal fluctuations of the field rather than zero-point vacuum fluctuations), the master equation becomes [9]:

$$\dot{\rho}_s = -\frac{i}{\hbar} [H, \rho_s] - \gamma (x - x') \left(\frac{\partial}{\partial x} - \frac{\partial}{\partial x'} \right) \rho_s - \frac{2m\gamma k_B T}{\hbar^2} (x - x')^2 \rho_s. \quad (2.41)$$

The first term alone (when the relaxation rate $\gamma = 0$) corresponds to the Von Neumann equation (equation 2.13). the second term is responsible for relaxation (or dampening) with its rate proportion to the “viscosity” of the particle in the harmonic bath. The third term is responsible for random fluctuations associated with quantum Brownian motion [9].

Zurek defines the diagonal as those elements which $x - x' = 0$ and $(\Delta x)^2 \approx (x' - x)^2$ as elements the square of the separation between off-diagonal elements [11].

In the macroscopic/classical limit \hbar is small compared to other combined terms with units of action (e.g. $\hbar \ll \sqrt{2m\gamma k_B T \langle (x - x')^2 \rangle}$) the high temperature particle evolution equation becomes dominated by the third term and the equation can be further approximated to [9],

$$\dot{\rho}_s = -\gamma \frac{(x - x')^2}{\lambda_T^2} \rho_s, \quad (2.42)$$

where the thermal De Broglie wavelength here is defined as $\lambda_T \equiv \hbar / \sqrt{2mk_B T}$. This linear differential equation can be solved as it is in the simple form $\frac{\partial y}{\partial t} = -cy$ and thus has a solution of

$$\rho_s(x, x', t) = \rho_s(x, x', 0) e^{-\gamma \left(\frac{x-x'}{\lambda_T}\right)^2 t} = \rho_s^{initial} e^{-t/\tau_{dec}}. \quad (2.43)$$

From this general solution, we can conclude that the coherence terms in the density matrix decay exponentially with a decoherence timescale $\tau_{dec} = \gamma^{-1} (\lambda_T / \Delta x)^2$. After a sufficiently long time t compared to the decoherence time τ_{dec} , the density matrix will be approximately diagonalized and the particle behaves classically.

An alternative derivation by Breuer and Petruccione [15] utilized an underlying master equation based on a general Markov process,

$$\dot{\rho}_s(t) = -i[H_s, \rho_s(t)] - \Lambda[\bar{x}, [\bar{x}, \rho_s(t)]], \quad (2.44)$$

where the Hamiltonian of the particle is $H_s = \frac{\vec{p}^2}{2m}$ with a coordinate \vec{x} . Equation 2.44 also has a similar solution to equation 2.41 in the “recoilless limit” (where damping effects are neglected). This means that the decay of the off-diagonal coherences occurs on a time scale much shorter than the dampening of the diagonal elements. Additionally, it is assumed that the free evolution corresponding to the Hamiltonian (for example the broadening of the state due to beam divergence) [15]. This leads to the solution

$$\rho_s(\vec{x}, \vec{x}', t) \approx \rho_s(\vec{x}, \vec{x}', 0) e^{-\Lambda(\vec{x}-\vec{x}')^2 t}, \quad (2.45)$$

where Breuer and Petruccione calls Λ the “decoherence rate” [15]. Nevertheless, the similarity between this Markovian decoherence solution and the decay of the density matrix due to quantum Brownian motion in equation 2.43 when $\Lambda = \gamma/\lambda_r^2$.

Oftentimes when the off-diagonal terms decay exponentially (as in equation 2.43 and equation 2.45) the absolute value of the terms in the exponent are combined to form the decoherence factor Γ . For example, in the case of equation 2.43, the decoherence factor is $\Gamma = t/\tau_{dec}$.

2.6 Mechanisms of Decoherence Due to Conducting Surfaces

The following subsections provide examples of application of this decoherence program by inserting particular physical models where an electron may decohere due to its interaction with a conducting surface acting as an environment. Each physical model presumes its own decoherence timescales τ_{dec} . These physical models are tested experimentally as described in Chapter 4. In the experiment, the distance y between the electron and the surface is not constant in time as it propagates over the surface (because

of the image charge force). Therefore, because of this the strength of the interaction changes over its propagation (i.e. τ_{dec} is a function of y), the decoherence evolution of the density matrix from the beginning of the surface at time T_i to the end of the surface at time T_f is modified to take the form

$$\rho_s(x, x', T_f) = \rho_s(x, x', T_i) e^{-\Gamma} = \rho_s(x, x', T_i) e^{-\int_{T_i}^{T_f} \frac{t}{\tau_{dec}} dt}. \quad (2.46)$$

Additionally, the decoherence factor Γ of these decoherence processes do not universally take the form $e^{-\Gamma} = e^{\alpha(\Delta x)^2}$. To take the example of Scheel and Buhmann (section 2.6.2 [17]) the decoherence factor is modified due to the assumption of an image charge travelling under both paths in their two path setup. However, for small $\Delta x \ll 1$ the first order term in the expansion of these decoherence factors is consistently $\Gamma^{(1)} \approx a_1 (\Delta x)^2$. This points to the importance of investigating decoherence effects by varying the parameter Δx at large values as an alternative to distinguishing between different effects. See Appendix C for a description of how this evolution of the density due to decoherence is implemented numerically as it relates to the decoherence experiment.

2.6.1 Free Electron-Surface Decoherence Models

The original decoherence model that focused on electron-surface decoherence was conceived by Anglin and Zurek [18,19]. The physical system is a classical image charge on the surface of the conductor that follows the free electron as it travels parallel to the surface (see figure 6). Joule heating, which the image charge experiences while

traversing the surface, causes dissipation with a relaxation time τ_{relax} . Back-action on the free electron leads to decoherence with a corresponding time τ_{dec} (called decorrelation time in [13]). The decoherence time is taken to be proportional to the relaxation time according to [13],

$$\tau_{dec} = \left(\frac{\lambda_{th}}{\Delta x} \right)^2 \tau_{relax}, \quad (2.47)$$

with the thermal de Broglie wavelength of $\lambda_{th} = \hbar / \sqrt{mk_b T}$ in accordance to

Sonnentag [20]. Anglin and Zurek proposes that power is dissipated due to the Ohmic resistance that the image charge experiences while it travels over the surface. For an image charge with velocity v (which is approximated to be equal to the velocity of the free electron that is at a distance y away from the interface of the surface), and a surface resistivity of ρ . According to Boyer and Chapman et al. this dissipated power is found to be [21,22]

$$P_{Joule} = \frac{e^2 \rho v^2}{16\pi y^3}. \quad (2.48)$$

This power loss is responsible for the relaxation (or dampening) time. Equating this power dissipation to the power associated with the change in kinetic energy of the image charge:

$$P = \frac{d}{dt} \left(\frac{1}{2} m v^2 \right) = m v \frac{dv}{dt}. \quad (2.49)$$

Taking the definition of relaxation time according to Zeh et. al. [10]:

$$\tau_{relax} \equiv v \left/ \left| \frac{dv}{dt} \right| \right. . \quad (2.50)$$

This can now be substituted into Eq. 2.48 and then be equated to loss of power due to image charge to arrive at the relaxation time due to Ohmic dissipation:

$$P = mv\dot{v} = \frac{mv^2}{\tau_{relax}} = \frac{e^2 \rho v^2}{16\pi y^3} \rightarrow \tau_{relax} = \frac{16\pi m y^3}{e^2 \rho}. \quad (2.51)$$

Thus, substituting this into equation 2.47, the resulting decoherence time scale is

$$\tau_{dec}^{Zurek} = \frac{4h^2}{\pi e^2 k_B T \rho} \frac{y^3}{(\Delta x)^2}. \quad (2.52)$$

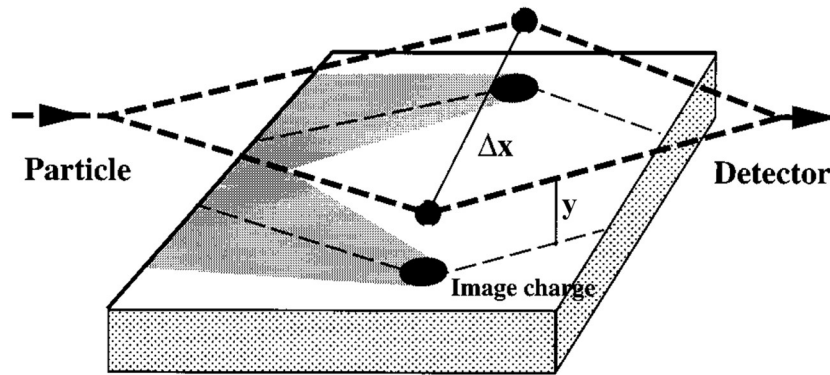


Figure 2.6. Original Electron-Surface Decoherence Model from Anglin and Zurek (image from [18]). Two electron paths that are separated by a distance Δx pass over a surface at height y and subsequently recombine at the detector. The resulting loss of contrast in this model is attributed to the Joule heating that the classical image charge experiences as transverse the surface.

The decoherence model by Scheel and Buhmann [17] is also based on the electron's interaction with its image charge, but it considers a full macroscopic quantum electrodynamic treatment. This considers the surface's linear dielectric response. Taking the low frequency limit where the Drude approximation $\varepsilon(\omega) \approx 1 + i/(\varepsilon_0 \rho \omega)$ holds for both gold [17] and doped silicon [23,24], the decoherence time scale is

$$\tau_{dec}^{Buhmann} = \frac{\pi \epsilon_0 \hbar^2}{e^2 k_B T \rho} \left[\frac{1}{2y} - \frac{1}{\sqrt{(2y)^2 + (\Delta x)^2}} \right]^{-1}. \quad (2.53)$$

In the limit $\Delta x \ll y$ this is equivalent to Equation 2.52.

Machnikowski's fully quantum many-body electron gas model implies that the primary decoherence mechanism is due to the dissipative effects of image charge formation rather than Ohmic resistivity effects [7]. It is notably dependent on the Fermi wave-vector for metals (k_{Fermi}). This decoherence time scale is

$$\tau_{dec}^{Machnikowski} = \frac{32 \epsilon_0 \hbar^2 k_{Fermi}}{\pi e^2 m k_B T} \left(\frac{y}{\Delta x} \right)^2. \quad (2.54)$$

Howie's model [24] is based on event probability e^{-P} rather than energy dissipation, where such events correspond to aloof scattering with long wavelength plasmons and "similar excitations" up to a cutoff frequency 0.6×10^{12} Hz. The stated expression for this probability is

$$P^{Howie} = \left[\frac{e^2 L \omega_m^2}{4 \pi^2 \hbar \sigma v^2} \right] \int_{\frac{y}{4 \Delta x}}^{\infty} \frac{\exp(-s)}{s} ds. \quad (2.55)$$

The exponential integral is approximated by [25],

$$-Ei(-\eta) = \int_{\eta}^{\infty} \frac{\exp(-s)}{s} ds \cong (A^{-7.7} + B)^{-0.13}, \quad (2.56)$$

where $\eta = y/4\Delta x$, $A = \log[(0.56146/\eta + 0.65)(1 + \eta)]$, and $B = \eta^4 e^{7.7\eta} (2 + \eta)^{3.7}$. Note that in the original article [24], η is mistakenly written as a factor of 16 different than the determined value (A. Howie, private communication). It should be mentioned that this theory has been further elaborated to be explained in terms of the electron's loss of

energy by emission of photons associated with the material's optical excitations (in a similar way the material may also undergo photon emission) [26,27].

There has been much interest in the potential to measure the effects of decoherence due to vacuum field fluctuations in such an experiment as a biprism interferometer [28–33]. It has been shown that, absent the surface, the decoherence factor Γ scales with $\sim(\Delta x)^2/(T^2 c^2)$ where T is the total time of flight of the electron [30,32] and c is the speed of light. This decoherence effect is said to be intrinsic to the electron propagating in free space; and if a surface is brought near the interferometer, decoherence due to vacuum field fluctuations may be either enhanced by up to a factor of 2 or suppressed (called “recoherence”) depending on if the plane of the separated paths is perpendicular or parallel to the surface respectively (see Figure 2.7) [32,33].

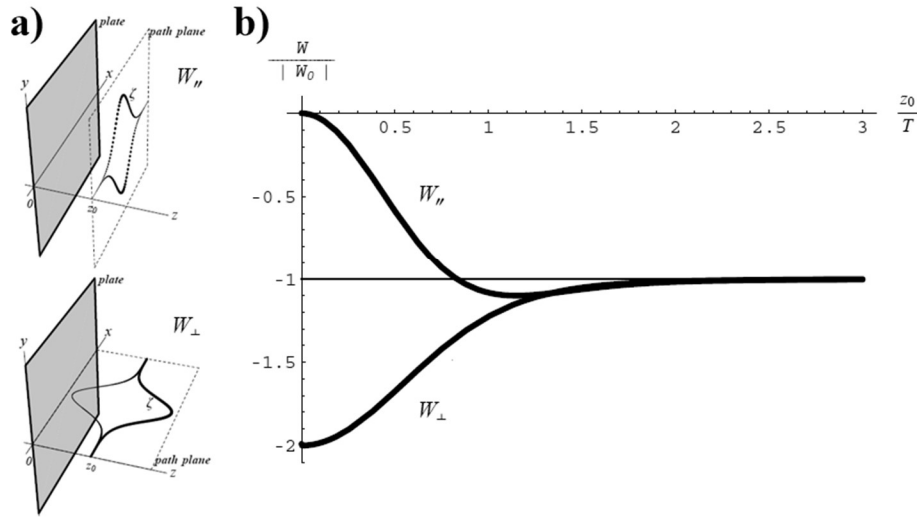


Figure 2.7: Surface Dependence on Decoherence due to Vacuum Field Fluctuations. a) Electron interferometer/separated path configuration either parallel (top) or perpendicular (bottom) to the surface. Here z_0 corresponds to the height of the initial state with respect to the surface (elsewhere defined as y as in figure 6 et al), and T is the total time of flight over the surface between separation and recombination of states. W corresponds to the negative of the decoherence factor $-\Gamma$. If no surface is present, $W = W_0 \approx -(\Delta x)^2/(T^2 c^2)$. b) The height

dependence of the decoherence factor with respect to the surface. As the interferometer is brought near the surface, the decoherence factor decreases toward zero in the parallel case. In the perpendicular case, the decoherence factor tends toward twice the vacuum field decoherence when no surface is present. Image taken from Hsiang and Lee [32].

2.7 Decoherence vs Dephasing

While the two terms are often used interchangeably, decoherence and dephasing are two distinct phenomena that result in the loss of observed interference (a loss of contrast). However, they are physically quite different, decoherence corresponds to a irreversible process while dephasing corresponds to a reversible process. Zurek differentiates dephasing and decoherence in the following way [9]: There are processes which lead to measures which lead to “ignorance” of phase information, but these processes may not lead to an imprint (i.e. a transfer of information) of the state of the system on the environment (this is what we call dephasing). Dephasing due to “Classical noise” is when a “classical perturbation” (for example random phase noise in the potential) leads to unitary (reversible) evolution, but the evolution remains “unknown”. This leads to the modification of the system/apparatus combined wave function such that [9],

$$|\Psi_{SA}\rangle = \left(\sum_j \alpha_j |A_j\rangle \right) \rightarrow \sum_j \alpha_j \exp(i\phi_j^{(n)}) |s_j\rangle |A_j\rangle = |\Psi_{SA}^{(n)}\rangle. \quad (2.57)$$

Here we use $|\Psi_{SA}^{(n)}\rangle$ to corresponds to different resulting realizations of random phase noise, a member of an ensemble of n final states. If the process is acting on the system (or the particle), the dephasing Hamiltonian takes the form

$$H_d^{(n)} = \sum_j \dot{\phi}_j^{(n)}(t) |s_j\rangle \langle s_j|. \quad (2.58)$$

Note that a similar Hamiltonian exists if dephasing occurs on the state of the apparatus. An important characteristic of $H_d^{(n)}$ is that it does not change the “nature” or the “degree of the system/apparatus correlations” [9]. It does not transfer information about the state of either the system or the apparatus onto the environment.

Note that each final state $|\Psi_{SA}^{(n)}\rangle$ is a pure state. Additionally, if the noise information $\phi_j^{(n)}$ is known or is acquirable, these pre-dephased state can be reconstructed. But when this is not the case (e.g., if different n corresponds to time-evolving iterations too fast to obtain the evolution of the phase noise), then the final system/apparatus state is written by the density matrix averaged over the ensemble of noise realizations:

$$\begin{aligned} \bar{\rho}_{SA} = \langle |\Psi_{SA}\rangle \langle \Psi_{SA}| \rangle &= \sum_j |\alpha_j|^2 |s_j\rangle \langle s_j| |A_j\rangle \langle A_j| + \\ &+ \sum_{j,k} \sum_n e^{i[\phi_j^{(n)} - \phi_k^{(n)}]} \alpha_j \alpha_k |s_j\rangle \langle s_k| |A_j\rangle \langle A_k|, \end{aligned} \quad (2.59)$$

where here $\langle \rangle$ denotes an ensemble average. This ensemble averaging does result in the reduction of the off-diagonal terms of the density matrix and results in a loss of contrast, hence the similar observed result when decoherence occurs. An important conclusion here is that dephasing is a loss of phase coherence *between members of the ensemble* rather than between pointer states in decoherence, and this loss of coherence is due to differences in the noise in phases each member experiences.

2.7.1 Correlation Function and Entropy

As outlined in Chapter 5; the questions which we arise at are what other physical characteristics differentiate decoherence vs dephasing. More specifically is it possible to

distinguish between the two processes with limited information given only an observed interference intensity pattern (without reverting to directly obtaining the wave's phase information of the individual members of the ensemble as in tomography and entropy measurements). The tool utilized here is the second order correlation function (also known as the degree of second order coherence) for a single source is written as [34]:

$$g^{(2)}(x_1, t_1; x_2, t_2) = \frac{\langle \psi^*(x_1, t_1) \psi(x_1, t_1) \psi^*(x_2, t_2) \psi(x_2, t_2) \rangle}{\langle |\psi(x_1, t_1)|^2 \rangle \langle |\psi(x_2, t_2)|^2 \rangle}. \quad (2.60)$$

Taking the case of the wave function at time t at the detecting plane, considering symmetric points about the origin ($x_1 = x$ and $x_2 = -x$), and interpreting the ensemble average to be either a time average or an average over an ensemble of different phase patterns, this becomes:

$$g^{(2)}(x; -x) = \frac{\langle \psi^*(x) \psi(x) \psi^*(-x) \psi(-x) \rangle}{\langle |\psi(x)|^2 \rangle \langle |\psi(-x)|^2 \rangle} = \frac{\langle I(x) I(-x) \rangle}{\langle I(x) \rangle \langle I(-x) \rangle}. \quad (2.61)$$

It is demonstrated from this final form of the second order correlation function that this measure, since it is in terms of the intensity distribution (after dephasing or decoherence) of each member final state, without any phase information of the wave functions.

Aside from the second order correlation function, entropy can be used to differentiate between dephasing and decoherence (although, in contrast to the former, the phase information or coherence terms of the density matrix does have to be known). In terms of a density matrix ρ (either pure or mixed) the entropy (particularly Von Neumann entropy) at a given time can be written as

$$S = -Tr(\rho \ln(\rho)), \quad (2.62)$$

where $Tr(\dots)$ denotes the full trace (sum of diagonal elements). This is typically more easily computed by rearranging this in terms of the density matrix's spectral decomposition (in terms of the eigenvalues λ_i of ρ):

$$S = -\sum_i \lambda_i \ln(\lambda_i). \quad (2.63)$$

It will be demonstrated in Chapter 5 how an increase in entropy, $\Delta S > 0$, of a quantum system after undergoing a process indicates that it is a decohering process (as it is related to nonunitary, irreversible evolution), and a process with unchanging entropy, $\Delta S = 0$, may be associated with dephasing (as dephasing is still unitary and thus reversible).

2.8 Chapter 2 Bibliography

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CHAPTER 3

OPTICAL ELECTRON SWITCH

3.1 Introduction

This Chapter details a free electron beam switch which was developed involving interaction with a laser-induced surface charge [1]. The original motivation of this experiment was the creation of an ultra-fast electron switch (within the femtosecond regime) [2]. Such a fast switch has important uses for the fast detection of electrons in experiments such as an electron Stern-Gerlach experiment [3], freefall experiments for electrons [4], plasmonic physics [5], the detection of ultra-fast physics [6,7], and the development of an electron dispersion compensator [8].

The concept behind this fast electron switch makes use of the short travel time-scales of the electron over a nanostructure. Specifically, the idea was to design a rectification switch using a nanofabricated diffraction grating combined with a laser (see Figure 3.1). The electric field of the optical laser induces electric dipoles on the top surface/edge of the 100 nm grating, and these dipoles would then in turn oscillate in phase with the field of the laser. Then, as the electron passes over these dipoles, it would feel a Coulomb force toward (or away, depending on the initial timing of arrival) from the surface as it passes over the beginning of the grating bar (a single solid portion of the grating). Matching the velocity and thus time of flight over the grating bar with the period of the oscillating laser field/dipole field over half the field's period ensures that the electron experiences a force in the same direction for the duration of its travel (thus the force becomes accumulative). Furthermore, the speed of this switching mechanism then simply depends on the speed of the electron and the width of the grating bars. As an

example, for a 3.98 keV electron and a 100 nm grating bar, the deflection switching mechanism can be as fast as $t_{switch} = a_{grating} / v_{flight} = (100 \text{ nm}) / (3.74 \times 10^7 \text{ m/s}) = 2.67 \text{ fs}$.

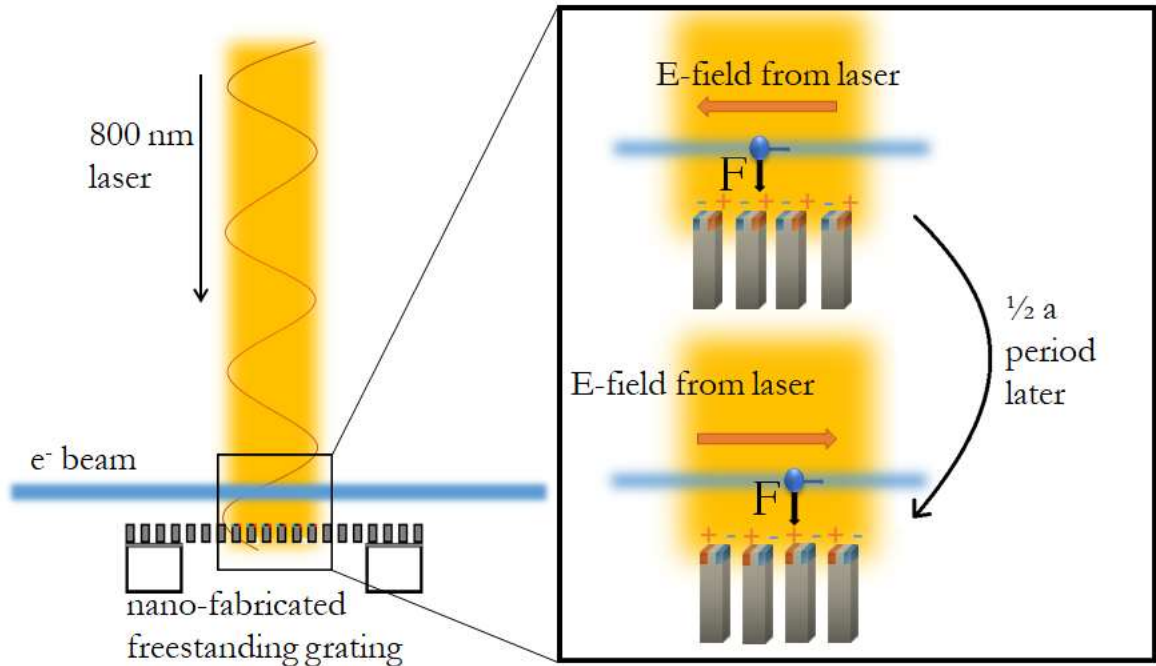


Figure 3.1: Fast Electron Rectification Switch Concept. If we can match the laser frequency with a 3.98 keV electron's travel time over a 100 nm periodic grating bar we can access a steering process that will be as fast as 2.67 fs [9,10].

However, upon attempting to observe deflections of the electron beam due to such a rectification effect, a much larger deflection angle had occurred [1]. It is this effect (which cannot be explained by the above rectification mechanism) that was measured and characterized.

3.2 Setup and Procedure

A 3.98 keV electron beam is collimated by two slits that have widths of 5 μm and 2 μm in the y-direction and are separated by 24 cm in the z-direction. This produces a y-direction beam divergence of $\approx (5 \mu\text{m} + 2 \mu\text{m}) / 24 \text{ cm} = 29 \mu\text{radians}$ (see figure 3.2). 6

cm after the second slit, the electron beam passes over a surface or grating in the x - z plane (primarily SiN, Au coated) with a beam width of 10 μm . This is while a laser (658-800 nm) is focused with a cylindrical lens on the wall near the e-beam's path. This cylindrical focusing is utilized to maximize the intensity of the laser along the electron's path over the surface. By turning the laser on and off via a mechanical chopper or an acousto-optic modulator (AOM), the resulting angle in which the electron propagates can be changed (from a straight-travelling beam to a deflected beam).

To measure the angle in which the beam is deflected, a 5 μm detection slit 24 cm after the surface samples a portion of the electron beam's profile in the y -direction. By scanning the beam in the y -direction with deflection plates (10 cm before the detection slit), an electron distribution is acquired using a multichannel scaler (MCS) software and counting electronics connected to a multichannel plate (MCP). By moving the detection slit by a known distance in the x -direction (as measured by the linear feedthrough's micrometer) and comparing how far in time the center of the histogram travelled, the width and position of the electron beam at the detection screen can be calibrated.

The lasers used were continuous-wave diode lasers with powers of 1 mW, 10 mW and 5 mW with respective wavelengths of 532 nm, 685 nm and 800 nm. The cylindrical lens produced a laser focus FWHM of 280 μm in the y -direction and retained the spot's length of 1 mm in the z -direction along the beam path. The idea behind not focusing the beam in the z direction is to maximize the time in which the beam experiences the charge distribution to maximize the force. With these wavelengths, deflections were observed (though with different magnitudes) indicating that the observation is robust in its generality.

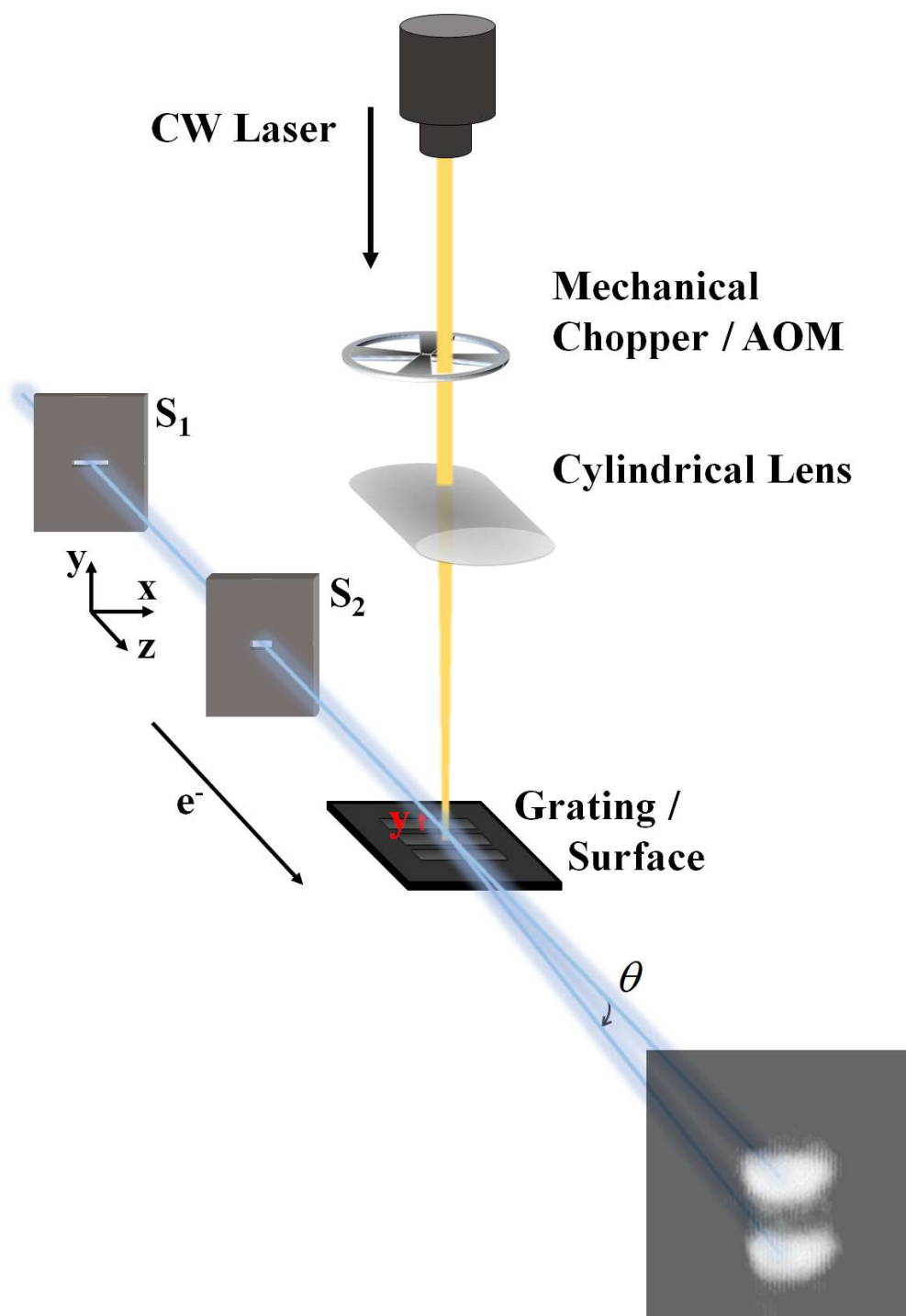


Figure 3.2: Experimental Setup for Surface Optical-Electron Switch. An electron beam is collimated by slits S_1 and S_2 and passes over a Grating/Surface. As the surface is illuminated by a laser beam, it is deflected by an angle θ when the surface is illuminated by a laser beam. For the electrons to switch from one angle/spatial position to another, a mechanical chopper (for low

frequency) or acousto-optic modulator (AOM, for high frequency) turned on and off the laser beam.

3.3 Measurements and Results

To observe the switching speed, the edge of the mount holding the detection slit was used to block the area where the deflected beam would hit the MCP detector (see Figure 3.3). Using the MCS it was found that the switching speed (from on to off) was approximately 6 μ s.

Using the MCS spatial calibration as a guide, the deflection angle was also measured as a function of chopping frequency. For low frequencies, this was achieved with a mechanical chopping wheel. Because this chopping frequency was limited to 2000 Hz and a considerable chopping angle was still observed, the mechanical chopper was replaced with the acousto-optic modulator as the switching mechanism for the laser. Angular deflection was observed up to a frequency of 2 MHz.

Interestingly, the deflection angle dropped roughly linearly with chopping frequency but becomes constant at approximately 100 Hz; then it drops linearly once more starting at approximately 300 kHz. Also, note that the deflection angle between using the mechanical chopper and the AOM during constant frequency region (a difference of a factor of ≈ 2) is due to the loss of intensity of the laser beam as it passed through the AOM.

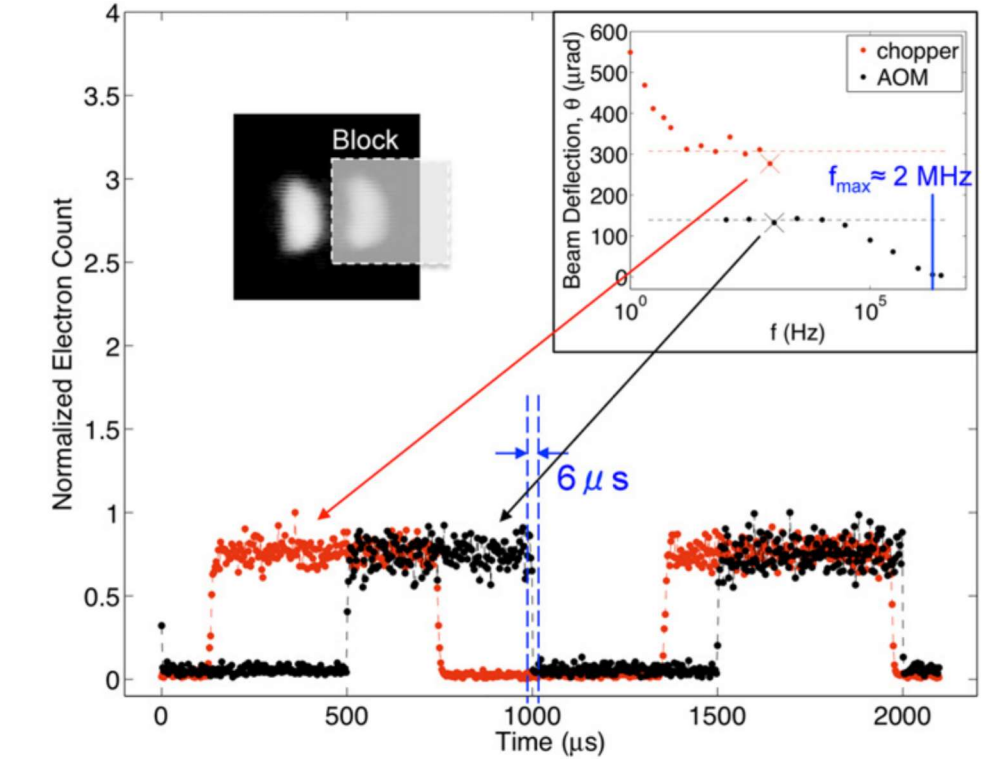


Figure 3.3 Electron-Optical Switch Speed. Plotted is the electron counts as a function of time as the laser is switched on and off. The chopping data for the mechanical chopper (red) at 818 Hz and the AOM (black) at 1000 Hz are shown. Top-left: A time accumulated electron image from the CCD camera shows the initial (left) and deflected electron beam (right). A semi-transparent rectangle “Block” represents the edge of the detection slit mount used to switch the electron beam “on” and “off”. Top-right: Plotted is the electron beam deflection as a function of the chopping frequency (using the AOM or mechanical chopper). The maximum chopping frequency is approximately 2 MHz. The red data points represent the data collected with the chopper and the black data points with the AOM.

A distance dependence measurement of this effect was also taken. Illustrative of how strong this effect is with such low power light, the electron beam can be steered or deflected when it is as far as 200 μm away from the surface (farther than which the deflection amplitude is no longer larger than the divergence angle, thus the deflected beam becomes indiscernible from the original beam), see Figure 3.4. Granted, the power of these lasers was not necessarily maximized, so the beam may potentially be deflected even farther from these surfaces.

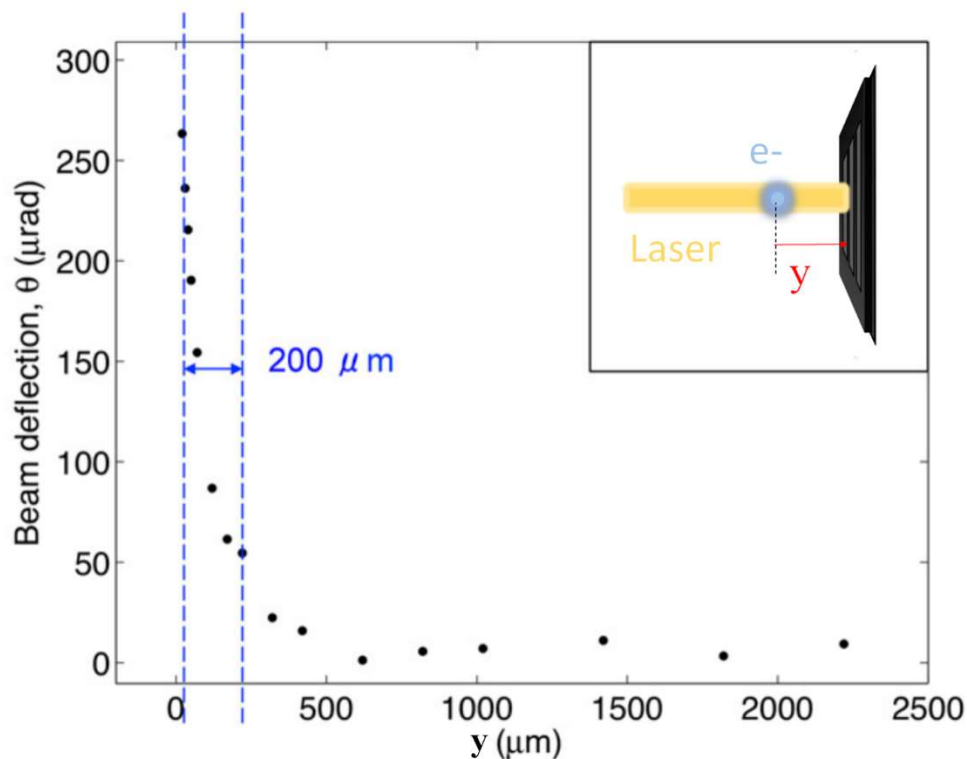


Figure 3.4 Beam Deflection as a Function of Distance Between the Electron Beam and the Surface. the electron beam can be deflected when it is as far as $200 \mu\text{m}$ away from the surface

One of the most remarkable aspects of this observed deflection mechanism is how the deflection angle changes as the laser beam laterally sweeps perpendicular in the x -direction to the beam's path (see Figure 3.5). While the electron deflects towards the surface as the center of the laser beam is directly over the surface, as the laser beam is moved either to either side of the electron's path the deflection angle amplitude decreases to zero and then further *inverts* in the opposite direction such that the beam deflects away from the surface, and of course further movement of the laser from the beam's path leads to a settling out of no deflection. From this deflection distribution as a function of laser position in the x -direction and the relative width of the laser width of $280 \mu\text{m}$ (which is comparable to the distance between the crossovers from attractive deflection to repulsive

deflection) is indicative of a formation of the charge distribution being dependent on the gradient of the intensity of the laser (which is what inspired the ponderomotive model for explaining this laser induced deflection phenomenon).

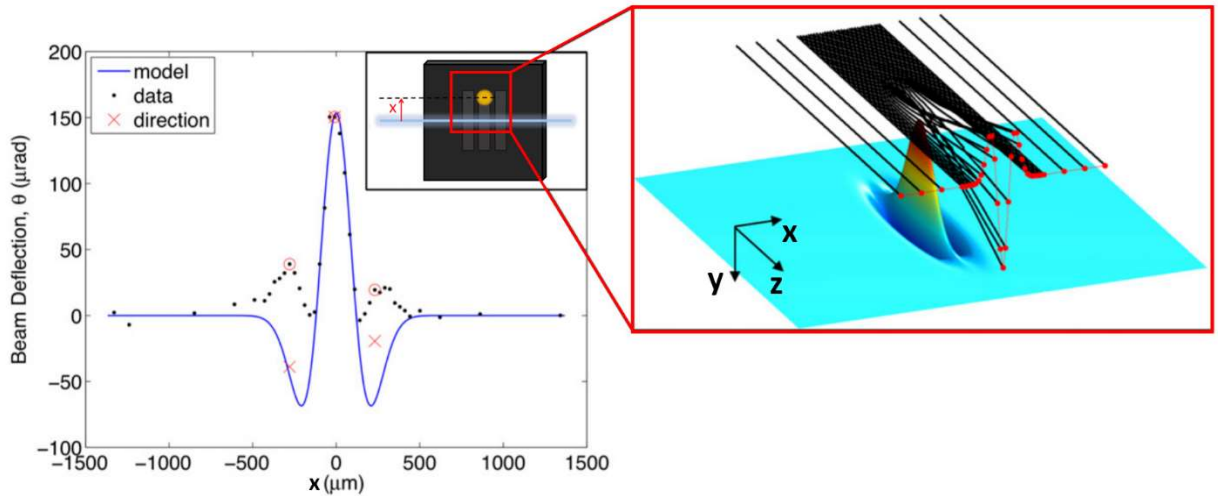


Figure 3.5: Change in Beam Deflection Angle as a Function of the Lateral Position (x) of the Laser Focus. Left: The measured deflection magnitude is measured as a function of the distance between the electron's path and the center of the laser spot. The direction of the deflection is measured at three positions (red circles). The value of these angles including the sign of the direction are indicated (red crosses). Reversals of deflection direction is attempted to be explained by a heuristic model (blue line) of a light-induced surface-charge redistribution based on a ponderomotive force. Right: Diagram of the electron trajectories (black lines) and surface-charge density on the surface (blue to red surface plot) is shown. The interaction between the electron beam and the surface charge distribution is such that it is attractive in the middle of the laser spot and repulsive at the sides of the laser spot (roughly beyond the width of the laser spot, as the FWHM of the laser is focused on the surface at $280 \mu\text{m}$).

In addition to a range of wavelengths, a range of available surface types were also investigated, including gold-palladium coated silicon nitride grating, bare silicon nitride grating, solid aluminum, and solid gallium arsenide (the last of which is unpublished). The general trend seen is that the surface-charge redistribution is driven by the intensity gradient of the laser due to a ponderomotive potential (as seen in Figure 3.5) and this what was found with metal coated SiN observation (Figure 3.5), but this is not the case for uncoated SiN (Figure 3.6) or aluminum. Combining this with issues with the

amplitude of the deflection being limited to only a few factors casts considerable doubt on the ponderomotive force model proposed to explain this deflection model outlined in [1].

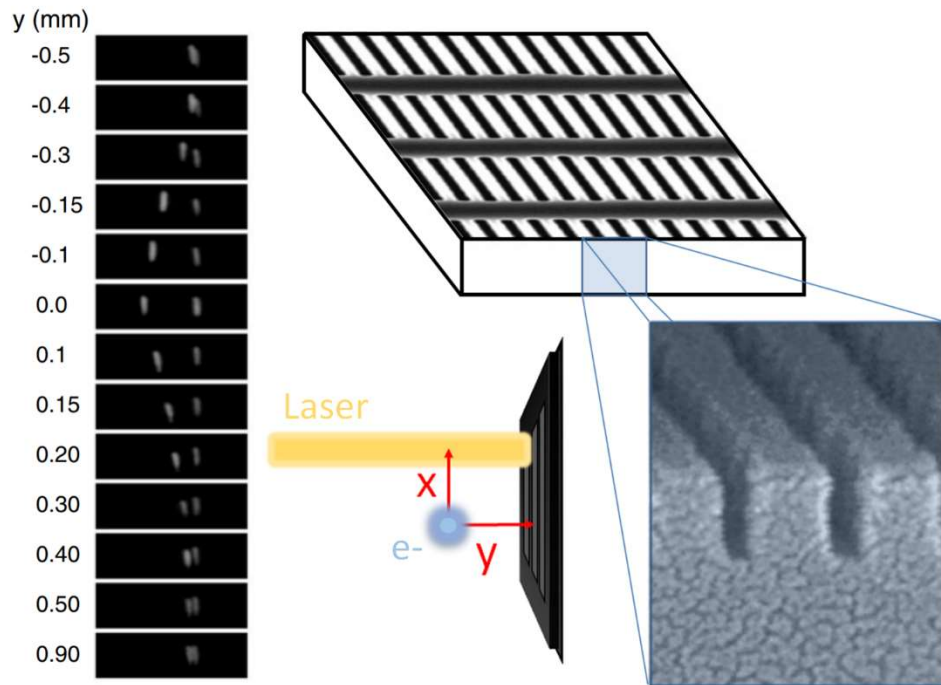


Figure 3.6: “Uncoated” Deflection Measurement. Electron beam deflection is measured as a function of the laser beam position x . This measurement is similar to that shown in figure 3.5, except the deflection is measured at a location on the surface where the coating was not visible, which we call: ‘uncoated’ or bare Silicon Nitride Grating. The deflection images are shown (left column). For all images the laser beam was chopped on and off, while the electron image was recorded continuously. Note that only deflection in one direction was observed in contrast to that reported in figure 3.5 for the coated SiN surface (for a more detailed description see text). An electron microscope image of the SiN surface is shown (top right). A higher magnification image of the edge view of a similar grating (bottom right) is reported earlier [11].

3.5 Conclusion and Outlook

Even without a complete understanding of the physical mechanism of the laser-induced surface charge redistribution which causes the deflection of the free electron, the setup still shows utility in applications such as electron beam lithography and microscopy where external electronics need to be kept isolated [12]. Additionally, further studies in understanding the mechanism of this laser-induced potential will be needed if one were to

investigate coherence effects after travelling over such an environment. Potential pathways of such an investigation include starting with more geometrically simpler surface (for example, a flat surface instead of a nanofabricated grating), using a range of materials which have been well characterized, and using a more comprehensive laser intensity dependence and wavelength dependence study.

3.6 Chapter 3 Bibliography

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CHAPTER 4

DECOHERENCE EXPERIMENT

4.1 Introduction

The continuous divide between quantum and classical physics can be described by decoherence theory. Decoherence is an irreversible process in which a quantum state entangles with an environment in such a way that it loses its wave interference properties [1,2]. For most experiments, maintaining a system's quantum coherence is desirable, and great efforts are made to isolate the system from its environment [3–6]. Additionally, it has been suggested that some sources of decoherence may be ubiquitous, such as those originating from vacuum field fluctuations or gravitation [7–12], and that decoherence in general is a critical element to resolving the quantum measurement problem [13]. Thus, experimentally sorting out various sources of decoherence and determining which dominate is desirable for both technical applications and fundamental studies, including the decoherence program [13].

There have been experiments in which the transition between the quantum and classical domain has been controlled through both the “distance” between states [14–16] and the strength of the interaction with the environment [16–20]. Most of these experiments involve various wave-matter interferometric techniques.

Here we will describe an decoherence setup that realizes Zurek's original thought experiment of diffracting charges through a grating and controlling the spatial quantum coherence with a conducting surface [21]. We have measured the effect of a gold and silicon surface and found upper bounds on the loss of contrast due to decoherence. These results refute current decoherence models premised on image charge [22–24]. We also

identify viable decoherence models based on dielectric excitation theory from effects including surface plasmons [25,26]. In addition, we propose a pathway to measure decoherence due to electromagnetic vacuum field fluctuations.

Sonnentag and Hasselbach previously used an electron biprism interferometer setup with separated arms passing over a semi-conducting surface before recombination [16]. In contrast, we used electron diffraction from a nano-grating and measured the effect of a conducting surface. Diffraction is well suited for measuring small losses in coherence, which is particularly useful in detecting weak decoherence channels. Sonnentag's and Hasselbach's measurements on doped n-type silicon reveals a decoherence strength that is a factor of $\approx 10^2$ too weak as compared to Zurek's image charge model. This is confirmed by our findings.

Their determination of the physical mechanism nevertheless supported image charge models [16,23] as the analysis ignored the strength of decoherence and was limited to a best fit of the functional form, as was done in a similar experiment by Röder and Lubk [27]. The implicit assumption is that a metallic surface (as used in the theory) behaves similarly as a silicon surface. The image charge models were thus considered valid. Our measurements which now also include the conductor gold as well as silicon, refute this conclusion and identify Howie's model [25,26] as viable.

4.2 Experimental Setup

A 1.67 keV electron beam (Kimball EGG-3101 electron gun) is sent through two collimation slits separated by 25 cm with a geometrical beam divergence of 61 μrad in the x -direction and 120 μrad in the y -direction (see Figure 4.1). This collimation gives a transverse coherence length of the electron beam of approximately 600 nm as determined

by diffraction images. This makes it possible to diffract the electrons from a 100 nm periodic nanofabricated grating [28,29]. The diffracted electron distribution is magnified 24 cm downstream by an electrostatic quadrupole lens, detected by a multichannel plate detector, backed by a phosphorous screen (Beam Imaging Solutions BOS-18), and imaged by a CCD camera. A LabVIEW image acquisition program [30] accumulates a two-dimensional streaming image from the camera. The vacuum chamber in which this experiment takes place is held at a pressure of $\approx 4 \times 10^{-5}$ Pa and is protected from external magnetic fields by two layers of mu-metal magnetic shielding.

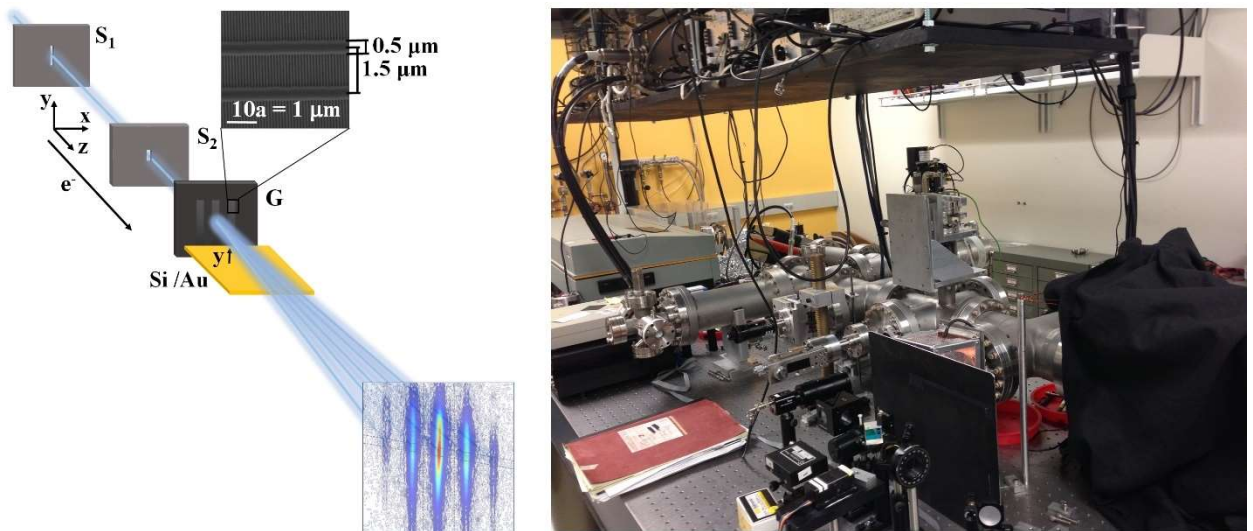


Figure 4.1: Experimental Setup. Left: Diagram of experiment. Electrons are prepared in a spatially coherent state by collimation with two slits (S_1 and S_2), then diffracted through a nanofabricated diffraction grating (G) before passing over either a doped silicon (Si) or gold (Au) surface, which acts as the decohering “environment”. Left: Schematic of Experimental setup with contour plot of data. Right: Image of the “Linear Electron eXperiment” (LEX) utilized for this Decoherence Experiment (as well as the optical electron switch experiment in Chapter 3).

A 1 cm^2 surface is then brought in from below the diffracted beam 3 mm after the grating such that the surface in the x - y plane is perpendicular to the diffraction grating bars. The surface height is adjusted to cut into the beam so that $1/3$ of the intensity of the

original beam reaches the detector. The surface is supported by a mechanical feedthrough whose angular pitch with respect to the beamline can be adjusted with a precision of approx. 0.2 mrad. This pitch of the surface is adjusted to maximize the electron beam's deflection due to image charge attraction. The Si surface was cleaned using a version of the industry-standard RCA cleaning method (without the oxide strip) [31], to remove dust or other contaminants (see Appendix D for more details).

4.3 Analysis

When an electron passes over a decohering surface, it interacts with the surface so that the interference pattern in the far field has lower visibility, and further decreases the closer the electron passes over the surface. Previously, the decoherence was measured in terms of the visibility of the interference pattern [14,16,18,27], i.e.

$$V_{is} = (I_{\max} - I_{\min}) / (I_{\max} + I_{\min}).$$

However, to measure smaller changes in contrast and reduce the uncertainty in measurement due to background counts, we measure coherence in terms of the transverse coherence length of the diffracted beam as observed at the detector [32]:

$$L_{coh} \approx \frac{\lambda_{dB}}{\theta_{coll}} \approx \frac{ad}{w_{FWHM}}. \quad (4.1)$$

Here a is the periodicity of the grating, d is the distance between neighboring diffraction peaks at the detection screen, and w_{FWHM} is the FWHM of a diffraction peak. Thus, here we associate a loss of coherence with an increase of the width of the diffraction peaks w_{FWHM} rather than a loss of visibility.

Two dimensional images of the electron interference pattern are recorded.

Lineouts of the diffractograms are extracted so that each x-direction horizontal lineout corresponds to a 4.8 μm range in the y-direction on the detector where electron detection events occurred. The lineouts are taken at a slant with the x-direction to compensate for the image skew. These diffraction lineouts are fitted by the expression:

$$I(x) = \left(\frac{\sin(\alpha(x-x_0))}{\alpha(x-x_0)} \right)^2 \times [G(x-x_1) + \sum_{n=1} G(x-x_1+nd) + G(x-x_1-nd)] + A_{bck} e^{-(x-x_2)^2/2c_3^2}, \quad (4.2)$$

where the first term corresponds to the single slit envelope and the diffraction peaks, and each individual peak,

$$G(x) = a_1 e^{-x^2/2c_1^2} + (1-a_1) e^{-x^2/2c_2^2}, \quad (4.3)$$

is approximated in terms of two Gaussians with overlapping means, which also very well fits the shape of the beam without diffraction. The full width half max width w_{FWHM} of all diffraction peaks is constrained to be the same for a single diffraction pattern, as is the peak to peak distance d taken to be constant. More details on this fitting method can be found in Appendix A. From this fit w_{FWHM} and d are extracted to compute the coherence length L_{coh} for a given distribution according to equation 4.1 (Figure 4.2). For more details about coherence length in this context, see section 2.4.3 for more details.

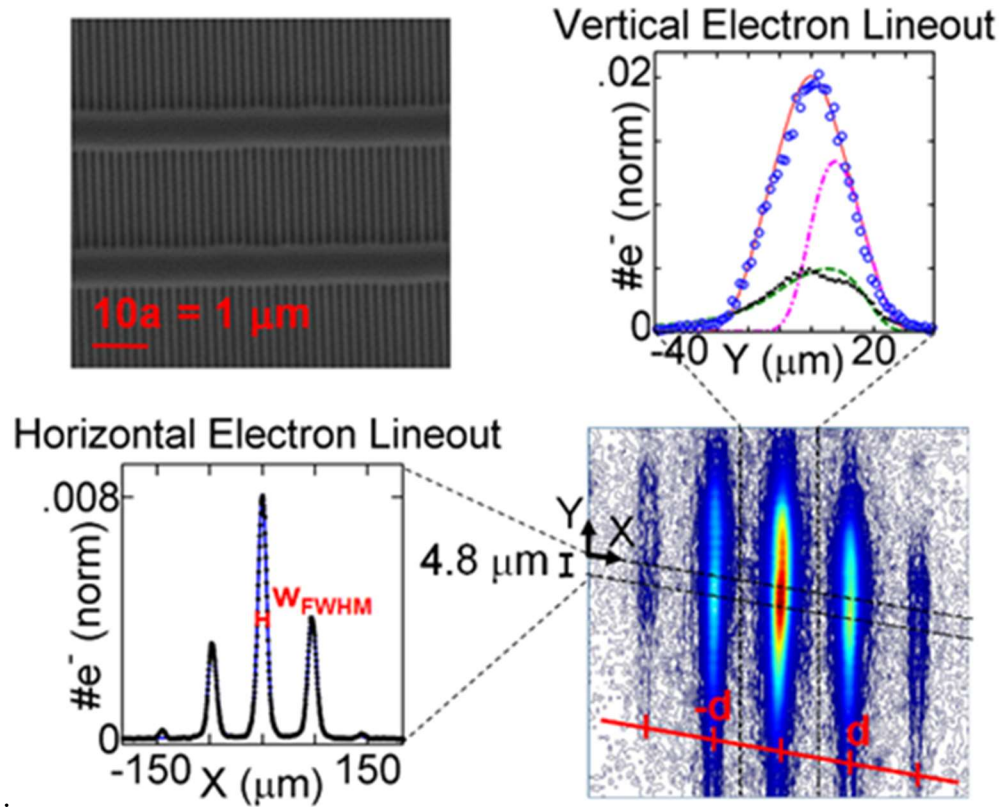


Figure 4.2: Analysis of Diffractogram. Bottom Right: Contour of accumulated CCD image of a diffractogram when the surface cuts the intensity by 1/3 of the original intensity. Top Right: vertical line-out (black solid dots) of zeroth order diffraction peak affected by image charge (see Appendix C for more details). Bottom Left: Horizontal Electron line-out of 4.8 μm of the Diffraction Pattern (Black solid dots). These lineouts are fitted by equation 4.2, and then assigned a coherence length according to $L_{coh} = ad/w_{FWHM}$. Top Left: Nanofabricated diffraction grating with periodicity $a = 100$ nm.

The advantage of using diffractometry over interferometry lies in their respective decoherence measures, L_{coh} and V_s . The background signal can be subtracted for diffraction without distorting the measured value of L_{coh} . This is not the case when measuring visibility in an interferometer. The visibility V_s drops off linearly due to a weak background signal, which can mask decoherence. For a weak decohering environment that scatters the incident beam and introduces background, diffractometry is thus well suited. For more details on this, see section 2.4.4.

4.4 Comparison between Experimental Results and Physical Models

As derived in section 2.5.2, decoherence over the surface modifies the density matrix of the electron according to [1,33]:

$$\rho_{final} = \rho_{initial} e^{-\int_{t_i}^{t_f} dt/\tau_{dec}} = \rho_{initial} e^{-\Gamma}, \quad (4.4)$$

where Γ is the decoherence factor. The decoherence time scale τ_{dec} is not only model-dependent, but also depends on the distance between paths Δx and the height above the surface y . For all electron-surface decoherence models described in section 2.6, the predicted final diffraction pattern is obtained by propagating the final density matrix ρ_{final} to the detection screen (see Appendix C for details). From this, the change in transverse coherence length is then obtained from the calculated far-field diffraction pattern using Equation 1.

Plotted in Figure 4.3 is a comparison of the coherence length as a function of vertical position Y at the detector for the case of two different n-type phosphorous doped silicon samples with resistivities 1-20 Ωcm and 1-10 Ωcm (data points). Our results agree with Hasselbach's experimental findings, who used a 1.5 Ωcm n-type doped silicon sample of 1 cm length using the same beam energy of 1.67 keV. The observed loss of contrast can be visualized in the diffractogram's diffraction peak broadening (Figure 4.3 top right), based on the histogram data collected from the CCD camera (see Appendix D for more details). The surface acting as a lens (e.g. a charge distribution on the surface on the lens) is ruled out as an explanation of the change in coherence length. This is because a simple lens model cannot simultaneously explain both the widths of the diffraction peaks and the peak periodicity values observed (see Appendix D for more details).

The experimental data is also compared to Zurek's model of classical image charge/Ohmic dissipation, Scheel and Buhmann's macroscopic quantum electrodynamic model and Howie's dielectric excitation theory model. The uncertainty associated with the theoretical curves (shaded regions I, II and III) in Figure 4.3 corresponds to the range of Si resistivity 1-20 Ωcm . The shaded region for Hasselbach's experimental fit (IV) corresponds to the published experimental uncertainty [16].

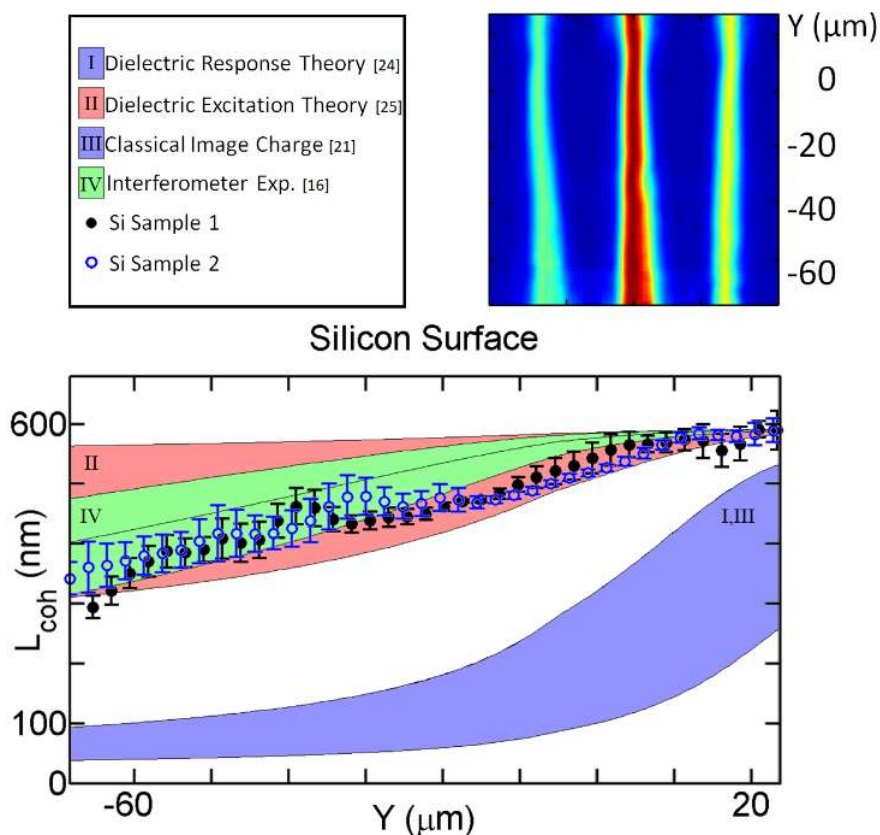


Figure 4.3 Transverse Coherence Length for a Silicon Surface. The diffraction pattern shows a loss of contrast as the diffraction peaks broaden for electrons that passed closer to the surface (top right). Our experimental findings (dotted) show agreement with Hasselbach's experimental fit (IV, green), and is consistent with modelling based on dielectric excitation theory (II, red). The data does not agree with models based on Ohmic dissipation due to classical image charge and macroscopic quantum electrodynamic theory using dielectric response (I and III, blue).

The observed loss of contrast in doped-silicon rules out Zurek's and Scheel's decoherence models. This is in contrast to the claim made earlier that Zurek's model is in adequate agreement with experiment [16]. Even if dephasing is present in our experiment, the observed loss of contrast is much smaller than predicted by the models and therefore the conclusion remains valid. Howie's dielectric excitation model agrees with our findings.

This experiment was also carried out for the case of a gold surface, and plotted in Figure 4.4 is the transverse coherence length as a function of height. For a metal with a resistivity of $2.2 \times 10^{-6} \Omega\text{cm}$ [34], no reduction in contrast is measured for an electron passing close to the gold surface. This is consistent with Zurek's and Scheel & Buhman's models. Machnikowski's quantum many body model based on image charge formation significantly overestimates the loss of coherence, despite being developed for high conductivity metals such as gold. Hence, Machnikowski's model can also be ruled out as a viable decoherence mechanism.

The general lack of height-dependence of the loss of contrast can be visualized in the diffraction peak's width of the diffraction pattern remaining approximately constant (Figure 4.4 top right). This height independence of the coherence length for the case of the gold surface contrasts with that of doped silicon. This may be connected to the much smaller resistivity of gold than doped silicon. No theoretical model is currently able to explain both results.

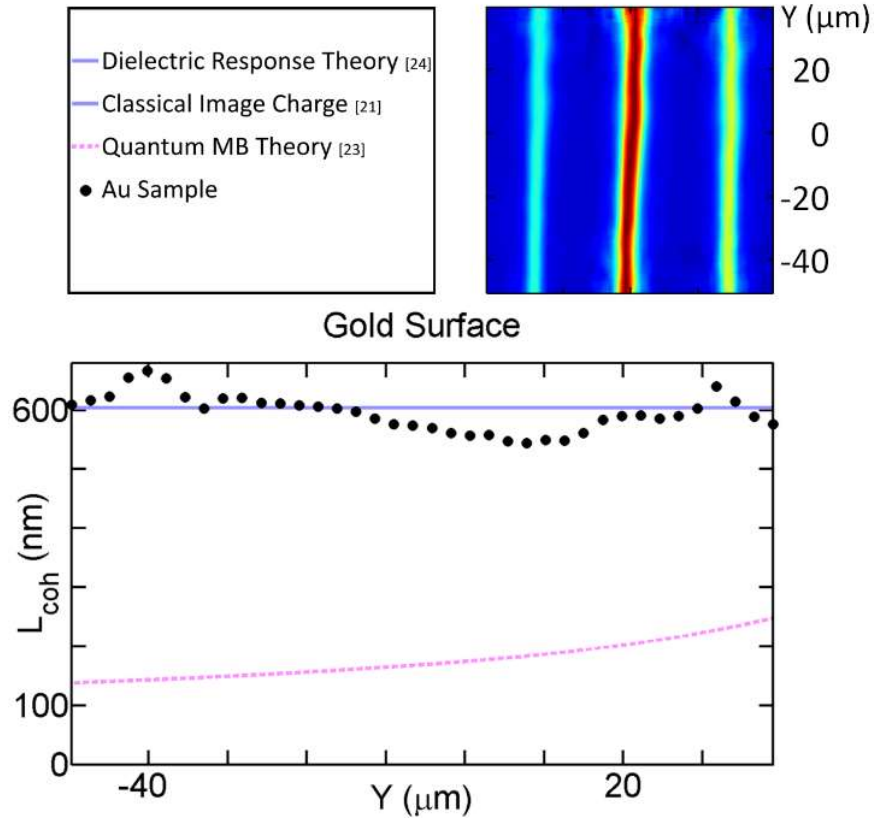


Figure 4.4: Transverse Coherence Length for a Gold Surface. For an initial coherence width of ~ 600 nm, no loss of coherence is observed. Here we can see that decoherence due to image charge formation in a quantum many-body electron gas model can also be ruled out.

4.5 Outlook and Conclusion

This diffractometer setup opens the door to more sensitive measurements of weak decoherence results. Consider that our modest experimental setup is limited by an initial coherence width (~ 600 nm) and that the decoherence factor in many cases scales as $(\Delta x)^2$. Given that it is now possible for transmission electron microscopes (TEM) to reach coherence lengths as large as 100 microns [35], we can thus improve our sensitivity by about 10^4 . This opens the pathway to study decoherence surface effects due to plasmon excitation [25,26,36], optical bandgap excitation, superconductive transitions, spin

dependent transport effects [37–39], coherent thermal near-fields [40–42] blackbody-like near-fields [43,44], etc.

There has been much interest in the potential to measure the effects of decoherence due to vacuum field fluctuations in electron interference [7,8,10,45–47]. It has been shown that, absent of the surface, the decoherence factor scales with $\Gamma \approx (\Delta x)^2 / (T_{flight}^2 c^2)$ where T_{flight} is the total time of flight of the electron [8,47]. Given that Δx is generally between 100 nm – 100 μ m and T_{flight} is roughly between 1 ns – 100 ns, this corresponds to a transverse velocity of $v_T \equiv \Delta x / T_{flight} \approx 10^5$ m/s and a decoherence factor of $\approx 10^7$, which is not currently feasible to observe. To observe such decoherence, the transverse velocity has to be increased by changing the experimental configuration (for example as in a quantum electron microscope [48,49]).

In conclusion, we have confirmed the loss of contrast in an electron diffraction pattern due to the introduction of a doped silicon surface with a strength consistent with Sonntag and Hasselbach’s biprism interferometer experiment. Our diffractometer setup is simpler in terms of its components and is particularly advantageous in observing weak decoherence effects. Thus, we have shown a new pathway to observe weak decoherence channels, including vacuum field decoherence. Additionally, for the case of a gold surface we have placed an upper bound on the loss of contrast that can be attributed to decoherence. Combining our silicon and gold decoherence results, it has been confirmed that the observed effect is strongly material dependent. We have ruled out a range of decoherence models due image charge based on classical theory [22], quantum many body theory [23], and dielectric theory [24]. For the materials and electron beam parameter range studied, our work remains consistent with decoherence effects due to

dielectric excitation theory from effects including surface plasmons [25,26]. These findings are consistent with the general decoherence program [1,2,13].

4.6 Chapter 4 Bibliography

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CHAPTER 5

DEPHASING VS DECOHERENCE

5.1 Introduction

The nature of the loss of quantum interference can be generally separated into two distinct processes: dephasing and decoherence. The effect of these two processes on interference can be seen most clearly in the combined phenomenological expression of the detected probability distribution of two matter-wave states of equal shape [1,2],

$$I(x, t_f) = \left| \psi_1(x, t_f) \right|^2 + \left| \psi_2(x, t_f) \right|^2 + 2 \operatorname{Re} \left(e^{-\Omega(x, t_f)} e^{-i\Theta(x, t_f)} \psi_1^*(x, t_f) \psi_2(x, t_f) + \text{H.O.T.} \right). \quad (5.1)$$

The third term, which is responsible for the interference, can be modulated by both the dephasing term $e^{-i\Theta(x, t_f)}$ (which represents the net distortion from dephasing) and the decoherence term $e^{-\Omega(x, t_f)}$ (which represents the net distortion from decoherence) where both Θ and Ω are real numbers. Notice the similarity between equation 5.1 and equation 2.15. Ignoring the higher order corrections, it turns out that the visibility (a measure of the loss of contrast) in this case is $V = e^{-\Omega(x, t_f)} \operatorname{Re} \left(e^{-i\Theta(x, t_f)} \right)$. Thus, we can see that both processes can contribute to loss of visibility.

There is however an important physical difference between the two processes. Decoherence, which involves entanglement with its environment as described in section 2.5.1, is time-irreversible. Dephasing on the other hand, which involves phase modulation of the wavefunction from an external field, is time-reversible. Unfortunately, visibility, transverse coherence length, and similar measures do not adequately distinguish between

decoherence and dephasing. This makes it hard to identify sources of contrast loss by looking at the intensity distribution alone, and thus take appropriate measures to reduce such a loss of contrast (if the goal is to observe high-contrast diffraction or interference).

As this relates to the work presented in Chapter 4, a separate issue is revealed. When probing the transition from quantum to classical mechanics, or testing if one is introducing a decoherence environment to a system, it is not immediately evident that the observed loss of contrast is due to decoherence rather than dephasing using the measurement methods that are traditionally utilized. This opens the concerning question of whether or not the transition between quantum and classical transition has actually been observed, or if only upper limits to the loss of coherence have been observed.

One straightforward way to determine if a process is a decohering one is to evaluate the Von Neuman entropy before and after the process:

$$S = -Tr(\rho \ln \rho) \quad (5.2)$$

When S remains constant in time, the process is time-reversible; as opposed to when S increases in time, the process is time-irreversible [3]. Calculating S however requires the determination of the off-diagonal elements (also known as the coherence terms) of the density matrix ρ . These terms cannot be determined by the intensity distribution alone, and require phase retrieval techniques such as holography or quantum state tomography [4].

Instead of relying on such methods, we have proposed using the method based on repetitive ensemble measurements of the propability distribution using a spatial correlation function of these measurements. Without knowing the details of the dephaser (defined as a process which causes dephasing), we show that, with repetitive

measurement, this method can in principle extract sufficient information to recover the loss of contrast in the diffraction pattern. Conversely, we show that the same process fails to recover the loss of contrast in the diffraction pattern for the case of a decoherer (defined as a process which causes decoherence).

5.2 Path Integral Simulation with Dephasing and Decoherence

The following is a description of how, via the path integral formalism [5,6], a discrete numerical simulation is used to produce a far field diffraction pattern after the electron undergoes either dephasing or decoherence in the near field of a diffraction grating (particularly right before the grating). The final density matrix in both cases is recorded. This is initially pursued to demonstrate that we can create a decoherer and a dephaser that both produce a similar loss of contrast. But by calculating the entropy before and after the simulation, it is shown that the dephaser does not change the entropy of the system while the decoherer increases the entropy in the system.

The parameters used are inspired by the decoherence experiment's setup outlined in Chapter 4. Figure 5.1 is a rough sketch of the grid planes used in this computation. These grid points are the positions considered in a finite sum approximation of the path integrals. Only straight-lined paths are considered, and an azimuthal equal velocity approximation is used for the propagator [6].

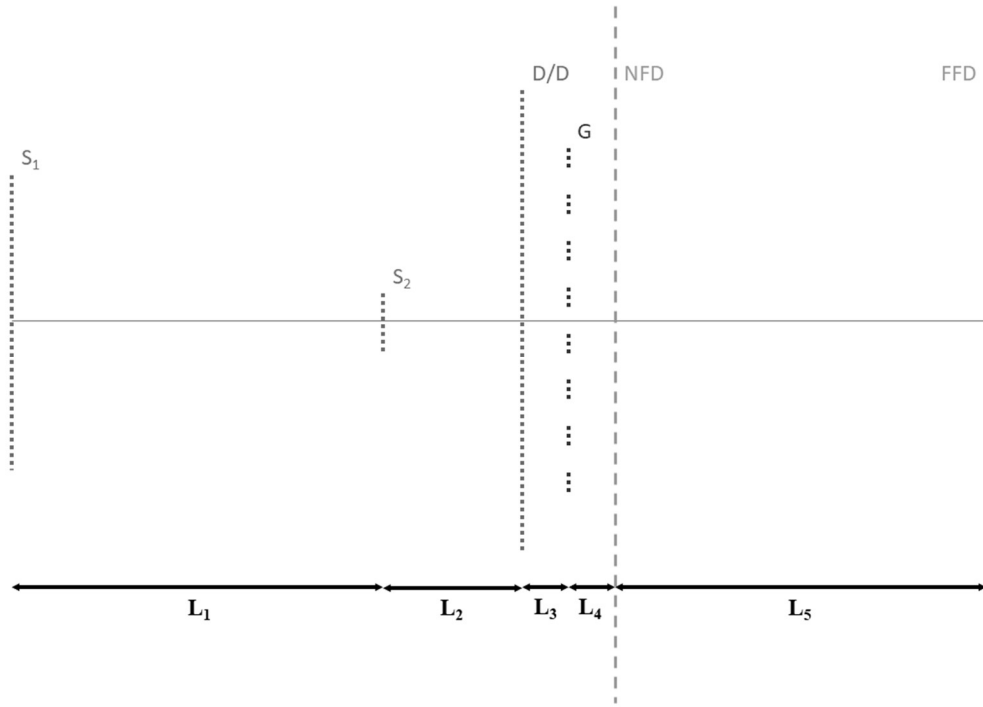


Figure 5.1: Diagram of Dephaser/Decoherer Path Integral Setup 1. A matter wave (with the mass of an electron and an energy of 1.67 keV) propagates incoherently from the first collimation slit (S_1) to a second slit, (S_2) to a plane acting as a dephaser or decoherer (D/D). It then propagates through a grating (G) and finally to the near field (NFD) and the Far Field (FFD).

Beginning with the dephaser case, the wavefunction propagates from one individual grid point x_k at the plane representing slit 1 to the plane for slit 2 with grid points x_j to produce the wave function ψ_2 at slit 2:

$$\psi_2^k(x_j) = \sum_j e^{-i2\pi\sqrt{(x_j-x_k)^2+L_1^2}/\lambda_{dB}}, \quad (5.3)$$

where $\lambda_{dB} = h/mv$ is the de-Broglie wavelength of the electron.

The wave propagation continues from the second slit from each grid point x_i to the plane representing the dephaser with grid points x_j :

$$\psi_3^k(x_j) = \sum_j e^{i\theta_n(x_j)} \sum_i \psi_2^k(x_i) e^{-i2\pi\sqrt{(x_j-x_i)^2+L_2^2}/\lambda_{dB}}. \quad (5.4)$$

A phase $e^{i\theta_n(x_j)}$ is applied to the wave function ψ_3 to act as the dephaser, a piecewise step function which consists of N blocks of 241 nm size with constant phase angle θ_n uniformly randomly varying from 0 to $2\pi c$ (see Figure 5.2). The quantity c is a tunable variable used to tune the dephasing effect; i.e. $0 \leq c \leq 1$ where $c=0$ means no dephasing and $c=1$ is maximal dephasing for this step function dephasing pattern.

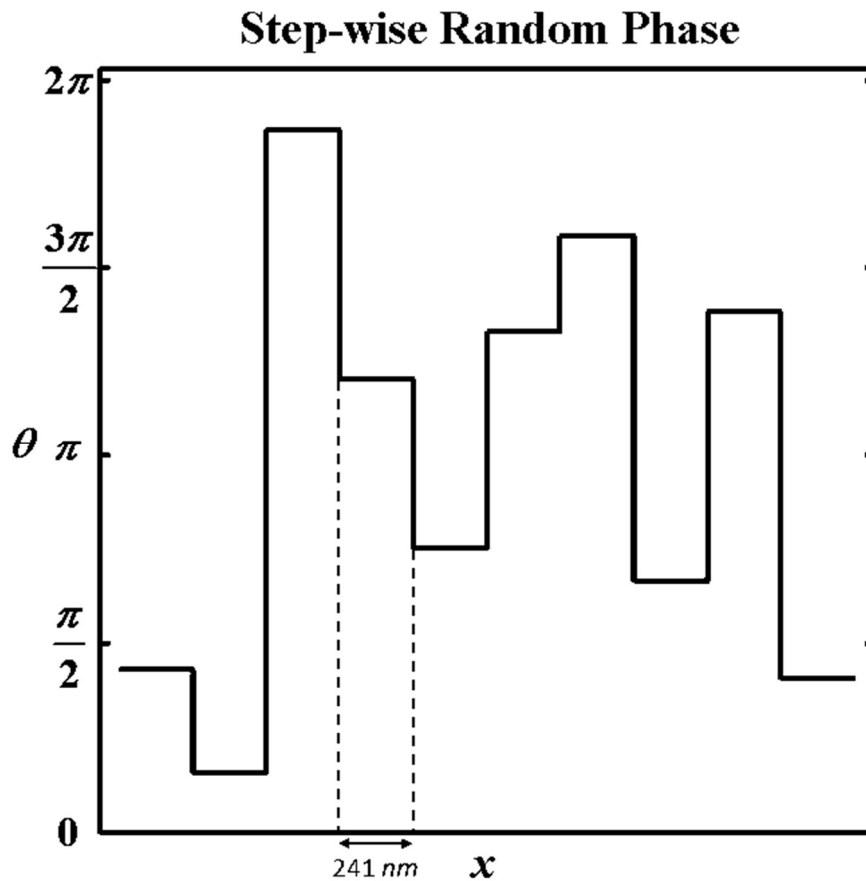


Figure 5.2. Step-wise Defined Random Phase used in Dephaser.

Next, the wave propagates to a grating at a distance of L_3 away, which has a 50/50 transmission ratio and 100 nm periodicity:

$$\psi_4^k(x_j) = \sum_j H(x_j) \sum_i \psi_3^k(x_i) e^{-i2\pi\sqrt{(x_j-x_i)^2+L_3^2}/\lambda_{dB}}, \quad (5.5)$$

where $H(x_j)$ represents the grating function (equals 1 for transmission and equals 0 for no transmission). Then the propagation continues to the near field of the grating, and then to the far field “detector”:

$$\begin{aligned} \psi_5^k(x_j) &= \sum_j \sum_i \psi_4^k(x_i) e^{-i2\pi\sqrt{(x_j-x_i)^2+L_4^2}/\lambda_{dB}} \\ \psi_6^k(x_j) &= \sum_j \sum_i \psi_5^k(x_i) e^{-i2\pi\sqrt{(x_j-x_i)^2+L_5^2}/\lambda_{dB}}. \end{aligned} \quad (5.6)$$

With such a wave function, initially from the k^{th} grid point at the first slit, we construct a density matrix (which is at the moment still coherent):

$$\rho_k = |\psi_6^k\rangle\langle\psi_6^k|. \quad (5.7)$$

We repeat the above series of path integrals for all N_s grid-points at the source and sum the density matrices together (and then normalize) to obtain the final density matrix associated with dephasing:

$$\rho_{final}^{deph} = \sum_k \rho_k = \sum_{k=1}^{N_s} |\psi_6^k\rangle\langle\psi_6^k|. \quad (5.8)$$

For our initial modeling of decoherence instead of dephasing, this path integral system is somewhat modified. The initial propagation from the first to second slit outlined in equation (5.3) remains the same. However, from the second slit to the decoherer, the only paths considered are those whose final position lies within the n^{th} 241 nm piecewise step section of the random phase. $e^{i\theta_n(x_j)}$ are initially integrated over:

$$\psi_3^{k,n}(x_j^{(n)}) = \sum_{j \in n} e^{i\theta_n(x_j^{(n)})} \sum_i \psi_2^k(x_i) e^{-i2\pi\sqrt{(x_j^{(n)}-x_i)^2+L_2^2}/\lambda_{dB}}. \quad (5.9)$$

Then from this smaller portion of the dephasing plane, the wave function continues to propagate to the grating:

$$\psi_4^{k,n}(x_j) = \sum_j H(x_j) \sum_{i \in n} \psi_3^{k,n}(x_i^{(n)}) e^{-i2\pi\sqrt{(x_j-x_i^{(n)})^2+L_3^2}/\lambda_{dB}}, \quad (5.10)$$

and as before to the near and far field:

$$\begin{aligned} \psi_5^{k,n}(x_j) &= \sum_j \sum_i \psi_4^{k,n}(x_i) e^{-i2\pi\sqrt{(x_j-x_i)^2+L_4^2}/\lambda_{dB}} \\ \psi_6^{k,n}(x_j) &= \sum_j \sum_i \psi_5^{k,n}(x_i) e^{-i2\pi\sqrt{(x_j-x_i)^2+L_5^2}/\lambda_{dB}}. \end{aligned} \quad (5.11)$$

Note as before that while up to this point a fully coherent density matrix has been produced,

$$\rho_{k,n} = |\psi_6^{k,n}\rangle\langle\psi_6^{k,n}|, \quad (5.12)$$

to produce the desired final density matrix representative of the entire process, not only does one add incoherently over all initial states at the source, but also over all N_p piecewise segments of the decoherer. Thus:

$$\rho_{final}^{dec} = \sum_n \sum_k \rho_{k,n} = \sum_{n=1}^{N_p} \sum_{k=1}^{N_s} |\psi_6^{k,n}\rangle\langle\psi_6^{k,n}|. \quad (5.13)$$

A summary of the parameters used in this path integral simulation to test the results of the effects of this dephaser and decohere can be found in Appendix E.1.

One can then determine the coherence length and time associated with the resulting probability distribution by taking the diagonal of the final density matrix,

$$P_{final}(x) = \text{diag}(\rho_{final}). \quad (5.14)$$

The von Neumann entropy S (Equation 5.2) of the system can be determined using the final density matrix, most easily by first determining the eigenvalues of the density matrix:

$$S = -\sum_i \lambda_i \ln(\lambda_i). \quad (5.15)$$

The results of doing this can be seen in Figure 5.3, where plotted is the final intensity distribution for the cases of 1) no dephasing/decoherence, 2) with dephasing, and 3) with decoherence (where $c=.7$). The coherence length in both cases decreases, and they decreased by roughly the same amount (although the spatial noise for the dephasing case is much larger). However, from the second slit to the detector, the change in entropy $\Delta S=0$ for the case of dephasing, whereas the entropy increases by $\Delta S= 2.7444$ for the case of decoherence.

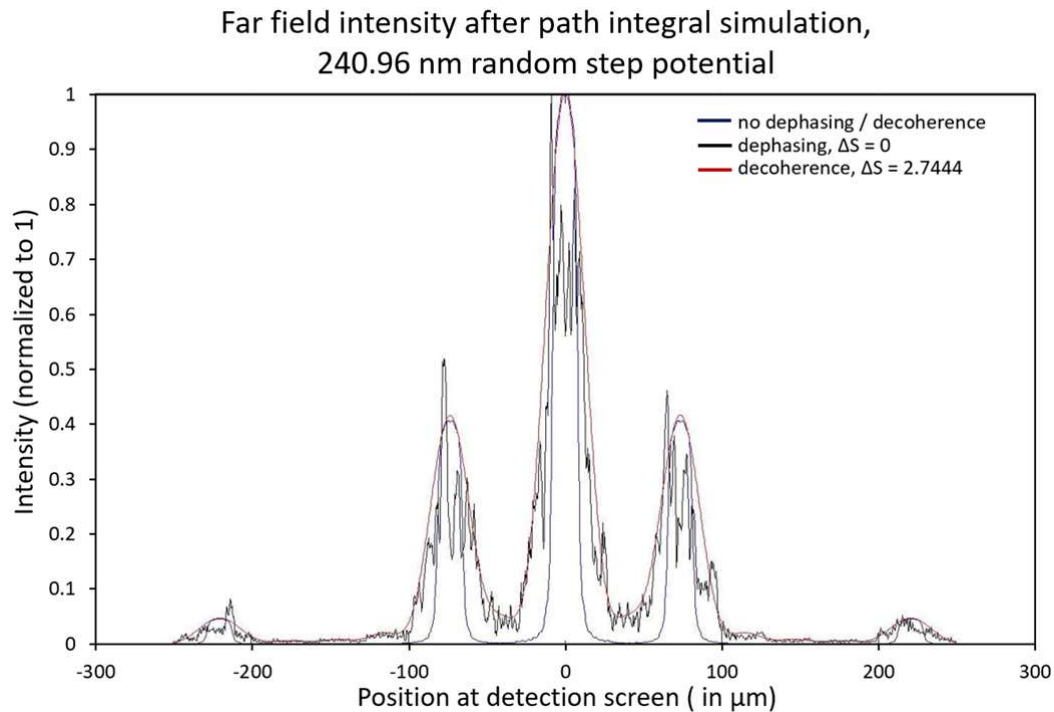


Figure 5.3: Far Field Intensity Pattern After Dephasing/Decoherence Path Integral Simulation 1. Adding dephasing and decoherence in this case widens the diffraction peaks, but in the case of decoherence, the entropy increases.

It can be concluded that these two processes both can alter the interference properties in proximately the same way (and if one were to take a time average, they can become indistinguishable). However, given that entropy changes in one case and remains unchanged in another, the underlying physical mechanisms indeed differ in a very fundamental way which further motivates a means to distinguish what is the cause of the lost of contrast post-diffraction/interference.

5.3 Spatial Correlation Method

Previously, Rui-Feng et al [7] developed an optical experiment that exhibited a loss of contrast. They managed to recover the diffraction pattern after it was severely distorted using a ground glass disk. Here they shined a red 632.8 nm laser through a double slit with a slit separation of $d = 1.5$ mm and slit width of .5 mm; and imaged the diffraction pattern at a distance $z = 20$ cm in the Fresnel diffraction region ($z \ll z_0$; $z_0 = d^2/\lambda \approx 3.5$ m) using a CCD camera (see Figure 5.4). They also placed a ground glass disk spinning at .5 Hz very close and right before the double slit. When the ground glass disk was removed, the camera can clearly image the near field pattern with its two main lobes and smaller near field fringes present. When the ground glass disk is present, the image is completely blurred away and no information seems to remain.

As the ground glass disk was spinning, images of the pattern were taken with a 100 μ s exposure time for each image. After collecting many blurred images (~ 1000), they used a second order correlation function on the spatial intensity distribution according to;

$$g^{(2)}(x, -x) = \langle I(x)I(-x) \rangle / (\langle I(x) \rangle \langle I(-x) \rangle). \quad (5.16)$$

where $I(x)$ represents the intensity measured on the CCD camera at position x in the direction of diffraction (taking $x=0$ to be the center of the camera) and $\langle \dots \rangle$ here representing averaging over time (or averaged over the frames). The result of this is was the production of a second order correlation pattern which closely fits the Fraunhofer pattern, or expected far field diffraction pattern that matched the experimental parameters. The implication of this is that after Fourier transformation of the second order correlation function, the original near field pattern can be restored.

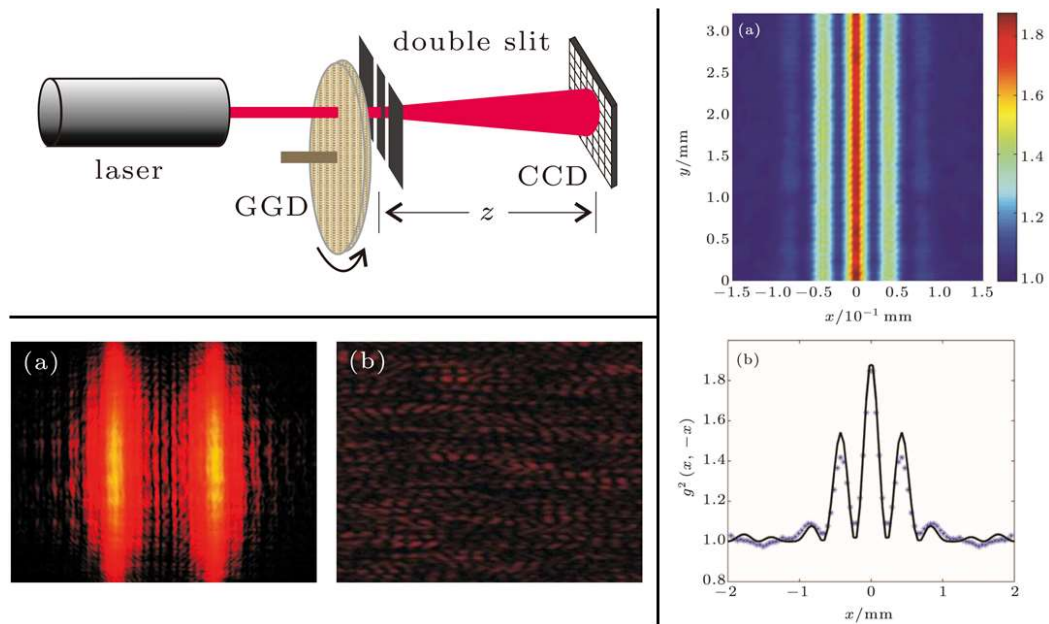


Figure 5.4: Ghost Imaging Experiment by Rui-Feng et al [7]. Top Left: Experimental setup. Laser light is sent through a rotating ground glass disk (GGD) before passing through a double slit and being imaged by a CCD camera in the Fresnel diffraction region. Bottom Left: (a) The Near Field intensity image obtained when no GGD is present shows a coherent diffraction pattern as opposed to (b) a blurred or scrambled pattern when the GGD is present. Right: by calculating the second order correlation function $g^{(2)}(x, -x)$ from a series of blurred images, the far field diffraction pattern is obtained. Thus after a Fourier transformation of $g^{(2)}(x, -x)$, near field information can be restored. See text and [3] for more details. Photos credited to Rui-Feng et al [7].

It is from this work we asked the questions: given that it appears that scrambled information is restored, is this recovery procedure one method to discern if the process which causes loss of contrast (the laser light passing through the ground glass disk) reversible or irreversible, and thus a dephasing or decoherence process? Under what parameters is this diffraction reconstitution possible? Can such a method be extended to matter-wave optics?

To test this, the path integral simulation described in Section 5.2 was modified so diffraction of the electron occurs through a double-slit rather than a grating, resembling the double slit experiment by Bach et al [8] (see Figure 5.5). An electron energy of 1.67 keV is used, but it starts with a fully coherent plane wave which propagates to the double-slit. The dephasing/decoherence takes place at the double-slit plane rather than being a separate plane (i.e. there is no propagation between the dephasing/decohering plane and the double slit). It then propagates to the far field detection plane. A summary of the parameters can be found in Appendix E.2.

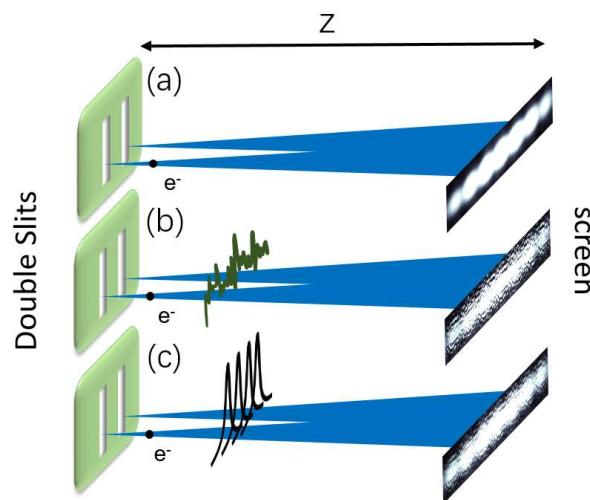


Figure 5.5. Dephasing vs Decoherence for the Case of the Double Slit. Sketch of the double slit setup when (a) no dephasing or decoherence is present, (b) dephasing and (c) decoherence. Contrast is lost for the cases of dephasing and decoherence. For dephasing, a random potential (dark green curve) using a sum of gaussians is used at the double-slit. For decoherence, the electron wave is split into a probabilistic sum of separate incoherent overlapping gaussian waves,

and then propagate to the detector. The diffraction image produced in (a) is attributed to Bach et al [8]. Image produced by Zilin Cheng.

For the dephaser, instead of the phase distribution being in the form of a step function, the spatial dephasing pattern used in $e^{i\theta(x)}$ is a smooth sum of 500 Gaussians:

$$\theta(x) = \sum_i A_i e^{-\left(\frac{x-x_i}{\sigma_i}\sqrt{2}\right)^2}, \quad (5.17)$$

where each A_i and x_i are evenly distributed random numbers within the intervals $[0, 2\pi]$ and $[-250 \text{ nm}, 250 \text{ nm}]$ respectively. σ_i is a normally distributed random number with a mean value of 4 nm and a standard deviation of .5 nm.

For the case of decoherence, the same phase is applied, and as before the wave propagation is cut into finite segments. However, this time instead of being cut into boxed segments, the entire double-slit plane is propagated over, and this time the wave function is truncated by a Gaussian function (similar to a grating or double slit function):

$$\psi^n(x) = \psi_d(x) A_0 e^{-\left(\frac{x-x_n}{\sigma_0}\sqrt{2}\right)^2}, \quad (5.18)$$

where $\psi_d(x)$ is the wave function at the double-slit with the smooth random phase pattern, $A_0 = 2.23 \times 10^{-5}$ and $\sigma_0 = 100/\sqrt{2}$ nm are constant values of and x_n is the central position of the Gaussian. For the incoherent adding of the path integrals (addition like before), the distance between these Gaussians is 12.5 nm and there are 40 Gaussians total. Plotted in Figure 5.6 are representative images of the random phase pattern and the summed Gaussians at the double slit plane.

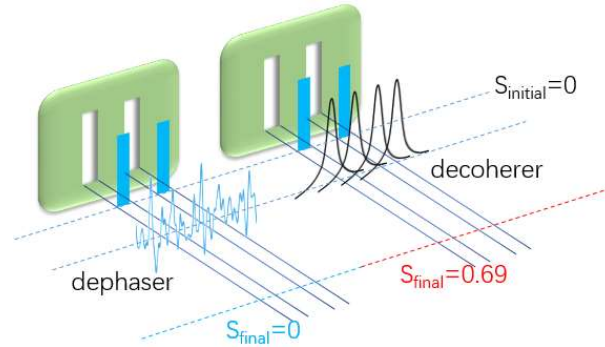


Figure 5.6: Representative Diagram of Dephasing and Decoherence at the Double Slit. the vertical lines show the range of the double slit. Left: the blue curve represents the smooth random phase also applied to the electron wave function. Right: example Gaussian distributions applied to the wave function. Note that here the widths and separations are not drawn to scale. For dephasing, only the phase is applied to the wave function while for decoherence both the random phase and (incoherently added) the Gaussians are applied to the electron wave function at the double slit. For both cases the diffraction pattern was calculated 500 times each with a different set of random numbers. Image Produced by Zilin Cheng

This path integral simulation was carried out 500 times for both the dephasing and decoherence case each with a different smooth random phase applied. Plotted in Figure 5.7 are example intensity distributions as measured in the far field after dephasing/decoherence, and the time average of each. Individually, although the main structure is maintained for both dephasing and decoherence (in that the position and relative amplitudes of the maxima are similar in both cases), a lower contrast for the case of decoherence is a distinguishing difference for a single iteration. For the near field, this is consistent with the work done by P Kazemi et. al [9]. where they were able to see interference minima for the case of dephasing in the near field quantum carpet, but not for the case of decoherence.

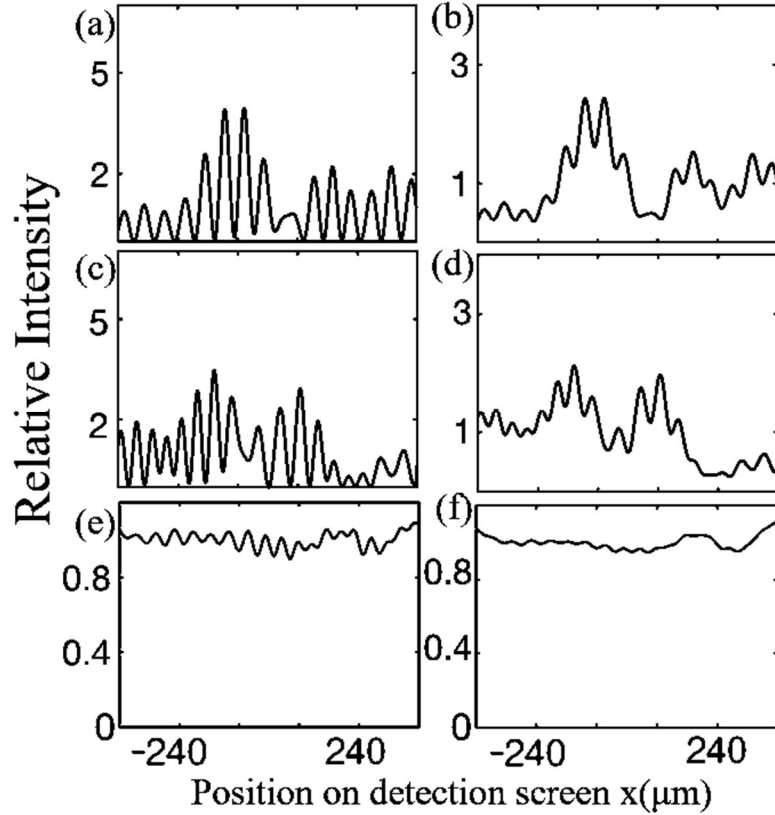


Figure 5.7 Example Intensity Distributions in Far Field after Dephasing/Decoherence for Path Integral Setup 2. (a) and (b) shows the intensity distribution resulting after experiencing the first random phase after dephasing and decoherence, respectively. (c) and (d) shows the intensity distribution after a different smooth random phase. Individually, although the main structure is maintained for both dephasing and decoherence (in that the position and relative amplitudes of the maxima are similar in both cases), a lower contrast for the case of decoherence is a distinguishing difference for a single iteration. (e) and (f) show the intensity distributions averaged over 500 iterations with different random phases. Image produced by Zilin Cheng.

Similar to Rui-Feng et al [7], the deviation of the correlation function (equation 5.16) is applied to the sequence of 500 phase-independent final intensity distributions in the far field for both the dephasing and decoherence simulations:

$$\begin{aligned}
 \Delta G^{(2)}(x_1, x_2) & \\
 &\equiv G^{(2)}(x_1, x_2) - \langle I_1(x_1) \rangle \langle I_2(x_2) \rangle \\
 &\equiv \left| \int dx'_1 dx'_2 h_1^*(x_1, x'_1) h_2(x_2, x'_2) G^{(1)}(x'_1, x'_2) \right|^2.
 \end{aligned} \tag{5.19}$$

The result is a recovery of what resembles the far field diffraction pattern for the case of dephasing and what appears to be only a single peak for the case of decoherence.

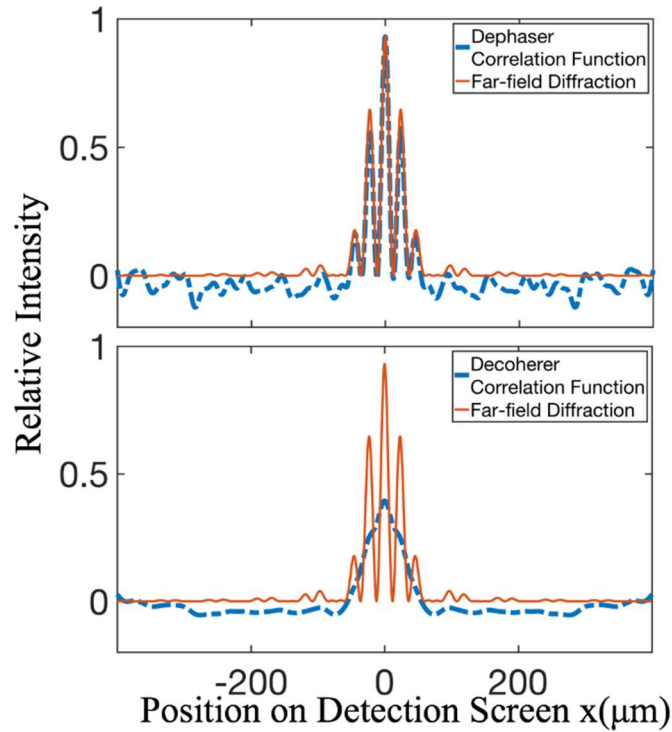


Figure 5.8: Effects of Applying the Correlation Function $g^{(2)}(x,-x)$. When applying the correlation function $g^{(2)}(x,-x)$ to 500 independent iterations of the far field pattern where (top) is the computation after dephasing while (bottom) is the computation after decoherence. The correlation function successfully recovers a far field pattern in the case of dephasing while this is not the case for decoherence. the diffraction pattern fits the dephaser correlation pattern well, as the peak to peak distance of the correlation pattern ($22.9 \mu\text{m}$) is close to the expected diffraction peak to peak distance ($24 \mu\text{m}$). Image produced by Zilin Cheng.

Fitting the autocorrelation pattern that came out of the dephasing case with the double slit diffraction pattern function in the small angle approximation (See Figure 5.8),

$$I(x) = 4w^2 \text{sinc}^2\left(\frac{wx}{\lambda L_2}\right) \cos^2\left(\frac{\pi dx}{\lambda L_2}\right), \quad (5.20)$$

where w is the width of the slits (50 nm), d is the distance between slits (150 nm), λ is the electron's wavelength (30.03 pm), and L_2 is the distance from the double slit to the far

field screen (24 cm). Using these values, one would expect that the distance between local maxima (peaks) in the diffraction pattern would be 24 μm , and the best fit to our autocorrelation pattern is a peak to peak distance of 22.9 μm .

The change in entropy from the source to detection for both dephasing and decoherence cases is computed as before (equation 5.15). For dephasing, the change of entropy was $\Delta S = 0$ whereas for decoherence the change in entropy was increased by $\Delta S = 0.69$, as anticipated from the previous path integral results. This reaffirms that the dephasing processes we theoretically realized are time-reversible while the decoherence process is time-irreversible.

5.4 Conclusion and Outlook

In conclusion, we have reaffirmed using a matter wave path integral simulation that the distinguishing feature between dephasing and decoherence processes is that the former is a time-reversible process and the latter is a time-irreversible process. Although the resulting time-averaged intensity patterns can be difficult to distinguish from each other at first glance, by taking a sequence of measurements and performing an autocorrelation computation on the time sequence in the far field, we have found that a far field diffraction pattern showing high visibility interference can indeed be recovered for the dephasing case, but not for the decoherence case. This result agrees with the experimental results by Stibor et. al. [10,11].

Questions arise regarding how to realize this result experimentally. Primarily, how fast does the imaging of individual patterns need to be in order to recover the far field diffraction pattern for the case of dephasing? Although in Stibor's case they

managed to recover interference by taking the positions of nearest and next nearest neighbors of individual electron events, they used a known modulation frequency. Therefore, we hypothesize that so long as the characteristic dephasing time (between modulations or “sequences”) is sufficiently slow compared to the time to accumulate a statistically significant far field pattern, a diffraction pattern should be recoverable.

Besides these results having implications for fundamental studies including thermodynamics in quantum mechanics and experiments pertaining to the quantum measurement problem, this process has application as a diagnostic tool for determining the source of loss of contrast in imaging involving diffraction such as transmission electron microscopy (TEM) and improving contrast in long-exposure images that are distorted over time.

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CHAPTER 6

CONCLUSIONS AND OUTLOOK

6.1 Optical-Electron Switch

Despite issues with having a complete understanding of the physical mechanism of the laser-induced surface charge redistribution which causes the deflection of the free electron, the setup still shows utility in applications such as electron beam lithography and microscopy where external electronics need to be kept isolated [1]. Additionally, further study in understanding the mechanism of this laser-induced potential will be needed if one were to study coherence effects after travelling over such an environment. Potential pathways of such an investigation include starting with more geometrically simpler and pristine surfaces, using a range of materials which have been well characterized, and using a more comprehensive laser intensity dependence and wavelength dependence study.

6.2 Decoherence Experiment

This diffractometer setup opens the door to more sensitive measurements of weak decoherence results. Consider that our modest experimental setup is limited by an initial coherence width (~ 600 nm) and that the decoherence factor in many cases scales as $(\Delta x)^2$. Given that it is now possible for transmission electron microscopes (TEM) to reach coherence lengths as large as 100 microns [2], the sensitivity can thus be improved by about 10^4 . The general method of detection present here opens the pathway to study spatially dependent decoherence surface effects due to plasmon excitation [3–5], optical

bandgap excitation, superconductive transitions, spin dependent transport effects [6–8], coherent thermal near-fields [9–11], blackbody-like near-fields [12,13], etc.

In this experiment, we have confirmed the loss of contrast in an electron diffraction pattern due to the introduction of a doped silicon surface with a strength consistent with Sonnentag and Hasselbach’s biprism interferometer experiment. Our diffractometer setup is simpler in terms of its components and is particularly advantageous in observing weak decoherence effects. Thus, we have shown a new pathway to observe weak decoherence channels, including vacuum field decoherence. Additionally, for the case of a gold surface we have placed an upper bound on the loss of contrast that can be attributed to decoherence. The silicon and gold decoherence results together confirm that the observed effect is strongly material dependent. We have ruled out a range of decoherence models due image charge based on classical theory [14], quantum many body theory [15], and dielectric theory [16]. For the materials and electron beam parameter range studied, our work remains consistent with decoherence effects due to dielectric excitation theory from effects including surface plasmons [4,5]. These findings are consistent with the general decoherence program [17–19].

If the goal is to study decoherence for its own sake, then there is a need for less complex and well characterized environments. Such an engineered environment reduces the number of possible decoherence channels. Fine-tuning the geometry of the material may be one way of doing this (such as low dimensional materials to reduce certain degrees of freedom and thus restricting the field modes, such as quantum dots, atomic and molecular gases, nano-wires, and low dimensional surfaces), as well as choosing

materials that suppress certain field channels and enhance others (eg thermal polaritons vs field induced polaritons), etc.

Independent of this, there is great need to study these experiments over an independent and wider parameter range. This was attempted to some degree by Sonnentag and Hasselbach (where they also varied Δx as well as y). However, in their case, they managed to confirm the small separation approximation where the decoherence factor varies with small Δx , but did not go into further detail to investigate outside this limit which is where the decoherence theories in Chapter 2 section 6 diverge (see Figure 6.1). Other important parameters besides Δx to serve the same purpose include temperature, the energy of the system, and the momentum exchange between the system and the environment.

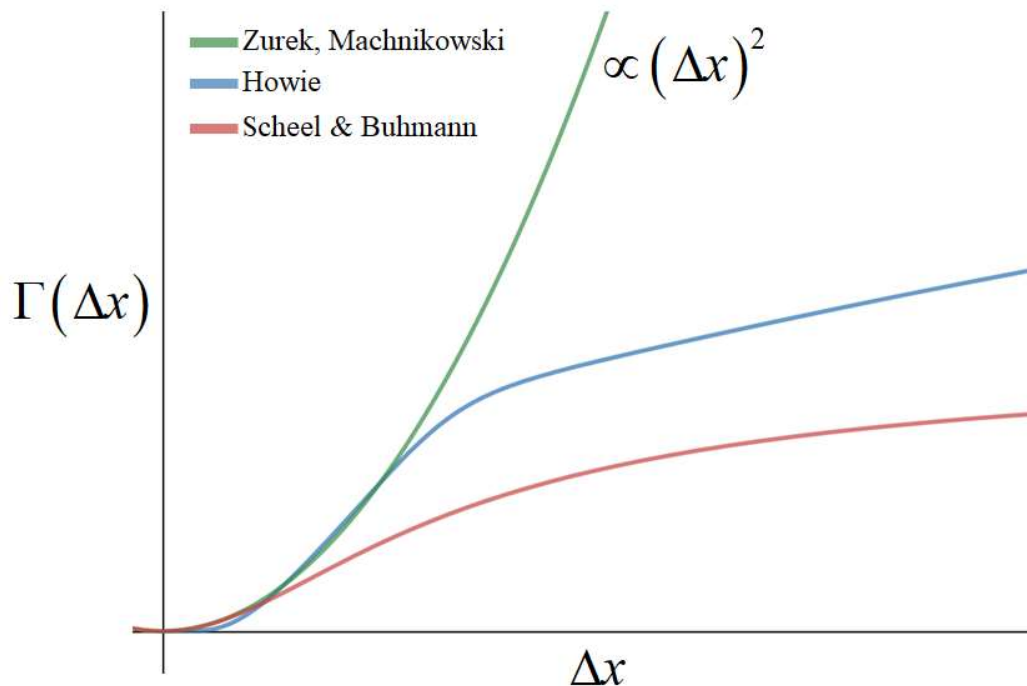


Figure 6.1: Illustration of the Functional form of the Decoherence Factor. For small Δx , these decoherence factor based on physical models described in Chapter 2 are all roughly proportional

to $(\Delta x)^2$, but diverge for larger Δx . Probing the decoherence factor over a wide enough range of Δx where such divergence is evident is an important cross-check of the validity and exclusion of any of these theories along with the check of the strength of the decoherence factor.

These kinds of decoherence experiments can serve as a great navigation tool for a vast amount of mesoscopic studies (including nanoscience, quantum information, biological and organic systems, etc) where it is not clear to what degree quantum or classical effects are taking place, and whether decoherence itself is playing a role. However, should this be a goal, these studies would be best served if the prior mentioned experiments are tailor made to investigate the precise underlying physics in question, once preliminary studies such as the ones investigated here are well understood. This general approach also applies to proposed tests of the fundamental of quantum mechanics (including nanomechanical oscillators [20], quantum optomechanics [21], tests of collapse models [22], and gravitational cat states [23–25]).

6.3 Dephasing vs. Decoherence

In this theoretical work, we have reaffirmed using a matter-wave path-integral simulation that the distinguishing feature between dephasing and decoherence processes is that the former is a time-reversible process and the latter is a time-irreversible process. Although the resulting time-averaged intensity patterns can be difficult to distinguish from each other at first glance, by taking a sequence of measurements and performing an correlation computation on the time sequence in the far field, we have found that a far field diffraction pattern, showing high visibility interference, can indeed be recovered for the dephasing case, but not for the decoherence case. This result agrees with the experimental results by Stibor et. al. [26,27].

The question arises how to realize this result experimentally. Primarily, how fast does the imaging of individual patterns need to be in order to recover the far field diffraction pattern for the case of dephasing? Although in Stibor's case they were able to recover interference by taking the positions of nearest and next nearest neighbors of individual electron events, they used a known modulation frequency. Therefore, we hypothesize that so long as the characteristic dephasing time (between modulations or "sequences") is sufficiently slow compared to the time to accumulate a statistically significant far field pattern, a diffraction pattern should be recoverable.

Besides these results having implications for fundamental studies including thermodynamics in quantum mechanics and experiments pertaining to the quantum measurement problem, this process has applications as a diagnostic tool for determining the source of loss of contrast in imaging involving diffraction such as transmission electron microscopy (TEM) and improving contrast in long-exposure images that are distorted over time.

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APPENDIX A

MATLAB CODE FOR DECOHERENCE EXPERIMENT ANALYSIS

A.1 Matlab Code for Decoherence Experiment Analysis

The following Matlab code is used to extract horizontal and vertical lineouts of the CCD integrated images of the MCP's phosphorous screen. See the below flowchart (figure A.1) for a diagrammatical description. After The acquired image data (from a LabView image acquisition program [1]) is uploaded in its .txt format and ordering the accumulated data values into their original pixel/matrix positions. A contour plot of the histogram is generated (figure 4.11 bottom right). At this point, the pixel locations of the maxima corresponding to the individual diffraction peaks are determined. These maxima are best-fitted to a line, which determines the slope of what will be the "tilted" horizontal lineouts. Next, the zeroth order diffraction peak is selected as representative of the vertical distribution of the diffraction pattern. An integrated sum (or line-out) of the entire diffraction peak is produced (creating for example the vertical experimental data points in figure 4.11 bottom left).

From such a vertical lineout (be electron beam near or far away from the surface) a range in the y-direction is selected to perform horizontal lineouts on; namely the domain corresponding to the vertical position along the center of the zeroth order peak which is at minimum 5% of the maximum intensity value of the vertical lineout. Then an integrated tilted horizontal lineout (interpolated from the data with a vertical width of 4.8 μm) is performed, one corresponding to each data point of the vertical lineout. Each horizontal lineout is then fitted to the function of Equation 4.1, with α fixed for all

lineouts determined by the lineout corresponding to the maximum intensity. To begin a fit, an initial guess (manual or otherwise) is made for all parameters except for α . Then after undergoing an r-square fitting routine to determine the best-fit parameters, some of these new parameters are plugged in as new initial guesses (d , x_1 , c_1 and c_2) which affect the position of the peaks, the periodicity and their widths. However all other parameters (α , x_0 , x_2 , c_3 , a_1 and A_{bck}) are held fixed. This final fit is then saved and the final parameters are then inserted as the next initial guess for the horizontal lineout fit. Finally. After recording the final parameters for all fits, the transverse coherence length is calculated using equation 2.29.

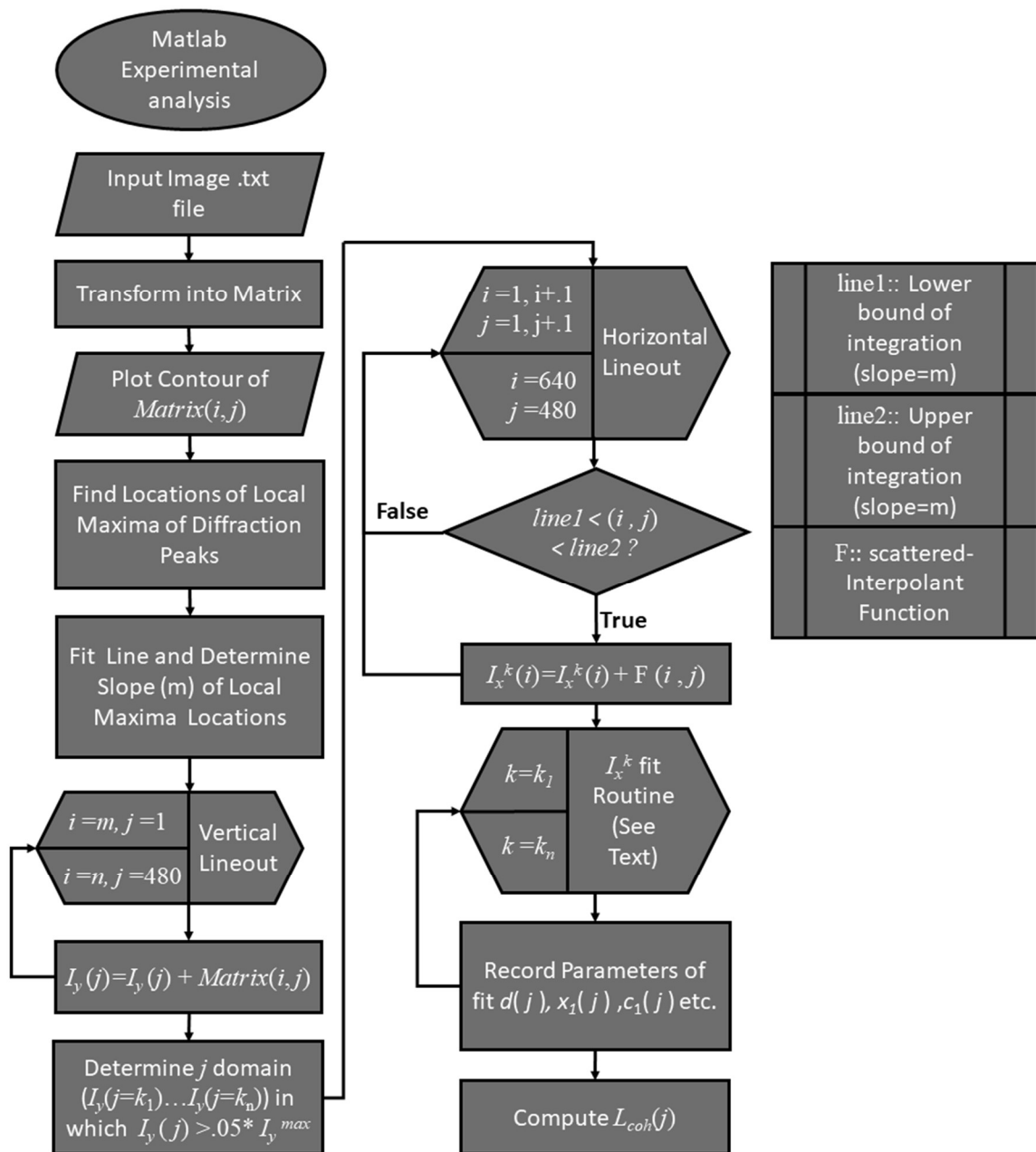


Figure A.1: Flowchart of Experimental Decoherence Image Analysis

```

1  xslope=[266.5,292.75,320.5];
2  yslope=[287,286,282.5];
3
4  cftool(xslope,yslope)
5  %%
6  clc;
7
8  i004_nearsurf_Au=zeros(480,640);
9  for i=1:640
10     for j=1:480
11         gogo=(j-1)*640+i;
12         i004_nearsurf_Au(j,i)=intensity(gogo);
13     end
14 end
15 %%
16 contour(i004_nearsurf_Au)
17 %%
18 slope=-.084;
19 %%
20 i004_nearsurf_Au(173:174,53)=0;
21 %intmatrix(171:172,52)=0;
22 %intmatrix(131,216)=0;
23 %intmatrix(134,216)=0;
24 contour(log(i004_nearsurf_Au))
25 %%
26
27 %%
28 %Nice_Contour_Generator
29
30 Xscale = [1:640]*{(72e-6)/27.1913}-7.73325e-4;
31 Yscale = 1.2e-6*[1:480]-3.45e-4;
32 centery=((1.2e-6*(317.5))-3.81e-4)-((1.2e-6*(240))-3.81e-4)
33 [mxx,myy] = meshgrid(Yscale,Xscale);
34 contour(myy,mxx,transpose((i004_nearsurf_Au)),1000)
35 %shading interp;
36 box on;
37 %view([0,90])
38 hold on
39 set(gca,'xtick',[])
40 set(gca,'ytick',[])
41
42 ylim([1.2e-6*(246)-3.45e-4 1.2e-6*(320)-3.45e-4])
43 %ylim([(1.2e-6)-3.81e-4 ((1.2e-6)*480)-3.81e-4]+centery)
44 xlim([-200e-6 200e-6])
45 hold off
46
47
48 %%
49 ylineout_004nearsurf_Au=zeros(1,480);
50 for i=1:480
51     for j=277:308
52         ylineout_004nearsurf_Au(i)=ylineout_004nearsurf_Au(i)+i004_nearsurf_Au(i,j);
53     end
54 end
55 %%
56
57 clc;
58 figure
59 plot(1.2e-6*[1:480]-3.45e-4,ylineout_004nearsurf_Au./max(ylineout_004nearsurf_Au),
    'k','markers',15) %246-320
60 hold on
61 plot(simulation_domain+6e-5,revised_nearsurf_simulation_Gold,'LineWidth',3)
62 xlim([1.2e-6*(246)-3.45e-4 1.2e-6*(320)-3.45e-4])
63 xlabel('Y (in microns)','FontSize',40)
64 ylabel('#e^{-}','FontSize',40)

```

```

65 title('Vertical Electron Lineout','FontSize',40)
66 legend('fit','experimental data')
67 %
68 hold off
69 %%
70 %creating lineouts in x direction
71
72 newdomain=zeros(640*480,2);
73
74 newdomain(:,1)=VarName1;
75 newdomain(:,2)=VarName2;
76 F = scatteredInterpolant(newdomain,intensity,'natural','nearest')
77
78 %%
79
80 clc;
81 xxdom=1:1:640;
82 yydom=1:1:480;
83 %red lines
84
85 for k=246
86 line1=slope.*(xxdom-xslope(2))+k-2;
87 line2=slope.*(xxdom-xslope(2))+k+2;
88
89 lineout_temp=zeros(1,numel(xxdom));
90 for i=1:numel(xxdom)
91     for j=1:numel(yydom)
92         if yydom(j)>=line1(i)
93             if yydom(j)<=line2(i)
94                 lineout_temp(i)=lineout_temp(i)+F(yydom(j),xxdom(i));
95             end
96         end
97     end
98 end
99 lineout_im004_Au(k,:)=lineout_temp;
100
101
102 end
103 beep on
104 beep
105
106 %%
107 clc;
108 100*delta/(1.9*(2*sqrt(2*log(2))))
109 3.1*(2*sqrt(2*log(2)))
110 %%
111 clc;
112 k=246;
113 %guessing section
114 %plot(lineout(345,:)./max(lineout(345,:)))
115 xdata=1:1:640;
116 xdata2=1.00003:1.0003:1.0018*6391;
117
118 enamp= 0.95%.99%0.9509;
119 alpha=0.046%.055%0.0532;
120 v=289.4%339.1864;
121 c1=291.2%336.7331;
122 delta=27.30%25.7624;
123 %delta=27.4
124 sigma=2.1%1.9589;
125 Scl=4 %4.4265 %Scaling factor determined on 11/30/16 from "beam only" fit
126 al=0.9%.9861; %Amplitude factor determined on 11/30/16 from "beam only" fit
127 bckamp=0.05;%0.0113;
128 bckwidth=0.0005;%0.0005;
129 bckmid=290.%;341.2022%350.0158;

```

```

130
131
132 %x=[enampout_007_1(k),alphaout_007_1(k),vout_007_1(k),clout_007_1(k),dout_007_1(k)
,wout_007_1(k)/(2*sqrt(2*log(2))),bckampout_007_1(k),bckwidthout_007_1(k),bckmid
lout_007_1(k),a1_1(k)]
133 x=[enamp,alpha,v,cl,delta,sigma,bckamp,bckwidth,bckmid,a1];
134 guess=x(1)*{(sin(x(2)*xdata2-x(3)))/(x(2)*xdata2-x(3))}.^2).*...
135 (
x(10)*exp(-((xdata2-x(4)).^2)/(2*x(6)^2))+{1-x(10)}*exp(-((xdata2-x(4)).^2)
/(2*Scl*x(6)^2))...
136
+x(10)*exp(-((xdata2-x(4)+x(5)).^2)/(2*x(6)^2))+{1-x(10)}*exp(-((xdata2-x(
4)+x(5)).^2)/(2*Scl*x(6)^2))...
137
+x(10)*exp(-((xdata2-x(4)-x(5)).^2)/(2*x(6)^2))+{1-x(10)}*exp(-((xdata2-x(
4)-x(5)).^2)/(2*Scl*x(6)^2))...
138
+x(10)*exp(-((xdata2-x(4)+2*x(5)).^2)/(2*x(6)^2))+{1-x(10)}*exp(-((xdata2-
x(4)+2*x(5)).^2)/(2*Scl*x(6)^2))...
139
+x(10)*exp(-((xdata2-x(4)-2*x(5)).^2)/(2*x(6)^2))+{1-x(10)}*exp(-((xdata2-
x(4)-2*x(5)).^2)/(2*Scl*x(6)^2))...
140
+x(10)*exp(-((xdata2-x(4)+3*x(5)).^2)/(2*x(6)^2))+{1-x(10)}*exp(-((xdata2-
x(4)+3*x(5)).^2)/(2*Scl*x(6)^2))...
141
+x(10)*exp(-((xdata2-x(4)-3*x(5)).^2)/(2*x(6)^2))+{1-x(10)}*exp(-((xdata2-
x(4)-3*x(5)).^2)/(2*Scl*x(6)^2))...
142
)+x(7)*exp(-x(8)*xdata2-x(9)).^2);
143
144
145 plot(xdata2,guess)
146 hold on
147 plot(xdata,lineout_im004_Au(k,:)./max(lineout_im004_Au(k,:)),'r')
148
149 plot(xdata,x(7)*exp(-x(8)*xdata2-x(9)).^2,'k')
150 xlim([235 355])
151 %xlim([290 320])
152 %xlim([1 640])
153 ylim([0 1.02])
154 hold off
155
156
157
158 %%
159 clc;
160 clock
161 %%
162
163 clc;
164 begintime=clock
165 xxdom=1:1:640;
166 yydom=1:1:480;
167 %alpha=alphaout1(321);
168 %k=256;
169 %x=[enampout_007_1(k),alphaout_007_1(k),vout_007_1(k),clout_007_1(k),dout_007_1(k)
,wout_007_1(k)/(2*sqrt(2*log(2))),bckampout_007_1(k),bckwidthout_007_1(k),bckmid
lout_007_1(k),a1_1(k)]
170 x=[enamp,alpha,v,cl,delta,sigma,bckamp,bckwidth,bckmid,a1];
171 for k=246:320 %maxima to ~5% of maxima
172 % k=322-running
173 %line1=slope.*(xxdom-xslope(2))+k-2;
174 %line2=slope.*(xxdom-xslope(2))+k+2;
175
176 %lineout_temp=zeros(1,numel(xxdom));

```

```

177 %for i=1:numel(xxdom)
178 %   for j=1:numel(yydom)
179 %       if yydom(j)>=line1(i)
180 %           if yydom(j)<=line2(i)
181 %               lineout_temp(i)=lineout_temp(i)+F(yydom(j),xxdom(i));
182 %           end
183 %       end
184 %   end
185 %end
186 %lineout_im004_Au(k,:)=lineout_temp;
187
188 ydata=lineout_im004_Au(k,:)./max(lineout_im004_Au(k,:));
189
190
191 %x=[enamp,alpha,v,c1,delta,sigma,bckamp,bckwidth,bckmid,bckamp2,bckwidth2,bckmid2]
192 ;
193 %lower and upper bounds force background to not fit peaks, or become
194 %negative
195 if k<316
196 lb=[-inf,-inf,-inf,-inf,-inf,-inf,0,0,0,.50];
197 ub=[inf,inf,inf,inf,inf,inf,inf,inf,0.0007,inf,.95];
198 end
199 if k>=316
200 lb=[-inf,-inf,-inf,-inf,-inf,-inf,0,0,0,.01];
201 ub=[inf,inf,inf,inf,inf,inf,inf,inf,0.0007,inf,.5];
202 end
203
204 %lb=[-inf,-inf,-inf,-inf,-inf,-inf,0,0,0,.50];
205 %ub=[inf,inf,inf,inf,inf,inf,inf,inf,0.0007,inf,.95];
206
207 f = @(x,xdata2)x(1)*((sin(x(2)*(xdata2-x(3)))/(x(2)*(xdata2-x(3))))).^2).*...
208 (
209     x(10)*exp(-((xdata2-x(4)).^2)/(2*x(6)^2))+ (1-x(10))*exp(-((xdata2-x(4)).^2)
210     / (2*Scl*x(6)^2))...
211     +x(10)*exp(-((xdata2-x(4)+x(5)).^2)/(2*x(6)^2))+ (1-x(10))*exp(-((xdata2-x(
212     4)+x(5)).^2)/(2*Scl*x(6)^2))...
213     +x(10)*exp(-((xdata2-x(4)-x(5)).^2)/(2*x(6)^2))+ (1-x(10))*exp(-((xdata2-x(
214     4)-x(5)).^2)/(2*Scl*x(6)^2))...
215     +x(10)*exp(-((xdata2-x(4)+2*x(5)).^2)/(2*x(6)^2))+ (1-x(10))*exp(-((xdata2-
216     x(4)+2*x(5)).^2)/(2*Scl*x(6)^2))...
217     +x(10)*exp(-((xdata2-x(4)-2*x(5)).^2)/(2*x(6)^2))+ (1-x(10))*exp(-((xdata2-
218     x(4)-2*x(5)).^2)/(2*Scl*x(6)^2))...
219     +x(10)*exp(-((xdata2-x(4)+3*x(5)).^2)/(2*x(6)^2))+ (1-x(10))*exp(-((xdata2-
220     x(4)+3*x(5)).^2)/(2*Scl*x(6)^2))...
221     +x(10)*exp(-((xdata2-x(4)-3*x(5)).^2)/(2*x(6)^2))+ (1-x(10))*exp(-((xdata2-
222     x(4)-3*x(5)).^2)/(2*Scl*x(6)^2))...
223     )+x(7)*exp(-x(8)*(xdata2-x(9)).^2);
224
225 x = lsqcurvefit(f,x,xdata2,ydata,lb,ub);
226 x2=[x(4),x(5),x(6)];
227
228 f2 = @(x2,xdata2)x(1)*((sin(x(2)*(xdata2-x(3)))/(x(2)*(xdata2-x(3))))).^2).*...
229 (
230     x(10)*exp(-((xdata2-x2(1)).^2)/(2*x2(3)^2))+ (1-x(10))*exp(-((xdata2-x2(1)).
231     ^2)/(2*Scl*x2(3)^2))...
232     +x(10)*exp(-((xdata2-x2(1)+x2(2)).^2)/(2*x2(3)^2))+ (1-x(10))*exp(-((xdata2
233     -x2(1)+x2(2)).^2)/(2*Scl*x2(3)^2))...

```

```

223      +x(10)*exp(-((xdata2-x2(1)-x2(2)).^2)/(2*x2(3)^2))+ (1-x(10))*exp(-((xdata2
224      -x2(1)-x2(2)).^2)/(2*Scl*x2(3)^2))...
225      +x(10)*exp(-((xdata2-x2(1)+2*x2(2)).^2)/(2*x2(3)^2))+ (1-x(10))*exp(-((xdat
226      a2-x2(1)+2*x2(2)).^2)/(2*Scl*x2(3)^2))...
227      +x(10)*exp(-((xdata2-x2(1)-2*x2(2)).^2)/(2*x2(3)^2))+ (1-x(10))*exp(-((xdat
228      a2-x2(1)-2*x2(2)).^2)/(2*Scl*x2(3)^2))...
229      +x(10)*exp(-((xdata2-x2(1)+3*x2(2)).^2)/(2*x2(3)^2))+ (1-x(10))*exp(-((xdat
230      a2-x2(1)+3*x2(2)).^2)/(2*Scl*x2(3)^2))...
231      +x(10)*exp(-((xdata2-x2(1)-3*x2(2)).^2)/(2*x2(3)^2))+ (1-x(10))*exp(-((xdat
232      a2-x2(1)-3*x2(2)).^2)/(2*Scl*x2(3)^2))...
233      )+x(7)*exp(-x(8)*xdata2-x(9)).^2);
234
235 x2 = lsqcurvefit(f2,x2,xdata2,ydata);
236
237 result_004_Au_02(k,:)=x(1)*((sin(x(2)*xdata2-x(3)))/(x(2)*xdata2-x(3))).^2).*
238 ..
239 (
240 x(10)*exp(-((xdata2-x2(1)).^2)/(2*x2(3)^2))+ (1-x(10))*exp(-((xdata2-x2(1)).
241      ^2)/(2*Scl*x2(3)^2))...
242      +x(10)*exp(-((xdata2-x2(1)+x2(2)).^2)/(2*x2(3)^2))+ (1-x(10))*exp(-((xdata2
243      -x2(1)+x2(2)).^2)/(2*Scl*x2(3)^2))...
244      +x(10)*exp(-((xdata2-x2(1)-x2(2)).^2)/(2*x2(3)^2))+ (1-x(10))*exp(-((xdata2
245      -x2(1)-x2(2)).^2)/(2*Scl*x2(3)^2))...
246      +x(10)*exp(-((xdata2-x2(1)+2*x2(2)).^2)/(2*x2(3)^2))+ (1-x(10))*exp(-((xdat
247      a2-x2(1)+2*x2(2)).^2)/(2*Scl*x2(3)^2))...
248      +x(10)*exp(-((xdata2-x2(1)-2*x2(2)).^2)/(2*x2(3)^2))+ (1-x(10))*exp(-((xdat
249      a2-x2(1)-2*x2(2)).^2)/(2*Scl*x2(3)^2))...
250      +x(10)*exp(-((xdata2-x2(1)+3*x2(2)).^2)/(2*x2(3)^2))+ (1-x(10))*exp(-((xdat
251      a2-x2(1)+3*x2(2)).^2)/(2*Scl*x2(3)^2))...
252      +x(10)*exp(-((xdata2-x2(1)-3*x2(2)).^2)/(2*x2(3)^2))+ (1-x(10))*exp(-((xdat
253      a2-x2(1)-3*x2(2)).^2)/(2*Scl*x2(3)^2))...
254      )+x(7)*exp(-x(8)*xdata2-x(9)).^2);
255
256 %chisqr calculation
257 %chisqr=0;
258 %norm_result=result_14(k,:)./sum(result_14(k,:));
259 %norm_ydata=ydata./sum(ydata);
260
261 %for i=1:numel(result_14(k,:))
262 %   chisqr=chisqr+((result(k,i)-ydata(i))^2)/result(k,i);
263 %   chisqr=chisqr+((norm_result(i)-norm_ydata(i))^2)/norm_result(i);
264 %end
265
266 %nu=numel(ydata)-(8); %9=free parameters/covariates
267 %reduced_chisqr(k)=chisqr/nu;
268
269 %reset x (initial guess for each k)
270 x(4)=x2(1);
271 x(5)=x2(2);
272 x(6)=x2(3);
273
274 dout_004_Au_2(k)=x(5);
275 wout_004_Au_2(k)=2*sqrt(2*log(2))*x(6);
276

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```

263 enampout_004_Au_2(k)=x(1);
264 alphaout_004_Au_2(k)=x(2);
265 vout_004_Au_2(k)=x(3);
266 clout_004_Au_2(k)=x(4);
267 bckamp1out_004_Au_2(k)=x(7);
268 bckwidth1out_004_Au_2(k)=x(8);
269 bckmid1out_004_Au_2(k)=x(9);
270 al_004_Au_2(k)=x(10);
271
272 k
273 end
274 beep on
275 beep
276 endtime=clock
277 x(2)
278
279 alpha
280 alpha=x(2)
281
282
283 %%
284 begintime-endtime
285 %%
286
287 %dout_007_1(256:334)*100./wout_007_1(256:334);
288 dout_004_Au_2(256)
289 wout_004_Au_2(256)
290 %%
291 (8.2152-5.2795)/5.2795
292 (25.7624-22.9957)/25.7624
293 %%
294 x(6)
295 wout(362)
296 %%
297 %figure %275-289
298 k=286; %246:320
299
300 x_lineout_data_004=result_004_Au_02(k,:);
301 xfit_004=lineout_im004_Au(k,:)/max(lineout_im004_Au(k,:));
302
303 plot(xdata*((72e-6)/27.1913)-7.73325e-4,x_lineout_data_004,'LineWidth',3)
304 hold on
305 plot(xdata*((72e-6)/27.1913)-7.73325e-4,xfit_004,'k','markers',15)
306 xlim([-200e-6 200e-6])
307 ylim([0 1.02])
308 xlabel('Y (in microns)', 'FontSize',40)
309 ylabel('#e^{-}', 'FontSize',40)
310 title('Horizontal Electron Lineout', 'FontSize',40)
311 legend('fit', 'experimental data')
312 hold off
313
314 %%
315 %275-289
316 %290-308
317
318
319 plot(1.2e-6*[246:320]-3.45e-4,lcoh_im_004_Au_2,'.-k','markers',15)%564.125
320 hold on
321 plot(simulation_domain+6e-5,real_coherence_length_zurek_gold,'g','LineWidth',3)
322 plot(simulation_domain+6e-5,real_coherence_length_mach_gold,'LineWidth',3)
323 plot(simulation_domain+6e-5,real_coherence_length_scheel_gold,'r','LineWidth',3)
324 plot(simulation_domain+6e-5,real_coherence_length_mach_gold_dblcheck,'m','LineWidht
h',3)
325 plot(simulation_domain+6e-5,real_coherence_length_levinson_gold,'k','LineWidth',3)
326

```



```

327
328 xlim([1.2e-6*(246)-3.45e-4 1.2e-6*(320)-3.45e-4])
329 xlabel('Y (in pixels)', 'FontSize', 40)
330 ylabel('L_{t} (in nm)', 'FontSize', 40)
331 title('Gold', 'FontSize', 40)
332 legend('experiment', 'Zurek', 'Machnikowski', 'Scheel & Buhmann', 'Machnikowski
dblcheck')
333 ylim([0 680])
334 hold off
335
336 %%
337 mean(lcoh_im_004_Au_2)
338 %%
339 plot(wout_004_Au_2(246:320), '.k')
340 %%
341 enamp= 0.7669%.99%0.9509;
342 alpha=0.048%.055%0.0532;
343 v=337.1342%339.1864;
344 c1=336.9912%336.7331;
345 delta=26.0218%25.7624;
346 %delta=27.4
347 sigma=1.9%1.9589;
348 Scl=4 %4.4265 %Scaling factor determined on 11/30/16 from "beam only" fit
349 a1=0.5698%.9861; %Amplitude factor determined on 11/30/16 from "beam only" fit
350 bckamp=0.2034;%0.0113;
351 bckwidth=0.0005;%0.0005;
352 bckmid=340.5628;%341.2022%350.0158;
353 %%
354 %plot(283:364,alphaout_006_1(283:364), '-k')
355 %plot(283:364,bckmidlout_006_1(283:364), '-k')
356 %plot(283:364,bckwidthlout_037_1(283:364), '-k')
357 plot(246:320,bckamlout_004_Au_2(246:320), '-k')
358 plot(246:320,a1_004_Au_2(246:320), '-k')
359 hold on
360 %xlim([333.9 334.1])
361 hold off
362
363 %%
364 clc;
365 plot(1:86,lcoh_im038_01, '-k')
366 hold on
367 plot([1:74]+11,lcoh_im034_01, '-b')
368 hold off
369
370 %%
371
372 plot(1.3e-6*[1:480]-4.173e-4,ylineout_i007_nearsurf_h4p435_1000_36000./max(ylineou
t_i007_nearsurf_h4p435_1000_36000), '-b')
373 hold on
374 plot(1.3e-6*[307:335]-4.173e-4,ylineout_i007_nearsurf_h4p435_1000_36000(307:335)./
max(ylineout_i007_nearsurf_h4p435_1000_36000(307:335)), '-m')
375 plot(1.3e-6*[300:345]-4.173e-4,lcoh_im038_01/500, '-r')
376 plot(simulation_domain,1.03*edist_no_surf_no_exclusion./max(edist_no_surf_no_exclu
sion), 'k')
377 plot(simulation_domain,1.03*edist_nosurf_exludedpaths./max(edist_nosurf_exludedpat
hs), 'g')
378 xlim([-0.5e-4 .5e-4])
379 ylim([0 1.1])
380 title('Crude Fit, Verticle Electron Distribution of 0th order')
381 xlabel('Position (in meters)')
382 ylabel('Intensity (normalized to max=1)')
383 legend('Experiment', 'Classical Simulation')
384 hold off
385
386 %%

```

```
387
388 plot(1.3e-6*[307:335]-4.18e-4,ylineout_i007_nearsurf_h4p435_1000_36000(307:335)./m
389 ax(ylineout_i007_nearsurf_h4p435_1000_36000(307:335)),'.-b')
390 hold on
391 plot(simulation_domain,1.03*edist_no_surf_no_exclusion./max(edist_no_surf_no_exclu
392 sion),'k')
393 xlim([-1e-4 1e-4])
394 ylim([0 1.1])
395 title('Crude Fit, Verticle Electron Distribution of 0th order')
396 xlabel('Position (in meters)')
397 ylabel('Intensity (normalized to max=1)')
398 legend('Experiment','Classical Simulation')
399 hold off
400 %%
401 mean(dout_004_Au_2(246:320))
402
403
404
```

A.2 Visualization of Loss of Coherence

In order to highlight the loss of contrast in the diffraction pattern, the accumulated image of the MCP detector that was taken by the CCD camera was transformed into the revised images shown in Figure 4.3 and Figure 4.4. Figure A.2 shows the images before and after this process. Line-outs of the image are extracted to obtain diffraction patterns. The line-outs are taken at a slant with the x -direction to compensate for image skew. This skew can be explained by small rotational misalignments between the optical elements in the system, however this does not affect the measured coherence length. In the y -direction a $4.8 \mu\text{m}$ range on the detector is integrated for each line-out. Each of these line-outs then correspond to an individual horizontal line on the diffractogram.

After the individual line-outs are fitted according to equation 4.2, the background term is subtracted from the line-out to show only the relative broadening. Each diffraction peak is normalized by its maximum intensity value for that order.

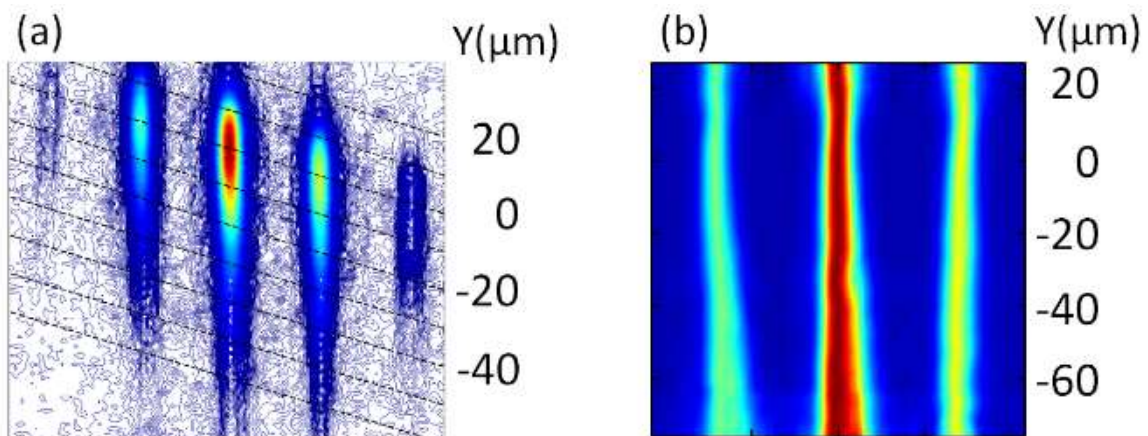


Figure A.2. Visualization of the Loss of Contrast. (a) Contour of data accumulated by CCD camera. (b) Resulting diffractogram based on data.

- [1] R. Bach, Electron Matter Interferometry and the Electron Double-Slit Experiment, Appendix B, Dissertation, University of Nebraska-Lincoln, 2014.

APPENDIX B

MATLAB CODE FOR CORERENCE LENGTH CALCULATION I

The following Program is the Program for Computing the transverse coherence length of the electron beam after decoherence has occurred based on the final density matrix of the electron state. This executed by 1) deconvoluting the final density as a sum of pure quantum states, 2) propagating each state to the far field using Fourier transformation, and 3) incoherently summing the resulting probability distributions from each of the pure quantum states. See Appendix C.2 for an extended description of how this is done.

```

1  clc;
2  w=2.2745d0*sqrt(2d0);
3  sigma=w/(2d0*sqrt(2d0*log(2d0)));
4
5  b=1/(2d0*(sigma^2));
6  rho_l=zeros(2001,2001);
7  near_field_x=zeros(1,2001);
8  rho_lp5=zeros(2001,2001);
9  coherence_dist=zeros(1,2001);
10 initial_coh_dist=zeros(1,2001);
11 probability=zeros(1,2001);
12
13
14 for i=1:2001
15     for j=1:2001
16         x=i*10d0/2000d0;
17         y=j*10d0/2000d0;
18         rho_l(i,j)=exp(-b*((x-5.005)^2+(y-5.005)^2));
19     end
20 end
21
22 for i=1:2001
23     near_field_x(i)=-5d0+(i-1)*.005d0;
24 end
25
26 %fwhmlp67=16.48; .4628
27 %fwhmlp67=189.1; %Attempt to obtain density width of 557nm (525nm)
28 %fwhmlp67=210.2; %Attempt to obtain density of 512nm (lcoh=570nm),new si
29 fwhmlp67=215.44; %Attempt to obtain density of 524.1nm (lcoh=583.1229nm), old si
30 %fwhmlp67=220.5; %Attempt to obtain density of 535.7nm (lcoh=595.5127m), gold
31
32
33 beta=fwhmlp67/(2d0*sqrt(log(2d0)));
34
35 for i=1:2001
36     for j=1:2001
37         rho_lp5(i,j)=rho_l(i,j)*exp(-((i-j)/beta)^2);
38     end
39 end
40
41
42 for i=1:2001
43     j=2002-i;
44     coherence_dist(i)=rho_lp5(i,j);
45     initial_coh_dist(i)=rho_l(i,j);
46     probability(i)=rho_l(i,i);
47 end
48
49
50 plot(near_field_x,coherence_dist,'.-k')
51 hold on
52 plot(near_field_x,initial_coh_dist,'.-b')
53 plot(near_field_x,probability,'.-m')
54 hold off
55
56
57 f = fit(transpose(near_field_x),transpose(coherence_dist),'gauss1')
58
59 clc;
60 coeffvals = coeffvalues(f);
61 width=2*sqrt(log(2))*coeffvals(3)
62
63
64 %%
65 %operator which acts as a grating to the wavefunction distribution

```

```

66 grating_operator=zeros(1,numel(near_field_x));
67
68 for i=1:numel(near_field_x)
69     if mod(near_field_x(i)*100,20)>= 0
70         if mod(near_field_x(i)*100,20)< 10
71             grating_operator(i)=1;
72         end
73     end
74 end
75
76 %%
77 %send coherent_function_through_grating
78 clc;
79 %first normalize rho_1
80 rho_1=rho_1/trace(rho_1);
81 for i=1:2001
82     wavefunction_1(i)=sqrt(rho_1(i,i))*grating_operator(i);
83 end
84 plot(near_field_x,wavefunction_1)
85
86 %%
87 clc;
88
89 wavefunction_1extended(1:1000)=0;
90 wavefunction_1extended(1001:3001)=wavefunction_1;
91 wavefunction_1extended(3002:4001)=0;
92 plot(wavefunction_1extended)
93 %%
94
95 farfield_x=[-2000:2000]*.72; %far field domain to obtain a ff peak_periodicity
of 72um
96
97 Y=fft(wavefunction_1extended);
98 farfieldintensity = real( Y .* conj( Y ) );
99 farfield_pattern=fftshift( farfieldintensity );
100 fourier_result_coherent=abs(farfield_pattern)/max(abs(farfield_pattern));
101 %%
102 plot(farfield_x,fourier_result_coherent,'.-k')
103 hold on
104 %xlim([68 76])
105 hold off
106 %%
107 clc;
108 % 0th order peak
109 format long
110 f =
fit(transpose(farfield_x(1960:2040)),transpose(fourier_result_coherent(1960:2040))
,'gauss1')
111 coeffvals = coeffvalues(f);
112 width=2*sqrt(log(2))*coeffvals(3);
113 .1*72/width % = 2.573496999326959
114 %%
115 clc;
116 % 1st order peak
117 format long
118 f =
fit(transpose(farfield_x(2060:2140)),transpose(fourier_result_coherent(2060:2140))
,'gauss1')
119 coeffvals = coeffvalues(f);
120 width=2*sqrt(log(2))*coeffvals(3);
121 .1*72/width % = 2.576545361683533
122
123 %%
124 clc;
125 2.2745/2.573496999326959%ratio of diagonal width to coherence length

```

```
126 2.2745/2.576545361683533
127 %%
128 clc;
129 1/(2*3.14159265)
130 %%
131 clc;
132
133 72*.1/(384.7587-367.3198)
134
```

```

1
2 plot(near_field_x,coherence_dist,'.-k')
3 hold on
4 plot(near_field_x,initial_coh_dist,'.-b')
5 plot(near_field_x,probability,'.-m')
6 hold off
7 %%
8
9 clc;
10
11 for i=1:2001
12     near_field_x(i)=-5d0+(i-1)*.005d0;
13 end
14
15 w=2.2745d0;
16 %wdblprime=.5;% produces lcoh=.557;
17 %wdblprime=.5120;% produces lcoh = .570
18 wdblprime=.5241;% produces lcoh = 583.1229, old si
19 %wdblprime=.5357;% produces lcoh = 595.5127, gold
20 sigmadbl=wdblprime/(2d0*sqrt(2d0*log(2d0)));
21 delx=.1;
22
23 wprime=sqrt((w*w)-(wdblprime*wdblprime));
24 sigmaprime=wprime/(2d0*sqrt(2d0*log(2d0)));
25
26
27 a0=exp(-(0).^2/(2*sigmaprime*sigmaprime));
28 a1=exp(-(delx).^2/(2*sigmaprime*sigmaprime));
29 a2=exp(-(2*delx).^2/(2*sigmaprime*sigmaprime));
30 a3=exp(-(3*delx).^2/(2*sigmaprime*sigmaprime));
31 a4=exp(-(4*delx).^2/(2*sigmaprime*sigmaprime));
32 a5=exp(-(5*delx).^2/(2*sigmaprime*sigmaprime));
33 a6=exp(-(6*delx).^2/(2*sigmaprime*sigmaprime));
34 a7=exp(-(7*delx).^2/(2*sigmaprime*sigmaprime));
35 a8=exp(-(8*delx).^2/(2*sigmaprime*sigmaprime));
36 a9=exp(-(9*delx).^2/(2*sigmaprime*sigmaprime));
37 a10=exp(-(10*delx).^2/(2*sigmaprime*sigmaprime));
38 a11=exp(-(11*delx).^2/(2*sigmaprime*sigmaprime));
39 a12=exp(-(12*delx).^2/(2*sigmaprime*sigmaprime));
40 a13=exp(-(13*delx).^2/(2*sigmaprime*sigmaprime));
41 a14=exp(-(14*delx).^2/(2*sigmaprime*sigmaprime));
42 a15=exp(-(15*delx).^2/(2*sigmaprime*sigmaprime));
43 a16=exp(-(16*delx).^2/(2*sigmaprime*sigmaprime));
44 a17=exp(-(17*delx).^2/(2*sigmaprime*sigmaprime));
45 a18=exp(-(18*delx).^2/(2*sigmaprime*sigmaprime));
46 a19=exp(-(19*delx).^2/(2*sigmaprime*sigmaprime));
47 a20=exp(-(20*delx).^2/(2*sigmaprime*sigmaprime));
48 a21=exp(-(21*delx).^2/(2*sigmaprime*sigmaprime));
49 a22=exp(-(22*delx).^2/(2*sigmaprime*sigmaprime));
50 a23=exp(-(23*delx).^2/(2*sigmaprime*sigmaprime));
51 a24=exp(-(24*delx).^2/(2*sigmaprime*sigmaprime));
52 a25=exp(-(25*delx).^2/(2*sigmaprime*sigmaprime));
53 a26=exp(-(26*delx).^2/(2*sigmaprime*sigmaprime));
54 a27=exp(-(27*delx).^2/(2*sigmaprime*sigmaprime));
55 a28=exp(-(28*delx).^2/(2*sigmaprime*sigmaprime));
56 a29=exp(-(29*delx).^2/(2*sigmaprime*sigmaprime));
57 a30=exp(-(30*delx).^2/(2*sigmaprime*sigmaprime));
58
59 rho_lp5_prob0=a0*exp(-(near_field_x).^2/(2*sigmadbl*sigmadbl));
60 rho_lp5_prob1a=a1*exp(-(near_field_x-delx).^2/(2*sigmadbl*sigmadbl));
61 rho_lp5_prob1b=a1*exp(-(near_field_x+delx).^2/(2*sigmadbl*sigmadbl));
62 rho_lp5_prob2a=a2*exp(-(near_field_x-2*delx).^2/(2*sigmadbl*sigmadbl));
63 rho_lp5_prob2b=a2*exp(-(near_field_x+2*delx).^2/(2*sigmadbl*sigmadbl));
64 rho_lp5_prob3a=a3*exp(-(near_field_x-3*delx).^2/(2*sigmadbl*sigmadbl));
65 rho_lp5_prob3b=a3*exp(-(near_field_x+3*delx).^2/(2*sigmadbl*sigmadbl));

```



```

66 rho_lp5_prob4a=a4*exp(-(near_field_x-4*delx).^2/(2*sigmadbl*sigmadbl));
67 rho_lp5_prob4b=a4*exp(-(near_field_x+4*delx).^2/(2*sigmadbl*sigmadbl));
68 rho_lp5_prob5a=a5*exp(-(near_field_x-5*delx).^2/(2*sigmadbl*sigmadbl));
69 rho_lp5_prob5b=a5*exp(-(near_field_x+5*delx).^2/(2*sigmadbl*sigmadbl));
70 rho_lp5_prob6a=a6*exp(-(near_field_x-6*delx).^2/(2*sigmadbl*sigmadbl));
71 rho_lp5_prob6b=a6*exp(-(near_field_x+6*delx).^2/(2*sigmadbl*sigmadbl));
72 rho_lp5_prob7a=a7*exp(-(near_field_x-7*delx).^2/(2*sigmadbl*sigmadbl));
73 rho_lp5_prob7b=a7*exp(-(near_field_x+7*delx).^2/(2*sigmadbl*sigmadbl));
74 rho_lp5_prob8a=a8*exp(-(near_field_x-8*delx).^2/(2*sigmadbl*sigmadbl));
75 rho_lp5_prob8b=a8*exp(-(near_field_x+8*delx).^2/(2*sigmadbl*sigmadbl));
76 rho_lp5_prob9a=a9*exp(-(near_field_x-9*delx).^2/(2*sigmadbl*sigmadbl));
77 rho_lp5_prob9b=a9*exp(-(near_field_x+9*delx).^2/(2*sigmadbl*sigmadbl));
78 rho_lp5_prob10a=a10*exp(-(near_field_x-10*delx).^2/(2*sigmadbl*sigmadbl));
79 rho_lp5_prob10b=a10*exp(-(near_field_x+10*delx).^2/(2*sigmadbl*sigmadbl));
80 rho_lp5_prob11a=a11*exp(-(near_field_x-11*delx).^2/(2*sigmadbl*sigmadbl));
81 rho_lp5_prob11b=a11*exp(-(near_field_x+11*delx).^2/(2*sigmadbl*sigmadbl));
82 rho_lp5_prob12a=a12*exp(-(near_field_x-12*delx).^2/(2*sigmadbl*sigmadbl));
83 rho_lp5_prob12b=a12*exp(-(near_field_x+12*delx).^2/(2*sigmadbl*sigmadbl));
84 rho_lp5_prob13a=a13*exp(-(near_field_x-13*delx).^2/(2*sigmadbl*sigmadbl));
85 rho_lp5_prob13b=a13*exp(-(near_field_x+13*delx).^2/(2*sigmadbl*sigmadbl));
86 rho_lp5_prob14a=a14*exp(-(near_field_x-14*delx).^2/(2*sigmadbl*sigmadbl));
87 rho_lp5_prob14b=a14*exp(-(near_field_x+14*delx).^2/(2*sigmadbl*sigmadbl));
88 rho_lp5_prob15a=a15*exp(-(near_field_x-15*delx).^2/(2*sigmadbl*sigmadbl));
89 rho_lp5_prob15b=a15*exp(-(near_field_x+15*delx).^2/(2*sigmadbl*sigmadbl));
90 rho_lp5_prob16a=a16*exp(-(near_field_x-16*delx).^2/(2*sigmadbl*sigmadbl));
91 rho_lp5_prob16b=a16*exp(-(near_field_x+16*delx).^2/(2*sigmadbl*sigmadbl));
92 rho_lp5_prob17a=a17*exp(-(near_field_x-17*delx).^2/(2*sigmadbl*sigmadbl));
93 rho_lp5_prob17b=a17*exp(-(near_field_x+17*delx).^2/(2*sigmadbl*sigmadbl));
94 rho_lp5_prob18a=a18*exp(-(near_field_x-18*delx).^2/(2*sigmadbl*sigmadbl));
95 rho_lp5_prob18b=a18*exp(-(near_field_x+18*delx).^2/(2*sigmadbl*sigmadbl));
96 rho_lp5_prob19a=a19*exp(-(near_field_x-19*delx).^2/(2*sigmadbl*sigmadbl));
97 rho_lp5_prob19b=a19*exp(-(near_field_x+19*delx).^2/(2*sigmadbl*sigmadbl));
98 rho_lp5_prob20a=a20*exp(-(near_field_x-20*delx).^2/(2*sigmadbl*sigmadbl));
99 rho_lp5_prob20b=a20*exp(-(near_field_x+20*delx).^2/(2*sigmadbl*sigmadbl));
100 rho_lp5_prob21a=a21*exp(-(near_field_x-21*delx).^2/(2*sigmadbl*sigmadbl));
101 rho_lp5_prob21b=a21*exp(-(near_field_x+21*delx).^2/(2*sigmadbl*sigmadbl));
102 rho_lp5_prob22a=a22*exp(-(near_field_x-22*delx).^2/(2*sigmadbl*sigmadbl));
103 rho_lp5_prob22b=a22*exp(-(near_field_x+22*delx).^2/(2*sigmadbl*sigmadbl));
104 rho_lp5_prob23a=a23*exp(-(near_field_x-23*delx).^2/(2*sigmadbl*sigmadbl));
105 rho_lp5_prob23b=a23*exp(-(near_field_x+23*delx).^2/(2*sigmadbl*sigmadbl));
106 rho_lp5_prob24a=a24*exp(-(near_field_x-24*delx).^2/(2*sigmadbl*sigmadbl));
107 rho_lp5_prob24b=a24*exp(-(near_field_x+24*delx).^2/(2*sigmadbl*sigmadbl));
108 rho_lp5_prob25a=a25*exp(-(near_field_x-25*delx).^2/(2*sigmadbl*sigmadbl));
109 rho_lp5_prob25b=a25*exp(-(near_field_x+25*delx).^2/(2*sigmadbl*sigmadbl));
110 rho_lp5_prob26a=a26*exp(-(near_field_x-26*delx).^2/(2*sigmadbl*sigmadbl));
111 rho_lp5_prob26b=a26*exp(-(near_field_x+26*delx).^2/(2*sigmadbl*sigmadbl));
112 rho_lp5_prob27a=a27*exp(-(near_field_x-27*delx).^2/(2*sigmadbl*sigmadbl));
113 rho_lp5_prob27b=a27*exp(-(near_field_x+27*delx).^2/(2*sigmadbl*sigmadbl));
114 rho_lp5_prob28a=a28*exp(-(near_field_x-28*delx).^2/(2*sigmadbl*sigmadbl));
115 rho_lp5_prob28b=a28*exp(-(near_field_x+28*delx).^2/(2*sigmadbl*sigmadbl));
116 rho_lp5_prob29a=a29*exp(-(near_field_x-29*delx).^2/(2*sigmadbl*sigmadbl));
117 rho_lp5_prob29b=a29*exp(-(near_field_x+29*delx).^2/(2*sigmadbl*sigmadbl));
118 rho_lp5_prob30a=a30*exp(-(near_field_x-30*delx).^2/(2*sigmadbl*sigmadbl));
119 rho_lp5_prob30b=a30*exp(-(near_field_x+30*delx).^2/(2*sigmadbl*sigmadbl));
120
121 rho_lp5_total=rho_lp5_prob0+rho_lp5_prob1a+rho_lp5_prob1b+rho_lp5_prob2a+rho_lp5_p
rob2b...
122
+rho_lp5_prob3a+rho_lp5_prob3b+rho_lp5_prob4a+rho_lp5_p
rob4b...
123
+rho_lp5_prob5a+rho_lp5_prob5b+rho_lp5_prob6a+rho_lp5_p
rob6b...
124
+rho_lp5_prob7a+rho_lp5_prob7b+rho_lp5_prob8a+rho_lp5_p

```

```

rob8b...
125 +rho_lp5_prob9a+rho_lp5_prob9b+rho_lp5_prob10a+rho_lp5_
    prob10b...
126 +rho_lp5_prob11a+rho_lp5_prob11b+rho_lp5_prob12a+rho_lp
    5_prob12b...
127 +rho_lp5_prob13a+rho_lp5_prob13b+rho_lp5_prob14a+rho_lp
    5_prob14b...
128 +rho_lp5_prob15a+rho_lp5_prob15b+rho_lp5_prob16a+rho_lp
    5_prob16b...
129 +rho_lp5_prob17a+rho_lp5_prob17b+rho_lp5_prob18a+rho_lp
    5_prob18b...
130 +rho_lp5_prob19a+rho_lp5_prob19b+rho_lp5_prob20a+rho_lp
    5_prob20b...
131 +rho_lp5_prob21a+rho_lp5_prob21b+rho_lp5_prob22a+rho_lp
    5_prob22b...
132 +rho_lp5_prob23a+rho_lp5_prob23b+rho_lp5_prob24a+rho_lp
    5_prob24b...
133 +rho_lp5_prob25a+rho_lp5_prob25b+rho_lp5_prob26a+rho_lp
    5_prob26b...
134 +rho_lp5_prob27a+rho_lp5_prob27b+rho_lp5_prob28a+rho_lp
    5_prob28b...
135 +rho_lp5_prob29a+rho_lp5_prob29b+rho_lp5_prob30a+rho_lp
    5_prob30b;
136
137 plot(near_field_x,probability,'m')
138 hold on
139 plot(near_field_x,rho_lp5_prob2a,'g')
140 plot(near_field_x,rho_lp5_prob15a,'g')
141 %plot(near_field_x,rho_lp5_prob1,'b')
142 plot(near_field_x,rho_lp5_total./max(rho_lp5_total),'k')
143 hold off
144
145 %%
146
147 for i=1:2001
148     wavefun_lp5_0(i)=sqrt(rho_lp5_prob0(i))*grating_operator(i);
149     wavefun_lp5_1a(i)=sqrt(rho_lp5_prob1a(i))*grating_operator(i);
150     wavefun_lp5_1b(i)=sqrt(rho_lp5_prob1b(i))*grating_operator(i);
151     wavefun_lp5_2a(i)=sqrt(rho_lp5_prob2a(i))*grating_operator(i);
152     wavefun_lp5_2b(i)=sqrt(rho_lp5_prob2b(i))*grating_operator(i);
153     wavefun_lp5_3a(i)=sqrt(rho_lp5_prob3a(i))*grating_operator(i);
154     wavefun_lp5_3b(i)=sqrt(rho_lp5_prob3b(i))*grating_operator(i);
155     wavefun_lp5_4a(i)=sqrt(rho_lp5_prob4a(i))*grating_operator(i);
156     wavefun_lp5_4b(i)=sqrt(rho_lp5_prob4b(i))*grating_operator(i);
157     wavefun_lp5_5a(i)=sqrt(rho_lp5_prob5a(i))*grating_operator(i);
158     wavefun_lp5_5b(i)=sqrt(rho_lp5_prob5b(i))*grating_operator(i);
159     wavefun_lp5_6a(i)=sqrt(rho_lp5_prob6a(i))*grating_operator(i);
160     wavefun_lp5_6b(i)=sqrt(rho_lp5_prob6b(i))*grating_operator(i);
161     wavefun_lp5_7a(i)=sqrt(rho_lp5_prob7a(i))*grating_operator(i);
162     wavefun_lp5_7b(i)=sqrt(rho_lp5_prob7b(i))*grating_operator(i);
163     wavefun_lp5_8a(i)=sqrt(rho_lp5_prob8a(i))*grating_operator(i);
164     wavefun_lp5_8b(i)=sqrt(rho_lp5_prob8b(i))*grating_operator(i);
165     wavefun_lp5_9a(i)=sqrt(rho_lp5_prob9a(i))*grating_operator(i);
166     wavefun_lp5_9b(i)=sqrt(rho_lp5_prob9b(i))*grating_operator(i);

```

```

167 wavefun_lp5_10a(i)=sqrt(rho_lp5_prob10a(i))*grating_operator(i);
168 wavefun_lp5_10b(i)=sqrt(rho_lp5_prob10b(i))*grating_operator(i);
169 wavefun_lp5_11a(i)=sqrt(rho_lp5_prob11a(i))*grating_operator(i);
170 wavefun_lp5_11b(i)=sqrt(rho_lp5_prob11b(i))*grating_operator(i);
171 wavefun_lp5_12a(i)=sqrt(rho_lp5_prob12a(i))*grating_operator(i);
172 wavefun_lp5_12b(i)=sqrt(rho_lp5_prob12b(i))*grating_operator(i);
173 wavefun_lp5_13a(i)=sqrt(rho_lp5_prob13a(i))*grating_operator(i);
174 wavefun_lp5_13b(i)=sqrt(rho_lp5_prob13b(i))*grating_operator(i);
175 wavefun_lp5_14a(i)=sqrt(rho_lp5_prob14a(i))*grating_operator(i);
176 wavefun_lp5_14b(i)=sqrt(rho_lp5_prob14b(i))*grating_operator(i);
177 wavefun_lp5_15a(i)=sqrt(rho_lp5_prob15a(i))*grating_operator(i);
178 wavefun_lp5_15b(i)=sqrt(rho_lp5_prob15b(i))*grating_operator(i);
179 wavefun_lp5_16a(i)=sqrt(rho_lp5_prob16a(i))*grating_operator(i);
180 wavefun_lp5_16b(i)=sqrt(rho_lp5_prob16b(i))*grating_operator(i);
181 wavefun_lp5_17a(i)=sqrt(rho_lp5_prob17a(i))*grating_operator(i);
182 wavefun_lp5_17b(i)=sqrt(rho_lp5_prob17b(i))*grating_operator(i);
183 wavefun_lp5_18a(i)=sqrt(rho_lp5_prob18a(i))*grating_operator(i);
184 wavefun_lp5_18b(i)=sqrt(rho_lp5_prob18b(i))*grating_operator(i);
185 wavefun_lp5_19a(i)=sqrt(rho_lp5_prob19a(i))*grating_operator(i);
186 wavefun_lp5_19b(i)=sqrt(rho_lp5_prob19b(i))*grating_operator(i);
187 wavefun_lp5_20a(i)=sqrt(rho_lp5_prob20a(i))*grating_operator(i);
188 wavefun_lp5_20b(i)=sqrt(rho_lp5_prob20b(i))*grating_operator(i);
189 wavefun_lp5_21a(i)=sqrt(rho_lp5_prob21a(i))*grating_operator(i);
190 wavefun_lp5_21b(i)=sqrt(rho_lp5_prob21b(i))*grating_operator(i);
191 wavefun_lp5_22a(i)=sqrt(rho_lp5_prob22a(i))*grating_operator(i);
192 wavefun_lp5_22b(i)=sqrt(rho_lp5_prob22b(i))*grating_operator(i);
193 wavefun_lp5_23a(i)=sqrt(rho_lp5_prob23a(i))*grating_operator(i);
194 wavefun_lp5_23b(i)=sqrt(rho_lp5_prob23b(i))*grating_operator(i);
195 wavefun_lp5_24a(i)=sqrt(rho_lp5_prob24a(i))*grating_operator(i);
196 wavefun_lp5_24b(i)=sqrt(rho_lp5_prob24b(i))*grating_operator(i);
197 wavefun_lp5_25a(i)=sqrt(rho_lp5_prob25a(i))*grating_operator(i);
198 wavefun_lp5_25b(i)=sqrt(rho_lp5_prob25b(i))*grating_operator(i);
199 wavefun_lp5_26a(i)=sqrt(rho_lp5_prob26a(i))*grating_operator(i);
200 wavefun_lp5_26b(i)=sqrt(rho_lp5_prob26b(i))*grating_operator(i);
201 wavefun_lp5_27a(i)=sqrt(rho_lp5_prob27a(i))*grating_operator(i);
202 wavefun_lp5_27b(i)=sqrt(rho_lp5_prob27b(i))*grating_operator(i);
203 wavefun_lp5_28a(i)=sqrt(rho_lp5_prob28a(i))*grating_operator(i);
204 wavefun_lp5_28b(i)=sqrt(rho_lp5_prob28b(i))*grating_operator(i);
205 wavefun_lp5_29a(i)=sqrt(rho_lp5_prob29a(i))*grating_operator(i);
206 wavefun_lp5_29b(i)=sqrt(rho_lp5_prob29b(i))*grating_operator(i);
207 wavefun_lp5_30a(i)=sqrt(rho_lp5_prob30a(i))*grating_operator(i);
208 wavefun_lp5_30b(i)=sqrt(rho_lp5_prob30b(i))*grating_operator(i);
209
210 end
211 %%
212 wavefun_lp5_0extended(1:1000)=0;
213 wavefun_lp5_0extended(1001:3001)=wavefun_lp5_0;
214 wavefun_lp5_0extended(3002:4001)=0;
215
216 wavefun_lp5_1aextended(1:1000)=0;
217 wavefun_lp5_1aextended(1001:3001)=wavefun_lp5_1a;
218 wavefun_lp5_1aextended(3002:4001)=0;
219 wavefun_lp5_1bextended(1:1000)=0;
220 wavefun_lp5_1bextended(1001:3001)=wavefun_lp5_1b;
221 wavefun_lp5_1bextended(3002:4001)=0;
222 wavefun_lp5_2aextended(1:1000)=0;
223 wavefun_lp5_2aextended(1001:3001)=wavefun_lp5_2a;
224 wavefun_lp5_2aextended(3002:4001)=0;
225 wavefun_lp5_2bextended(1:1000)=0;
226 wavefun_lp5_2bextended(1001:3001)=wavefun_lp5_2b;
227 wavefun_lp5_2bextended(3002:4001)=0;
228 wavefun_lp5_3aextended(1:1000)=0;
229 wavefun_lp5_3aextended(1001:3001)=wavefun_lp5_3a;
230 wavefun_lp5_3aextended(3002:4001)=0;
231 wavefun_lp5_3bextended(1:1000)=0;

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232 wavefun_lp5_3bextended(1001:3001)=wavefun_lp5_3b;
233 wavefun_lp5_3bextended(3002:4001)=0;
234 wavefun_lp5_4aextended(1:1000)=0;
235 wavefun_lp5_4aextended(1001:3001)=wavefun_lp5_4a;
236 wavefun_lp5_4aextended(3002:4001)=0;
237 wavefun_lp5_4bextended(1:1000)=0;
238 wavefun_lp5_4bextended(1001:3001)=wavefun_lp5_4b;
239 wavefun_lp5_4bextended(3002:4001)=0;
240 wavefun_lp5_5aextended(1:1000)=0;
241 wavefun_lp5_5aextended(1001:3001)=wavefun_lp5_5a;
242 wavefun_lp5_5aextended(3002:4001)=0;
243 wavefun_lp5_5bextended(1:1000)=0;
244 wavefun_lp5_5bextended(1001:3001)=wavefun_lp5_5b;
245 wavefun_lp5_5bextended(3002:4001)=0;
246
247 wavefun_lp5_6aextended(1:1000)=0;
248 wavefun_lp5_6aextended(1001:3001)=wavefun_lp5_6a;
249 wavefun_lp5_6aextended(3002:4001)=0;
250 wavefun_lp5_6bextended(1:1000)=0;
251 wavefun_lp5_6bextended(1001:3001)=wavefun_lp5_6b;
252 wavefun_lp5_6bextended(3002:4001)=0;
253 wavefun_lp5_7aextended(1:1000)=0;
254 wavefun_lp5_7aextended(1001:3001)=wavefun_lp5_7a;
255 wavefun_lp5_7aextended(3002:4001)=0;
256 wavefun_lp5_7bextended(1:1000)=0;
257 wavefun_lp5_7bextended(1001:3001)=wavefun_lp5_7b;
258 wavefun_lp5_7bextended(3002:4001)=0;
259 wavefun_lp5_8aextended(1:1000)=0;
260 wavefun_lp5_8aextended(1001:3001)=wavefun_lp5_8a;
261 wavefun_lp5_8aextended(3002:4001)=0;
262 wavefun_lp5_8bextended(1:1000)=0;
263 wavefun_lp5_8bextended(1001:3001)=wavefun_lp5_8b;
264 wavefun_lp5_8bextended(3002:4001)=0;
265 wavefun_lp5_9aextended(1:1000)=0;
266 wavefun_lp5_9aextended(1001:3001)=wavefun_lp5_9a;
267 wavefun_lp5_9aextended(3002:4001)=0;
268 wavefun_lp5_9bextended(1:1000)=0;
269 wavefun_lp5_9bextended(1001:3001)=wavefun_lp5_9b;
270 wavefun_lp5_9bextended(3002:4001)=0;
271 wavefun_lp5_10aextended(1:1000)=0;
272 wavefun_lp5_10aextended(1001:3001)=wavefun_lp5_10a;
273 wavefun_lp5_10aextended(3002:4001)=0;
274 wavefun_lp5_10bextended(1:1000)=0;
275 wavefun_lp5_10bextended(1001:3001)=wavefun_lp5_10b;
276 wavefun_lp5_10bextended(3002:4001)=0;
277
278 wavefun_lp5_11aextended(1:1000)=0;
279 wavefun_lp5_11aextended(1001:3001)=wavefun_lp5_11a;
280 wavefun_lp5_11aextended(3002:4001)=0;
281 wavefun_lp5_11bextended(1:1000)=0;
282 wavefun_lp5_11bextended(1001:3001)=wavefun_lp5_11b;
283 wavefun_lp5_11bextended(3002:4001)=0;
284 wavefun_lp5_12aextended(1:1000)=0;
285 wavefun_lp5_12aextended(1001:3001)=wavefun_lp5_12a;
286 wavefun_lp5_12aextended(3002:4001)=0;
287 wavefun_lp5_12bextended(1:1000)=0;
288 wavefun_lp5_12bextended(1001:3001)=wavefun_lp5_12b;
289 wavefun_lp5_12bextended(3002:4001)=0;
290 wavefun_lp5_13aextended(1:1000)=0;
291 wavefun_lp5_13aextended(1001:3001)=wavefun_lp5_13a;
292 wavefun_lp5_13aextended(3002:4001)=0;
293 wavefun_lp5_13bextended(1:1000)=0;
294 wavefun_lp5_13bextended(1001:3001)=wavefun_lp5_13b;
295 wavefun_lp5_13bextended(3002:4001)=0;
296 wavefun_lp5_14aextended(1:1000)=0;
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297 wavefun_lp5_14aextended(1001:3001)=wavefun_lp5_14a;
298 wavefun_lp5_14aextended(3002:4001)=0;
299 wavefun_lp5_14bextended(1:1000)=0;
300 wavefun_lp5_14bextended(1001:3001)=wavefun_lp5_14b;
301 wavefun_lp5_14bextended(3002:4001)=0;
302 wavefun_lp5_15aextended(1:1000)=0;
303 wavefun_lp5_15aextended(1001:3001)=wavefun_lp5_15a;
304 wavefun_lp5_15aextended(3002:4001)=0;
305 wavefun_lp5_15bextended(1:1000)=0;
306 wavefun_lp5_15bextended(1001:3001)=wavefun_lp5_15b;
307 wavefun_lp5_15bextended(3002:4001)=0;
308
309 wavefun_lp5_16aextended(1:1000)=0;
310 wavefun_lp5_16aextended(1001:3001)=wavefun_lp5_16a;
311 wavefun_lp5_16aextended(3002:4001)=0;
312 wavefun_lp5_16bextended(1:1000)=0;
313 wavefun_lp5_16bextended(1001:3001)=wavefun_lp5_16b;
314 wavefun_lp5_16bextended(3002:4001)=0;
315 wavefun_lp5_17aextended(1:1000)=0;
316 wavefun_lp5_17aextended(1001:3001)=wavefun_lp5_17a;
317 wavefun_lp5_17aextended(3002:4001)=0;
318 wavefun_lp5_17bextended(1:1000)=0;
319 wavefun_lp5_17bextended(1001:3001)=wavefun_lp5_17b;
320 wavefun_lp5_17bextended(3002:4001)=0;
321 wavefun_lp5_18aextended(1:1000)=0;
322 wavefun_lp5_18aextended(1001:3001)=wavefun_lp5_18a;
323 wavefun_lp5_18aextended(3002:4001)=0;
324 wavefun_lp5_18bextended(1:1000)=0;
325 wavefun_lp5_18bextended(1001:3001)=wavefun_lp5_18b;
326 wavefun_lp5_18bextended(3002:4001)=0;
327 wavefun_lp5_19aextended(1:1000)=0;
328 wavefun_lp5_19aextended(1001:3001)=wavefun_lp5_19a;
329 wavefun_lp5_19aextended(3002:4001)=0;
330 wavefun_lp5_19bextended(1:1000)=0;
331 wavefun_lp5_19bextended(1001:3001)=wavefun_lp5_19b;
332 wavefun_lp5_19bextended(3002:4001)=0;
333 wavefun_lp5_20aextended(1:1000)=0;
334 wavefun_lp5_20aextended(1001:3001)=wavefun_lp5_20a;
335 wavefun_lp5_20aextended(3002:4001)=0;
336 wavefun_lp5_20bextended(1:1000)=0;
337 wavefun_lp5_20bextended(1001:3001)=wavefun_lp5_20b;
338 wavefun_lp5_20bextended(3002:4001)=0;
339
340 wavefun_lp5_21aextended(1:1000)=0;
341 wavefun_lp5_21aextended(1001:3001)=wavefun_lp5_21a;
342 wavefun_lp5_21aextended(3002:4001)=0;
343 wavefun_lp5_21bextended(1:1000)=0;
344 wavefun_lp5_21bextended(1001:3001)=wavefun_lp5_21b;
345 wavefun_lp5_21bextended(3002:4001)=0;
346 wavefun_lp5_22aextended(1:1000)=0;
347 wavefun_lp5_22aextended(1001:3001)=wavefun_lp5_22a;
348 wavefun_lp5_22aextended(3002:4001)=0;
349 wavefun_lp5_22bextended(1:1000)=0;
350 wavefun_lp5_22bextended(1001:3001)=wavefun_lp5_22b;
351 wavefun_lp5_22bextended(3002:4001)=0;
352 wavefun_lp5_23aextended(1:1000)=0;
353 wavefun_lp5_23aextended(1001:3001)=wavefun_lp5_23a;
354 wavefun_lp5_23aextended(3002:4001)=0;
355 wavefun_lp5_23bextended(1:1000)=0;
356 wavefun_lp5_23bextended(1001:3001)=wavefun_lp5_23b;
357 wavefun_lp5_23bextended(3002:4001)=0;
358 wavefun_lp5_24aextended(1:1000)=0;
359 wavefun_lp5_24aextended(1001:3001)=wavefun_lp5_24a;
360 wavefun_lp5_24aextended(3002:4001)=0;
361 wavefun_lp5_24bextended(1:1000)=0;
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362 wavefun_lp5_24bextended(1001:3001)=wavefun_lp5_24b;
363 wavefun_lp5_24bextended(3002:4001)=0;
364 wavefun_lp5_25aextended(1:1000)=0;
365 wavefun_lp5_25aextended(1001:3001)=wavefun_lp5_25a;
366 wavefun_lp5_25aextended(3002:4001)=0;
367 wavefun_lp5_25bextended(1:1000)=0;
368 wavefun_lp5_25bextended(1001:3001)=wavefun_lp5_25b;
369 wavefun_lp5_25bextended(3002:4001)=0;
370
371 wavefun_lp5_26aextended(1:1000)=0;
372 wavefun_lp5_26aextended(1001:3001)=wavefun_lp5_26a;
373 wavefun_lp5_26aextended(3002:4001)=0;
374 wavefun_lp5_26bextended(1:1000)=0;
375 wavefun_lp5_26bextended(1001:3001)=wavefun_lp5_26b;
376 wavefun_lp5_26bextended(3002:4001)=0;
377 wavefun_lp5_27aextended(1:1000)=0;
378 wavefun_lp5_27aextended(1001:3001)=wavefun_lp5_27a;
379 wavefun_lp5_27aextended(3002:4001)=0;
380 wavefun_lp5_27bextended(1:1000)=0;
381 wavefun_lp5_27bextended(1001:3001)=wavefun_lp5_27b;
382 wavefun_lp5_27bextended(3002:4001)=0;
383 wavefun_lp5_28aextended(1:1000)=0;
384 wavefun_lp5_28aextended(1001:3001)=wavefun_lp5_28a;
385 wavefun_lp5_28aextended(3002:4001)=0;
386 wavefun_lp5_28bextended(1:1000)=0;
387 wavefun_lp5_28bextended(1001:3001)=wavefun_lp5_28b;
388 wavefun_lp5_28bextended(3002:4001)=0;
389 wavefun_lp5_29aextended(1:1000)=0;
390 wavefun_lp5_29aextended(1001:3001)=wavefun_lp5_29a;
391 wavefun_lp5_29aextended(3002:4001)=0;
392 wavefun_lp5_29bextended(1:1000)=0;
393 wavefun_lp5_29bextended(1001:3001)=wavefun_lp5_29b;
394 wavefun_lp5_29bextended(3002:4001)=0;
395 wavefun_lp5_30aextended(1:1000)=0;
396 wavefun_lp5_30aextended(1001:3001)=wavefun_lp5_30a;
397 wavefun_lp5_30aextended(3002:4001)=0;
398 wavefun_lp5_30bextended(1:1000)=0;
399 wavefun_lp5_30bextended(1001:3001)=wavefun_lp5_30b;
400 wavefun_lp5_30bextended(3002:4001)=0;
401
402 %%
403
404 farfield_x=[-2000:2000]*.72; %far field domain to obtain a ff peak_periodicity
    of 72um
405
406 Y=fft(wavefun_lp5_0extended);
407 farfieldintensity = real( Y .* conj( Y ) );
408 farfield_pattern=fftshift( farfieldintensity );
409 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
410 scaledresult_lp5_0=a0*fourier_result;
411
412 Y=fft(wavefun_lp5_laextended);
413 farfieldintensity = real( Y .* conj( Y ) );
414 farfield_pattern=fftshift( farfieldintensity );
415 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
416 scaledresult_lp5_la=a1*interp( farfield_x-1*delx,fourier_result,farfield_x);
417 Y=fft(wavefun_lp5_lbextended);
418 farfieldintensity = real( Y .* conj( Y ) );
419 farfield_pattern=fftshift( farfieldintensity );
420 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
421 scaledresult_lp5_lb=a1*interp( farfield_x+1*delx,fourier_result,farfield_x);
422
423 Y=fft(wavefun_lp5_2aextended);
424 farfieldintensity = real( Y .* conj( Y ) );
425 farfield_pattern=fftshift( farfieldintensity );

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426  fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
427  scaledresult_lp5_2a=a2*interp1(farfield_x-2*delx,fourier_result,farfield_x);
428  Y=fft(wavefun_lp5_2bextended);
429  farfieldintensity = real( Y .* conj( Y ) );
430  farfield_pattern=fftshift( farfieldintensity );
431  fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
432  scaledresult_lp5_2b=a2*interp1(farfield_x+2*delx,fourier_result,farfield_x);
433
434  Y=fft(wavefun_lp5_3aextended);
435  farfieldintensity = real( Y .* conj( Y ) );
436  farfield_pattern=fftshift( farfieldintensity );
437  fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
438  scaledresult_lp5_3a=a3*interp1(farfield_x-3*delx,fourier_result,farfield_x);
439  Y=fft(wavefun_lp5_3bextended);
440  farfieldintensity = real( Y .* conj( Y ) );
441  farfield_pattern=fftshift( farfieldintensity );
442  fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
443  scaledresult_lp5_3b=a3*interp1(farfield_x+3*delx,fourier_result,farfield_x);
444
445  Y=fft(wavefun_lp5_4aextended);
446  farfieldintensity = real( Y .* conj( Y ) );
447  farfield_pattern=fftshift( farfieldintensity );
448  fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
449  scaledresult_lp5_4a=a4*interp1(farfield_x-4*delx,fourier_result,farfield_x);
450  Y=fft(wavefun_lp5_4bextended);
451  farfieldintensity = real( Y .* conj( Y ) );
452  farfield_pattern=fftshift( farfieldintensity );
453  fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
454  scaledresult_lp5_4b=a4*interp1(farfield_x+4*delx,fourier_result,farfield_x);
455
456  Y=fft(wavefun_lp5_5aextended);
457  farfieldintensity = real( Y .* conj( Y ) );
458  farfield_pattern=fftshift( farfieldintensity );
459  fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
460  scaledresult_lp5_5a=a5*interp1(farfield_x-5*delx,fourier_result,farfield_x);
461  Y=fft(wavefun_lp5_5bextended);
462  farfieldintensity = real( Y .* conj( Y ) );
463  farfield_pattern=fftshift( farfieldintensity );
464  fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
465  scaledresult_lp5_5b=a5*interp1(farfield_x+5*delx,fourier_result,farfield_x);
466
467  Y=fft(wavefun_lp5_6aextended);
468  farfieldintensity = real( Y .* conj( Y ) );
469  farfield_pattern=fftshift( farfieldintensity );
470  fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
471  scaledresult_lp5_6a=a6*interp1(farfield_x-6*delx,fourier_result,farfield_x);
472  Y=fft(wavefun_lp5_6bextended);
473  farfieldintensity = real( Y .* conj( Y ) );
474  farfield_pattern=fftshift( farfieldintensity );
475  fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
476  scaledresult_lp5_6b=a6*interp1(farfield_x+6*delx,fourier_result,farfield_x);
477
478  Y=fft(wavefun_lp5_7aextended);
479  farfieldintensity = real( Y .* conj( Y ) );
480  farfield_pattern=fftshift( farfieldintensity );
481  fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
482  scaledresult_lp5_7a=a7*interp1(farfield_x-7*delx,fourier_result,farfield_x);
483  Y=fft(wavefun_lp5_7bextended);
484  farfieldintensity = real( Y .* conj( Y ) );
485  farfield_pattern=fftshift( farfieldintensity );
486  fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
487  scaledresult_lp5_7b=a7*interp1(farfield_x+7*delx,fourier_result,farfield_x);
488
489  Y=fft(wavefun_lp5_8aextended);
490  farfieldintensity = real( Y .* conj( Y ) );

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491 farfield_pattern=fftshift( farfieldintensity );
492 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
493 scaledresult_lp5_8a=a8*interp1(farfield_x-8*delx,fourier_result,farfield_x);
494 Y=fft(wavefun_lp5_8bextended);
495 farfieldintensity = real( Y .* conj( Y ) );
496 farfield_pattern=fftshift( farfieldintensity );
497 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
498 scaledresult_lp5_8b=a8*interp1(farfield_x+8*delx,fourier_result,farfield_x);
499
500 Y=fft(wavefun_lp5_9aextended);
501 farfieldintensity = real( Y .* conj( Y ) );
502 farfield_pattern=fftshift( farfieldintensity );
503 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
504 scaledresult_lp5_9a=a9*interp1(farfield_x-9*delx,fourier_result,farfield_x);
505 Y=fft(wavefun_lp5_9bextended);
506 farfieldintensity = real( Y .* conj( Y ) );
507 farfield_pattern=fftshift( farfieldintensity );
508 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
509 scaledresult_lp5_9b=a9*interp1(farfield_x+9*delx,fourier_result,farfield_x);
510
511 Y=fft(wavefun_lp5_10aextended);
512 farfieldintensity = real( Y .* conj( Y ) );
513 farfield_pattern=fftshift( farfieldintensity );
514 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
515 scaledresult_lp5_10a=a10*interp1(farfield_x-10*delx,fourier_result,farfield_x);
516 Y=fft(wavefun_lp5_10bextended);
517 farfieldintensity = real( Y .* conj( Y ) );
518 farfield_pattern=fftshift( farfieldintensity );
519 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
520 scaledresult_lp5_10b=a10*interp1(farfield_x+10*delx,fourier_result,farfield_x);
521
522 Y=fft(wavefun_lp5_11aextended);
523 farfieldintensity = real( Y .* conj( Y ) );
524 farfield_pattern=fftshift( farfieldintensity );
525 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
526 scaledresult_lp5_11a=a11*interp1(farfield_x-11*delx,fourier_result,farfield_x);
527 Y=fft(wavefun_lp5_11bextended);
528 farfieldintensity = real( Y .* conj( Y ) );
529 farfield_pattern=fftshift( farfieldintensity );
530 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
531 scaledresult_lp5_11b=a11*interp1(farfield_x+11*delx,fourier_result,farfield_x);
532
533 Y=fft(wavefun_lp5_12aextended);
534 farfieldintensity = real( Y .* conj( Y ) );
535 farfield_pattern=fftshift( farfieldintensity );
536 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
537 scaledresult_lp5_12a=a12*interp1(farfield_x-12*delx,fourier_result,farfield_x);
538 Y=fft(wavefun_lp5_12bextended);
539 farfieldintensity = real( Y .* conj( Y ) );
540 farfield_pattern=fftshift( farfieldintensity );
541 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
542 scaledresult_lp5_12b=a12*interp1(farfield_x+12*delx,fourier_result,farfield_x);
543
544 Y=fft(wavefun_lp5_13aextended);
545 farfieldintensity = real( Y .* conj( Y ) );
546 farfield_pattern=fftshift( farfieldintensity );
547 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
548 scaledresult_lp5_13a=a13*interp1(farfield_x-13*delx,fourier_result,farfield_x);
549 Y=fft(wavefun_lp5_13bextended);
550 farfieldintensity = real( Y .* conj( Y ) );
551 farfield_pattern=fftshift( farfieldintensity );
552 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
553 scaledresult_lp5_13b=a13*interp1(farfield_x+13*delx,fourier_result,farfield_x);
554
555 Y=fft(wavefun_lp5_14aextended);

```



```

556 farfieldintensity = real( Y .* conj( Y ) );
557 farfield_pattern=fftshift( farfieldintensity );
558 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
559 scaledresult_lp5_14a=a14*interp1(farfield_x-14*delx,fourier_result,farfield_x);
560 Y=fft(wavefun_lp5_14bextended);
561 farfieldintensity = real( Y .* conj( Y ) );
562 farfield_pattern=fftshift( farfieldintensity );
563 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
564 scaledresult_lp5_14b=a14*interp1(farfield_x+14*delx,fourier_result,farfield_x);
565
566 Y=fft(wavefun_lp5_15aextended);
567 farfieldintensity = real( Y .* conj( Y ) );
568 farfield_pattern=fftshift( farfieldintensity );
569 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
570 scaledresult_lp5_15a=a15*interp1(farfield_x-15*delx,fourier_result,farfield_x);
571 Y=fft(wavefun_lp5_15bextended);
572 farfieldintensity = real( Y .* conj( Y ) );
573 farfield_pattern=fftshift( farfieldintensity );
574 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
575 scaledresult_lp5_15b=a15*interp1(farfield_x+15*delx,fourier_result,farfield_x);
576
577 Y=fft(wavefun_lp5_16aextended);
578 farfieldintensity = real( Y .* conj( Y ) );
579 farfield_pattern=fftshift( farfieldintensity );
580 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
581 scaledresult_lp5_16a=a16*interp1(farfield_x-16*delx,fourier_result,farfield_x);
582 Y=fft(wavefun_lp5_16bextended);
583 farfieldintensity = real( Y .* conj( Y ) );
584 farfield_pattern=fftshift( farfieldintensity );
585 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
586 scaledresult_lp5_16b=a16*interp1(farfield_x+16*delx,fourier_result,farfield_x);
587
588 Y=fft(wavefun_lp5_17aextended);
589 farfieldintensity = real( Y .* conj( Y ) );
590 farfield_pattern=fftshift( farfieldintensity );
591 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
592 scaledresult_lp5_17a=a17*interp1(farfield_x-17*delx,fourier_result,farfield_x);
593 Y=fft(wavefun_lp5_17bextended);
594 farfieldintensity = real( Y .* conj( Y ) );
595 farfield_pattern=fftshift( farfieldintensity );
596 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
597 scaledresult_lp5_17b=a17*interp1(farfield_x+17*delx,fourier_result,farfield_x);
598
599 Y=fft(wavefun_lp5_18aextended);
600 farfieldintensity = real( Y .* conj( Y ) );
601 farfield_pattern=fftshift( farfieldintensity );
602 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
603 scaledresult_lp5_18a=a18*interp1(farfield_x-18*delx,fourier_result,farfield_x);
604 Y=fft(wavefun_lp5_18bextended);
605 farfieldintensity = real( Y .* conj( Y ) );
606 farfield_pattern=fftshift( farfieldintensity );
607 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
608 scaledresult_lp5_18b=a18*interp1(farfield_x+18*delx,fourier_result,farfield_x);
609
610 Y=fft(wavefun_lp5_19aextended);
611 farfieldintensity = real( Y .* conj( Y ) );
612 farfield_pattern=fftshift( farfieldintensity );
613 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
614 scaledresult_lp5_19a=a19*interp1(farfield_x-19*delx,fourier_result,farfield_x);
615 Y=fft(wavefun_lp5_19bextended);
616 farfieldintensity = real( Y .* conj( Y ) );
617 farfield_pattern=fftshift( farfieldintensity );
618 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
619 scaledresult_lp5_19b=a19*interp1(farfield_x+19*delx,fourier_result,farfield_x);
620

```

```

621 Y=fft(wavefun_lp5_20aextended);
622 farfieldintensity = real( Y .* conj( Y ) );
623 farfield_pattern=fftshift( farfieldintensity );
624 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
625 scaledresult_lp5_20a=a20*interp1(farfield_x-20*delx,fourier_result,farfield_x);
626 Y=fft(wavefun_lp5_20bextended);
627 farfieldintensity = real( Y .* conj( Y ) );
628 farfield_pattern=fftshift( farfieldintensity );
629 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
630 scaledresult_lp5_20b=a20*interp1(farfield_x+20*delx,fourier_result,farfield_x);
631
632
633 Y=fft(wavefun_lp5_21aextended);
634 farfieldintensity = real( Y .* conj( Y ) );
635 farfield_pattern=fftshift( farfieldintensity );
636 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
637 scaledresult_lp5_21a=a21*interp1(farfield_x-21*delx,fourier_result,farfield_x);
638 Y=fft(wavefun_lp5_21bextended);
639 farfieldintensity = real( Y .* conj( Y ) );
640 farfield_pattern=fftshift( farfieldintensity );
641 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
642 scaledresult_lp5_21b=a21*interp1(farfield_x+21*delx,fourier_result,farfield_x);
643
644 Y=fft(wavefun_lp5_22aextended);
645 farfieldintensity = real( Y .* conj( Y ) );
646 farfield_pattern=fftshift( farfieldintensity );
647 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
648 scaledresult_lp5_22a=a22*interp1(farfield_x-22*delx,fourier_result,farfield_x);
649 Y=fft(wavefun_lp5_22bextended);
650 farfieldintensity = real( Y .* conj( Y ) );
651 farfield_pattern=fftshift( farfieldintensity );
652 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
653 scaledresult_lp5_22b=a22*interp1(farfield_x+22*delx,fourier_result,farfield_x);
654
655 Y=fft(wavefun_lp5_23aextended);
656 farfieldintensity = real( Y .* conj( Y ) );
657 farfield_pattern=fftshift( farfieldintensity );
658 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
659 scaledresult_lp5_23a=a23*interp1(farfield_x-23*delx,fourier_result,farfield_x);
660 Y=fft(wavefun_lp5_23bextended);
661 farfieldintensity = real( Y .* conj( Y ) );
662 farfield_pattern=fftshift( farfieldintensity );
663 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
664 scaledresult_lp5_23b=a23*interp1(farfield_x+23*delx,fourier_result,farfield_x);
665
666 Y=fft(wavefun_lp5_24aextended);
667 farfieldintensity = real( Y .* conj( Y ) );
668 farfield_pattern=fftshift( farfieldintensity );
669 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
670 scaledresult_lp5_24a=a24*interp1(farfield_x-24*delx,fourier_result,farfield_x);
671 Y=fft(wavefun_lp5_24bextended);
672 farfieldintensity = real( Y .* conj( Y ) );
673 farfield_pattern=fftshift( farfieldintensity );
674 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
675 scaledresult_lp5_24b=a24*interp1(farfield_x+24*delx,fourier_result,farfield_x);
676
677 Y=fft(wavefun_lp5_25aextended);
678 farfieldintensity = real( Y .* conj( Y ) );
679 farfield_pattern=fftshift( farfieldintensity );
680 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
681 scaledresult_lp5_25a=a25*interp1(farfield_x-25*delx,fourier_result,farfield_x);
682 Y=fft(wavefun_lp5_25bextended);
683 farfieldintensity = real( Y .* conj( Y ) );
684 farfield_pattern=fftshift( farfieldintensity );
685 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));

```

```

686 scaledresult_lp5_25b=a25*interp1(farfield_x+25*delx,fourier_result,farfield_x);
687
688 Y=fft(wavefun_lp5_26aextended);
689 farfieldintensity = real( Y .* conj( Y ) );
690 farfield_pattern=fftshift( farfieldintensity );
691 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
692 scaledresult_lp5_26a=a26*interp1(farfield_x-26*delx,fourier_result,farfield_x);
693 Y=fft(wavefun_lp5_26bextended);
694 farfieldintensity = real( Y .* conj( Y ) );
695 farfield_pattern=fftshift( farfieldintensity );
696 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
697 scaledresult_lp5_26b=a26*interp1(farfield_x+26*delx,fourier_result,farfield_x);
698
699 Y=fft(wavefun_lp5_27aextended);
700 farfieldintensity = real( Y .* conj( Y ) );
701 farfield_pattern=fftshift( farfieldintensity );
702 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
703 scaledresult_lp5_27a=a27*interp1(farfield_x-27*delx,fourier_result,farfield_x);
704 Y=fft(wavefun_lp5_27bextended);
705 farfieldintensity = real( Y .* conj( Y ) );
706 farfield_pattern=fftshift( farfieldintensity );
707 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
708 scaledresult_lp5_27b=a27*interp1(farfield_x+27*delx,fourier_result,farfield_x);
709
710 Y=fft(wavefun_lp5_28aextended);
711 farfieldintensity = real( Y .* conj( Y ) );
712 farfield_pattern=fftshift( farfieldintensity );
713 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
714 scaledresult_lp5_28a=a28*interp1(farfield_x-28*delx,fourier_result,farfield_x);
715 Y=fft(wavefun_lp5_28bextended);
716 farfieldintensity = real( Y .* conj( Y ) );
717 farfield_pattern=fftshift( farfieldintensity );
718 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
719 scaledresult_lp5_28b=a28*interp1(farfield_x+28*delx,fourier_result,farfield_x);
720
721 Y=fft(wavefun_lp5_29aextended);
722 farfieldintensity = real( Y .* conj( Y ) );
723 farfield_pattern=fftshift( farfieldintensity );
724 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
725 scaledresult_lp5_29a=a29*interp1(farfield_x-29*delx,fourier_result,farfield_x);
726 Y=fft(wavefun_lp5_29bextended);
727 farfieldintensity = real( Y .* conj( Y ) );
728 farfield_pattern=fftshift( farfieldintensity );
729 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
730 scaledresult_lp5_29b=a29*interp1(farfield_x+29*delx,fourier_result,farfield_x);
731
732 Y=fft(wavefun_lp5_30aextended);
733 farfieldintensity = real( Y .* conj( Y ) );
734 farfield_pattern=fftshift( farfieldintensity );
735 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
736 scaledresult_lp5_30a=a30*interp1(farfield_x-30*delx,fourier_result,farfield_x);
737 Y=fft(wavefun_lp5_30bextended);
738 farfieldintensity = real( Y .* conj( Y ) );
739 farfield_pattern=fftshift( farfieldintensity );
740 fourier_result=abs(farfield_pattern)/max(abs(farfield_pattern));
741 scaledresult_lp5_30b=a30*interp1(farfield_x+30*delx,fourier_result,farfield_x);
742
743 %%
744
745 totalscaledresult=scaledresult_lp5_0+scaledresult_lp5_1a+scaledresult_lp5_1b+scale
dresult_lp5_2a+scaledresult_lp5_2b+...
746
747 scaledresult_lp5_3a+scaledresult_lp5_3b+scale
dresult_lp5_4a+scaledresult_lp5_4b+...

```

```

748 scaledresult_lp5_5a+scaledresult_lp5_5b+sca
      dresult_lp5_6a+scaledresult_lp5_6b+...
749 scaledresult_lp5_7a+scaledresult_lp5_7b+sca
      dresult_lp5_8a+scaledresult_lp5_8b+...
750 scaledresult_lp5_9a+scaledresult_lp5_9b+sca
      dresult_lp5_10a+scaledresult_lp5_10b+...
751 scaledresult_lp5_11a+scaledresult_lp5_11b+sca
      ledresult_lp5_12a+scaledresult_lp5_12b+...
752 scaledresult_lp5_13a+scaledresult_lp5_13b+sca
      ledresult_lp5_14a+scaledresult_lp5_14b+...
753 scaledresult_lp5_15a+scaledresult_lp5_15b+sca
      ledresult_lp5_16a+scaledresult_lp5_16b+...
754 scaledresult_lp5_17a+scaledresult_lp5_17b+sca
      ledresult_lp5_18a+scaledresult_lp5_18b+...
755 scaledresult_lp5_19a+scaledresult_lp5_19b+sca
      ledresult_lp5_20a+scaledresult_lp5_20b+...
756 scaledresult_lp5_21a+scaledresult_lp5_21b+sca
      ledresult_lp5_22a+scaledresult_lp5_22b+...
757 scaledresult_lp5_23a+scaledresult_lp5_23b+sca
      ledresult_lp5_24a+scaledresult_lp5_24b+...
758 scaledresult_lp5_25a+scaledresult_lp5_25b+sca
      ledresult_lp5_26a+scaledresult_lp5_26b+...
759 scaledresult_lp5_27a+scaledresult_lp5_27b+sca
      ledresult_lp5_28a+scaledresult_lp5_28b+...
760 scaledresult_lp5_29a+scaledresult_lp5_29b+sca
      ledresult_lp5_30a+scaledresult_lp5_30b;
761 %%
762 %plot(farfield_x,fourier_result_coherent,'k')
763 hold on
764 %plot(farfield_x,fourier_result_lp5_0,'b')
765 plot(farfield_x,totalscaledresult./max(totalscaledresult),'m')
766 xlim([-30 30])
767 hold off
768 %%
769
770 plot(totalscaledresult,'m')
771 hold on
772 xlim([1950 2050])
773 hold off
774
775
776 %%
777
778 format long
779 f =
      fit(transpose(farfield_x(1950:2050)),transpose(totalscaledresult(1950:2050)),'gaus
      s1');
780 coeffvals = coeffvalues(f);
781 width=2*sqrt(log(2))*coeffvals(3);

```

```
782 length=.1*72/width % = 0.618384553064904
783
784
```

APPENDIX C

THEORETICAL METHOD FOR CLASSICAL BEAM

PROPAGATION AND CALCULATION OF TRANSVERSE

COHERENCE LENGTH

C.1 Classical Simulation Perpendicular to the Surface

The electron distribution measured at the detector in the Y-direction is modeled (perpendicular to the plane of the surface) by classical simulation. The simulation starts with a distribution of initial positions and momentum which is defined by the 1st and 2nd slits. With a 1st slit of height of 19 μm and a second slit with a height of 12.8 μm separated by 25 cm, this provides a beam with a divergence of ~ 120 μrad . This produces a small transverse coherence length in the y-direction (~ 250 nm), therefore a classical approach for motion in the y-direction is appropriate.

Therefore, the initial positions $y(0)$ and corresponding initial velocities $v_y(0)$ at the beginning of the surface are

$$\begin{aligned}
 y(0) &= s_1 + b \cdot (25 \text{ cm} + 6 \text{ cm}); \quad b = (s_2 - s_1) / (25 \text{ cm}) \\
 v_y(0) &= v_0 \frac{b}{\sqrt{1+b^2}} \\
 z(0) &= 0 \\
 v_z(0) &= v_0 \frac{1}{\sqrt{1+b^2}},
 \end{aligned} \tag{C.1}$$

with $-9.5 \mu\text{m} \leq s_1 \leq 9.5 \mu\text{m}$, $-6.4 \mu\text{m} \leq s_2 \leq 6.4 \mu\text{m}$ in steps of 10 nm.

Over the 1 cm surface, the electron evolves per newton's equations of motion with a force in the y-direction due to image charge. Thus, the kinematic equations are

$$\begin{aligned}
 \dot{y}(t_i) &= v_y(t_i) \\
 \dot{v}_y(t_i) &= -\frac{kq^2}{4m_e(y(t_i)+H)^2} \text{ (over surface)} \\
 \dot{z}(t_i) &= v_z \text{ (const)} \\
 \dot{v}_z(t_i) &= 0,
 \end{aligned} \tag{C.2}$$

where H is the height of the surface. Only electrons which do not contact the surface are considered (i.e. trajectories that collide within 10 nm of the surface are thrown out). This is done in time steps of ~ 825 femtoseconds (the total time of flight over the surface is ~ 413 picoseconds).

After reaching the end of the surface the electron undergoes free propagation another 23 cm to the detection plan, that is

$$\begin{aligned}
 \dot{y}(t_i) &= v_y(t_i) \\
 \dot{v}_y(t_i) &= 0 \text{ (free propogation)} \\
 \dot{z}(t_i) &= v_z \text{ (const)} \\
 \dot{v}_z(t_i) &= 0.
 \end{aligned} \tag{C.3}$$

For computation time and simplicity this is completed in only one time-step: $\Delta t = (23 \text{ cm})/v_z$. The final positions of the electrons are binned into 600 nm intervals along the y-direction. After the accumulation of all the trajectories that reach the detection plane, an electron distribution is produced in the Y-direction that can be compared to experimental results.

In the simulation, the surface is cut in at a height $H = -590$ nm below the central axis of the electron beam resulting in only 1/3 of the original electron beam flux making it to the detector. This distribution is compared to the case of the electric image charge force turned off, as well as when the surface is brought far away from the beam. From this it can be shown that the classical simulation of propagation of this electron beam with a travelling image charge well-approximates what is observed experimentally at the detector (see Figure C.1).

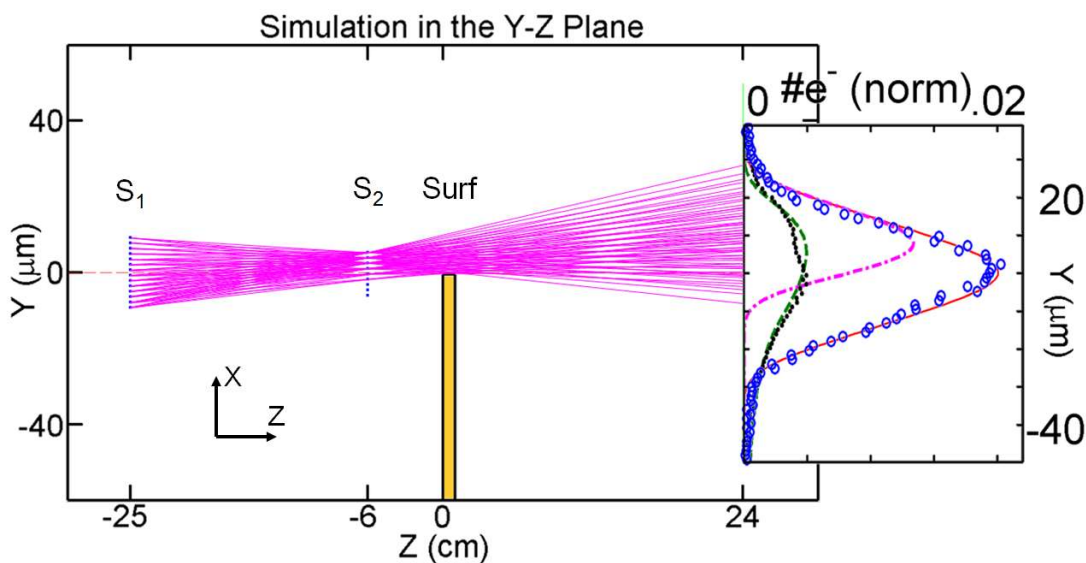


Figure C.1: Classical Simulation in the Y-Z Plane. Left: The initial positions and velocities at the surface (Surf) are prepared corresponding to ballistic motion from the two collimating slits (S1 and S2). The electron then propagates over the surface with an image charge attraction in the Y-direction, and afterward freely propagates to the detector. The trajectories imaged are a sample of the case those when the surface cuts the beam but no image charge is present. Right: Simulation when there is no wall (solid red line) compared to when the surface is raised to cut 1/3 of the beam (dashed and dotted-dashed lines). When the surface is not present, the experimentally observed distribution (blue open dots) closely fits the simulation when no surface is present. When experimentally the surface cuts 1/3 of the electron flux (black closed dots), the distribution closely fits the simulation when image charge is present (green dashed line) as opposed to no image charge (pink dashed dotted line).

C.2 Quantum Decoherence Simulation Parallel to the Surface

To compute the evolution of the electron's density matrix in the x -direction as it passes over the surface, we first prepare the initial density matrix of the free electron by considering a partially coherent Gaussian beam,

$$\rho_{initial}(x, x') = \frac{1}{\sigma_0^{coh} \sqrt{2\pi}} \exp\left(-\frac{(x-x_0)^2}{2(\sigma_0^{coh})^2}\right) \exp\left(-\frac{(x')^2}{2(\sigma'_{initial})^2}\right). \quad (C.4)$$

Here x and x' describe the coordinates of the matrix element in the direction of the diagonal and in the direction orthogonal to the diagonal respectively (Figure C.2). The position x_0 indicates the center of the Gaussian. The width of the Gaussian in the x' direction, $w'_{initial} \equiv 2\sqrt{2 \ln(2)} \sigma'_{initial}$, is proportional to the transverse coherence length. The spatial width along x , $w \equiv 2\sqrt{2 \ln(2)} \sigma_0^{coh}$ is determined by a path integral simulation taking into consideration propagation through the first two collimation slits and reaching the beginning of the surface [28]. Note that if $w'_{initial}$ equals w , then the initial beam is fully coherent. If $w'_{initial}$ is smaller than w , then the initial beam is partially coherent as in Figure C.2 (left).

The initial state of the electron $\rho_{initial}$ now starts right before the surface at time t_i . We model the change in transverse coherence length of the electron over the surface due to a given decoherence process by considering the evolution of the density matrix of the electron. It changes according to [33]:

$$\rho_{final} = \rho_{initial} e^{-\int_{t_i}^{t_f} dt / \tau_{dec}}, \quad (C.5)$$

where the decoherence time scale τ_{dec} is model-dependent and depends on $\Delta\mathbf{x}$ and $y(t)$.

When computing the integral in equation C.5 the simulated trajectories $y(t)$ are then inserted.

Each element in the density matrix is computed according to equation C.5 with the corresponding model considered. Note that $2x' \equiv \Delta\mathbf{x}$ is the distance between symmetric elements across the main diagonal, and equals the variable $\Delta\mathbf{x}$ used in the models. The final state of the electron ρ_{final} is now right after the surface at time t_f . The density of the electron after the surface now has the form

$$\rho_{final}(x, x') = \frac{1}{\sigma_0^{coh} \sqrt{2\pi}} \exp\left(-\frac{(x-x_0)^2}{2(\sigma_0^{coh})^2}\right) \exp\left(-\frac{(x')^2}{2(\sigma'_{final})^2}\right), \quad (C.6)$$

when the width of the final state orthogonal to the diagonal is smaller than the width of the initial state ($w'_{final} < w'_{initial}$) then decoherence has occurred.

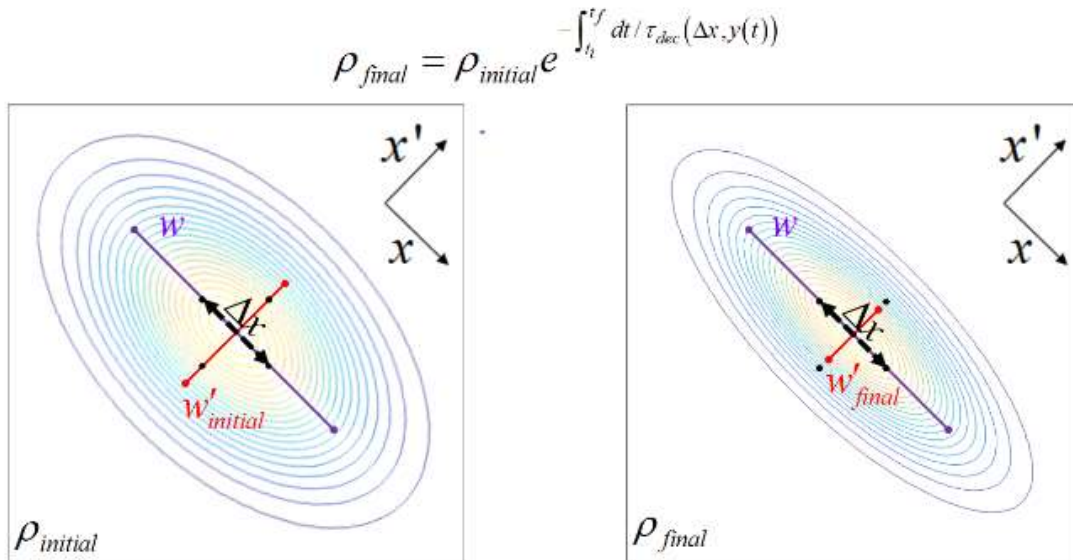


Figure C.2: Evolution of Density Matrix when Propagating over the Surface. As a result of decoherence, the initial state (left) evolves such that the off-diagonal elements reduce in amplitude. Hence the state's width w' decrease ($w'_{initial} \geq w'_{final}$).

For each final position bin at the detector where electrons landed, the final density matrix at the detector is computed by incoherently adding the individual matrices of each electron that reaches that bin. Making use of the ability to write a partial coherent state as a sum of coherent (i.e. pure) states (see Figure C.3),

$$\rho_{final} = \sum_{n=1}^{\infty} c_n \rho_n^{coh}, \quad (C.7)$$

then we can write ρ_{final} as a sum of Gaussian coherent states,

$$\rho_{final} \approx \sum_{n=1}^N \exp\left(-\frac{(x_0 - x_n)^2}{2(\sigma_{env})^2}\right) \times \exp\left(-\frac{(x - x_0 - x_n)^2 + (x')^2}{2(\sigma_2^{coh})^2}\right), \quad (C.8)$$

where $\sigma_2^{coh} = \sigma'_{final}$ describes the width of the reduced pure states after decoherence, and

$$\sigma_{env} = \sqrt{(\sigma_0^{coh})^2 - (\sigma_2^{coh})^2} \quad (C.9)$$

is the width of the envelope of the convolution.

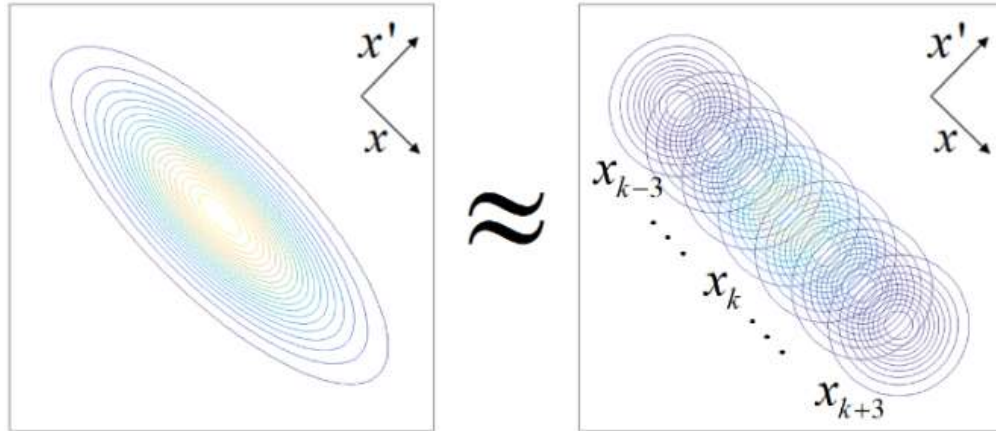


Figure C.3 Deconvolution of a Partial Coherent (Mixed) State by a Series of Coherent (Pure) States.

The initial state is now propagated to the state right after the surface. Next, each wave function corresponding to one of the reduced pure states is acted upon by a grating function (emulating the nanofabricated grating) followed by a Fourier Transform to determine the far field pattern. This is repeated for each of the reduced pure states and the resulting probability distribution patterns give the far field diffraction pattern (Figure C.4 bottom right). It is from this final pattern that a transverse coherence width $L_{coh}(y_{detector})$ is computed using $L_{coh} \approx \lambda_{dB} / \theta_{coll} \approx ad / w_{FWHM}$, where a is the periodicity of the grating, w_{FWHM} is the width of the computed diffraction peaks in the far field, and d is the distance between diffraction peaks. It is these values $L_{coh}(y_{detector})$ which produce the theoretical curves in the Figures 4.3 and 4.4.

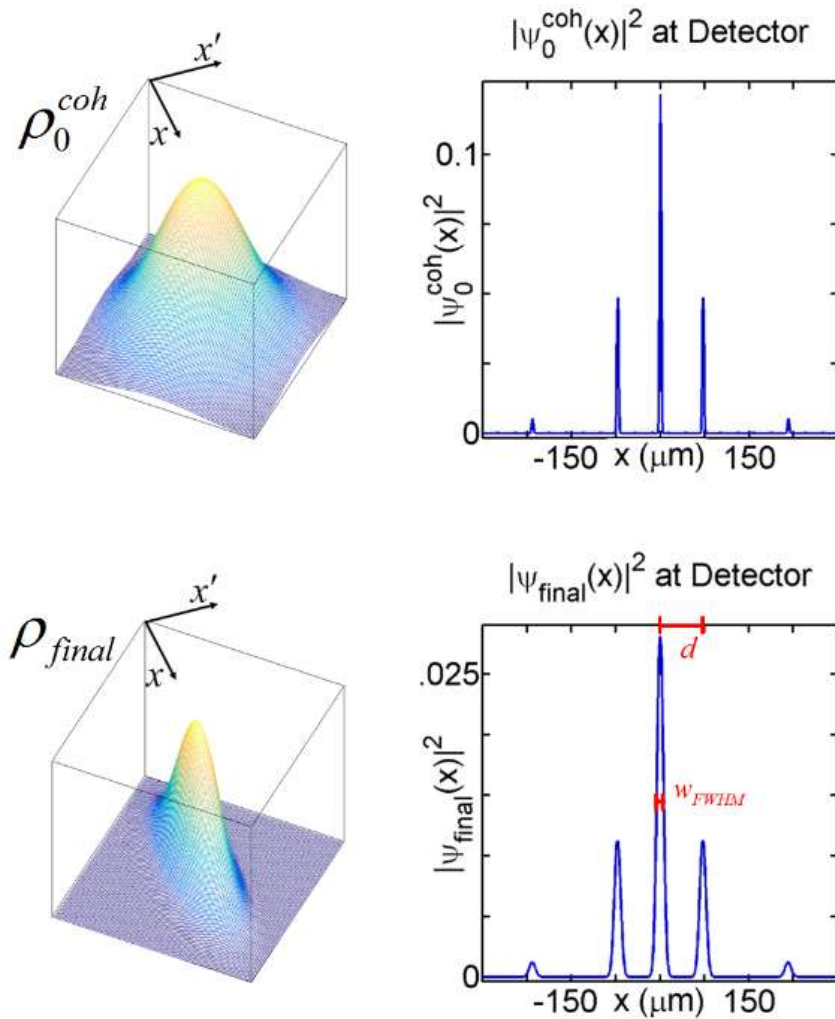


Figure C.4: Reduction of Coherence Elements in the Density Matrix and Corresponding Decrease in Coherence Length. Top Left: Density matrix of a coherent Gaussian electron beam. Top Right: Grating diffraction pattern in the far field after Fourier transformation of coherent state. Bottom Left: Final density matrix after decoherence evolution according to Equation 2. Bottom Right: Grating diffraction pattern in the far field after Fourier transformation of deconvoluted partial coherent state. Notice the stark difference in the widths in the diffraction peaks for the case of the fully coherent case (Top Right) as compared to the partial coherent case (Bottom Right).

C.3 Fortran Code for Classical Beam Propagation and Coherence

Propagation

The following is the Fortran code used to produce the classical vertical electron distributions as the electron passes over a surface and lands on the detector, and the corresponding loss of coherence computation based on the various theoretical models outlined in Chapter 2.6 . See the flowchart below (Figure C.5) and the description of the program outlined in Appendix C.2.

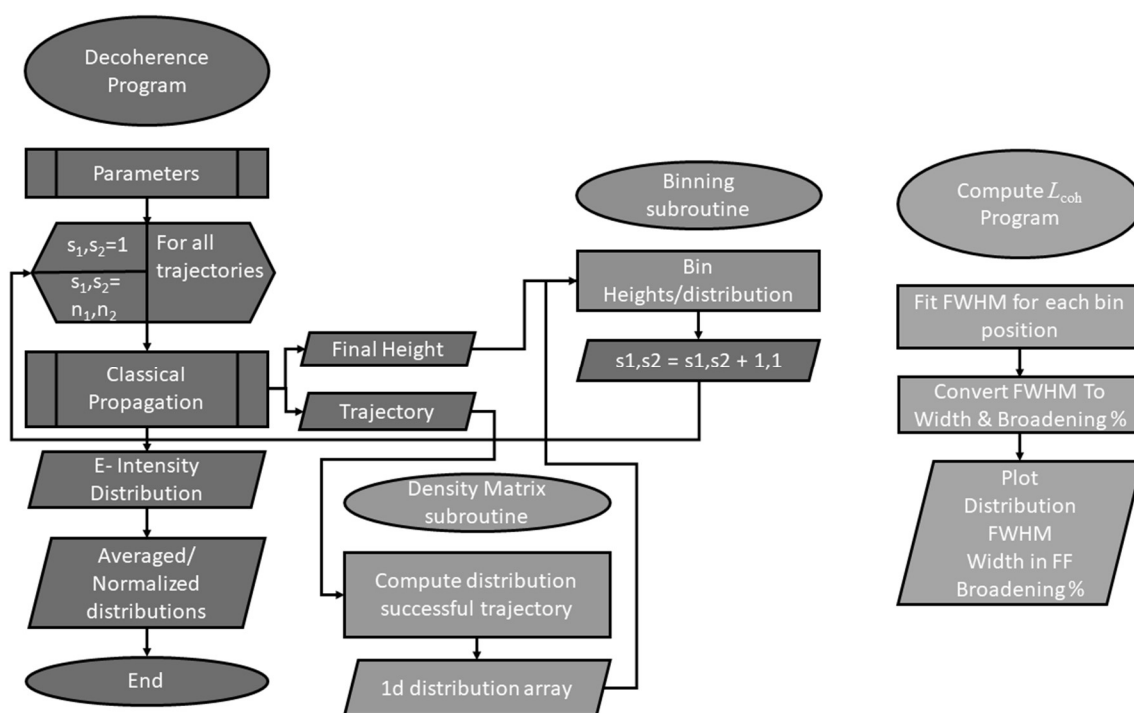


Figure C.5. Flowchart of Fortran Code for Classical Beam Propagation and Coherence Propagation

```

1  #!/bin/sh
2  #SBATCH --ntasks=7
3  #SBATCH --mem-per-cpu=1024
4  #SBATCH --time=01:00:00
5  #SBATCH --job-name=Fortran
6  #SBATCH --error=scheel.%J.err
7  #SBATCH --output=scheel.%J.out
8
9  mpirun ./test.x
10
  
```

```

1  PROGRAM Decoherence
2  !===== MPI =====
3      use mpi
4  !=====
5
6      IMPLICIT NONE
7      common/par/ me,q,k,v0,theta,length
8      real*8 me,q,k,v0,theta,finalheight,trajectory(500)
9      real*8 length
10     real*8 rho_lp5(2001,2001),near_field_x(2001),reduced_diagonal(2001)
11     real ratio
12     integer s1,s2,flag
13     integer counter,succeses
14     integer Nbin
15         integer, parameter :: N = 549
16     parameter(Nbin=1100)
17     real*8 binvalue(Nbin),gratingarray(32)
18     real*8 accum_reduced_diagonal(Nbin,2001)
19     real*8 binlower(Nbin),binupper(Nbin),binposition(Nbin)
20
21 !===== MPI =====
22     integer ind
23     real*8, dimension(:), allocatable :: y_local
24     integer numnodes,myid,rc,ierr,start_local,end_local,N_local
25     real*8 allsum
26
27     character(len=8) :: fmt !format descriptor
28     character(5) x1
29     fmt = '(I5.5)' ! an integer of width 5 with zeros at the left
30
31 !=====
32 !===== MPI =====
33     call mpi_init( ierr )
34     call mpi_comm_rank ( mpi_comm_world, myid, ierr )
35     call mpi_comm_size ( mpi_comm_world, numnodes, ierr )
36
37     write(x1,fmt) myid !converting integer to string using an 'internal file'
38
39     ! OPEN(UNIT=15,FILE='off_diagonal_dist_scheel456'//trim(x1)//'.dat')
40
41
42
43     N_local = N/numnodes
44     ! allocate ( y_local(N_local) )
45
46     ! start_local = N_local*myid + 1 + 732
47     ! end_local = N_local*myid + N_local + 732
48
49     start_local = N_local*myid + 1
50     end_local = N_local*myid + N_local
51
52 !=====
53
54
55
56     OPEN(UNIT=11,FILE='propogation_curvedsurface.dat')
57     OPEN(UNIT=12,FILE='trajectory_curvedsurface.dat')
58     OPEN(UNIT=13,FILE='debug.dat')
59         OPEN(UNIT=15,FILE='off_diagonal_dist_howie456'//trim(x1)//'.dat')
60     OPEN(UNIT=16,FILE='paths_determination.dat')
61     OPEN(UNIT=17,FILE='initial_coherence_distribution.dat')
62
63     call parameters
64     call gratinginitialization(gratingarray)
65     call initialdensitymatrix(rho_lp5,near_field_x)

```

```

66      call
        bininitialization(Nbin,binlower,binupper,binvalue,binposition,accum_reduced_diagonal)
67      call write_rho(rho_lp5,near_field_x)
68
69      counter=0
70      suceses=0
71      !      do s1=1,1901
72      !      do s2=1,1281
73      do s1=1,1901
74      do s2=start_local,end_local
75      call
        propagate(trajectory,finalheight,s1,s2,counter,suceses,flag,gratingarray)
        if (flag.eq.0) then
76
77          call howiedecoherence(trajectory,reduced_diagonal,rho_lp5)
78          !call scheeldecoherence(trajectory,reduced_diagonal,rho_lp5)
79          !call zurekdecoherence(trajectory,reduced_diagonal,rho_lp5)
80          !call machdecoherence(trajectory,reduced_diagonal,rho_lp5)
81          !call hasslebachdecoherence(trajectory,reduced_diagonal,rho_lp5)
82
83          call
84          binning(finalheight,reduced_diagonal,Nbin,binlower,binupper,binvalue,accum_reduced_diagonal,s1,s2)
85
86      endif
87      enddo !end of slit2 do loop
88      enddo !end of slit1 do loop
89      write(6,*) 'total runs= ', counter
90      write(6,*) 'total landing hits= ', suceses
91      !      ratio=suceses*100.0/counter
92      ratio=suceses*100.0/1623398.0
93      write(6,*) 'percent of beam= ', ratio
94      call writeelectrondistribution(binvalue,binposition,Nbin)
95      call writeoffdiagonal(binposition,accum_reduced_diagonal,Nbin)
96      close(11)
97      close(13)
98      close(14)
99      close(15)
100     close(16)
101     close(17)
102
103     !===== MPI
104     call mpi_finalize(rc)
105     !=====
106
107     Stop
108     End Program
109
110
111     !=====
112     !=====
113     !=====
114     !=====
115
116     subroutine parameters
117     implicit none
118     common/par/ me,q,k,v0,theta,length
119     real*8 me,q,k,v0,theta,length

```



```

120
121 me=9.11d-31
122 q=(1.6d-19)*.8425d0
123 k=8.988d9
124 !v0=1.676d7 !corresponds to a .8keV beam
125 v0=2.422d7 !corresponds to a 1.67keV beam
126 length=1.00d-2
127
128
129 return
130 end
131
132
133 subroutine
propagate (trajectory,finalheight,s1,s2,counter,suceses,flag,gratingarray)
implicit none
134
135 real*8 endoftim,delt
136 integer ido,tel,i,s1,s2,flag,counter,j,suceses
137 real*8 fcn,t,tend,tft,y(4)
138 common/par/ me,q,k,v0,theta,length
139 real*8 me,q,k,v0,yprime(4),tfinal
140 real*8 length,surfheight,theta,finalheight
141 real*8 slitlposition,slit2position,cube
142 external fcn,divprk,sset
143 real*8 trajectory(500)!,sucestay(40000,500)
144 real*8 gratingarray(32)
145 real*8 chargeforce,deflection
146
147
148 do i=1,500
149 trajectory(i)=0d0
150 enddo
151
152
153 t=0.0
154 do i=1,4
155 y(i)=0d0
156 enddo
157
158 y(1)=0d0 !initial x coordinate
159
160 counter=counter+1
161 flag=0
162
163 slitlposition=(-9.5d-6)+(s1-1)*(1d-8)
164 slit2position=(-6.4d-6)+(s2-1)*(1d-8)
165
166
167 theta=datan((slit2position-slitlposition)/(25d-2))
168
169 ! deflection=
170 ! surfheight=-.59d-6 !-1d0+dsqrt(1d0+((y(1)-5.0d-4)*(y(1)-5.0d-4)))+3d-6
171 surfheight=-.81d-6
172
173
174 y(1)=0d0
175 y(2)=v0*dcos(theta) !initial x velocity of beam
176 y(3)=slitlposition+(31d-2)*((slit2position-slitlposition)/(25d-2))
177 !initial y coordinate of beam,curved (1.67keV)
178 y(4)=v0*dsin(theta) !initial y velocity of beam
179
180 ! write(11,111) y(3)
181
182 ! do i=1,16
183 ! if (y(3).ge.gratingarray(2*i-1)) then

```

```

184 !   if (y(3).le.gratingarray(2*i)) then
185 !       flag=1
186 !   endif
187 !   endif
188 !   enddo
189
190 !   chargeforce=deflection*me*v0*v0/(length*23.0d-2)
191
192   yprime(1)=y(2)   !y(1)=x, y(2)=vx
193   yprime(2)=0d0
194   yprime(3)=y(4)   !y(3)=y, y(4)=vy
195   yprime(4)=-k*q*q/(4*(y(3)+surfheight)*(y(3)+surfheight)*me)
196
197
198
199
200   ido=1
201   tel=0
202   tft=0.0d0
203   endoftim=length/v0
204
205   if (s1.eq.1) then
206   if (s2.eq.1) then
207       write(6,*) 'initial=', surfheight
208   endif
209   endif
210
211   delt=endoftim/500d0
212   do i=1,500
213
214       tft=tft+endoftim/500d0
215       tend=tft
216
217       y(1)=y(1)+(y(2)*delt)
218       !y(2)=y(2)
219       y(3)=y(3)+(y(4)*delt)
220       y(4)=y(4)+(yprime(4)*delt)
221       yprime(4)=-k*q*q/(4*(y(3)+surfheight)*(y(3)+surfheight)*me)
222       surfheight=-.81d-6 !+(4*3.33333d-6)*(tft/endoftim)
223       trajectory(i)=y(3)+surfheight
224       if (y(3)+surfheight.le.5d-8) then
225           flag=1
226       endif
227   enddo
228   if (s1.eq.1) then
229   if (s2.eq.1) then
230       write(6,*) 'final=', surfheight
231   endif
232   endif
233   !travel another 23cm, free propogation
234
235   tfinal=(23d-2)/v0
236
237   y(1)=y(1)+(y(2)*tfinal)
238   y(3)=y(3)+(y(4)*tfinal)
239
240   if (flag.eq.0) then
241
242   !   write(11,111) y(3)
243   !   finalheight=y(3)
244   !   suceseses=suceseses+1
245   !       do i=1,500
246   !           write(12,112) trajectory(i)
247   !       enddo
248   endif

```

```

249
250 ! write (*,'(A,2x,I5)') '+ Number= ', counter
251
252 !write(6,*) counter
253
254 ! write(6,*) 'finished loop'
255 ! write(6,*) 'total runs= ', counter
256 ! write(6,*) 'total landing hits= ', suceses
257 ! ratio=suceses*100.0/counter
258 ! write(6,*) 'percent of beam= ', ratio
259
260
261
262
263 format(1E15.8)
264 format(1E15.8)
265 format(3E15.8,1I12.6)
266 return
267 end
268
269 !-----
270
271 subroutine initialdensitymatrix(rho_lp5,near_field_x)
272 implicit none
273
274
275 real*8 rho_1(2001,2001),b,x,y,near_field_x(2001)
276 real*8 rho_lp5(2001,2001),fwhmlp67,beta,w,sigma
277 integer i,j
278
279 do i=1,2001
280 do j=1,2001
281 rho_1(i,j)=0d0
282 rho_lp5(i,j)=0d0
283 enddo
284 enddo
285
286 w=2.2745d0*dsqrt(2d0)
287 sigma=w/(2d0*dsqrt(2d0*dlog(2d0)))
288
289 b=1/(2d0*(sigma**2))
290
291 do i=1,2001
292 do j=1,2001
293 x=i*10d0/2000d0
294 y=j*10d0/2000d0
295 rho_1(i,j)=dexp(-b*((x-5.005)**2+(y-5.005)**2))
296 enddo
297 enddo
298
299 do i=1,2001
300 near_field_x(i)=-5d0+(i-1)*.005d0
301 enddo
302
303
304 fwhmlp67=215.44d0
305 beta=fwhmlp67/(2d0*dsqrt(dlog(2d0)))
306
307 do i=1,2001
308 do j=1,2001
309 rho_lp5(i,j)=rho_1(i,j)*exp(-((i-j)/beta)**2)
310 enddo
311 enddo
312
313

```

```

314 return
315 end
316
317 !-----
318 subroutine howiedecoherence(trajectory,reduced_diagonal,rho_lp5)
319 implicit none
320
321 real*8 trajectory(500),reduced_diagonal(2001),rho_lp5(2001,2001)
322 common/par/ me,q,k,v0,theta,length
323 real*8 me,q,k,v0,theta,length
324 real*8 delt
325 integer i,j,m
326 real*8 Pi,hbar,h,kbolt,delx
327 real*8 resistivity,resistivitygold,resistivitisilicon
328 real*8 conductivity
329 real*8 inversezurektime,P,numerator,coefficient,expintegral
330 real*8 A,B,howie,nu
331 real*8 omegam
332
333 omegam=.6d12 !for semiconductors
334
335 delt=length/v0/500d0 !assuming 500 steps (see propogation)
336 resistivitygold=2.2d-8
337 resistivitisilicon=.01d0
338 resistivity=resistivitisilicon !parameter
339 conductivity=1/resistivity
340 hbar=1.05457d-34
341 Pi=3.14159265d0
342 kbolt=1.38065d-23
343 h=hbar*2.0d0*Pi
344
345 coefficient=(q*q*length*omegam*omegam)/(4.0d0*Pi*Pi*hbar*conductivity*v0*v0)
346
347
348 do i=1,2001
349 reduced_diagonal(i)=0d0
350 enddo
351
352 do m=1,1
353 do i=890,1112 !it is unnecessary to calculate the change at the tails, suff small
354 j=2002-i
355 delx=abs((i*(5d-6)/1000d0)-(j*(5d-6)/1000d0))
356 if(delx == 0.0d0) then
357 P=0.0d0
358 endif
359 if(delx /= 0.0d0) then
360 nu=trajectory(m)/(4.0d0*delx)
361 A=dlog(.65d0+(0.56146d0/nu))*(1+nu)
362 B=(nu**4)*exp(7.7d0*nu)*(2.0d0+nu)**(3.7)
363 expintegral=(A**(-7.7))+B)**(-.13)
364 P=coefficient*expintegral
365 endif
366 howie=dexp(-P/500d0)
367 reduced_diagonal(i)=rho_lp5(i,j)*howie
368 enddo
369 enddo
370
371 do m=2,500
372 do i=890,1112 !it is unnecessary to calculate the change at the tails, suff small
373 j=2002-i
374 delx=abs((i*(5d-6)/1000d0)-(j*(5d-6)/1000d0))
375 if(delx == 0.0d0) then
376 P=0.0d0
377 endif
378 if(delx /= 0.0d0) then

```

```

379         nu=trajectory(m)/(4.0d0*delx)
380         A=dlog(.65d0+(0.56146d0/nu))*(1+nu)
381         B=(nu**4)*exp(7.7d0*nu)*(2.0d0+nu)**(3.7)
382         expintegral=(A**(-7.7))+B)**(-.13)
383         P=coefficient*expintegral
384     endif
385
386         howie=dexp(-P/500d0)
387         reduced_diagonal(i)=reduced_diagonal(i)*howie
388     enddo
389 enddo
390
391
392 return
393 end
394 !-----
395 !-----
396 subroutine hasslebachdecoherence(trajectory,reduced_diagonal,rho_lp5)
397 implicit none
398
399 real*8 trajectory(500),reduced_diagonal(2001),rho_lp5(2001,2001)
400 common/par/ me,q,k,v0,theta,length
401 real*8 me,q,k,v0,theta,length
402 real*8 delt,b,a
403 integer i,j,m
404 real*8 Pi,hbar,h,kbolt,Tkelvin
405 real*8 resistivity,resistivitygold,resistivitysilicon
406 real*8 inversehasstime,hassexp,numerator
407
408 delt=length/v0/500d0 !assuming 500 steps (see propogation)
409
410 a=(10.9d0-5.8d0)*(1d-6)/(500d0)
411
412
413 do i=1,2001
414     reduced_diagonal(i)=0d0
415 enddo
416
417 do m=1,1
418     do i=890,1112 !it is unnecessary to calculate the change at the tails, suff small
419         j=2002-i
420         b=a*((i*(5d-6)/1000d0)-(j*(5d-6)/1000d0))**2
421         hassexp=dexp(-b/(trajectory(m)**3))
422         reduced_diagonal(i)=rho_lp5(i,j)*hassexp
423     enddo
424 enddo
425
426 do m=2,500
427     do i=890,1112 !it is unnecessary to calculate the change at the tails, suff small
428         j=2002-i
429         b=a*((i*(5d-6)/1000d0)-(j*(5d-6)/1000d0))**2
430         hassexp=dexp(-b/(trajectory(m)**3))
431         reduced_diagonal(i)=reduced_diagonal(i)*hassexp
432     enddo
433 enddo
434
435
436 return
437 end
438 !-----
439 !-----
440 subroutine scheidcoherence(trajectory,reduced_diagonal,rho_lp5)
441 implicit none

```

```

442
443 real*8 trajectory(500),reduced_diagonal(2001),rho_lp5(2001,2001)
444 common/par/ me,q,k,v0,theta,length
445 real*8 me,q,k,v0,theta,length
446 real*8 delt
447 integer i,j,m
448 real*8 Pi,hbar,h,kbolt,Tkelvin,epsnot
449 real*8 resistivity,resistivitygold,resistivitysilicon
450 real*8 coefficient,gamma,scheel,bracket,xsquared
451 real*8 rprimerot
452
453 delt=length/v0/500d0 !assuming 500 steps (see propogation)
454 resistivitygold=2.2d-8
455 resistivitysilicon=.01d0
456 resistivity=resistivitysilicon !parameter
457 hbar=1.05457d-34
458 Pi=3.14159265d0
459 kbolt=1.38065d-23
460 Tkelvin=300.0d0
461 h=hbar*2.0d0*Pi
462 epsnot=8.85d-12
463
464
465 rprimerot=(2.0d0*epsnot)*resistivity
466
467 coefficient=(q*q*kbolt*Tkelvin*rprimerot)/(2.0d0*Pi*epsnot*hbar*hbar)
468
469
470 do i=1,2001
471   reduced_diagonal(i)=0d0
472 enddo
473
474 do m=1,1
475   do i=890,1112 !it is unnecessary to calculate the change at the tails, suff small
476     j=2002-i
477     xsquared=((i*(5d-6)/1000d0)-(j*(5d-6)/1000d0))**2
478     bracket=(1/(2.0d0*trajectory(m)))-1/sqrt((4.0d0*trajectory(m)**2)+xsquared)
479     gamma=-delt*coefficient*bracket
480     scheel=dexp(gamma)
481     reduced_diagonal(i)=rho_lp5(i,j)*scheel
482   enddo
483 enddo
484
485 do m=2,500
486   do i=890,1112 !it is unnecessary to calculate the change at the tails, suff small
487     j=2002-i
488     xsquared=((i*(5d-6)/1000d0)-(j*(5d-6)/1000d0))**2
489     bracket=(1/(2.0d0*trajectory(m)))-1/sqrt((4.0d0*trajectory(m)**2)+xsquared)
490     gamma=-delt*coefficient*bracket
491     scheel=dexp(gamma)
492     reduced_diagonal(i)=reduced_diagonal(i)*scheel
493   enddo
494 enddo
495
496
497 return
498 end
499
500 !-----
501 subroutine zurekdecoherence(trajectory,reduced_diagonal,rho_lp5)
502 implicit none
503
504 real*8 trajectory(500),reduced_diagonal(2001),rho_lp5(2001,2001)
505 common/par/ me,q,k,v0,theta,length

```

```

506 real*8 me,q,k,v0,theta,length
507 real*8 delt
508 integer i,j,m
509 real*8 Pi,hbar,h,kbolt,Tkelvin
510 real*8 resistivity,resistivitygold,resistivitysilicon
511 real*8 inversezurektime,zurek,numerator
512
513 delt=length/v0/500d0 !assuming 500 steps (see propogation)
514 resistivitygold=2.2d-8
515 resistivitysilicon=.01d0
516 resistivity=resistivitysilicon !parameter
517 hbar=1.05457d-34
518 Pi=3.14159265d0
519 kbolt=1.38065d-23
520 Tkelvin=300.0d0
521 h=hbar*2.0d0*Pi
522
523 do i=1,2001
524     reduced_diagonal(i)=0d0
525 enddo
526
527 do m=1,1
528     do i=890,1112 !it is unnecessary to calculate the change at the tails, suff small
529         j=2002-i
530
531         numerator=(Pi*(q**2)*kbolt*Tkelvin*resistivity*((i*(5d-6)/1000d0)-(j*(5d-6)/1000d0))**2)
532         inversezurektime=numerator/((4d0*h**2)*(trajectory(m)**3))
533         zurek=dexp(-delt*inversezurektime)
534         reduced_diagonal(i)=rho_lp5(i,j)*zurek
535     enddo
536 enddo
537
538 do m=2,500
539     do i=890,1112 !it is unnecessary to calculate the change at the tails, suff small
540         j=2002-i
541
542         numerator=(Pi*(q**2)*kbolt*Tkelvin*resistivity*((i*(5d-6)/1000d0)-(j*(5d-6)/1000d0))**2)
543         inversezurektime=numerator/((4d0*h**2)*(trajectory(m)**3))
544         zurek=dexp(-delt*inversezurektime)
545         reduced_diagonal(i)=reduced_diagonal(i)*zurek
546     enddo
547 enddo
548
549 return
550 end
551 !-----
552 !-----
553
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566 delt=length/v0/500d0 !assuming 500 steps (see propogation)
567 resistivitygold=2.2d-8
568 resistivitysilicon=.01d0
569 resistivity=resistivitysilicon !parameter
570 hbar=1.05457d-34
571 Pi=3.14159265d0
572 kbolt=1.38065d-23
573 Tkelvin=300.0d0
574 h=hbar*2.0d0*Pi
575 epsnot=8.85d-12
576 epsi=2.0d0
577 kfermi=1.2d10
578
579 lambdadb=2.0d0*Pi*hbar/dsqrt(2.0d0*me*kbolt*Tkelvin)
580
581 coefficient=(q**2)/(2*Pi*epsnot*epsi*hbar*kfermi)
582
583 do i=1,2001
584   reduced_diagonal(i)=0d0
585 enddo
586
587 do m=1,1
588   do i=890,1112 !it is unnecessary to calculate the change at the tails, suff small
589     j=2002-i
590     xsquared=((i*(5d-6)/1000d0)-(j*(5d-6)/1000d0))**2
591     taur_inverse=coefficient/(trajectory(m)**2)
592     taud_inverse=(Pi/32.0d0)*taur_inverse*xsquared/(lambdadb)**2
593     mach=dexp(-delt*taud_inverse)
594     reduced_diagonal(i)=rho_lp5(i,j)*mach
595   enddo
596 enddo
597
598 do m=2,500
599   do i=890,1112 !it is unnecessary to calculate the change at the tails, suff small
600     j=2002-i
601     xsquared=((i*(5d-6)/1000d0)-(j*(5d-6)/1000d0))**2
602     taur_inverse=coefficient/(trajectory(m)**2)
603     taud_inverse=(Pi/32.0d0)*taur_inverse*xsquared/(lambdadb)**2
604     mach=dexp(-delt*taud_inverse)
605     reduced_diagonal(i)=reduced_diagonal(i)*mach
606   enddo
607 enddo
608
609
610 return
611 end
612 !-----
613
614
615
616 subroutine
bininitialization(Nbin,binlower,binupper,binvalue,binposition,accum_reduced_diagon
al)
617 implicit none
618
619 integer Nbin,i,j
620 real*8 accum_reduced_diagonal(Nbin,2001),binvalue(Nbin)
621 real*8 binlower(Nbin),binupper(Nbin),binposition(Nbin)
622 real*8 lowerbound,binsize
623
624 lowerbound=-6d-4
625 binsize=(6d-4)/1000d0
626
627 do i=1,Nbin

```



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628   binlower(i)=lowerbound+binsize*(i-1)
629   binupper(i)=lowerbound+binsize*i
630   binposition(i)=(binlower(i)+binupper(i))/2.0d0
631   binvalue(i)=0d0
632   enddo
633
634   do i=1,Nbin
635     do j=1,2001
636       accum_reduced_diagonal(i,j)=0d0
637     enddo
638   enddo
639
640   return
641   end
642
643   !-----
644
645   subroutine
binning(finalheight,reduced_diagonal,Nbin,binlower,binupper,binvalue,accum_reduced
_diagonal,s1,s2)
646   implicit none
647
648   integer Nbin,i,j,s1,s2
649   real*8 accum_reduced_diagonal(Nbin,2001)
650   real*8 binlower(Nbin),binupper(Nbin)
651   real*8 lowerbound,binsize,binvalue(Nbin)
652   real*8 reduced_diagonal(2001),finalheight,norm
653   norm=0d0
654
655   do i=1,2001
656     norm=norm+reduced_diagonal(i)
657   enddo
658
659   do i=1,2001
660     reduced_diagonal(i)=reduced_diagonal(i)/norm
661   enddo
662
663   do i=1,Nbin
664     if (binlower(i).le.finalheight) then
665       if (finalheight.le.binupper(i)) then
666         binvalue(i)=binvalue(i)+1d0
667         ! if (binlower(i).ge.-1.82d-5) then
668         ! if (binupper(i).le.1.82d-5) then
669         !   write(16,*) s1,' ',s2
670         !   endif
671         !   endif
672         do j=1,2001
673           accum_reduced_diagonal(i,j)=accum_reduced_diagonal(i,j)+reduced_diagonal(j)
674         enddo
675       endif
676     endif
677   enddo
678
679   return
680   end
681
682   !-----
683
684   subroutine writeelectrondistribution(binvalue,binposition,Nbin)
685   implicit none
686
687   integer Nbin,i
688   real*8 binposition(Nbin),binvalue(Nbin)
689
690   do i=1,Nbin

```

```

691  write(14,114) binposition(i), binvalue(i)
692  enddo
693
694      format(100E16.6E4)
695
696  return
697  end
698
699  !-----
700
701  subroutine writeoffdiagonal(binposition,accum_reduced_diagonal,Nbin)
702  implicit none
703
704  integer Nbin,i,j
705  real*8 binposition(Nbin),accum_reduced_diagonal(Nbin,2001)
706
707  do i=1,Nbin
708      do j=890,1112
709          write(15,115) binposition(i), accum_reduced_diagonal(i,j)
710      enddo
711  enddo
712
713      format(100E16.6E4)
714
715  return
716  end
717
718  !-----
719
720  subroutine gratinginitialization(gratingarray)
721  implicit none
722
723  real*8 gratingarray(32),offset
724  integer i
725  offset=(-11d-6)+.5d-6
726
727
728  do i=1,31,2
729      gratingarray(i)=(.75d-6)*(i-1)+offset
730  enddo
731
732  do i=2,32,2
733      gratingarray(i)=(.75d-6)*(i-2)+.5d-6+offset
734  enddo
735
736  do i=1,32
737      write(6,*) gratingarray(i)
738  enddo
739
740  return
741  end
742
743  !-----
744
745
746  subroutine write_rho(rho_lp5,near_field_x)
747  implicit none
748
749  real*8 rho_lp5(2001,2001),near_field_x(2001)
750  integer i,j
751
752  do i=1,2001
753      j=2002-i
754      write(17,117) near_field_x(i),rho_lp5(i,j)
755  enddo

```

```
756
757
758     format(100E16.6E4)
759
760 return
761 end
762
```

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- [2] H.-P. Breuer and F. Petruccione, in *Theory Open Quantum Syst.* (Oxford University Press, 2002), pp. 232–242.

APPENDIX D

SURFACES & GRATING; MOUNT DESIGN AND PREP

D.1 Summary

The following outlines details of the surface and grating mounts used to control the two, as well as the surface preparation needed to minimize sources of dephasing and other contamination in the experiment.

D.2 Surface and Grating Mounts

This experiment underwent two iterations of surface/grating mounts. Both are made primarily of aluminum to minimize the introduction of local magnetic fields.

The first was a monolithic, compact design that was top-loaded into the system (see Figures D.1-D.3). The free-standing grating sat on a lip which extended out by 1mm and whose top was gently held from falling over by a bronze clamp (as well as a ground channel to reduce charging of the grating bars). A large circular hole allows electrons to travel through the grating. The surface itself was separated by 2mm from the grating and held upside-down by two small aluminum clamps. Outside the vacuum chamber the feedthrough was supported by a translational stage which was used to control the height of the surface with respect to the electron beam, as well as a 2-D wobble mount, which provided control over the angle of the surface.

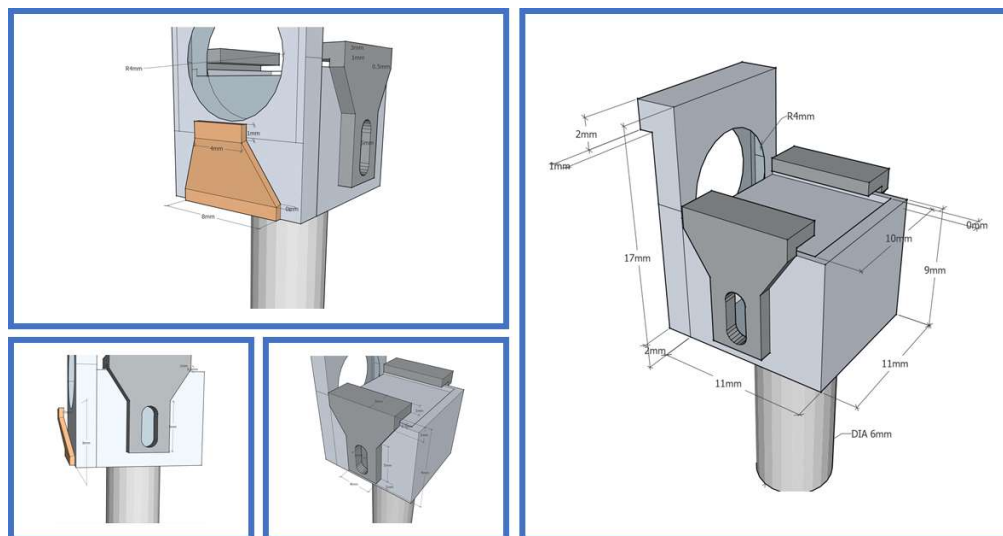


Figure D.1: Schematic of First Surface/Grating Mount



Figure D.2: Preparation Image of Gold Surface and Grating in Mount. Left: View of nanofabricated grating. Right: View of entire feedthrough (without the external translation stage and wobble mount)

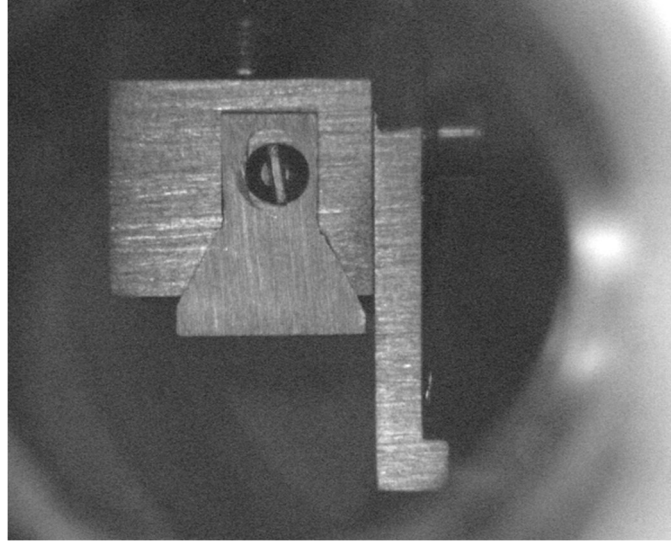


Figure D.3: In-Vacuum Image of Surface/Grating Mount.

Later, two new mounts were designed to hold the grating and slit independently (designed by Liyun Zhang). These mounts were held with separate feedthroughs that are loaded horizontally with respect to the ground. The Grating Mount is similar in functionality as the grating had in the first design, except that its angle is held fixed and it has the ability to translate two directions: in the x-transverse direction with respect to the electron beam (and perpendicular to the direction the grating bars), and in the z-direction along the path of the electron beam. This allows for more control of the distance between the grating and the surface, as well as sampling of multiple portions of the surface.

The surface mount is also horizontally loaded with the surface sitting on top. The surface is glued down with a small drop of Silver paste (using a precision pipet). A small link of silver paste is also used to connect the top of the surface (at its edge) to the mount for grounding purposes. Outside the vacuum system the mount is also supported by a two-dimensional translation stage (in the y-direction to control the height, and the x-direction to sample different portions of the surface). Also, the angular pitch is controlled

by a connected rotational stage. This rotational stage has the advantage of rotating in only one direction (not axial to the beamline as the previous wobble mount) and it is micrometer rotational control allowing for more precise adjustment of the pitch.

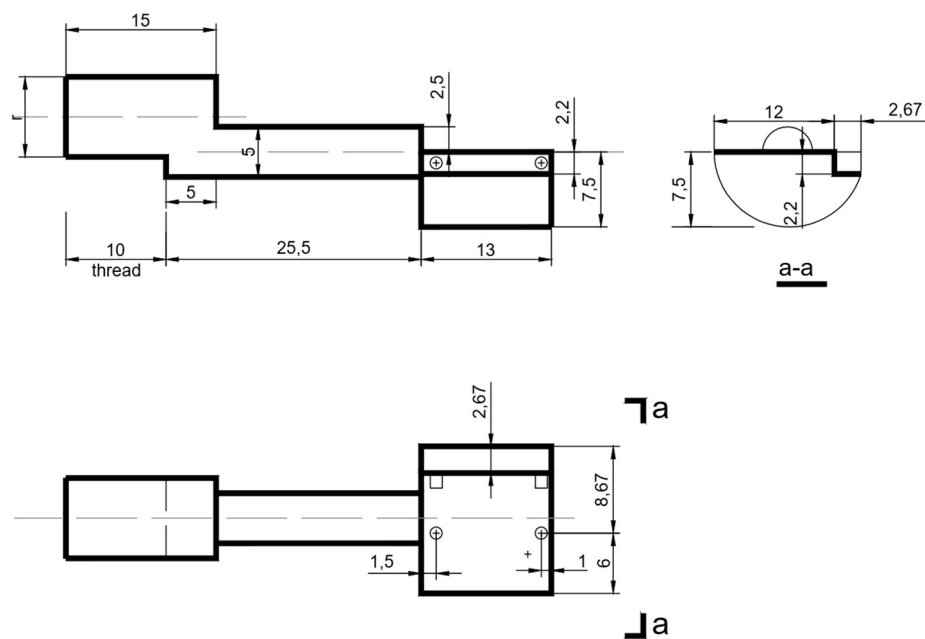


Figure D.4: Second Mount Schematic of Surface. Courtesy of Liyun Zhang. Labeled numbers are in millimeters

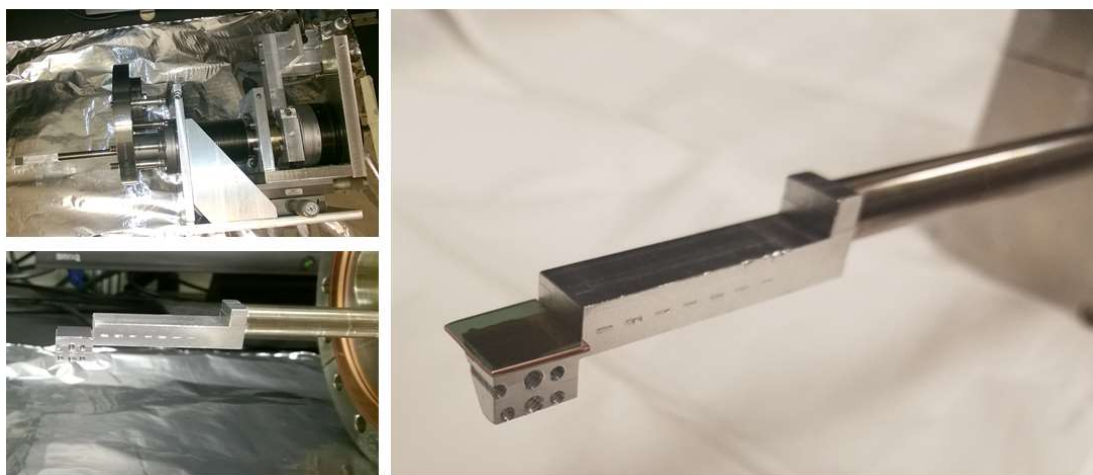


Figure D.5: Out of Chamber Images of Surface Mount. Top Left: Top view of combined image of surface mount, feedthrough, and translational/rotation stage. Bottom Left: Side view of surface mount. Right: Zoomed image of mount and surface.

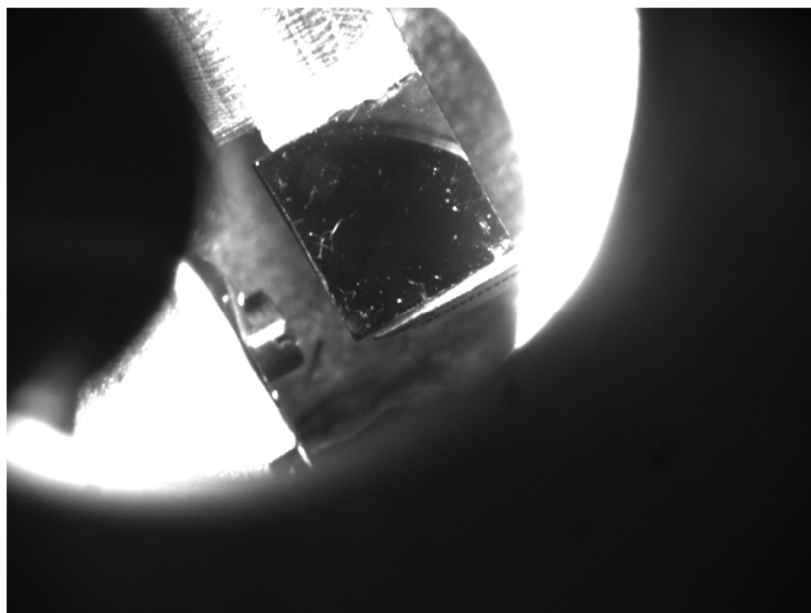


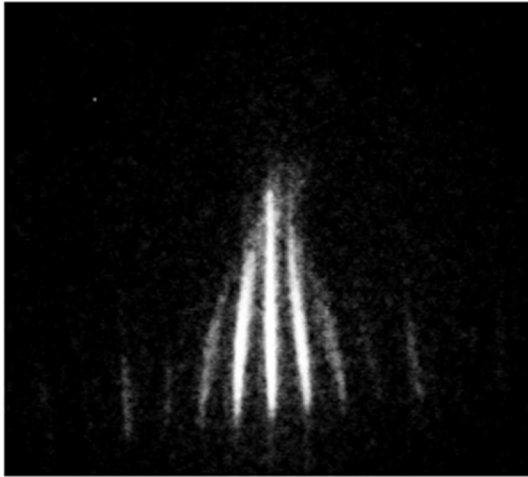
Figure D.6: Top View of Surface Mount and Grating Mount

Other advantages of this upgrade includes, being able to modify the surface or the grating outside of the vacuum system without exposing the other to the elements outside, and independent observation of the electron beams interaction with the grating, the surface, and combined.

D.3 Surface Preparation

Great care needs to be taken to ensure that the surface remains clean of dust or other contaminants. The effects of dust can be observed in the diffraction pattern and reduce contrast, lowering the sensitivity of our experiment. These dust particles tend to charge up and thus deflect the electron diffraction distribution, typically in the form of lensing (see Figure D.7).

Large Dust Particle on Surface



Clean Position on Surface

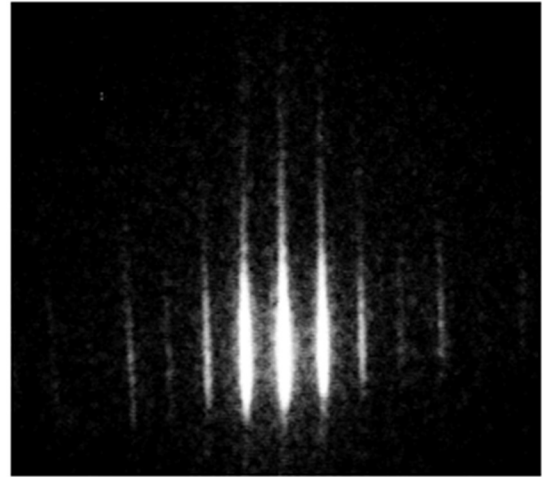


Figure D.7. Effects of Dust on Surface. Left: Diffraction pattern at the detector after interacting with a dust particle on the surface. In such circumstances, deflections (such as lensing) can occur. Right: Clean Position on the surface. No dust or contaminants present result in straight interference fringes in the vertical direction.

After cutting to size (1 cm²) the surface with a boron carbide wafer cutter, the Si surface was cleaned using a version of the industry-standard RCA cleaning method (without the oxide strip), to remove dust or other contaminants [1]. Specifically, the cleaning procedure that was underwent is as follows:

- i. Initial Prep: All glassware is initially cleaned with piranha solution (3:1 mixture of sulfuric acid and hydrogen peroxide) to eliminate any initial contaminants introduced during the cleaning process.
- ii. Pre-RCA clean: The silicon surface is first sonicated for 30 minutes in acetone for large contaminants, followed by 30 min in isopropanol to clean off the acetone. The surface is then immediately blow-dried with nitrogen gas. The surface is then submerged in deionized water (and is kept in this state whenever any inaction during the cleaning is taking place)
- iii. RCA clean:
 - a. the first step is used to remove organics and particles. It involves submerging the surface in a solution of deionized water, 29% Ammonium Hydroxide, and 30% Hydrogen peroxide in a volume ratio of 5:1:1. These solutions were mixed and

measured using disposable glass pipets and each part was allowed its own Pipet straw. The surface was held here for 10 minutes at approximately 80 degrees Celsius on a hotplate. Upon taking the surface out of the solution it was immediately rinsed with a squeeze bottle of deionized water and then submerged into deionized water

- b. The second step, which usually involves removal of an oxide layer via hydrofluoric acid, was skipped.
 - c. The third step is used to remove ions. It involves transferring the surface from the deionized water where it was last left to a solution of deionized water, 37% hydrochloric acid, and 30% hydrogen peroxide in a volume ratio of 6:1:1 at approximately 80 degrees Celsius for 10 minutes.
- iv. Post RCA clean: the surface was taken out with a tweezer and immediately rinsed with deionized water and blow-dried with nitrogen gas. It was then placed in a cleaned dry sample container for immediate transfer to installation into the vacuum chamber (taking roughly 45 minutes until the chamber was closed and began pumping down).

The uncoated gold mirror was immediately installed into the vacuum system upon unpackaging to minimize exposure. In both cases, contaminants were successfully eliminated.

Dirty Samples

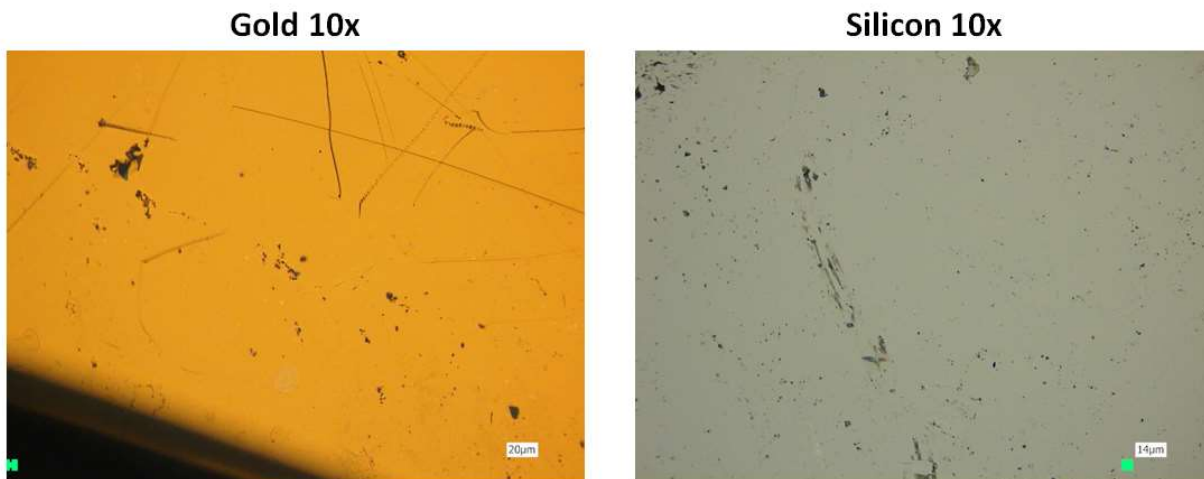


Figure D.8: Uncleaned Silicon and Gold Samples. Not appropriately cleaning the sample results in distortion of diffraction pattern as in Figure 4.9 left.

Cleaned Sample

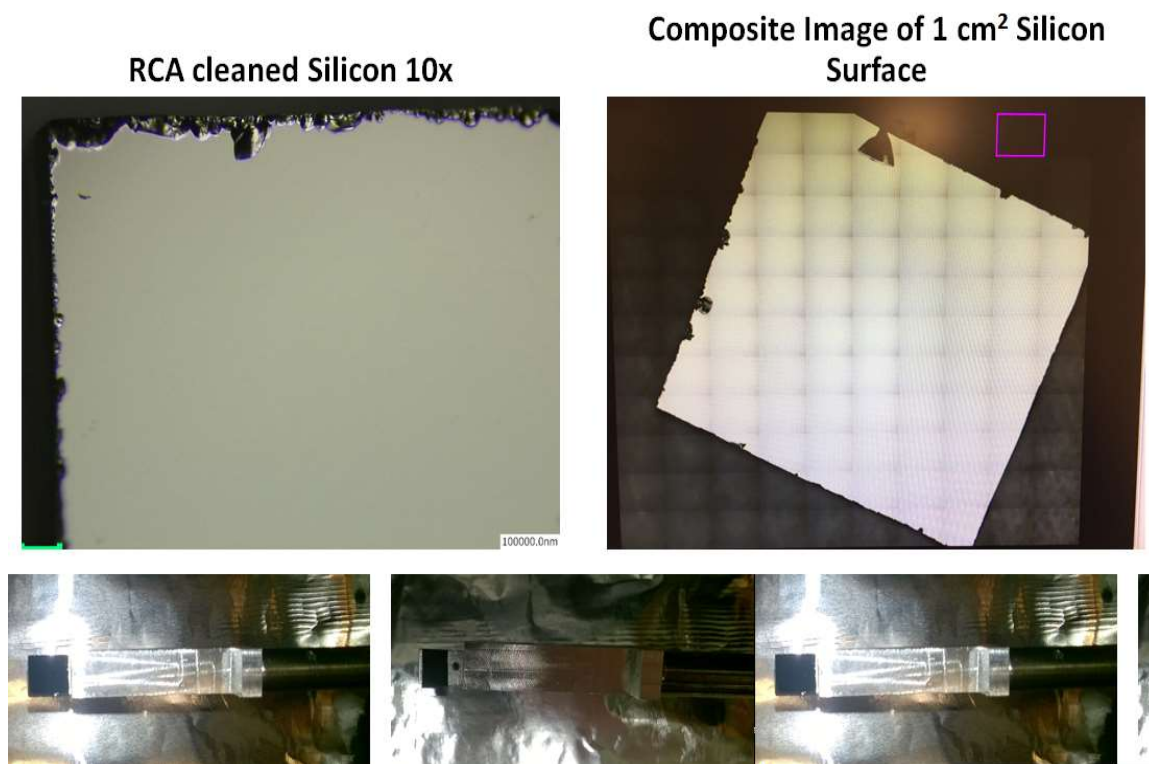


Figure D.9: Image of RCA cleaned Si Surfaces. Top Left: Optical Laser Microscope Image of 10x magnification of corner of Si Surface 1. Top Right Composite image of 1 cm^2 silicon surface. Bottom Left: Out of vacuum chamber image of Si surface 1. Bottom Right: Out of vacuum chamber image of Si surface 2.

D.4 Pitch Alignment

To measure the relative pitch of the surface, a small HeNe laser was mounted on top of the rotational stage. The laser would cast a spot on the wall with 1 mm square Cartesian graph paper 3.3 m away. As the stage rotated, the laser spot moved vertically on the wall. The precision of the laser spot vertically on the graph paper was approximately .5 mm. thus the angular pitch with respect to the beamline can be adjusted with a precision of approx. 0.2 mrad.

This pitch of the surface is adjusted to maximize the electron beam's deflection due to image charge attraction. In practice, what this means is the diffraction pattern was imaged at many pitch angles (near the optimum at steps of ≈ 0.2 mrad) all such that the beam current is 1/3 the original beam current (without the surface). Then the angle in which the image charge most deflects the beam is chosen as the one to be analyzed.

D.5 Effects of Lensing

As is elaborated upon in Chapter 5, a loss of contrast does not imply that decoherence has occurred, as dephasing is also possible cause. Here we will give attention to one form of dephasing: lensing, particularly a simple lens. Suppose a spatial charge distribution is formed on the surface such that the diffraction electron beams are broadened (or focused). This is a reasonable supposition, as the effects of dust particles or other contaminants appear to affect the diffraction pattern in this way (see figure 4.8). It should also be noted that the periodicity of the diffraction peaks also changed in this observation, which is what gave us the suspicion that lensing was occurring in the first place. Indeed, placing a convex lens after a grating can cause simultaneous focusing of the periodicity of the diffraction peaks and an increase in the width of the diffraction peaks.

In the experimental diffraction images for the case of silicon, (figure 4.3 and figure D.10) even after cleaning there is a noticeable amount of reduction in the diffraction peak to peak distance along with broadening. Therefore, it is critical to investigate whether a grating-simple lens model can simultaneously predict both observations in a quantifiable way.

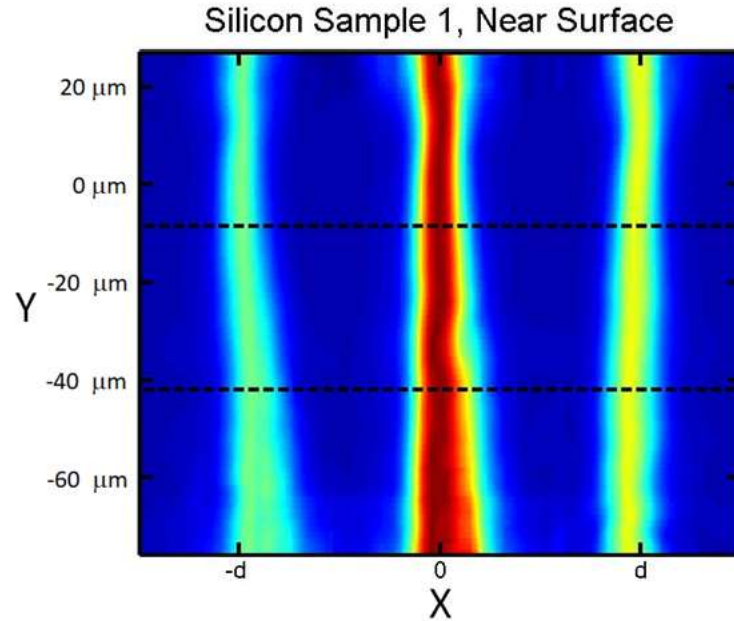


Figure D.10. Diffractogram Image for the case of Silicon

Sketched in Figure D.11 is a combined ray & beam diagram representing the effects of the diffraction beams undergoing diffraction from a grating (G) due to a lens (L). the lens and the grating are separated by a distance $z_3 = .3 \text{ cm} \rightarrow 1.3 \text{ cm}$. From the lens, the distance between the lens to the detection screen (Det.) is $z_4 = Z - z_3$, where $Z = 24 \text{ cm}$ is the distance from the grating to the detector. Without a lens, the observed diffraction peak periodicity is d and the diffraction peaks have a width of w . With a lens that has a focal length of f , the observed diffraction peak periodicity is d' and the diffraction peaks have a width of w' . Starting from a measured difference in peak periodicity from d to d' and treating the diffraction beams as rays, basic optics formulas will be used to calculate the lens's focal length, and then treating the diffraction beams as Gaussian beams, beam optics formulas are used to calculate what the new diffraction peak's width w' would be.

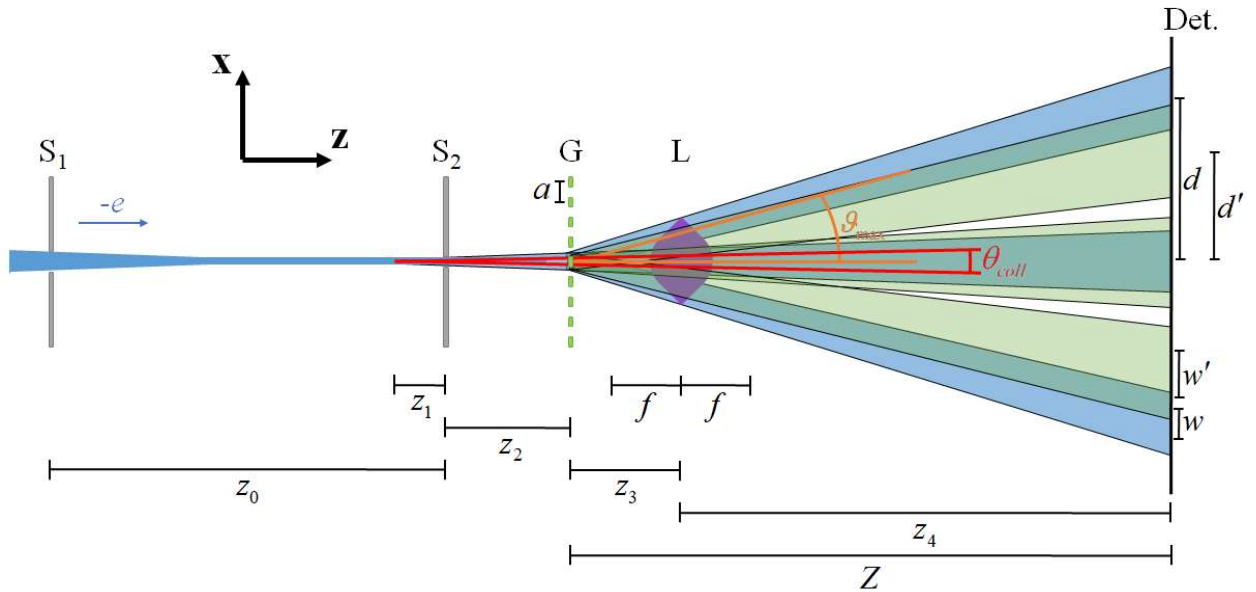


Figure D.11. Collimated Grating-Lens System. sketched is an electron beam (blue) collimated by two slits (S_1 and S_2) that undergoes diffraction through a grating (G) and further propagates to the detection screen (Det.). Without no lens (L) with focal length (f) present, the resulting diffraction pattern at the detection screen has a peak periodicity of d and a FWHM of w . When a lens is present, the diffraction beams (light green) alter in their divergence and land at new positions on the detector. This final pattern has a peak periodicity of d' and the peaks have a FWHM of w' .

The important basic optics formula to start with is based on the exit equation of a ray from a lens of focal length f . two central assumptions are made. The first assumption is that the position along the x -direction in which the ray enters the lens (define as x) is equal to the position in which the ray leaves the lens (this is the “thin lens approximation”). The second assumption is that the change in the slope $\Delta m = m_2 - m_1$ of a ray from entering the lens with slope m_1 to exiting the lens with slope m_2 , is proportional to the distance away from the central axis of the lens (i.e. $\Delta m = ax$, where a is the proportionality constant).

From this, the first order diffraction ray starting at a central point at the grating will pass through the lens and will land on the detector at a height d' with respect to the central axis according to (equation 1.7 in [2]),

$$d' = \left[z_3 + z_4 \left(1 - \frac{z_3}{f} \right) \right] m_1. \quad (\text{D.1})$$

The entrance slope m_1 can be calculated from the diffraction angle using the diffraction equation,

$$m_1 = \tan(\theta_{coll}) \approx \sin(\theta_{coll}) = \lambda_{dB}/a, \quad (\text{D.2})$$

where a is the periodicity of the grating. Rearranging equation D.2 in terms of the focal length yields

$$f = z_3 \left[1 - \frac{1}{z_4} \left(\frac{ad'}{\lambda_{dB}} - z_3 \right) \right]^{-1}. \quad (\text{D.3})$$

Note that it can be seen through this equation that although a focal length can be either positive or negative, it can only have one solution for a given set of parameters.

It can now be inferred what kind of peak broadening would come for a particular focal length. The primary equations used are the beam optics lens equations 3.2-5 through 3.2-9a from [3]. After passing through the lens, the new divergence angle is proportional to the old divergence angle by

$$\theta_{coll}' = \theta_{coll}/M, \quad (\text{D.4})$$

where the magnification is written in terms of the parameters $r^{beam} = z_{not}^{beam}/(z_{beam} - f)$

and $M_r^{beam} = |f/(z_{beam} - f)|$,

$$M = \frac{M_r^{beam}}{\sqrt{1 + r^2}}. \quad (\text{D.5})$$

Here $z_{beam} \equiv z_1 + z_2 + z_3$ is the distance between the initial waist position (before the second slit) and the lens, and $z_{not}^{beam} = W_0/\theta_{coll}$ is the initial depth of beam's focus (i.e. the

Raleigh length) with waist W_0 . With an initial, unfocused divergence angle of

$\theta_{coll} = 33 \mu\text{rad}$, the distance from the second slit to the beam waist position is determined

to be $z_1 = S_2 / \tan(\theta_{coll}) = 7.57 \text{ cm}$ and the Raleigh length would be

$z_{not}^{beam} \approx 2.5 \mu\text{m} / 33 \mu\text{rad} = 7.57 \text{ m}$. That $z_{not}^{beam} \approx z_1$ is not particularly surprising in light of

Figure 3.1-4 of [3].

Once the new collimation angle is established, the final beam's width can be calculated trigonometrically back from the new waist location due to the lens. This waist location can be found using the equation,

$$z'_{beam} = \left(M^2 (z_{beam} - f) \right) + f . \quad (\text{D.6})$$

And then the final beam's width can be computed as

$$w'(d', z_3) = \tan(\theta_{coll}') \left(z_4 + f - \left(M^2 (z_{beam} - f) \right) \right) . \quad (\text{D.7})$$

As a reminder, f is expressed in terms of d' and z_3 .

Plotted in Figure D.12 are curves of the final FWHM (w') vs peak periodicity (d'), each curve corresponding to a lens with a particular distance to the grating z_3 , and are parameterized by their focal length f . This is compared with the experimentally observed values extracted from the horizontal lineouts for different vertical positions (from figure D.10). The intersection of these curves along with the data corresponds to the width and periodicity with no lens present ($d = 72 \mu\text{m}$ and $w = 13 \mu\text{m}$).

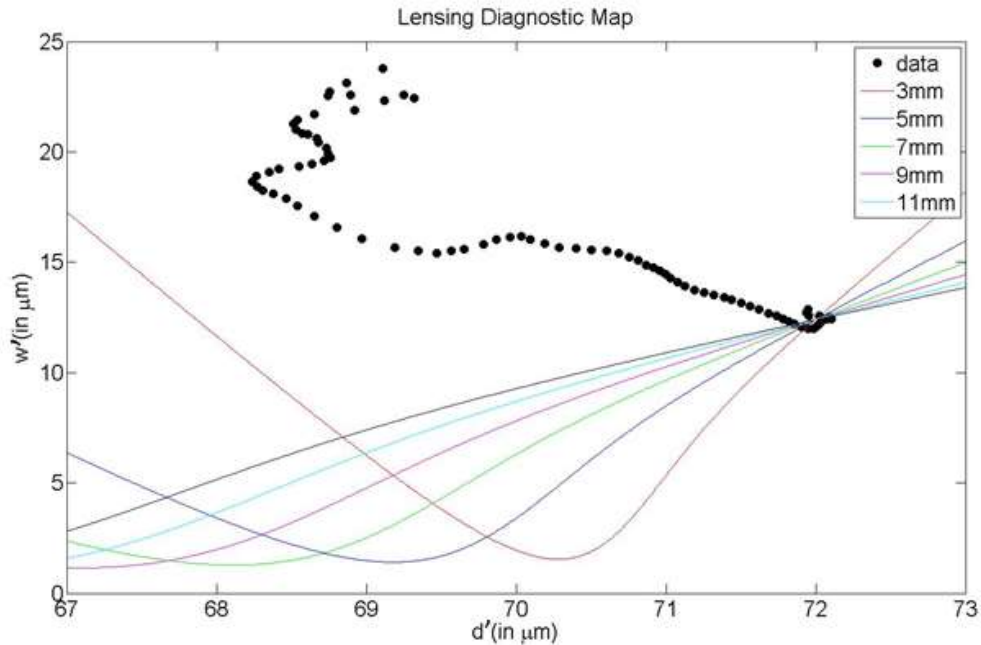


Figure D.12. Lensing Diagnostic Map

If one assumes that different heights to the surface corresponds to different focusing powers (or different focal lengths) it is clear that a simple lens model cannot explain the behavior of the loss of contrast and change in peak periodicity, because the general trend is that there would be a focusing of the peak's widths before a defocusing as the peak to peak distance comes together, as well as these curves generally do not fall in the same general area on this parameter space as the experimental data. It is still possible that the physical reality is well explained by a more complex lens model (such as a multiple lens model). Nevertheless, we can exclude a simple single lens model to explain the general loss of contrast.

D.6 Appendix D Bibliography

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- [2] H. Liebl, in *Appl. Charg. Part. Opt.* (Springer, Berlin, Heidelberg, 2008), pp. 1–3.
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APPENDIX E

PROGRAMS FOR DEPHASING VS DECOHERENCE

The following contains the computations and program while investigating the similarities and differences between dephasing and decoherence as described in Chapter 5.

E.1 Decoherence and Dephasing Path Integral Program Version 1

This is the original version of the decoherence and dephasing path integral code. Stated parameters are based on the experimental setup described in Chapter 4: Decoherence Experiment, where two collimating slits are used, a decoherer is set up separate from the grating. The decoherer contains incoherent summing of random blocks with phase jumps ranging matching that of Section D.1 . The random phase includes random blocks of phase jumps ranging from 0 to $2\pi c$, where $0 \leq c \leq 1$ acts as the variable that changes the contrast. See Chapter 5 section 2 for more details.

The following table (D.1) outlines the set of parameters used in the path integral to test the results of the effects of dephasing/decoherence.

Plane Name	Width	# of Grid-Points	Section Between	Azimuthal Length
Slit 1	12.7 μm	24	Slit 1 & Slit 2	$L_1 = 24 \text{ cm}$
Slit 2	2.5 μm	1500	Slit 2 & Dephaser / Decoherer	$L_2 = 5.5 \text{ cm}$
Dephaser / Decoherer	20 μm	5000	Dephaser / Decoherer & Grating	$L_3 = .5 \text{ cm}$
Grating	15 μm	12000	Grating & Near Field	$L_4 = .5 \text{ cm}$
Near Field	20 μm	1500	Near Field & Far Field	$L_5 = 24 \text{ cm}$
Far Field	60 μm	1500		

Table E.1: Parameters for Path Integral Simulation Setup 1

```

1  PROGRAM Path_Integral_Decoherence
2  !Author:Peter Beierle
3  !Last Revised 10/13/2015
4  implicit none
5
6  integer Nf,Nl, Ng,Ns,Nscr,Ngg,Nd,endrun
7  parameter (Nf=24,Nl=1500,Ng=12000,Ns=1500,Nscr=1500,Nd=5000)
8  parameter (Ngg=5000, endrun=100)
9  integer j,i,inc,k,m,numberofslits,nn,i2,incend,jend
10 integer (2) ihr,imin,isec,i100th,starttime,endtime
11 real programtime
12 real*8 hbar,h,c,position,d,norm,me,Pi,gam,ee ,D0
13 real*8 lambdae,sourcesize,dsource,ve,D2,D3,phaseslope,phaststep
14 real*8 Dsg,Dgg, gndglssize,dgndglss
15 real*8 Energy,kernel,screen3size,dscreen3,lenssize,dlens
16 real*8 dist1,dist2,lngh,image (Ngg)
17 complex*8 kern3(Nl,Ng),kern2(Ng,Ngg),kern(Ngg,Ns),kern0(Ns,1)
18 complex*8 kern4(Nscr,Nl)
19 complex*8 phiin(1),phi2(Nl),amp(Ng),phi0(Ns)
20 complex*8 phigndglss(Ngg)
21 complex*8 cmI,phioutx,imagephase(Ngg)
22 complex*8 phiscreen(Nscr),phil(Ng)
23 real*8 probscreen(Nscr),probscreenmem(Nscr,Nf)
24 real*8 probscreenaverage(Nscr)
25 real*8 probgrating(Ng),probgratingmem(Ng,Nf)
26 real*8 probgratingaverage(Ng),finalprob2(Nl, endrun)
27 real*8 x,prob2(Nl)
28 real*8 dsecondslit,secondslit
29 real*8 phasecurveglobal
30 real*8 dfirstslit,firstslit
31 complex*8 matrix(Nscr,Nscr),finalmatrix(Nscr,Nscr)
32 complex*8 matrix2(Nl,Nl),finalmatrix2(Nl,Nl)
33 complex*8 matrix3(Ns,Ns),finalmatrix3(Ns,Ns)
34 real*8 sigma2(1000),acumphase(1000),positionphase,returnvalue
35 integer runner,runnumber,idum,nnmodnumofpnts
36
37 !for random phase
38 integer Q,p,numofpoints
39 parameter (Q=123456)
40 real*8 dephasingsize,value(1000),sigma(1000)
41 !call rnset(Q)
42
43 dephasingsize=0.7
44 runnumber=1
45
46
47 !do i=1,Nscr
48 ! do j=1,Nscr
49 !   finalmatrix(i,j)=0d0
50 ! enddo
51 !enddo
52
53 !do i=1,Nl
54 ! do j=1,Nl
55 !   finalmatrix2(i,j)=0d0
56 ! enddo
57 !enddo
58
59 !do i=1,Ns
60 ! do j=1,Ns
61 !   finalmatrix3(i,j)=0d0
62 ! enddo
63 !enddo
64
65 open(unit=17,file='phase.dat') !phase written

```

```

66
67
68
69 ee=1.6d-19
70 Pi=3.14159265d0
71 h=6.626d-34
72 hbar=h/2d0/Pi
73 c=3.d8
74 d=100.d-9
75 me=9.11d-31
76 Energy=1670d0*ee+me*c*c
77 !ve=dsqrt(2.*Energy/(.511E6/c**2.)) !non relativistic leftover
78 gam=Energy/(me*c*c)
79 ve=sqrt(1d0-1d0/(gam*gam))*c
80 lambdae=h/(gam*me*ve)
81 write(6,*) "The gamma factor is ",gam
82 write(6,*) "The electron velocity is ",ve
83
84 firstslit=12.7d-6
85 write(6,*) "The first slit is ",firstslit, " wide."
86 secondslit=2.5d-6 !10.22E-6 !14.59E-6
87 write(6,*) "The second slit is ",secondslit, " wide."
88 lenssize=20000d-9
89 gndglssize=20d-6
90 write(6,*) "the ground glass size is ",gndglssize," wide"
91 write(6,*) "The lenssize is ",lenssize, " wide."
92 sourcesize=15000d-9 !YOU NEED TO CHANGE THE NUMBER OF SLITS!
93 write(6,*) "The grating source is ",sourcesize, " wide."
94 screen3size=500d-6
95 write(6,*) "The detection screen is ",screen3size, " wide."
96
97 dfirstslit=firstslit/Nf
98 dsecondslit=secondslit/Ns
99 dlens=lenssize/Nl
100 dsource=sourcesize/Ng
101 dscreen3=screen3size/Nscr
102 dgndglss=gndglssize/Ngg
103 D0=.24d0 !distance from the first slit to the second slit
104 Dsg=.06d0-.005d0 !0.3
105 write(6,*) "The dis from the 2nd slit to ground glass is ",Dsg
106 Dgg=.005d0
107
108 D2=.005d0 !distance at UNL
109 write(6,*) "The distance from the grating to the lens is ",D2
110
111 D3=0.24d0 !distance at UNL 0.231
112 write(6,*) "The distance from the lens to the screen is ",D3
113
114
115 !call gettim(ihr,imin,isec,i100th)
116 !starttime=0.
117 !starttime=ihr*60*60+imin*60+isec
118
119 cmI=(0,1) !the complex number I
120
121
122
123
124 ! The next subroutines sets up the path integral kernels
125 write(6,*) "01"
126 call
127 firstkernelsubroutine(kern,Ngg,Ns,gndglssize,dgndglss,secondslit,dsecondslit,D
sg,lambdae)
call
secondkernelsubroutine(kern2,Ng,Ngg,sourcesize,dsource,gndglssize,dgndglss,Dgg

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```

,lambdae)
128 call
thirdkernalsubroutine (kern3,Nl,Ng,lenssize,dlens,source,dsource,D2,lambdae)
129 call
fourthkernalsubroutine (kern4,Nscr,Nl,screen3size,dscreen3,lenssize,dlens,D3,lambdae)

130
131
132 !           The next subroutine sets up the amplitude at the grating
133 call gratingamplitude (amp,source,dsource,Ng)
134
135
136
137
138 do runnumber=1,endrunc
139 do i=1,Nl
140 finalprob2 (i,runnumber)=0d0
141 enddo
142 enddo
143
144 do runnumber=1,endrunc
145
146 do i=1,200 !value is an array of 100 random numbers from 0 to 1
147 call ran0 (idum,returnvalue)
148 value (i)=returnvalue
149 enddo
150
151
152 numofpoints=25 !should be a factor of 5000
153 p=1
154
155 do k=1,Ngg
156 nn=k
157 image (nn)=dephasingsize*2.0*Pi*value (p)
158 imagephase (nn)=cmI*dsin (image (nn)) +dcos (image (nn))
159 nnmodnumofpnts=MOD (nn,numofpoints)
160 if (nnmodnumofpnts.eq.0) then
161 p=p+1
162 endif
163 enddo
164
165
166
167
168 do k=1,Ngg
169 nn=k
170 x=(gndglsssize/2d0-dgndglss*nn)
171 write (17,*) x, image (k)
172 enddo
173
174
175
176
177 ! -----start of large incoherent loop-----
178 incend=Nf
179
180 do inc=1,incend
181
182 call
zerothkernel (kern0,Ns,firstslit,dfirstslit,inc,secondslit,dsecondslit,D0,lambdae)

183
184 !This routine propogates from the first slit to the second slit
185 call wavefunction1 (Ns,kern0,phi0)
186

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187      !The next routine propagates from the source (second slit) to the gndglss
188      call
      wavefunction2 (phi0,Ngg,Ns,kern,phigndglss,imagephase)

189
190      !The next routine propagates from the gndglss to the grating
191      call wavefunction3 (phigndglss,Ng,Ngg,kern2,phil,amp)
192
193      !The next routine propagates from the grating to the "lens" (just the
      nearfield)
194      call
      wavefunction4 (phil,Nl,Ng,kern3,phi2)
195
196      !The next routine propagates from the lens to the screen
197      call wavefunction5 (phi2,Nscr,Nl,kern4,phiscreen)
198
199
200      !the probability is calculated next
201      call
      probabilitycalculation (phiscreen,probscreen,probscreenmem,prob2,finalprob2,Nscr,
      Nl,runnumber,inc,incend,endrun,phi2)

202
203
204      ! calculation of matrices
205      ! call
      matrixcalculation (phiscreen,phi2,phi0,matrix,finalmatrix,matrix2,finalmatrix2,matr
      ix3,finalmatrix3,Nscr,Nl,Ns)

206
207      enddo !close incoherent loop
208      write(6,*) 'end of runnumber',runnumber
209      enddo !end of runnumber loop
210
211
212
213      ! the incoherent sum at the screen is calculated next
214      call screenincoherentsumming (Nscr,incend,inc,probscreenaverage,probscreenmem)
215
216
217
218
219      ! next write data to file
220      call
      writeprobabilities (Nscr,Nl,screen3size,dscreen3,probscreenaverage,runnumber,endrun
      ,finalprob2)

221
222      !call writematrices (Nscr,Nl,Ns,finalmatrix,finalmatrix2,finalmatrix3)
223
224
225      ! next find runtime
226
227      ! call gettim(ihr,imin,isec,i100th)
228      ! endtime=0.
229      ! endtime=ihr*60*60+imin*60+isec
230
231      ! programtime=(endtime-starttime)/60.
232      ! write(6,*) 'Program run time = ',programtime
233
234      format (E12.6,X,E12.6) !there was a 666 there
235      format (E12.6,X,E12.6)
236
237      END
238
239
240      !-----
241      subroutine

```

```

firstkernalsubroutine (kern,Ngg,Ns,gndglssize,dgndglss,secondslit,dsecondslit,Dsg,
lambdae)
242 implicit none
243 integer i,j,Ngg,Ns
244 real*8 gndglssize,dgndglss,secondslit,dsecondslit,Dsg,lambdae
245 real*8 dist1,dist2,lngh,kernel,Pi
246 complex*8 cmI,kern(Ngg,Ns)
247 Pi=3.14159265d0
248 cmI=(0,1) !the complex number I
249
250 do i=1,Ngg
251 do j=1,Ns
252 dist1=(gndglssize/2d0-dgndglss*i) !source stand for grating
253 dist2=(secondslit/2d0-dsecondslit*j)
254 lngh=sqrt((dist1-dist2)**2d0+(Dsg)**2d0)
255 kernel=0d0
256 kernel=2d0*Pi*lngh/(lambdae)
257 kern(i,j)=cmI*dsin(kernel)+dcos(kernel)
258 enddo
259 enddo
260 write(6,*) "02"
261 return
262 end
263
264 !-----
265 subroutine
secondkernalsubroutine (kern2,Ng,Ngg,sourcesize,dsource,gndglssize,dgndglss,Dgg,lambdae)
266 implicit none
267 integer i,j,Ng,Ngg
268 real*8 sourcesize,dsource,gndglssize,dgndglss,Dgg,lambdae
269 real*8 dist1,dist2,lngh,kernel,Pi
270 complex*8 cmI,kern2(Ng,Ngg)
271 Pi=3.14159265d0
272 cmI=(0,1) !the complex number I
273
274 do i=1,Ng
275 do j=1,Ngg
276 dist1=(sourcesize/2d0-dsource*i)
277 dist2=(gndglssize/2d0-dgndglss*j)
278 lngh=sqrt((dist1-dist2)**2d0+(Dgg)**2d0)
279 kernel=0d0
280 kernel=2d0*Pi*lngh/(lambdae)
281 kern2(i,j)=cmI*dsin(kernel)+dcos(kernel)
282 enddo
283 enddo
284 write(6,*) "03"
285 return
286 end
287 !-----
288 subroutine
thirdkernalsubroutine (kern3,N1,Ng,lenssize,dlens,sourcesize,dsource,D2,lambdae)
289 implicit none
290 integer i,j,N1,Ng
291 real*8 lenssize,dlens,sourcesize,dsource,D2,lambdae
292 real*8 dist1,dist2,lngh,kernel,Pi
293 complex*8 cmI,kern3(N1,Ng)
294 Pi=3.14159265d0
295 cmI=(0,1) !the complex number I
296
297 do i=1,N1
298 do j=1,Ng
299 dist1=(lenssize/2d0-dlens*i)
300 dist2=(sourcesize/2d0-dsource*j)
301 lngh=sqrt((dist1-dist2)**2d0+(D2)**2d0)

```



```

302         kernel=0
303         kernel=2d0*Pi*lngh/ (lambdae)
304         kern3 (i,j)=cmI*dsin (kernel)+dcos (kernel)
305         enddo
306     enddo
307     write (6,*) "04"
308 return
309 end
310 !-----
311 subroutine
fourthkernal subroutine (kern4,Nscr,Nl,screen3size,dscreen3,lenssize,dlens,D3,lambda
e)
312 implicit none
313 integer i,j,Nscr,Nl
314 real*8 screen3size,dscreen3,lenssize,dlens,D3,lambdae
315 real*8 dist1,dist2,lngh,kernel,Pi
316 complex*8 cmI,kern4 (Nscr,Nl)
317 Pi=3.14159265d0
318 cmI=(0,1) !the complex number I
319
320     do i=1,Nscr
321         do j=1,Nl
322             dist1=(screen3size/2d0-dscreen3*i)
323             dist2=(lenssize/2d0-dlens*j)
324             lngh=sqrt ((dist1-dist2)**2d0+(D3)**2d0)
325             kernel=0d0
326             kernel=2d0*Pi*lngh/ (lambdae)
327             kern4 (i,j)=cmI*dsin (kernel)+dcos (kernel)
328         enddo
329     enddo
330     write (6,*) "05"
331 return
332 end
333
334 !-----
335
336
337 subroutine gratingamplitude (amp,sourcesize,dsource,Ng)
338 implicit none
339 integer numberofslits,jend,k,m,j,nn,Ng
340 real*8 x,sourcesize,dsource
341 complex*8 amp (Ng)
342 numberofslits=150 !sourcesize/d
343 jend=int (Ng/numberofslits/2)
344 do k=0,numberofslits-1
345     do m=0,1
346         do j=1,jend
347             nn=j+k*jend*2+m*jend
348             x=(sourcesize/2d0-dsource*nn)
349             amp (nn)=m !1. for pure phasegrating
350         enddo
351     enddo
352 enddo
353 return
354 end
355
356 !-----
357
358 subroutine
zerothkernel (kern0,Ns,firstslit,dfirstslit,inc,secondslit,dsecondslit,D0,lambdae)
359 implicit none
360 integer Ns,i,j,inc
361 real*8 firstslit,dfirstslit,secondslit,dsecondslit,D0,lambdae
362 real*8 kernel,dist1,dist2,lngh,Pi

```

```

363 complex*8 cmI,kern0 (Ns,1)
364 Pi=3.14159265d0
365 cmI=(0,1) !the complex number I
366 do i=1,Ns
367     do j=1,1
368         dist1=(firstslit/2d0-dfirstslit*inc)
369         dist2=(secondslit/2d0-dsecondslit*i)
370         lngh=sqrt((dist1-dist2)**2d0+(D0)**2d0)
371         kern0=0d0
372         kern0=2d0*Pi*lngh/(lambdae)
373         kern0(i,j)=cmI*dsin(kern0)+dcos(kern0)
374     enddo
375 enddo
376 return
377 end
378 !-----
379
380 subroutine wavefunction1 (Ns,kern0,phi0)
381 integer Ns,i,i2
382 complex*8 phiin(1),phi0 (Ns),phioutx
383 complex*8 kern0 (Ns,1)
384     phiin(:)=1d0
385     phi0(:)=0d0
386     write(6,*) "1"
387     do i=1,Ns
388         phioutx=0d0
389         do i2=1,1
390             phioutx=phioutx+kern0(i,i2)*phiin(i2)
391         enddo
392     phi0(i)=phioutx
393 enddo
394 return
395 end
396 !-----
397
398
399 subroutine
wavefunction2 (phi0,Ngg,Ns,kern,phigndgls,imagephase)

400 implicit none
401 integer Ngg,Ns,i,i2
402 complex*8 phi0 (Ns),phigndgls (Ngg),phioutx
403 complex*8 kern (Ngg,Ns),imagephase (Ngg)
404     phigndgls(:)=0d0
405     write(6,*) "2"
406     do i=1,Ngg
407         phioutx=0d0
408         do i2=1,Ns
409             phioutx=phioutx+kern(i,i2)*phi0(i2)
410         enddo
411     phigndgls(i)=phioutx*imagephase(i)
412     ! write(6,*) phil(i)
413     enddo
414 return
415 end
416 !-----
417
418 subroutine wavefunction3 (phigndgls,Ng,Ngg,kern2,phil,amp)
419 implicit none
420 integer Ngg,Ng,i,i2
421 complex*8 phigndgls (Ngg),phioutx,phil (Ng)
422 complex*8 kern2 (Ng,Ngg),amp (Ng)
423
424     phil(:)=0d0
425     do i=1,Ng

```

```

426         phioutx=0d0
427         do i2=1,Ngg
428             phioutx=phioutx+kern2(i,i2)*phigndgls(i2)
429         enddo
430         phil(i)=phioutx*amp(i)
431
432     enddo
433 return
434 end
435
436
437 !-----
438
439 subroutine wavefunction4(phi1,N1,Ng,kern3,phi2)
440 implicit none
441 integer N1,Ng,i,j
442 complex*8 phi2(N1),phioutx,kern3(N1,Ng),phil(Ng)
443 write(6,*) "2"
444 phi2(:)=0d0
445 do i=1,N1
446     phioutx=0d0
447     do j=1,Ng
448         phioutx=phioutx+kern3(i,j)*phil(j)
449     enddo
450     phi2(i)=phioutx
451 ! write(6,*) phi2(i)
452 enddo
453 write(6,*) "3"
454 return
455 end
456
457 !-----
458
459 subroutine wavefunction5(phi2,Nscr,N1,kern4,phiscreen)
460 implicit none
461 integer Nscr,N1,i,j
462 complex*8 phiscreen(Nscr),phi2(N1),kern4(Nscr,N1),phioutx
463
464     phiscreen(:)=0d0
465     do i=1,Nscr
466         phioutx=0d0
467         do j=1,N1
468             phioutx=phioutx+kern4(i,j)*phi2(j)
469         enddo
470         phiscreen(i)=phioutx
471     enddo
472
473     write(6,*) "4"
474 return
475 end
476
477
478 !-----
479
480
481 subroutine
482 probabilitycalculation(phiscreen,probscreen,probscreenmem,prob2,finalprob2,Nscr,N1
483 ,runnumber,inc,incend,endrun,phi2)
484 implicit none
485 integer i,Nscr,inc,incend,runnumber,N1,endrun
486 real*8 probscreen(Nscr),norm,probscreenmem(Nscr,incend)
487 complex*8 phiscreen(Nscr),phi2(N1)
488 real*8 prob2(N1),finalprob2(N1,endrun)

```

```

489     do i=1,Nscr
490         probscreen(i)=phiscreen(i)*conjg(phiscreen(i))
491     enddo
492
493     norm=0
494     do i=1,Nscr
495         norm=norm+probscreen(i)
496     enddo
497
498     write(6,*) "before"
499
500     do i=1,Nscr
501         probscreen(i)=1/norm*phiscreen(i)*conjg(phiscreen(i))
502     enddo
503
504     write(6,*) "after"
505
506     do i=1,Nscr
507         probscreenmem(i,inc)=probscreen(i)
508     enddo
509
510     !not normalized correctly
511     prob2(:)=0d0
512     do i=1,N1
513         prob2(i)=phi2(i)*conjg(phi2(i))
514     enddo
515
516
517     do i=1,N1
518         finalprob2(i,runnumber)=finalprob2(i,runnumber)+prob2(i)
519     enddo
520
521     return
522 end
523
524 !-----
525
526 subroutine
matrixcalculation(phiscreen,phi2,phi0,matrix,finalmatrix,matrix2,finalmatrix2,matr
ix3,finalmatrix3,Nscr,N1,Ns)
527 implicit none
528
529 integer i,j,Nscr,N1,Ns
530 complex*8 phiscreen(Nscr),matrix(Nscr,Nscr),finalmatrix(Nscr,Nscr)
531 complex*8 phi2(N1),matrix2(N1,N1),finalmatrix2(N1,N1)
532 complex*8 phi0(Ns),matrix3(Ns,Ns),finalmatrix3(Ns,Ns)
533
534     do i=1,Nscr
535         do j=1,Nscr
536             matrix(i,j)=phiscreen(i)*conjg(phiscreen(j))
537         enddo
538     enddo
539
540     do i=1,Nscr
541         do j=1,Nscr
542             finalmatrix(i,j)=finalmatrix(i,j)+matrix(i,j)
543         enddo
544     enddo
545
546     do i=1,N1
547         do j=1,N1
548             matrix2(i,j)=phi2(i)*conjg(phi2(j))
549         enddo
550     enddo
551

```

```

552     do i=1,Nl
553         do j=1,Nl
554             finalmatrix2(i,j)=finalmatrix2(i,j)+matrix2(i,j)
555         enddo
556     enddo
557
558     do i=1,Ns
559         do j=1,Ns
560             matrix3(i,j)=phi0(i)*conjg(phi0(j))
561         enddo
562     enddo
563
564     do i=1,Ns
565         do j=1,Ns
566             finalmatrix3(i,j)=finalmatrix3(i,j)+matrix3(i,j)
567         enddo
568     enddo
569 return
570 end
571
572 !-----
573
574 subroutine
screenincoherentsumming(Nscr,incend,inc,probscreenaverage,probscreenmem)
575 implicit none
576
577 integer i,inc,incend,Nscr
578 real*8 probscreenaverage(Nscr),probscreenmem(Nscr,incend)
579
580     probscreenaverage(:)=0d0
581     do i=1,Nscr
582         do inc=1,incend
583             probscreenaverage(i)=probscreenaverage(i)+probscreenmem(i,inc)
584         enddo
585     enddo
586 return
587 end
588
589 !-----
590
591 subroutine
writeprobabilities(Nscr,Nl,screen3size,dscreen3,probscreenaverage,runnumber,endrun
,finalprob2)
592 implicit none
593 integer i,j,Nscr,Nl,runnumber,endrun
594 real*8 position,screen3size,dscreen3
595 real*8 probscreenaverage(Nscr),finalprob2(Nl,endrun)
596
597     open(unit=12,file='PX.dat') !probability distribution
598     open(unit=13,file='probabilitydephasor.dat') !density matrix at dephasor
599
600
601     do j=1,Nscr
602         position=(screen3size/2d0-dscreen3*j)
603         write(12,666) position,probscreenaverage(j)
604     enddo
605
606     do runnumber=1,endrun
607         do i=1,Nl
608             write(13,*) runnumber, finalprob2(i,runnumber)
609         enddo
610     enddo
611
612     format(E12.6,X,E12.6) !there was a 666 there
613

```

```

614 return
615 end
616
617 !-----
618
619 subroutine writematrices (Nscr,Nl,Ns,finalmatrix,finalmatrix2,finalmatrix3)
620 implicit none
621
622 integer i,j,Nscr,Nl,Ns
623 complex*8 finalmatrix(Nscr,Nscr),finalmatrix2(Nl,Nl),finalmatrix3(Ns,Ns)
624
625 open(unit=14,file='matrixscreen.dat') !density matrix at screen
626 open(unit=15,file='matrixlens.dat') !density matrix at lens
627 open(unit=16,file='matrixsecondslit.dat')!density matrix at 2nd slit
628
629
630 do i=1,Nscr
631 do j=1,Nscr
632 write(14,667) finalmatrix(i,j)
633 enddo
634 enddo
635
636
637 do i=1,Nl
638 do j=1,Nl
639 write(15,667) finalmatrix2(i,j)
640 enddo
641 enddo
642
643 do i=1,Ns
644 do j=1,Ns
645 write(16,667) finalmatrix3(i,j)
646 enddo
647 enddo
648
649 format(E12.6,X,E12.6)
650
651 return
652 end
653
654
655 !-----
656
657
658 subroutine bubblepot (acumphase,sigma2,idum,runnumber)
659 !use msimsl
660 implicit none
661 !this program has its own random number generator to avoid
662 !using msimsl
663 integer i,endset,j,runnumber
664 parameter(endset=40000)
665 real*8 devmean,devdeviation,x1(endset),x2(endset),sigma(endset),z1(1000),z2(1000)
666 real*8 ampmean,ampdeviation,y1(endset),y2(endset),amplitude(endset)
667 real*8 Pi,phase(1000),velocity,hbar,totallength(1000),sigma2(1000)
668 integer idum
669 real*8 value
670 real*8 acumphase(1000)
671 !integer Q!,p,numofpoints(1000)
672 !parameter(Q=987654)
673 !real*8 dephasingsize,value(1000)
674 !call rnsset(Q)
675
676 open(unit=11,file='phasetest.dat') !testingthephase
677
678

```

```

679
680
681 do i=1,1000
682 acumphase(i)=0.0
683 enddo
684
685 !open(unit=12,file='random.dat')
686 hbar=6.582e-16
687 Pi=3.14159265
688 velocity=2.422E7
689
690
691 devmean=250.E-9
692 devdeviation=250.E-9
693 ampdeviation=.35
694 ampmean=0.
695
696 do i=1,1000
697 phase(i)=0.0
698 totallength(i)=0.0
699 enddo
700
701 !using the box-mueller method
702 do j=1,1000
703 do i=1,endset
704 call ran0(idum,value)
705 x1(i)=value
706 call ran0(idum,value)
707 x2(i)=value
708 call ran0(idum,value)
709 y1(i)=value
710 call ran0(idum,value)
711 y2(i)=value
712
sigma(i)=(devdeviation/(2*sqrt(2.0)))*sqrt(-2.0*log(x1(i)))*cos(2*Pi*x2(i))+d
evmean
713
amplitude(i)=(ampdeviation/(2*sqrt(2.0)))*sqrt(-2.0*log(y1(i)))*cos(2*Pi*y2(i)
)+ampmean
714 phase(j)=phase(j)+(sqrt(Pi)*abs(sigma(i))*amplitude(i)/sqrt(log(16.0)))
715 totallength(j)=totallength(j)+sigma(i)
716 enddo
717 !write(*,*) j
718 enddo
719
720 do i=1,1000
721 call ran0(idum,value)
722 z1(i)=value
723 call ran0(idum,value)
724 z2(i)=value
725
sigma2(i)=(devdeviation/(2*sqrt(2.0)))*sqrt(-2.0*log(z1(i)))*cos(2*Pi*z2(i))+
devmean
726 enddo
727
728 do i=1,1000
729 acumphase(i)=phase(i)/(velocity*hbar)
730 enddo
731 !do i=1,1000
732 ! write(12,*) acumphase(i),sigma2(i)
733 !enddo
734 if (runnumber.eq.1) then
735 do i=1,1000
736 write(11,*) acumphase(i),sigma2(i)
737 enddo

```

```

738 endif
739
740 return
741 end
742
743 !-----
744
745 subroutine randomnumberdistros(accumphase,sigma2,idum,runnumber)
746 implicit none
747 ! this is a patch subroutine that uses the output of bubblepot and sets the
748 ! fwhm of the accumulated phase as ampdeviation
749 integer i,runnumber
750 real*8 devmean,devdeviation,ampmean,ampdeviation,Pi
751 real*8 accumphase(1000),sigma2(1000),value
752 integer idum
753 real*8 x1(1000),x2(1000),y1(1000),y2(1000)
754
755 open(unit=11,file='phasetest2.dat') !testingthephase
756 devmean=250.0d-9
757 devdeviation=250.0d-9
758 ampmean=0.0d0
759 ampdeviation=1.0335d3*1.1935d0
760 Pi=3.14159265d0
761
762 do i=1,1000
763 call ran0(idum,value)
764 x1(i)=value
765 call ran0(idum,value)
766 x2(i)=value
767 call ran0(idum,value)
768 y1(i)=value
769 call ran0(idum,value)
770 y2(i)=value
771
772 sigma2(i)=(devdeviation/(2.0d0*sqrt(2.0d0)))*(sqrt(-2.0d0*log(x1(i)))*cos(2.0d0*P
i*x2(i)))+devmean
773
774 accumphase(i)=(ampdeviation/(2.0d0*sqrt(2.0d0)))*(sqrt(-2.0d0*log(x1(i)))*cos(2.0d
0*Pi*x2(i)))+ampmean
775 enddo
776
777 if (runnumber.eq.1) then
778 do i=1,1000
779 write(11,*) accumphase(i),sigma2(i)
780 enddo
781 endif
782
783 !return
784 end
785
786 !-----
787
788 subroutine ran0(idum,returnvalue)
789 implicit none
790 integer idum,ia,im,iq,ir,mask
791 real*8 returnvalue,am
792 parameter(ia=16807,im=2147483647,am=1.0d0/im)
793 parameter(iq=127773,ir=2836,mask=123459876)
794
795 integer k
796 idum=ieor(idum,mask)
797 k=idum/iq
798 idum=ia*(idum-k*iq)-ir*k
799 if(idum.lt.0) idum=idum+im
800 returnvalue=am*idum

```



```
799 idum=ieor(idum,mask)
800 return
801 end
802
```

E.2 Dephasing Path Integral Program Version 2

This is the reduced and revised version of the dephasing and decoherence path integral code, rewritten by Zilin Chen. It is based on a double-slit setup (no collimating

slits) with random potentials acting on the wave function based on a sum of random Gaussian potentials. See Chapter 5 for more details. Table D.2 outlines the parameters used in this program;

Plane Name	Width	# of Grid-Points	Section Between	Azimuthal Length
Source	15 μm	1500	Source & Double Slit	$L_1 = 24 \text{ cm}$
Double Slit Screen	500 nm	1000	Dephaser / Decoherer & Double Slit	0 cm
Dephaser / Decoherer	500 nm	1000	Double Slit & Far Field	$L_2 = 24 \text{ cm}$
Distance btw. Slits	150 nm	300		
Slit Width	50	100		
Far Field	800 μm	1500		

Table E.2: Parameters for Path Integral Simulation Setup 2

```

1  PROGRAM Dephaser
2  !includes incoherent summing at first slit
3  ! phaseslope, phasestep can be set at a value, the amp can be turned on and
   off
4  !use msimsl
5  !turned off dephas
6
7  implicit none
8
9  integer Nsource,Nin,Nout,Ndet,endrun,p,q,r,Nx,idum
10 integer blksum,blknuml,blknum,blknumm !if block exceed range,block number
   will be changed
11 parameter (Nsource=1500,Nin=1000,Nout=1000,Ndet=1500,endrun=500,blknum=2)
12
13 integer blkwid(blknum),blkwidl !the first one is for grating, the second one
   is for source
14 real* ee,Pi,h,hbar,c,d,a,me,Energy,gam,ve,lambdae
15 real* source,dsource,phiin,dphiin,phiout,dphiout
16 real* Dsd,Dds,dephase,image(Nin,endrun),delx,w
17 real* screen,dscreen
18 complex* kern2(Ndet,Nout),kern(Nin,Nsource),decfactor(Nin)
19 complex* amp(Nin)
20 complex* cmI,imagephase(Nin)
21 complex* wavephidet(Ndet),wavephiin(Nin),wavephiout(Nout)
22 real* probscreenmem(Ndet,endrun)
23 integer runnumber
24
25
26 real* dephasingsize
27 !call rnset(Q)
28 dephasingsize=0.7d0
29
30
31 idum=6
32
33
34 ee=1.6d-19
35 Pi=3.14159265d0
36 h=6.626d-34
37 hbar=h/2d0/Pi
38 c=3.d8
39
40
41 d=150d-9 !periodicity of grating
42 a=50d-9 !slit width of grating
43
44 me=9.11d-31
45 Energy=1670d0*ee+me*c*c
46 gam=Energy/(me*c*c)
47 ve=sqrt(1d0-1d0/(gam*gam))*c
48 lambdae=h/(gam*me*ve)
49 write(6,*) "The gamma factor is ",gam
50 write(6,*) "The electron velocity is ",ve
51
52 source=15d-6
53 write(6,*) "The source is ",source, " wide."
54 screen=8d-4
55 write(6,*) "The screen is ",screen, " wide."
56 dephase=0.5d-6
57 write(6,*) "the dephasor ",dephase," wide"
58
59 phiin=dephase
60 phiout=dephase
61
62 dsource=source/Nsource

```

```

63     dscreen=screen/Ndet
64     dphiin=phiin/Nin
65     dphiout=phiout/Nout
66
67     delx=0.25d0*a !shift of gaussian
68     w=2d0*a !width of gaussian
69
70     blknum1=1 !separate source into 25 parts
71     blkwid1=Nsource/blknum1 !make sure it is an integer
72     Nx=idmint(dephase/(delx))!this is how many gaussians are separated on the
73     grating,if want to close decoherer, make it 1.
74     Nx=1
75
76     Dsd=.24d0 !distanace from the source to the dephasor
77     write(6,*) "The distance from the source to dephasor is ",Dsd
78
79     Dds=.24d0 !distance from the dephasor to the detectorscreen
80     write(6,*) "The distance from the dephasor to the detectorscreen is ",Dds
81
82     cmI=(0,1) !the complex number I
83
84     ! The next subroutines sets up the path integral kernels
85     write(6,*) "01"
86
87     call
88     firstkernalsubroutine(kern,Nin,Nsource,phiin,dphiin,source,dsource,Dsd,lambdae)
89     call
90     secondkernalsubroutine(kern2,Ndet,Nout,screen,dscreen,phiout,dphiout,Dds,lambda
91     e)
92
93     ! The next subroutine sets up the amplitude at the grating
94     call gratingamplitude(amp,phiin,Nin,d,a)
95     call gratingwrite(amp,Nin,phiin,dphiin)
96
97
98     do runnumber=1,endrunc
99     wavephiin(:)=0d0
100    probscreenmem(:,runnumber)=0d0
101
102    !-----random widthblock on grating -----
103    !this routine create random with block
104    call randomblock(idum,blknum,blknumm,Nin,blkwid)!if close blocked
105    source, make the blkwid very big
106
107
108    !-----smooth phase-----!choose one of these
109    potential
110    call
111    smoothpotential(dephasingsize,idum,Nin,image,imagephase,runnumber,endrunc)
112
113    !-----
114
115    write(6,*) "grating block number is",blknumm
116
117    do q=1,blknum1
118
119    !This routine propogates from the source to the place right
120    before grating
121    write(6,*) "source block no.",q
122
123    call wavefunctional(Nin,Nsource,kern,wavephiin,q,blkwid1)
124    !plot wavephiin
125    call plotwavephiin(Nin,wavephiin)

```

```

120 !-----tiltphase potential ----- !choose one of these
potential
121 !create tilt potential in each block
122 !call
tiltphase(idum,imagephase,image,Nin,runnumber,endrun,blknum,blknum
m,blkwid)
123 !write phase to check
124 call phasewrite(endrun,Nin,image)
125 !dephasor
126 call dephasor(wavephiin,Nin,imagephase,Nsource)
127 !grating
128
129 call grating(wavephiin,Nin,amp)
130
131
132 !There starts the decoherent loop
133 !-----start of decoherence loop-----
134 !wavephiout will change in every loop
135
136
137 do r=1,Nx
138 write(6,*) r,Nx,q,blknum1
139 blksum=0 !this number is accumulating blockwidth
140 do p=1,blknumm
141 call decohereregulator(Nin,dephase,defactor,r,dex,w)
142
143 call
decohere(defactor,wavephiout,wavephiin,Nin,Nout)!to
cancel decoherer, you need go into this route and
comment out defactor
144 !The next routine propagates from after the grating to
the detector
145 call plotwavephiout(Nout,wavephiout)
146 call
wavefunction2(Ndet,Nout,kern2,wavephiout,wavephidet,p,blkw
id,blksum,blknum)
147
148 !the probability is calculated next
149 call
probabilitycalculation(wavephidet,probscreenmem,Ndet,runnu
mber,endrun)
write(6,*) 'block ',p
enddo
write(6,*) blksum
enddo !close decoherence loop
enddo
write(6,*) 'end of runnumber',runnumber
157
158
159 enddo
160 !next write data to file
161 call writeprobabilities(probscreenmem,Ndet,endrun)
162
163
164 format(E20.6,X,E20.6) !there was a 666 there
165 format(E20.6,X,E20.6)
166
167 END
168
169
170
171
172
173

```

```

174
175 !-----
176
177 subroutine
firstkernalsubroutine (kern,Nin,Nsource,phiin,dphiin,source,dsource,Dsd,lambdae)
178 implicit none
179 integer i,j,Nin,Nsource
180 real*8 phiin,dphiin,Dsd,lambdae
181 real*8 dist1,dist2,lngh,kernel,Pi,source,dsource
182 complex*8 cmI,kern(Nin,Nsource)
183 Pi=3.14159265d0
184 cmI=(0d0,1d0) !the complex number I
185
186
187 do i=1,Nin
188 do j=1,Nsource
189 dist1=phiin/2d0-dphiin*i+dphiin/2d0 !checked
190 dist2=source/2d0-dsource*(j)+dsource/2d0 !source !checked
191 !write(6,*) 'the coordinates of',j,' source point is ',dist2
192 lngh=sqrt((dist1-dist2)**2d0+(Dsd)**2d0)
193 !write(6,*) 'the length of source',j,' to phiin',i,' is',lngh
194 kernel=2d0*Pi*lngh/(lambdae)
195 !write(6,*) i,'to',j, kernel
196 kern(i,j)=cmI*dsin(kernel)+dcos(kernel)
197 !write(6,*) j,' to ',i, real(kern(i,j)),imag(kern(i,j))
198 enddo
199 !write(6,*) 'the coordinates of',i,' phiin point is ',dist1
200 enddo
201 write(6,*) "02"
202 return
203 end
204
205 !-----
206
207 subroutine
secondkernalsubroutine (kern2,Ndet,Nout,screen,dscreen,phiout,dphiout,Dds,lambdae)
208 implicit none
209 integer i,j,Nout,Ndet
210 real*8 screen,dscreen,phiout,dphiout,Dds,lambdae
211 real*8 dist1,dist2,lngh,kernel,Pi
212 complex*8 cmI,kern2(Ndet,Nout)
213 Pi=3.14159265d0
214 cmI=(0d0,1d0) !the complex number I
215
216
217 do i=1,Ndet
218 do j=1,Nout
219 dist1=(screen/2d0-dscreen*i+dscreen/2d0)
220 dist2=(phiout/2d0-dphiout*j+dphiout/2d0)
221 lngh=sqrt((dist1-dist2)**2d0+(Dds)**2d0)
222 kernel=2d0*Pi*lngh/(lambdae)
223 kern2(i,j)=cmI*dsin(kernel)+dcos(kernel)
224 enddo
225 enddo
226 write(6,*) "03"
227 return
228 end
229
230 !-----
231
232 subroutine gratingamplitude (amp,phiin,Nin,d,a)
233 implicit none
234 integer hfdist,hfsltwid,Nin,j
235 real*8 a,d,phiin
236 complex*8 amp(Nin)

```

```

237     amp(:)=0
238
239     hfdist=idnint(d/phiin/2*Nin)
240     hfsltwid=idnint(a/phiin/2*Nin)
241
242
243
244     do j=(Nin/2-hfdist)-hfsltwid, (Nin/2-hfdist)+hfsltwid
245         amp(j)=1
246     enddo
247     do j=(Nin/2+hfdist)-hfsltwid, (Nin/2+hfdist)+hfsltwid
248         amp(j)=1
249     enddo
250
251
252     return
253 end
254
255
256 !-----
257 !modified grating to remove unsymmetric phenomenon
258
259 ! subroutine gratingamplitude (amp,Nin)
260 ! implicit none
261 ! integer jend,k,m,j,nn,Nin
262 ! complex*8 amp(Nin)
263
264     ! jend=25
265     ! do k=0,199
266         ! do m=0,1
267             ! do j=1,jend
268                 ! nn=j+k*jend*2+m*jend
269
270                 ! amp(nn)=m
271             ! enddo
272         ! enddo
273     ! enddo
274     ! do j=1,jend
275         ! nn=j+10000
276         ! amp(nn)=0d0
277     ! enddo
278 ! return
279 ! end
280 !-----
281 subroutine gratingwrite(amp,Nin,phiin,dphiin)
282 implicit none
283 integer Nin,i
284 real*8 phiin,dphiin
285 complex*8 amp(Nin)
286
287 open(unit=15,file='grating.dat')
288 do i=1,Nin
289     write(15,666) (phiin/2d0-dphiin*i), Real(amp(i))
290 enddo
291 format(E20.6,X,E20.6)
292 close(15)
293
294 return
295 end
296
297
298 !-----
299
300 subroutine phasewrite(endrun,Nin,image)
301 integer i,runnumber,Nin,endrun

```

```

302 real*8 image(Nin, endrun)
303
304 open(unit=14, file='phase.dat')
305 do runnumber=1, endrun
306   do i=1, Nin
307     write(14, *) runnumber, image(i, runnumber)
308   enddo
309 enddo
310   format(E20.6, X, E20.6)
311 close(14)
312
313 return
314 end
315
316 !-----
317
318 subroutine wavefunction1(Nin, Nsource, kern, wavephiin, q, blkwid1)
319 implicit none
320 integer Nin, Nsource, i, i2, q, blkwid1
321 complex*8 wavephiin(Nin), phisource(Nsource)
322 complex*8 kern(Nin, Nsource), phiinsum
323   phisource(:)=1d0
324   wavephiin(:)=0d0
325   write(6, *) "1"
326
327   do i=1, Nin
328     phiinsum=0d0
329     do i2=(q-1)*blkwid1+1, q*blkwid1
330       phiinsum=phiinsum+kern(i, i2)*phisource(i2)
331       !write(6, *) i2, 'to', i, kern(i, i2)
332     enddo
333     wavephiin(i)=phiinsum
334     !write(6, *) wavephiin(i)
335   enddo
336 return
337 end
338
339 !-----
340 subroutine plotwavephiin(Nin, wavephiin)
341 implicit none
342 integer Nin, i
343 real*8 phiin_probability(Nin)
344 complex*8 wavephiin(Nin)
345   do i=1, Nin
346     phiin_probability(i)=wavephiin(i)*conjg(wavephiin(i))
347   enddo
348 open(unit=18, file='wavephiin.dat')
349   do i=1, Nin
350     write(18, 666) real(wavephiin(i)), phiin_probability(i)
351   enddo
352   format(E20.6, X, E20.6)
353 close(18)
354
355 return
356 end
357
358
359
360 !-----
361 subroutine dephasor(wavephiin, Nin, imagephase, Nsource)
362 implicit none
363 integer i, Nin, Nsource
364 complex*8 wavephiin(Nin), imagephase(Nsource)
365   do i=1, Nin
366     wavephiin(i)=wavephiin(i)*imagephase(i)

```



```

367     enddo
368 return
369 end
370
371
372 !-----
373
374 subroutine grating(wavephiin,Nin,amp)
375 implicit none
376 integer Nin,i
377 complex*8 wavephiin(Nin),amp(Nin)
378 do i=1,Nin
379     wavephiin(i)=wavephiin(i)*amp(i)
380     !write(6,*) wavephiout(i)
381 enddo
382
383
384
385 return
386 end
387 !-----
388 subroutine decohereregenerator(Nin,dephase,decfactor,r,dex,w)
389 implicit none
390 integer Nin,i,r
391 real*8 A,w,Pi,l,dephase,dex
392 complex*8 decfactor(Nin)
393
394 Pi=3.14159265d0
395
396 A=dex/sqrt(w*Pi)
397
398 l=dephase/Nin
399
400
401 do i=1,Nin
402     !if (dexp(-(((i-1)*l-r*w/10)/w)**2).le.1d-6) then
403
404     decfactor(i)=A*dexp(-(((i-1)*l-r*dex)/w)**2)
405
406 enddo
407
408
409
410
411
412 return
413 end
414 !-----
415 subroutine decohere(decfactor,wavephiout,wavephiin,Nin,Nout)
416 implicit none
417 integer i,Nin,Nout
418 complex*8 wavephiin(Nin),wavephiout(Nout),decfactor(Nin)
419
420
421
422
423 do i=1,Nout
424     wavephiout(i)=wavephiin(i)!*decfactor(i)!comment out decfactor to cancel
425     decoherer
426     !write(6,*) wavephiout(i)
427 enddo
428
429
430

```

```

431
432 return
433 end
434 !-----
435 !plot the wave right after the grating
436 subroutine plotwavephiout(Nout,wavephiout)
437 implicit none
438 integer Nout,i
439 real*8 phiout_probability(Nout)
440 complex*8 wavephiout(Nout)
441 do i=1,Nout
442   phiout_probability(i)=wavephiout(i)*conjg(wavephiout(i))
443 enddo
444
445   open(unit=17,file='wavephiout.dat')
446   do i=1,Nout
447     write(17,666) Imag(wavephiout(i)), phiout_probability(i)
448   enddo
449   format(E20.6,X,E20.6)
450   close(17)
451
452 return
453 end
454
455
456
457 !-----
458 subroutine randomblock(idum,blknum,blknumm,Nin,blkwid)
459 implicit none
460 integer idum,Nin,blknum,i,blknumm
461 integer blkwid(blknum),blkwidsum
462 real*8 returnvalue,Pi,y1,x1,x2
463 blkwidsum=0
464 blkwid(:)=0
465 Pi=3.14159265d0
466
467 do i=1,blknum-1
468   !this is box muller method
469   call ran0(idum,returnvalue)
470   x1=returnvalue
471   call ran0(idum,returnvalue)
472   x2=returnvalue
473   y1=dsqrt(-2.0d0*dlog(x1))*dcos(2.0d0*Pi*x2)
474   !y2=dsqrt(-2.0d0*dlog(x1))*dsin(2.0d0*Pi*x2)
475   blkwid(i)=idnint((300.0d0*y1)+20000.0d0)
476   blkwidsum=blkwidsum+blkwid(i)
477   !in case of blocks exceed the width of grating
478   if (blkwidsum.ge.Nin) then
479     blkwidsum=blkwidsum-blkwid(i)
480     blknumm=i
481     exit
482   endif
483   !write(6,*) blkwid(i)
484   ! write(28,*) amplitude(i), x0(i), sigma(i)
485 enddo
486   blkwid(blknumm)=Nin-blkwidsum !the rest points will form the last block
487   write(6,*) blkwid
488
489
490 return
491 end
492 !-----
493
494 subroutine
tiltphase(idum,imagephase,image,Nin,runnumber,endrun,blknum,blknumm,blkwid)

```

```

495 implicit none
496 integer idum,p,i,Nin,runnumber,endrun,blknum,blknumm,blkwid(blknum),x,blkwidsum
497 real*8 k(blknum),image(Nin,endrun),returnvalue,center
498 complex*8 imagephase(Nin),cmI
499
500 cmI=(0d0,1d0)      !the complex number I
501 blkwidsum=0
502 do i=1,blknumm
503   call ran0(idum,returnvalue)
504   k(i)=(-8d-1)*returnvalue+4d-1
505   write(6,*) returnvalue !slope
506 enddo
507
508 do p=1,blknumm
509   do i=blkwidsum+1,blkwidsum+blkwid(p)
510     center=(blkwid(p)+1)/2
511     x=i-blkwidsum !so it starts from 1 again
512     image(i,runnumber)=(x-center)*k(p)
513     imagephase(i)=cmI*dsin(image(i,runnumber))+dcos(image(i,runnumber))
514   enddo
515   blkwidsum=blkwidsum+blkwid(p)
516 enddo
517
518 write(6,*) "tiltphase is created"
519 return
520 end
521
522 !-----
523
524 subroutine
525 smoothpotential(dephasingsize,idum,Nin,image,imagephase,runnumber,endrun)
526 implicit none
527 integer Ngauss,idum,runnumber,endrun
528 parameter(Ngauss=500)
529 integer Nin,i,j,x0(Ngauss)
530 real*8 dephasingsize,image(Nin,endrun),Pi,returnvalue,amplitude(Ngauss)
531 real*8 x1,x2,y1,sigma(Nin),sumimage(Nin),maxsum
532 complex*8 imagephase(Nin),cmI
533 Pi=3.14159265d0
534 cmI=(0,1)      !the complex number I
535
536 do i=1,Nin
537   sumimage(i)=0d0
538 enddo
539
540 !open(unit=28,file='debug.dat') !phase written
541
542 do i=1,Ngauss
543   call ran0(idum,returnvalue)
544   amplitude(i)=dephasingsize*2.0d0*Pi*returnvalue
545   call ran0(idum,returnvalue)
546   x0(i)=idnint(returnvalue*Nin)
547
548   call ran0(idum,returnvalue)
549   x1=returnvalue
550   call ran0(idum,returnvalue)
551   x2=returnvalue
552   y1=dsqrt(-2.0d0*dlog(x1))*dcos(2.0d0*Pi*x2)
553   !y2=dsqrt(-2.0d0*dlog(x1))*dsin(2.0d0*Pi*x2)
554   sigma(i)=(1d0*y1)+8d0
555   ! write(28,*) amplitude(i), x0(i), sigma(i)
556 enddo
557
558 do i=1,Ngauss

```

```

559   do j=1,Nin
560       sumimage(j)=sumimage(j)+amplitude(i)*dexp(-((j-x0(i))/(dsqrt(2.0d0)*sigma(i))) *
          *2)
561   enddo
562 enddo
563
564 !find the maximum value of sumimage
565 maxsum=sumimage(1)
566 do i=1,Nin-1
567   if (maxsum.le.sumimage(i+1)) then
568     maxsum=sumimage(i+1)
569   endif
570 enddo
571
572 do j=1,Nin
573   image(j,runnumber)=sumimage(j)*dephasingsize*2*Pi
574   imagephase(j)=cmI*dsin(image(j,runnumber))+dcos(image(j,runnumber))
575 enddo
576
577 return
578 end
579 !-----
580
581 subroutine
wavefunction2(Ndet,Nout,kern2,wavephiout,wavephidet,p,blkwid,blksum,blknum)

582 implicit none
583 integer Ndet,Nout,i,i2,p,blknum,blkwid(blknum),blksum
584 complex*8 phidetsum
585 complex*8 kern2(Ndet,Nout),wavephidet(Ndet),wavephiout(Nout)
586
587
588
589   wavephidet(:)=0d0
590   write(6,*) "2"
591   do i=1,Ndet
592     phidetsum=0d0
593     do i2=blksum+1,blksum+blkwid(p)
594       phidetsum=phidetsum+kern2(i,i2)*wavephiout(i2)
595     enddo
596     wavephidet(i)=phidetsum
597     !write(6,*) wavephiout(i)
598   enddo
599   blksum=blksum+blkwid(p)
600 return
601 end
602
603 !-----
604
605 subroutine probabilitycalculation(wavephidet,probscreenmem,Ndet,runnumber,endrun)
606 implicit none
607 integer i,Ndet,runnumber,endrun
608 real*8 probscreen(Ndet),norm,probscreenmem(Ndet,endrun)
609 complex*8 wavephidet(Ndet)
610   probscreen(:)=0d0
611   do i=1,Ndet
612     probscreen(i)=wavephidet(i)*conjg(wavephidet(i))
613   enddo
614
615   norm=0d0
616   do i=1,Ndet
617     norm=norm+probscreen(i)
618   enddo
619   write(6,*) norm

```

```

620     write(6,*) "before"
621
622     do i=1,Ndet
623         probscreen(i)=(1/norm)*probscreen(i)
624     enddo
625
626     write(6,*) "after"
627
628     do i=1,Ndet
629         probscreenmem(i,runnumber)=probscreen(i)+probscreenmem(i,runnumber)
630     enddo
631
632
633     return
634 end
635
636 !-----
637
638 subroutine writeprobabilities(probscreenmem,Ndet,endrun)
639 implicit none
640 integer i,Ndet,runnumber,endrun
641 real*8 probscreenmem(Ndet,endrun)
642
643 open(unit=13,file='probabilitydetector.dat') !probability on detector
644 do runnumber=1,endrun
645     do i=1,Ndet
646         write(13,*) runnumber, probscreenmem(i,runnumber)
647     enddo
648 enddo
649 format(E20.6,X,E20.6) !there was a 666 there
650
651 close(13)
652
653 return
654 end
655
656 !-----
657
658 subroutine ran0(idum,returnvalue)
659 implicit none
660 integer idum,ia,im,iq,ir,mask
661 real*8 returnvalue,am
662 parameter(ia=16807,im=2147483647,am=1.0d0/im)
663 parameter(iq=127773,ir=2836,mask=123459876)
664
665 integer k
666 idum=ieor(idum,mask)
667 k=idum/iq
668 idum=ia*(idum-k*iq)-ir*k
669 if(idum.lt.0) idum=idum+im
670 returnvalue=am*idum
671 idum=ieor(idum,mask)
672 return
673 end
674
675
676
677 !-----

```

E.3 Decoherence Path Integral Program Version 2

This is the revised and reduced version of the decoherence path integral code, written by Zilin Chen. It is based on a double-slit setup (no collimating slits) with an

incoherent summing of Gaussians at the grating with random potentials acting on the wave function identical to that of D.3. See Chapter 5 for more details

```

1      PROGRAM Decoherer
2      !includes incoherent summing at first slit
3      ! phaseslope, phasestep can be set at a value, the amp can be turned on and
      off
4      !use msimsl
5      !turned off dephas
6
7      implicit none
8
9      integer Nsource,Nin,Nout,Ndet,endrun,p,q,r,Nx,idum
10     integer blksum,blknum1,blknum,blknumm !if block exceed range,block number
      will be changed
11     parameter (Nsource=1500,Nin=1000,Nout=1000,Ndet=1500,endrun=1,blknum=2)
12
13     integer blkwid(blknum),blkwid1 !the first one is for grating, the second one
      is for source
14     real*8 ee,Pi,h,hbar,c,d,a,me,Energy,gam,ve,lambdae
15     real*8 source,dsource,phiin,dphiin,phiout,dphiout
16     real*8 Dsd,Dds,dephase,image(Nin,endrun),delx,w
17     real*8 screen,dscreen
18     complex*8 kern2(Ndet,Nout),kern(Nin,Nsource),decfactor(Nin)
19     complex*8 amp(Nin)
20     complex*8 cmI,imagephase(Nin)
21     complex*8 wavephidet(Ndet),wavephiin(Nin),wavephiout(Nout)
22     real*8 probscreenmem(Ndet,endrun)
23     integer runnumber
24
25
26     real*8 dephasingsize
27     !call rnsset(Q)
28     dephasingsize=0.7d0
29
30
31     idum=5
32
33
34     ee=1.6d-19
35     Pi=3.14159265d0
36     h=6.626d-34
37     hbar=h/2d0/Pi
38     c=3.d8
39
40
41     d=150d-9 !periodicity of grating
42     a=50d-9 !slit width of grating
43
44     me=9.11d-31
45     Energy=1670d0*ee+me*c*c
46     gam=Energy/(me*c*c)
47     ve=sqrt(1d0-1d0/(gam*gam))*c
48     lambdae=h/(gam*me*ve)
49     write(6,*) "The gamma factor is ",gam
50     write(6,*) "The electron velocity is ",ve
51
52     source=15d-6
53     write(6,*) "The source is ",source, " wide."
54     screen=8d-4
55     write(6,*) "The screen is ",screen, " wide."
56     dephase=0.5d-6
57     write(6,*) "the dephaser ",dephase," wide"
58
59     phiin=dephase
60     phiout=dephase
61
62     dsource=source/Nsource

```

```

63     dscreen=screen/Ndet
64     dphiin=phiin/Nin
65     dphiout=phiout/Nout
66
67     delx=0.25d0*a !shift of gaussian
68     w=2d0*a !width of gaussian
69
70     blknum1=1 !seperate source into 25 parts
71     blkwid1=Nsource/blknum1 !make sure it is an integer
72     Nx=idnint(dephase/(delx))!this is how many gaussians are on the grating
73
74
75     Dsd=.24d0 !distanace from the source to the dephasor
76     write(6,*) "The distance from the source to dephasor is ",Dsd
77
78     Dds=.24d0 !distance from the dephasor to the detectorscreen
79     write(6,*) "The distance from the dephasor to the detectorscreen is ",Dds
80
81     cmI=(0,1) !the complex number I
82
83 ! The next subroutines sets up the path integral kernels
84 write(6,*) "01"
85
86 call
87 firstkernelsubroutine (kern,Nin,Nsource,phiin,dphiin,source,dsource,Dsd,lambdae)
88 call
89 secondkernelsubroutine (kern2,Ndet,Nout,screen,dscreen,phiout,dphiout,Dds,lambda
90 e)
91
92 ! The next subroutine sets up the amplitude at the grating
93 call gratingamplitude (amp,phiin,Nin,d,a)
94 call gratingwrite (amp,Nin,phiin,dphiin)
95
96
97
98 do runnumber=1,endrun
99     wavephiin(:)=0d0
100     probscreenmem(:,runnumber)=0d0
101
102 !-----random widthblock on grating -----
103 !this routine create random with block
104 call randomblock (idum,blknum,blknumm,Nin,blkwid)
105
106 !-----smooth phase-----!choose one of these
107 potential
108 call
109 smoothpotential (dephasingsize,idum,Nin,image,imagephase,runnumber,endrun)
110
111 !-----
112
113 write(6,*) "grating block number is",blknumm
114
115 do q=1,blknum1
116     !This routine propogates from the source to the place right
117     !before grating
118     write(6,*) "source block no.",q
119     call wavefunction1 (Nin,Nsource,kern,wavephiin,q,blkwid1)
120     !plot wavephiin
121     call plotwavephiin (Nin,wavephiin)
122 !-----tiltphase potential ----- !choose one of these
123 potential

```

```

121         !create tilt potential in each block
122         !call
            tiltphase(idum,imagephase,image,Nin,runnumber,endrun,blknum,blknum
            m,blkwid)
123         !write phase to check
124         call phasewrite(endrun,Nin,image)
125         !dephasor
126         call dephasor(wavephiin,Nin,imagephase,Nsource)
127         !grating
128
129         call grating(wavephiin,Nin,amp)
130
131
132     !There starts the decoherent loop
133     !-----start of decoherence loop-----
134     !wavephiout will change in every loop
135
136
137         do r=1,Nx
138             write(6,*) r,Nx,q,blknum1
139             blksum=0 !this number is accumulating blockwidth
140             do p=1,blknumm
141                 call decoheregenerator(Nin,dephase,decfactor,r,delx,w)
142
143                 call decohere(decfactor,wavephiout,wavephiin,Nin,Nout)
144                 !The next routine propagates from after the grating to
                    the detector
145                 call plotwavephiout(Nout,wavephiout)
146                 call
                    wavefunction2(Ndet,Nout,kern2,wavephiout,wavephidet,p,blk
                    id,blksum,blknum)
147
148                 !the probability is calculated next
149                 call
                    probabilitycalculation(wavephidet,probscreenmem,Ndet,runnu
                    mber,endrun)
150                 write(6,*) 'block ',p
151             enddo
152             write(6,*) blksum
153         enddo !close decoherence loop
154     enddo
155
156     write(6,*) 'end of runnumber',runnumber
157
158
159     enddo
160     !next write data to file
161     call writeprobabilities(probscreenmem,Ndet,endrun)
162
163
164     format(E20.6,X,E20.6) !there was a 666 there
165     format(E20.6,X,E20.6)
166
167     END
168
169
170
171
172
173
174
175     !-----
176
177     subroutine
        firstkernalsubroutine(kern,Nin,Nsource,phiin,dphiin,source,dsource,Dsd,lambdae)

```



```

178 implicit none
179 integer i,j,Nin,Nsource
180 real*8 phiin,dphiin,Dsd,lambdae
181 real*8 dist1,dist2,lng,h,kernel,Pi,source,dsource
182 complex*8 cmI,kern(Nin,Nsource)
183 Pi=3.14159265d0
184 cmI=(0d0,1d0) !the complex number I
185
186
187 do i=1,Nin
188 do j=1,Nsource
189 dist1=phiin/2d0-dphiin*i+dphiin/2d0 !checked
190 dist2=source/2d0-dsource*(j)+dsource/2d0 !source !checked
191 !write(6,*) 'the coordinates of',j,' source point is ',dist2
192 lngh=sqrt((dist1-dist2)**2d0+(Dsd)**2d0)
193 !write(6,*) 'the length of source',j,' to phiin',i,' is',lngh
194 kernel=2d0*Pi*lngh/(lambdae)
195 !write(6,*) i,'to',j, kernel
196 kern(i,j)=cmI*dsin(kernel)+dcos(kernel)
197 !write(6,*) j,' to ',i, real(kern(i,j)),imag(kern(i,j))
198 enddo
199 !write(6,*) 'the coordinates of',i,' phiin point is ',dist1
200 enddo
201 write(6,*) "02"
202 return
203 end
204
205 !-----
206
207 subroutine
208 secondkernalsubroutine(kern2,Ndet,Nout,screen,dscreen,phiout,dphiout,Dds,lambdae)
209 implicit none
210 integer i,j,Nout,Ndet
211 real*8 screen,dscreen,phiout,dphiout,Dds,lambdae
212 real*8 dist1,dist2,lng,h,kernel,Pi
213 complex*8 cmI,kern2(Ndet,Nout)
214 Pi=3.14159265d0
215 cmI=(0d0,1d0) !the complex number I
216
217 do i=1,Ndet
218 do j=1,Nout
219 dist1=(screen/2d0-dscreen*i+dscreen/2d0)
220 dist2=(phiout/2d0-dphiout*j+dphiout/2d0)
221 lngh=sqrt((dist1-dist2)**2d0+(Dds)**2d0)
222 kernel=2d0*Pi*lngh/(lambdae)
223 kern2(i,j)=cmI*dsin(kernel)+dcos(kernel)
224 enddo
225 enddo
226 write(6,*) "03"
227 return
228 end
229
230 !-----
231
232 subroutine gratingamplitude(amp,phiin,Nin,d,a)
233 implicit none
234 integer hfdist,hfsltwid,Nin,j
235 real*8 a,d,phiin
236 complex*8 amp(Nin)
237 amp(:)=0
238
239 hfdist=idnint(d/phiin/2*Nin)
240 hfsltwid=idnint(a/phiin/2*Nin)
241

```

```

242
243
244     do j=(Nin/2-hfdist)-hfsltwid, (Nin/2-hfdist)+hfsltwid
245         amp(j)=1
246     enddo
247     do j=(Nin/2+hfdist)-hfsltwid, (Nin/2+hfdist)+hfsltwid
248         amp(j)=1
249     enddo
250
251
252 return
253 end
254
255
256 !-----
257 !modified grating to remove unsymmetric phenomenon
258
259 ! subroutine gratingamplitude (amp,Nin)
260 ! implicit none
261 ! integer jend,k,m,j,nn,Nin
262 ! complex*8 amp(Nin)
263
264     ! jend=25
265     ! do k=0,199
266         ! do m=0,1
267             ! do j=1,jend
268                 ! nn=j+k*jend*2+m*jend
269
270                 ! amp(nn)=m
271             ! enddo
272         ! enddo
273     ! enddo
274     ! do j=1,jend
275         ! nn=j+10000
276         ! amp(nn)=0d0
277     ! enddo
278 ! return
279 ! end
280 !-----
281 subroutine gratingwrite(amp,Nin,phiin,dphiin)
282 implicit none
283 integer Nin,i
284 real*8 phiin,dphiin
285 complex*8 amp(Nin)
286
287 open(unit=15,file='grating.dat')
288     do i=1,Nin
289         write(15,666) (phiin/2d0-dphiin*i), Real(amp(i))
290     enddo
291     format(E20.6,X,E20.6)
292 close(15)
293
294 return
295 end
296
297
298 !-----
299
300 subroutine phasewrite(endrun,Nin,image)
301 integer i,runnumber,Nin,endrun
302 real*8 image(Nin,endrun)
303
304 open(unit=14,file='phase.dat')
305 do runnumber=1,endrun
306     do i=1,Nin

```

```

307         write(14,*) runnumber, image(i,runnumber)
308     enddo
309 enddo
310     format(E20.6,X,E20.6)
311 close(14)
312
313 return
314 end
315
316 !-----
317
318 subroutine wavefunction1(Nin,Nsource,kern,wavephiin,q,blkwid1)
319 implicit none
320 integer Nin,Nsource,i,i2,q,blkwid1
321 complex*8 wavephiin(Nin),phisource(Nsource)
322 complex*8 kern(Nin,Nsource),phiinsum
323     phisource(:)=1d0
324     wavephiin(:)=0d0
325     write(6,*) "1"
326
327     do i=1,Nin
328         phiinsum=0d0
329         do i2=(q-1)*blkwid1+1,q*blkwid1
330             phiinsum=phiinsum+kern(i,i2)*phisource(i2)
331             !write(6,*) i2,'to',i,kern(i,i2)
332         enddo
333         wavephiin(i)=phiinsum
334         !write(6,*) wavephiin(i)
335     enddo
336 return
337 end
338
339 !-----
340 subroutine plotwavephiin(Nin,wavephiin)
341 implicit none
342 integer Nin,i
343 real*8 phiin_probability(Nin)
344 complex*8 wavephiin(Nin)
345     do i=1,Nin
346         phiin_probability(i)=wavephiin(i)*conjg(wavephiin(i))
347     enddo
348 open(unit=18,file='wavephiin.dat')
349     do i=1,Nin
350         write(18,666) real(wavephiin(i)), phiin_probability(i)
351     enddo
352     format(E20.6,X,E20.6)
353 close(18)
354
355 return
356 end
357
358
359 !-----
360
361 subroutine dephasor(wavephiin,Nin,imagephase,Nsource)
362 implicit none
363 integer i,Nin,Nsource
364 complex*8 wavephiin(Nin),imagephase(Nsource)
365     do i=1,Nin
366         wavephiin(i)=wavephiin(i)*imagephase(i)
367     enddo
368 return
369 end
370
371

```

```

372 !-----
373
374 subroutine grating(wavephiin,Nin,amp)
375 implicit none
376 integer Nin,i
377 complex*8 wavephiin(Nin),amp(Nin)
378 do i=1,Nin
379     wavephiin(i)=wavephiin(i)*amp(i)
380     !write(6,*) wavephiout(i)
381 enddo
382
383
384
385 return
386 end
387 !-----
388 subroutine decohereregenerator(Nin,dephase,decfactor,r,dexl,w)
389 implicit none
390 integer Nin,i,r
391 real*8 A,w,Pi,l,dephase,dexl
392 complex*8 decfactor(Nin)
393
394 Pi=3.14159265d0
395
396 A=dexl/sqrt(w*Pi)
397
398 l=dephase/Nin
399
400
401 do i=1,Nin
402     !if (dexp(-(((i-1)*l-r*w/10)/w)**2).le.1d-6) then
403
404         decfactor(i)=A*dexp(-(((i-1)*l-r*dexl)/w)**2)
405
406 enddo
407
408
409
410
411
412 return
413 end
414 !-----
415 subroutine decohere(decfactor,wavephiout,wavephiin,Nin,Nout)
416 implicit none
417 integer i,Nin,Nout
418 complex*8 wavephiin(Nin),wavephiout(Nout),decfactor(Nin)
419
420
421
422
423 do i=1,Nout
424     wavephiout(i)=wavephiin(i)*decfactor(i)
425     !write(6,*) wavephiout(i)
426 enddo
427
428
429
430
431
432 return
433 end
434 !-----
435 !plot the wave right after the grating
436 subroutine plotwavephiout(Nout,wavephiout)

```

```

437 implicit none
438 integer Nout,i
439 real*8 phiout_probability(Nout)
440 complex*8 wavephiout(Nout)
441   do i=1,Nout
442     phiout_probability(i)=wavephiout(i)*conjg(wavephiout(i))
443   enddo
444
445   open(unit=17,file='wavephiout.dat')
446     do i=1,Nout
447       write(17,666) Imag(wavephiout(i)), phiout_probability(i)
448     enddo
449     format(E20.6,X,E20.6)
450   close(17)
451
452 return
453 end
454
455
456
457 !-----
458 subroutine randomblock(idum,blknum,blknumm,Nin,blkwid)
459 implicit none
460 integer idum,Nin,blknum,i,blknumm
461 integer blkwid(blknum),blkwidsum
462 real*8 returnvalue,Pi,y1,x1,x2
463 blkwidsum=0
464 blkwid(:)=0
465 Pi=3.14159265d0
466
467 do i=1,blknum-1
468   !this is box muller method
469   call ran0(idum,returnvalue)
470   x1=returnvalue
471   call ran0(idum,returnvalue)
472   x2=returnvalue
473   y1=dsqrt(-2.0d0*dlog(x1))*dcos(2.0d0*Pi*x2)
474   !y2=dsqrt(-2.0d0*dlog(x1))*dsin(2.0d0*Pi*x2)
475   blkwid(i)=idnint((300.0d0*y1)+20000.0d0)
476   blkwidsum=blkwidsum+blkwid(i)
477   !in case of blocks exceed the width of grating
478   if (blkwidsum.ge.Nin) then
479     blkwidsum=blkwidsum-blkwid(i)
480     blknumm=i
481     exit
482   endif
483   !write(6,*) blkwid(i)
484   ! write(28,*) amplitude(i), x0(i), sigma(i)
485 enddo
486   blkwid(blknumm)=Nin-blkwidsum !the rest points will form the last block
487   write(6,*) blkwid
488
489
490 return
491 end
492 !-----
493
494 subroutine
495 tiltphase(idum,imagephase,image,Nin,runnumber,endrun,blknum,blknumm,blkwid)
496 implicit none
497 integer idum,p,i,Nin,runnumber,endrun,blknum,blknumm,blkwid(blknum),x,blkwidsum
498 real*8 k(blknum),image(Nin,endrun),returnvalue,center
499 complex*8 imagephase(Nin),cmI
500 cmI=(0d0,1d0) !the complex number I

```

```

501 blkwidsum=0
502 do i=1,blknumm
503   call ran0(idum,returnvalue)
504   k(i)=(-8d-1)*returnvalue+4d-1
505   write(6,*) returnvalue !slope
506 enddo
507
508 do p=1,blknumm
509   do i=blkwidsum+1,blkwidsum+blkwid(p)
510     center=(blkwid(p)+1)/2
511     x=i-blkwidsum !so it starts from 1 again
512     image(i,runnumber)=(x-center)*k(p)
513     imagephase(i)=cmI*dsin(image(i,runnumber))+dcos(image(i,runnumber))
514   enddo
515   blkwidsum=blkwidsum+blkwid(p)
516 enddo
517
518 write(6,*) "tiltphase is created"
519 return
520 end
521
522 !-----
523
524 subroutine
525 smoothpotential(dephasingsize,idum,Nin,image,imagephase,runnumber,endrun)
526 implicit none
527 integer Ngauss,idum,runnumber,endrun
528 parameter(Ngauss=500)
529 integer Nin,i,j,x0(Ngauss)
530 real*8 dephasingsize,image(Nin,endrun),Pi,returnvalue,amplitude(Ngauss)
531 real*8 x1,x2,y1,sigma(Nin),sumimage(Nin),maxsum
532 complex*8 imagephase(Nin),cmI
533 Pi=3.14159265d0
534 cmI=(0,1) !the complex number I
535
536 do i=1,Nin
537   sumimage(i)=0d0
538 enddo
539
540 !open(unit=28,file='debug.dat') !phase written
541
542 do i=1,Ngauss
543   call ran0(idum,returnvalue)
544   amplitude(i)=dephasingsize*2.0d0*Pi*returnvalue
545   call ran0(idum,returnvalue)
546   x0(i)=idnint(returnvalue*Nin)
547
548   call ran0(idum,returnvalue)
549   x1=returnvalue
550   call ran0(idum,returnvalue)
551   x2=returnvalue
552   y1=dsqrt(-2.0d0*dlog(x1))*dcos(2.0d0*Pi*x2)
553   !y2=dsqrt(-2.0d0*dlog(x1))*dsin(2.0d0*Pi*x2)
554   sigma(i)=(1d0*y1)+8d0
555   ! write(28,*) amplitude(i), x0(i), sigma(i)
556 enddo
557
558 do i=1,Ngauss
559   do j=1,Nin
560     sumimage(j)=sumimage(j)+amplitude(i)*dexp(-(j-x0(i))/(dsqrt(2.0d0)*sigma(i)))*
561     *2)
562   enddo
563 enddo

```

```

563
564 !find the maximum value of sumimage
565 maxsum=sumimage(1)
566 do i=1,Nin-1
567   if (maxsum.le.sumimage(i+1)) then
568     maxsum=sumimage(i+1)
569   endif
570 enddo
571
572 do j=1,Nin
573   image(j,runnumber)=sumimage(j)*dephasingsize*2*Pi
574   imagephase(j)=cmI*dsin(image(j,runnumber))+dcos(image(j,runnumber))
575 enddo
576
577 return
578 end
579 !-----
580
581 subroutine wavefunction2(Ndet,Nout,kern2,wavephiout,wavephidet,p,blkwid,blksum,blknum)
582 implicit none
583 integer Ndet,Nout,i,i2,p,blknum,blkwid(blknum),blksum
584 complex*8 phidetsum
585 complex*8 kern2(Ndet,Nout),wavephidet(Ndet),wavephiout(Nout)
586
587
588
589 wavephidet(:)=0d0
590 write(6,*) "2"
591 do i=1,Ndet
592   phidetsum=0d0
593   do i2=blksum+1,blksum+blkwid(p)
594     phidetsum=phidetsum+kern2(i,i2)*wavephiout(i2)
595   enddo
596   wavephidet(i)=phidetsum
597   !write(6,*) wavephiout(i)
598 enddo
599 blksum=blksum+blkwid(p)
600 return
601 end
602
603 !-----
604
605 subroutine probabilitycalculation(wavephidet,probscreenmem,Ndet,runnumber,endrun)
606 implicit none
607 integer i,Ndet,runnumber,endrun
608 real*8 probscreen(Ndet),norm,probscreenmem(Ndet,endrun)
609 complex*8 wavephidet(Ndet)
610 probscreen(:)=0d0
611 do i=1,Ndet
612   probscreen(i)=wavephidet(i)*conjg(wavephidet(i))
613 enddo
614
615 norm=0d0
616 do i=1,Ndet
617   norm=norm+probscreen(i)
618 enddo
619 write(6,*) norm
620 write(6,*) "before"
621
622 do i=1,Ndet
623   probscreen(i)=(1/norm)*probscreen(i)
624 enddo
625

```

```

626     write(6,*) "after"
627
628     do i=1,Ndet
629         probscreenmem(i,runnumber)=probscreen(i)+probscreenmem(i,runnumber)
630
631     enddo
632
633     return
634 end
635
636 !-----
637
638 subroutine writeprobabilities(probscreenmem,Ndet,endrun)
639 implicit none
640 integer i,Ndet,runnumber,endrun
641 real*8 probscreenmem(Ndet,endrun)
642
643 open(unit=13,file='probabilitydetector.dat') !probability on detector
644 do runnumber=1,endrun
645     do i=1,Ndet
646         write(13,*) runnumber, probscreenmem(i,runnumber)
647     enddo
648 enddo
649 format(E20.6,X,E20.6) !there was a 666 there
650
651 close(13)
652
653 return
654 end
655
656 !-----
657
658 subroutine ran0(idum,returnvalue)
659 implicit none
660 integer idum,ia,im,iq,ir,mask
661 real*8 returnvalue,am
662 parameter(ia=16807,im=2147483647,am=1.0d0/im)
663 parameter(iq=127773,ir=2836,mask=123459876)
664
665 integer k
666 idum=ieor(idum,mask)
667 k=idum/iq
668 idum=ia*(idum-k*iq)-ir*k
669 if(idum.lt.0)idum=idum+im
670 returnvalue=am*idum
671 idum=ieor(idum,mask)
672 return
673 end
674
675
676
677 !-----
678

```


E.4 Matlab Code for Entropy Calculation

```

%Entropy Calculation
%Author: Peter Beierle
%Last modified:7/6/2016

for i=1:numel(VarName1)
    element(i)=VarName1(i)+sqrt(-1)*VarName2(i);
end

matrix=zeros(1500,1500);
for i=1:1500
    for j=1:1500
        gogo=(j-1)*1500+i;
        matrix(j,i)=element(gogo);
    end
end

totalprob=0;
for i=1:1500
    totalprob=totalprob+matrix(i,i);
end

matrix=matrix/totalprob;

for i=1:1500
    probability(i)=matrix(i,i);
end
%plot(probability)

values=eig(matrix);

eigenmatrix=zeros(1500,1500);
for i=1:1500
    eigenmatrix(i,i)=values(i);
end

logvalues=(log(values));

diagonalloggedmatrix=zeros(1500,1500);
for i=1:1500
    diagonalloggedmatrix(i,i)=logvalues(i);
end

%product=matrix*diagonalloggedmatrix;
product=eigenmatrix*diagonalloggedmatrix;

entropy=0;
for i=1:1500

```

```
entropy=entropy+product(i,i);  
end  
entropy
```

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E.5 Matlab Code for Correlation Calculation

```

%written by peter beierle
%last revised 09.08.2016
%testing correlation of fields equation
clc;
pi=3.14159265;
x1=rand(1,1);
x1prime=rand(1,1);

x2=rand(1,1);
x2prime=rand(1,1);

lambda=1;
i=sqrt(-1);
n=10000;
phiR1=rand(n,1)*2*pi;
phiR2=rand(n,1)*2*pi;

E1star_x1prm=exp(-i*phiR1)*exp(-i*2*pi*x1prime/lambda);
E2star_x2prm=exp(-i*phiR2)*exp(-i*2*pi*x2prime/lambda);
E1_x1=exp(i*phiR1)*exp(i*2*pi*x1/lambda);
E2_x2=exp(i*phiR2)*exp(i*2*pi*x2/lambda);

E1star_x1=exp(-i*phiR1)*exp(-i*2*pi*x1/lambda);
E1_x1prm=exp(i*phiR1)*exp(i*2*pi*x1prime/lambda);

E2star_x2=exp(-i*phiR2)*exp(-i*2*pi*x2/lambda);
E2_x2prm=exp(i*phiR2)*exp(i*2*pi*x2prime/lambda);

left=sum(E1star_x1prm.*E2star_x2prm.*E1_x1.*E2_x2)/n
%right1 is from Incoherent Coincidence Imaging... PRL (2004)
right1=(sum(E1star_x1.*E1_x1prm)*sum(E2star_x2.*E2_x2prm)/(n*n))+sum(E1star_x1.*E2_x2prm)*sum(E2star_x2.*E1_x1prm)/(n*n)
%right2 is from J.W. Goodman's Statistical Optics
right2=(sum(E1star_x1prm.*E1_x1)*sum(E2star_x2prm.*E2_x2)/(n*n))+sum(E1star_x1prm.*E2_x2)*sum(E2star_x2prm.*E1_x1)/(n*n)

left =

    0.7179 + 0.6951i

right1 =

    0.7180 - 0.6962i

right2 =

    0.7180 + 0.6962i

```

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List of Figures

Chapter 1: Introduction

- 1.1. Double Slit Diffraction: Wave Interference vs Classical Distribution3
- 1.2. Double Slit Experiment with Classical Bullets5

Chapter 2: Theory

- 2.1. Image Charge Configuration12
- 2.2. Coherent Interference between Two States17
- 2.3. Far Field Double-slit Interference Pattern for Various Visibility Values21
- 2.4. Schematic of Collimated Diffraction22
- 2.5. Comparison between Visibility and Normalized Transverse Coherence Length26
- 2.6. Original Electron-Surface Decoherence Model from Anglin and Zurek34
- 2.7. Surface Dependence on Decoherence due to Vacuum Field Fluctuations36

Chapter 3: Optical Electron Switch

- 3.1. Fast Electron Rectification Switch Concept43
- 3.2. Experimental Setup for Surface Optical-Electron Switch.45
- 3.3. Electron-Optical Switch Speed47
- 3.4. Beam Deflection as a Function of Distance Between the Electron Beam and the Surface48
- 3.5. Change in Beam Deflection Angle as a Function of the Lateral Position (x) of the Laser Focus49
- 3.6. “Uncoated” Deflection Measurement50

Chapter 4: Decoherence Experiment

- 4.1. Experimental Setup56
- 4.2. Analysis of Diffractogram59
- 4.3. Transverse Coherence Length for a Silicon Surface62
- 4.4. Transverse Coherence Length for a Gold Surface63

Chapter 5: Dephasing vs Decoherence

- 5.1 Diagram of Dephaser/Decoherer Path Integral Setup 168
- 5.2. Step-wise Defined Random Phase used in Dephaser69
- 5.3. Far Field Intensity Pattern After Dephasing/Decoherence Path Integral Simulation 172
- 5.4. Ghost Imaging Experiment by Rui-Feng et al74
- 5.5 Dephasing vs Decoherence for the Case of the Double Slit75
- 5.6. Representative Diagram of Dephasing and Decoherence at the Double Slit77

5.7. Example Intensity Distributions in Far Field after Dephasing/Decoherence for Path Integral Setup 2.....	78
5.8. Effects of Applying the Correlation Function $g^{(2)}(x,-x)$	79
Chapter 6 Conclusion and Outlook	
6.1. Illustration of the Functional form of the Decoherence Factor	84
Appendix A: Matlab Code for Decoherence Experiment Analysis	
A.1. Flowchart of Experimental Decoherence Image Analysis	90
A.2. Visualization of the Loss of Contrast	99
Appendix C: Theoretical Method for Classical Beam Propagation and Calculation of Transverse Coherence Length	
C.1. Classical Simulation in the Y-Z Plane	120
C.2. Evolution of Density Matrix when Propagating over the Surface	122
C.3. Deconvolution of a Partial Coherent (Mixed) State by a Series of Coherent (Pure) States	124
C.4. Reduction of Coherence Elements in the Density Matrix and Corresponding Decrease in Coherence Length	125
C.5. Flowchart of Fortran Code for Classical Beam Propagation and Coherence Propagation	126
Appendix D: Surfaces & Grating; Mount Design and Prep	
D.1. Schematic of First Surface/Grating Mount	141
D.2. Preparation Image of Gold Surface and Grating in Mount	141
D.3. In-Vacuum Image of Surface/Grating Mount	142
D.4. Second Mount Schematic of Surface	143
D.5. Out of Chamber Images of Surface Mount	143
D.6. Top View of Surface Mount and Grating Mount	144
D.7. Effects of Dust on Surface	145
D.8. Uncleaned Silicon and Gold Samples	146
D.9. Image of RCA cleaned Si Surfaces	147
D.10. Diffractogram Image for the case of Silicon	149
D.11. Collimated Grating-Lens System	153
D.12. Lensing Diagnostic Map	159
List of Tables	
Appendix E: Programs for Dephasing vs Decoherence	
E.1. Parameters for Path Integral Simulation Setup 1	155
E.2. Parameters for Path Integral Simulation Setup 2	170